

Online Help



**TDSHT3
HDMI Compliance Test Software**

077-0024-01

Adapted from TDSHT3 HDMI Compliance Test Software Online Help,
Version 3.0.1

www.tektronix.com

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Table of Contents

| | |
|---|-----------|
| About the TDSHT3 HDMI Compliance Test Software | 1 |
| Introduction | 3 |
| Conventions | 3 |
| Feedback..... | 3 |
| Updates through the Web Site..... | 4 |
| Getting Started..... | 5 |
| Compatibility | 5 |
| Recommended Accessories | 5 |
| Requirements and Restrictions..... | 6 |
| Default Layouts and Templates..... | 6 |
| Default Settings..... | 8 |
| How to Use the Software..... | 11 |
| Error Codes | 18 |
| Operating Basics | 23 |
| Software View..... | 23 |
| General Purpose Knob | 34 |
| Enable Remote Control of Test Equipment..... | 34 |
| Configure New IP Address for GPIB-ENET | 39 |
| Remote Control Caution..... | 43 |
| Remote GPIB Commands | 46 |
| Dialog Boxes | 48 |
| How to..... | 53 |
| Calculate Tbit..... | 53 |
| Deskew | 55 |

| | |
|--|------------|
| Select Which Tests to Run | 57 |
| Configure | 59 |
| Connect | 63 |
| View Waveform | 110 |
| Test | 124 |
| Measurement Algorithms | 255 |
| Software CRU Technology | 255 |
| Test Methods | 261 |
| Source | 261 |
| Sink | 270 |
| Cable | 275 |
| Report Generator | 277 |
| About Report Generator | 277 |
| How to Start Report Generator | 277 |
| Shortcut Keys | 278 |
| How to Operate Report Generator | 279 |
| Template Editor | 279 |
| Report Layout Editor | 317 |
| Report Viewer | 334 |
| How to | 344 |
| Report Generator Error Codes | 352 |

About the TDSHT3 HDMI Compliance Test Software

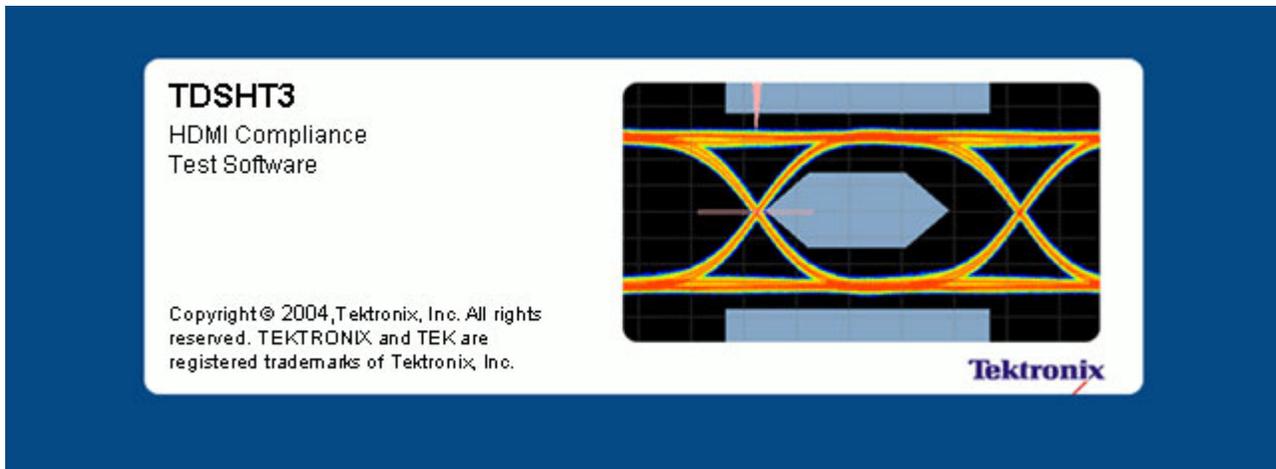


Figure 1: TDSHT3 HDMI Compliance Test Software

The TDSHT3 HDMI Compliance Test Software is a High Definition Multimedia Interface (HDMI) compliance test solution. This software helps the test, validation, and design engineers perform both HDMI physical layer validation and compliance testing. The TDSHT3 HDMI Compliance Test Software provides credible test results in conformance with the HDMI standards and test specifications.

The TDSHT3 HDMI Compliance Test Software offers automated tests for:

- **Source**
 - Clock-Data Tests: Eye Diagram (Test ID 7-10), Duty Cycle (Test ID 7-8), Rise Time (Test ID 7-4), Fall Time (Test ID 7-4), Clock Jitter (Test ID 7-9), Over/Undershoot V-H (Test ID 7-5), Over/Undershoot V-L (Test ID 7-5), Inter-Pair Skew (Test ID 7-6)
 - Data-Data Tests: Inter-Pair Skew (Test ID 7-6)
 - Single-Ended Tests: Intra-Pair Skew (Test ID 7-7), Low Amplitude + (Test ID 7-2), Low Amplitude - (Test ID 7-2)

Sink

- Differential Tests: Min/Max-Diff Swing Tolerance (Test ID 8-5), Jitter Tolerance (Test ID 8-7)
- Single-Ended Tests: Intra-Pair Skew (Test ID 8-6)

Cable

- Differential Tests: Eye Diagram (Test ID 5-3)

The software offers automatic 'one-button' testing that ensures faster validation with higher reliability.

The software supports only single-link HDMI device resolutions.

Introduction

Conventions

This document uses the following conventions:

- When steps require a sequence of selections by using the software interface, the '>' delimiter marks each transition between a menu and an option, for example, **File > Minimize**.
- Commands, button names, menu names, and dialog box names are indicated with bold font and title case. For example, Click **Open** from the shortcut menu.
- Device under Test (DUT) refers to the HDMI Source, Sink, or Cable being tested.
- Two or more adjacent hyperlinks are separated by '|.'

The software uses the following convention:

- Three dots '...' next to any command means that the command opens a dialog box, which requires input.

Feedback

Tektronix values your feedback on our products. To help us serve you better, please send us your suggestions, ideas, or comments on the TDSHT3 HDMI Compliance Test Software.

Direct your feedback via e-mail to **HDMIFeedback@tek.com** or FAX at **(503) 627-5695** and include the following information. Please be as specific as possible.

General information

- Instrument model number and hardware options, if any
- Probes used
- Your name, company, mailing address, phone number, FAX number, e-mail id

- Please indicate if you would like to be contacted by Tektronix about your suggestions or comments

Program specific information

- Software version number
- Description of the problem such that technical support can duplicate the problem
- The instrument setup file of the oscilloscope and the application are also required to identify the problem
- If possible, save the waveform on which you are performing the test as a .wfm file

***Note:** To know the software version number, click **Help** > **About** in the software.*

Once you have gathered this information, you can contact technical support by e-mail. When you use e-mail, be sure to type in the subject line 'TDSHT3 HDMI Compliance Test Software Problem,' and then attach the .wfm files. You can then attach the file to your e-mail (depending on the capabilities of your e-mail editor).

Updates through the Web Site

Periodic software upgrades may be available.

To check for upgrades:

1. Go to the Tektronix Web site (www.tektronix.com).
2. Click **Software and Drivers** to link to the **Software and Firmware Finder** Web page.
3. Enter the product name 'TDSHT3 HDMI Compliance Test Software' to find available software upgrades.



Getting Started

Compatibility

For information on oscilloscope compatibility, refer to the *Optional Applications Software on Windows-Based Oscilloscopes Installation Manual*, Tektronix part number 071-1888-XX. The manual is also available as a PDF file.

Recommended Accessories

Supported Probes

- P7350 - 5 GHz differential probe
- P7350SMA – 5 GHz differential probe
- P7330 - 4 GHz differential probe
- P6330 - 4 GHz differential probe
- P7380 - 8 GHz differential probe
- P7240 - 4 GHz single-ended probe

Supported Test Fixtures

- HDMI TPA-P-DI
- HDMI TPA-P-SE
- HDMI TPA-P-TDR
- HDMI-TPA-R-DI
- HDMI-TPA-R-SE
- HDMI-TPA-R-TDR

Requirements and Restrictions

Do not change the oscilloscope settings when the test runs. If you change the settings when the test runs, the software may give abnormal test results.

Prerequisites

- TekVisa must be installed on the oscilloscope. If you do not have TekVisa, you can download it from <http://www.tek.com/site/sw/search/1,1058,,00.html>
- If the signal is not connected and the noise level is less than 50 mV, then the software detects and displays a message such as 'Improper Waveform.'

For better and reliable results

- Before you run any test, calibrate the probes and oscilloscope for Signal Path Compensation.*
- If the signal is not connected and the noise level is less than 50 mV, then the software detects and gives a message such as 'Invalid Signal.'

* To calibrate an oscilloscope, on the oscilloscope menu bar, click **Utilities** > **Instrument Calibration**, and then click **Calibrate**.

Default Layouts and Templates

Templates under C:\TekApplications\TDSHT3\ReportGenerator\Templates

Source Clock-Data Tests

- Source_Clock_Data_Eye.rgt
- Source_Clock_Data_Jitter.rgt
- Source_Clock_Data_Max_Duty_Cycle.rgt
- Source_Clock_Data_Min_Duty_Cycle.rgt
- Source_Clock_Data_Clock_Overshoot_VH+.rgt
- Source_Clock_Data_Clock_Undershoot_VH-.rgt
- Source_Clock_Data_Data_Overshoot_VH+.rgt
- Source_Clock_Data_Data_Undershoot_VH-.rgt
- Source_Clock_Data_Clock_Overshoot_VL-.rgt

- Source_Clock_Data_Clock_Undershoot_VL+.rgt
- Source_Clock_Data_Data_Overshoot_VL-.rgt
- Source_Clock_Data_Data_Undershoot_VL+.rgt
- Source_Clock_Data_Clock_Rise_Time.rgt
- Source_Clock_Data_Data_Rise_Time.rgt
- Source_Clock_Data_Clock_Fall_Time.rgt
- Source_Clock_Data_Data_Fall_Time.rgt
- Source_Clock_Data_Inter_Pair_Skew.rgt

Source Data-Data Tests

Source_Data_Data_Inter_Pair_Skew.rgt

Source Single-Ended Tests

- Source_SingleEnded_Intra_Pair_Skew.rgt
- Source_SingleEnded_Low_Amplitude+.rgt
- Source_SingleEnded_Low_Amplitude-.rgt

Cable

- Cable_EyeDiagram_Eye_TP1.rgt
- Cable_EyeDiagram_Jitter_TP1.rgt
- Cable_EyeDiagram_Eye_TP2.rgt
- Cable_EyeDiagram_Jitter_TP2.rgt

Sink Tests

- Sink_Min_Diff_Swing_Vol.rgt
- Sink_Max_Diff_Swing_Vol.rgt
- Sink_Intra_Pair_Skew.rgt
- Sink_Jitter_Tol.rgt

Layouts under C:\TekApplications\TDSHT3\ReportGenerator\Layouts

- Sink.rpl
- Source.rpl
- Cable.rpl
- Source_Clock_Data_Over_Undershoot_VH.rpl
- Source_Clock_Data_Over_Undershoot_VL.rpl

Default Settings

Table 1: Default Settings

| Parameter | Selection | Default Setting |
|----------------------|-----------------|---|
| Select | | |
| | Flow Controls | Select |
| | Device Type Tab | Source (Clock-Data Tests) |
| | Source Test | Eye Diagram |
| | Sink Test | Min/Max-Diff Swing Tolerance (Differential) |
| | Cable Test | Eye Diagram |
| | | |
| Source Configuration | | |
| | Clock Input | Ch1 |
| | Data Input | Ch2 |
| | | |
| CRU | | |
| | Clock | PLL |
| | | |
| Others | | |
| | Ref Level Units | Percentage |
| | | |
| Clock/Data Selection | | |
| | Clock | Ch1 |
| | Data | Ch2 |

Table 1: Default Settings (Contd.)

| Parameter | Selection | Default Setting |
|--------------------|--------------------------|--|
| Sink Configuration | | |
| | DTG file path | C:\TekApplications\TDSHT3\Patterns\TEST5-3 EyeDiagram 1920X1081i 60Hz Gray RGB.dtg |
| | Clock output from DTG | A1 |
| | Data0 output from DTG | B1 |
| | Data1 output from DTG | B2 |
| | Data2 output from DTG | C1 |
| | | |
| Signal Sources | | |
| | Signal Sources Tab | DTG AWG Unavailable |
| | Control Type | GPIB |
| | Board Type | GPIB0 |
| | GPIB Address (Primary) | 1 |
| | GPIB Address (Secondary) | 0 |
| | | |
| View Waveform | | |
| | Clock/Data Waveforms | |
| | | |
| Result Summary | | |
| | View Jitter Plot | Unavailable |
| | View Eye Plot | Unavailable |
| | | |
| Result Details | | |
| | View Jitter Plot | Unavailable |
| | View Eye Plot | Unavailable |
| | Result Statistics | Unavailable |

Table 1: Default Settings (Contd.)

| Parameter | Selection | Default Setting |
|---------------------------|--------------------------|---|
| Deskew | | |
| | External | From Input Setup - Input - Ch1 |
| | | From Input Setup - Hysteresis - 10% |
| | | From Input Setup - Ref Level - 50% |
| | | To Input Setup - Input - Ch2 |
| | | To Input Setup - Hysteresis - 10% |
| | | To Input Setup - Ref Level - 50% |
| | | Slope - Rise |
| | | Slope - # of Slopes - 1 |
| | Internal | From Input Setup - Input - Ch1 |
| | | To Input Setup - Input - Ch2 |
| | | Slope - Rise |
| Report Generator | | |
| | Generate Report Tab | Select Report - C:\TekApplications\TDSHT3\ReportGenerator\Layouts\Source.rpl |
| | Define Report Layout Tab | Edit Report Layout - C:\TekApplications\TDSHT3\ReportGenerator\Layouts\Source_Clock_Data_Eye_Diagram.rpl |
| | Define Test Template Tab | C:\TekApplications\TDSHT3\ReportGenerator\Templates\Source_Clock_Data_Eye.rgt |
| Report Configuration pane | | |
| | Pair (CK, D) | Data0 |
| | Resolution | 1920*1080i |
| | Refresh Rate | 60Hz |
| | Report File | C:\TekApplications\TDSHT3\ReportGenerator\Layouts |
| | Enable Preview | Selected |
| | | |
| Report Configuration | | |

Table 1: Default Settings (Contd.)

| Parameter | Selection | Default Setting |
|-----------|--|-----------------|
| Advanced | | |
| | Device ID | TDSHT3 - 001 |
| | Device Details | HDMI Device |
| | Pair (Single-Ended) | Data0 |
| | Pair (D, D) | Data0 - Data1 |
| | Use oscilloscope settings for image report | Selected |

How to Use the Software

How to Start the Software

When you start the software, a warning message box may appear.



Figure 2: Warning Message box

This happens due to the following reasons:

- 1. Oscilloscope bandwidth is less than 4 GHz.** For higher resolution HDMI signals, you need at least a 4 GHz oscilloscope. Your oscilloscope bandwidth is less than 4 GHz. You cannot measure less than 1 ns Tbit signals accurately.
- 2. Serial Pattern Trigger option is not available.** Source Intra-pair skew test requires serial trigger (Option ST) but it is not found in the oscilloscope. You cannot perform the Source intra-pair skew test.
- 3. Maximum available record length for two channels is less than 16 M.** For HDMI compliance testing, you need at least 16 M record length in two channels. This is available with Option 4 M or above, but it is not available

in the installed oscilloscope. The software runs the eye and jitter measurements with the maximum available record length.

Depending on the type of oscilloscope that you have, you can start the software in different ways.

1. For supported B series oscilloscopes, select **App > HDMI Compliance Test Software**.



Figure 3: Run Application (for B-series oscilloscopes)

2. For TDS7000 series oscilloscopes, select **File > Run Application > HDMI Compliance Test Software**.

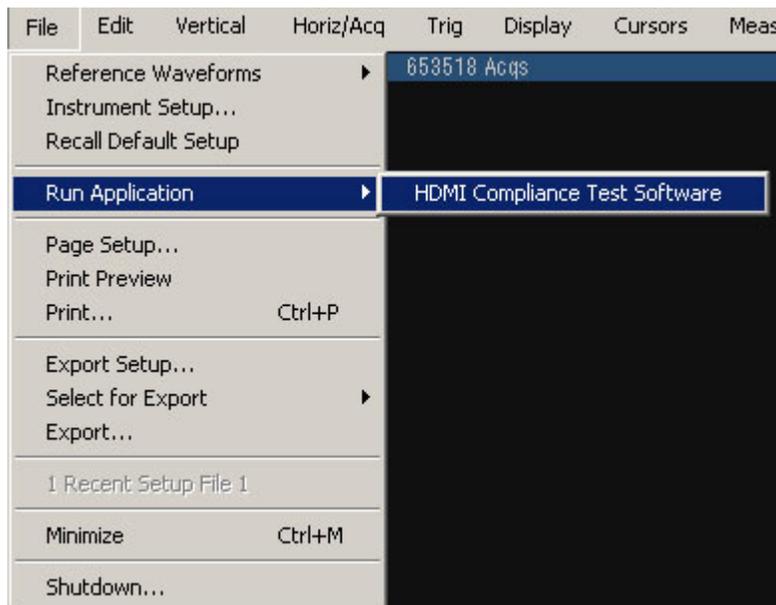


Figure 4: Run Application (for 7000-series oscilloscopes)

3. For DPO70000 series and DSA70000 oscilloscopes, select **Analyze > HDMI Compliance Test Software**.



Figure 5: Run Application (for DPO70000/DSA70000-series oscilloscopes)

4. A splash screen indicates that the software loading is in progress.

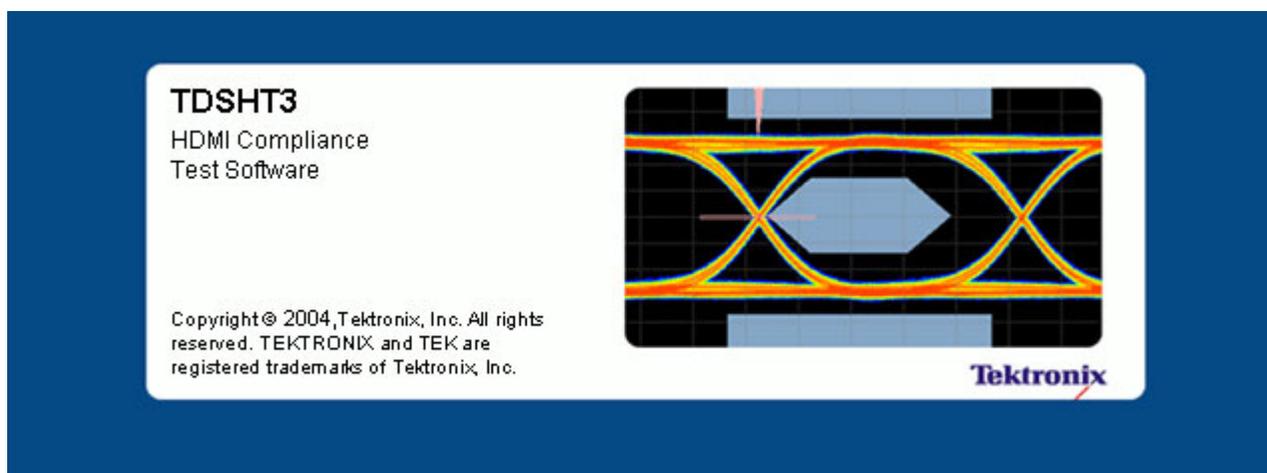


Figure 6: Splash screen indicating software loading in progress

5. The oscilloscope display resizes to fit in the upper part of the screen. The lower part of the oscilloscope screen displays the TDSHT3 HDMI Compliance Test Software.

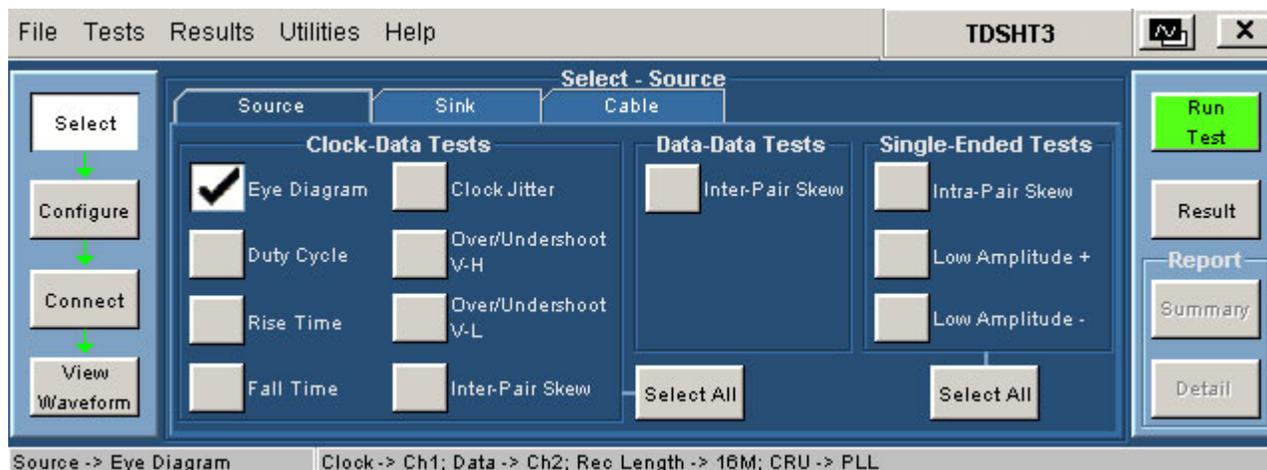


Figure 7: Application Interface

6. The software is automatically set to its default settings.
7. If you gain access to the oscilloscope functions, then the oscilloscope display appears full screen and the TDSHT3 HDMI Compliance Test Software recedes to the background.
8. To return to the TDSHT3 HDMI Compliance Test Software, click **APP** on the top right of the oscilloscope display.

How to Minimize and Maximize the Software

The software appears even when you minimize the oscilloscope display.

- To minimize the window, click **File > Minimize**. The TDSHT3 HDMI Compliance Test Software window minimizes to the Windows taskbar. The upper part of the screen has the oscilloscope display and the lower part of the screen has the desktop.
- To restore the minimized window to its previous size, click its taskbar button.
- To hide the window, click **Hide** on the top-right of the software window.

*Note: If you click **Hide**, the TDSHT3 HDMI Compliance Test Software window goes to the background and the oscilloscope fills the display.*

How to Return to the Software

When you gain access to the oscilloscope functions, the oscilloscope fills the display. You can gain access to the oscilloscope functions in the following ways:

- Choose either the menu bar or the toolbar mode on the oscilloscope, and then gain access to the menus.
- Click **App > Restore Application** for B series, click **Analyze > Restore Application** for DPO70000/DSA70000 series, or click **APP** on the top right of the TDS7000 series oscilloscope display to return to the software.

How to Exit the Software

To quit the software:

- On the menu bar, click **File > Exit**.
- The **Exit** dialog box appears.

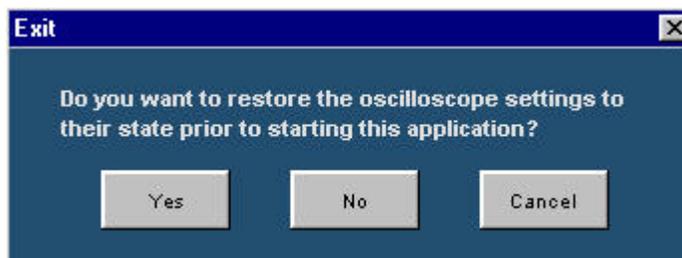


Figure 8: Exit dialog box

- Click either **Yes**, **No**, or **Cancel**. **Yes** is selected by default. When the software runs, it automatically changes some oscilloscope settings. When you quit the software, you can choose whether to retain these settings or restore the previous settings.

***Note:** Using other methods to quit the software may result in an abnormal termination of the software.*

Software Folders and File Names

The TDSHT3 HDMI Compliance Test Software uses file name extensions to identify the file type. The following table lists the default folder names and their purpose:

Table 2: Software Folders and File Names

| Folder | Purpose |
|--|--|
| C:\TekApplications\TDSHT3 | This is the software data folder. |
| C:\TekApplications\TDSHT3\Temp | This folder stores the software intermediate files. |
| C:\TekApplications\TDSHT3\Images | This folder stores all the images. |
| C:\TekApplications\TDSHT3\Data | This folder stores all the software data. |
| C:\TekApplications\TDSHT3\setup | This folder stores all the save and recall files. |
| C:\TekApplications\TDSHT3\Demo Tools | This folder stores the demo waveforms. |
| C:\TekApplications\TDSHT3\Report Generator | This folder stores the report generator files, layouts, and templates. |

Shortcut Keys

Table 3: Shortcut Keys

| Menu | Shortcut Key |
|----------------------------------|--------------|
| File | Alt+F |
| Tests | Alt+T |
| Results | Alt+R |
| Utilities | Alt+U |
| Help | Alt+H |
| File > Recall Compliance Default | Alt+F+D |
| File > Recall | Alt+F+R |
| File > Recall > First Recent | Alt+F+E+1 |
| File > Recall > Second Recent | Alt+F+E+2 |
| File > Recall > Third Recent | Alt+F+E+3 |
| File > Recall > Fourth Recent | Alt+F+E+4 |
| File > Save | Alt+F+S |

| | |
|---|-------------|
| File > Recall Recent | Alt+F+E |
| File > Preferences | Alt+F+P |
| File > Preferences > Position Eye Mask in Center | Alt+F+P+M |
| File > Preferences > Acquisition Alert Message | Alt+F+P+A |
| File > Preferences > Trigger (Rise/Fall Time or Over/Undershoot) > Pulse Width | Alt+F+P+T+W |
| File > Preferences > Trigger (Rise/Fall Time or Over/Undershoot) > Edge Trigger | Alt+F+P+T+E |
| File > Minimize | Alt+F+M |
| File > Exit | Alt+F+X |
| Tests > Select | Alt+T+S |
| Tests > Select > Source | Alt+T+S+S |
| Tests > Select > Sink | Alt+T+S+K |
| Tests > Select > Cable | Alt+T+S+C |
| Tests > Configure | Alt+T+C |
| Tests > Connect | Alt+T+N |
| Tests > View Waveform | Alt+T+V |
| Results > Summary | Alt+R+S |
| Results > Details | Alt+R+D |
| Utilities > Report Generator | Alt+U+R |
| Utilities > Deskew | Alt+U+D |
| Help > Help Topics | Alt+H+T |
| Help > About HDMI | Alt+H+A |

Error Codes

The following table lists the error codes, their descriptions, and the possible solutions:

Table 4: Error Codes

| Error Code | Error Message | Description | Possible Solution |
|------------|---|--|---|
| 101 | Input is 'Not Conn.' | Both sources are selected as not connected. | Select valid channels (Ch1-Ch2, Ref1-Ref2) for at least clock/data source/data source (differential tests) or for input1/input2 (single-ended tests). |
| 102 | Conflict in the selection of inputs. | The sources that are selected for the two inputs are the same. The inputs clock source and data source for differential tests, input 1 and input 2 for single-ended tests. | Select different channel sources for input 1 and input 2 for single-ended tests and different channel sources for clock source and data source for differential tests. |
| 103 | The combination of Ref and Live input signals is not valid. | The software supports both Ref or both Live combinations of channels. | Select both ref channels or both live channels for clock and data sources. |
| 104 | Ref Wfm is not valid. | The software cannot switch on ref waveforms. Ref waveforms could be empty. | Recall the required ref waveform from the appropriate file on the oscilloscope. |
| 110 | Unable to acquire waveform. | The oscilloscope is not able to acquire the signal and trigger. | Ensure that the software configurations are proper. Check the probes and test fixture connections. If the test uses serial trigger, ensure that the CTL pattern is present on the waveform. |
| 111 | Not enough acquisitions to perform the test. | The software expects to acquire a minimum number of acquisitions that are configured. | Ensure that the software configurations are proper. Check the probes and test fixture connections. |
| 113 | Error in importing the Wfm. | The software could not import the waveform from acquisition. This happens when there is no valid waveform in the acquisition memory. | Check the probes and test fixture connections. Run the test again. |
| 114 | Improper Wfm. | Signal is not probed at the proper test points. | Refer to the connections diagram and probe the proper signal. |
| 115 | Ref Wfms have different Record Lengths/Sample Rates. | The ref waveforms have different sample rates and/or record lengths. | Use waveforms that are acquired simultaneously for ref waveforms. |

Table 4: Error Codes (Contd.)

| Error Code | Error Message | Description | Possible Solution |
|------------|--|---|--|
| 121 | Ref Levels entered are outside the range of the Wfm. | Unable to locate the edges on the waveform at the transition because the levels configured do not fall within the transition of the waveform. | Enter the Ref Level voltage value where the transition occurs on the waveform. Enter 50 percent of the level of the peak-to-peak transition level for mid ref levels, 80 percent of the peak-to-peak for high ref levels, and 20 percent of the peak-to-peak for low ref levels. |
| 122 | ((Hysteresis Level/2) + Ref Level) cannot be greater than 100 percent. | ((Hysteresis Level/2) + Ref Level) has to be within 100 percent for edge finding. | Set both the ref and (Hysteresis Level/2) to be less than 100 percent. |
| 123 | High Level is less than or equal to Low Level. | The configured high-level value is less than the low level value. | Configure the high level to be greater than the low level. |
| 131 | Error in calculating Tbit. | Not a valid clock waveform. | Supply a valid clock waveform and run the test again. |
| 132 | Clock input is required to calculate Tbit. | The Tbit value has to be calculated before you run a test that uses only data source(s). | Select and run a test that uses clock source for Tbit value. Click Connect , select clock source, and then click Re-calculate Tbit before you run the test. |
| 152 | Select any test to continue. | Configure, Connect, View Waveform, and Run Test need at least one test to be selected. | Select at least one test before you click either Configure, Connect, View Waveform, or Run Test . |
| 161 | Unable to recover clock. | Improper waveform or the software components are missing. | Supply the proper waveform. Reinstall the software. |
| 171 | Unable to find edges. | The waveform may be noisy or the hysteresis level may be low. | Check the probes and test fixture connections. Increase the hysteresis band level. |
| 172 | Not enough edges. | Number of edges found on the waveform is less than the minimum number of edges that is required for the test. | Decrease the horizontal scale to have more complete cycles of the waveform. Adjust the hysteresis level of the signal to find the edge at the required level. |
| 173 | Unable to calculate skew. | Could not find the mid of the waveform. | Check the probes and test fixture connections. |
| 174 | CTL pattern not found. | The CTL pattern 0010101011 was not found on the waveform. | Ensure that the appropriate pattern is present on the source waveform. Change the polarity of the waveform. |
| 175 | Option ST is not installed on the oscilloscope. | Option ST is not available on the oscilloscope. | Install Option ST. |
| 177 | Unable to find overshoot/undershoot. | Signal is not probed at the proper test points. | Follow the instructions in the setup diagram and probe the proper signal. |
| 178 | Unable to calculate Vswing. | Signal is not probed at the proper test points. | Follow the instructions in the setup diagram and probe the proper signal. |
| 181 | Check the DTG connection. | DTG connection has failed. This | <ul style="list-style-type: none"> Switch on the DTG and wait for the |

Table 4: Error Codes (Contd.)

| Error Code | Error Message | Description | Possible Solution |
|------------|--|--|---|
| | | <p>could happen if:</p> <ul style="list-style-type: none"> • The DTG is not switched on. • There is a mismatch in the GPIB-ENET configuration, software GPIB configuration, or DTG remote control configuration. • The GPIB cable is not connected properly. | <p>DTG software to load.</p> <ul style="list-style-type: none"> • Check GPIB connections. • Ensure that the primary and secondary addresses of DTG in the remote control match the GPIB-ENET configuration of the oscilloscope. • Ensure that the GPIB-ENET configuration on your oscilloscope matches the signal sources configuration in the software. |
| 182 | File not found in the DTG. | The configured file is not found in the DTG. | Ensure that the specified file in the software is present in the DTG. Specify a file name that is present in the DTG. |
| 183 | Invalid logical channel. | The logical channel is invalid. | Provide a proper logical channel. |
| 184 | Conflict in selection of outputs from the DTG. | The same physical channel (A1, A2, B1, B2, C1, C2, D1, D2) is selected for any two logical channels (Clock, Data0, Data1, Data2). | Select different physical channels (A1, A2, B1, B2, C1, C2, D1, D2) for a given logical channel (Clock, Data0, Data1, Data2). |
| 191 | Check the AWG connection. | <p>AWG connection has failed. This could happen if:</p> <ul style="list-style-type: none"> • the AWG is not switched on • there is a mismatch in the GPIB-ENET configuration, application GPIB configuration, and AWG remote control configuration • if the GPIB cable is not connected properly. | Switch on the AWG and wait for the AWG software to load. Check GPIB connections. Ensure that the primary address of AWG in the Utility > Network > Address matches with the GPIB-ENET configuration of the oscilloscope. Ensure that the GPIB-ENET configuration on your oscilloscope matches the signal sources configuration in the software. |
| 192 | File not found in the AWG. | File is not present in the AWG. | Ensure that the required file is present in the AWG. |
| 193 | Check the Signal Sources connection. | <p>Signal sources connection has failed. It may be due to DTG or AWG connection failure. DTG connection has failed. This could happen if:</p> <ul style="list-style-type: none"> • The DTG is not switched on <p>There is a mismatch in the GPIB-ENET configuration, software GPIB configuration, and DTG remote control configuration</p> <p>If the GPIB cable is not connected properly</p> | <p>For DTG connection failure:</p> <p>Switch on the DTG and wait for the DTG software to load. Check the GPIB connections. Ensure that the primary address of DTG in the remote control matches the GPIB-ENET configuration of the oscilloscope. Ensure that the GPIB-ENET configuration on your oscilloscope matches the signal sources configuration in the software.</p> |

Table 4: Error Codes (Contd.)

| Error Code | Error Message | Description | Possible Solution |
|------------|--|---|---|
| | | properly. AWG connection has failed. This could happen if: The AWG is not switched on There is a mismatch in the GPIB-ENET configuration, software GPIB configuration, and AWG remote control configuration If the GPIB cable is not connected properly Primary addresses of DTG and AWG are same. | For AWG connection failure: Switch on the AWG and wait for the AWG software to load. Check the GPIB connections. Ensure that the primary address of AWG in the Utility > Network > Address matches with the GPIB-ENET configuration of the oscilloscope. Ensure that the GPIB-ENET configuration on your oscilloscope and signal sources configuration in the software match. Select distinct primary addresses for DTG and AWG. |
| 194 | Jitter value is unavailable. | Signal is not probed at the proper test points. | Follow the instructions in the setup diagram and probe the proper signal. |
| 201 | Edges on the Wfm are lesser than the configured number of edges. | Deskew number of edges set by the user to perform the deskew is not available on the waveform. | Ensure that the edges in the waveform and the display in the numeric input are the same. Adjust the horizontal scale to increase the number of transitions that is required to adjust the deskew. |
| 202 | Calculated skew is greater than the oscilloscope skew range. | The calculated skew value is greater than the oscilloscope deskew range. | The deskew will be done to the maximum deskew value that is applicable to the oscilloscope. |
| 203 | Cycle has less than 20 sample points. | Insufficient number of samples in a complete cycle. The number of data points in the identified cycle is less than 20. | Increase the sampling rate. |
| 211 | Select the test point(s) to continue. | No test points are selected. | Select any one or both of the test points in cable configuration. |
| 221 | Mask cannot be moved beyond this position. | Upper and lower masks have exceeded their boundary values. The mask co-ordinates are beyond the plottable area. | Change the Mask Movement mode from Coarse to Fine. After changing to Fine, you will be able to move a bit further. If you are already in Fine mode, and this message appears, then you are in the maximum/minimum possible position. |
| 222 | Unable to calculate mask margins. | An error occurred while calculating the mask margins. | The signal may be wrong (noise, invalid pattern). Connection to the probe tip may be loose. Recheck the connection and run the test again. |

Operating Basics

Software View

TDSHT3 HDMI Compliance Test Software Window

The software window includes a menu bar, selection pane, test selection pane, execution pane, and status bar. The client pane changes between the configuration pane, parameter selection pane, connection pane, and view waveform pane depending on what you have selected in the selection pane. After you run the test, the client pane automatically changes to the result pane.

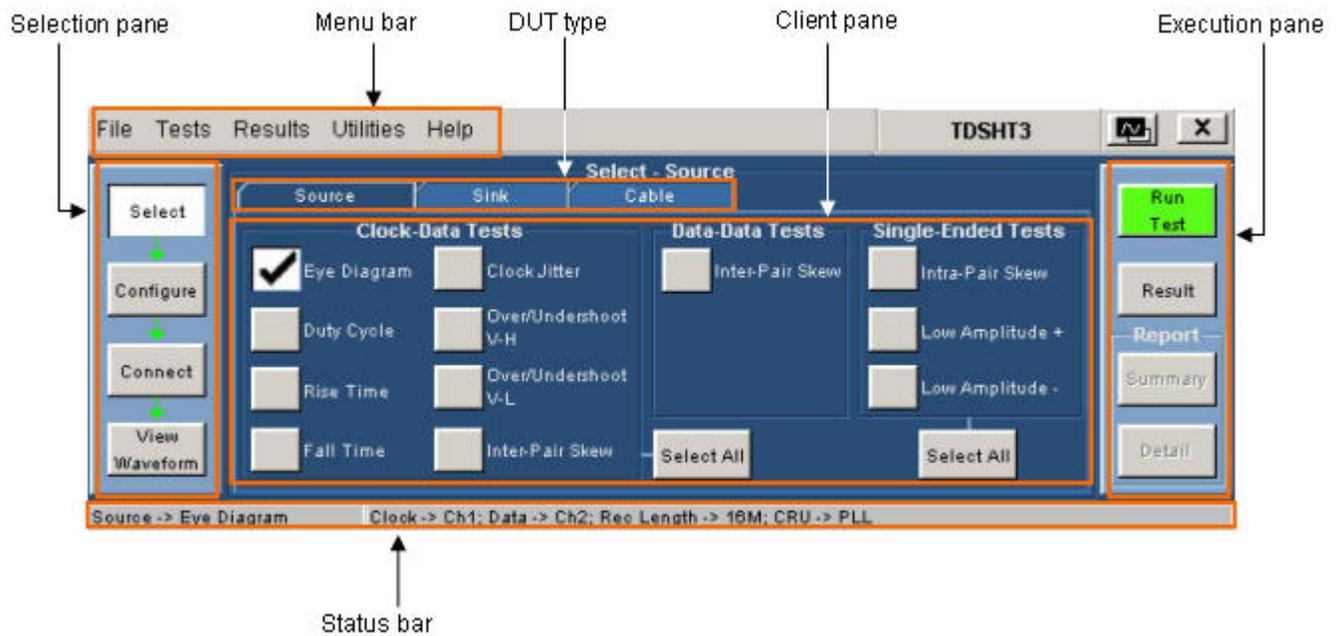


Figure 9: Application Window

TDSHT3 HDMI Compliance Test Software Interface Controls

The software uses a Microsoft Windows interface.

Note: The oscilloscope software shrinks to fit in the top part of the display when the TDSHT3 HDMI Compliance Test Software runs.

The software interface uses the following controls:

Table 5: Application Interface Controls

| Control | Description |
|--------------------|---|
| Menu bar | The Menu bar provides access to the software menus. It is located at the top of the software window. |
| Area/Tab | An Area/Tab control encloses visual frame with a set of related options. |
| Option button | An Option button allows you to select either a command or a task. |
| Drop-down list box | A Drop-down list box lists items from which you can select one item. |
| Field | A Field is a box where you can enter text or values. |
| Check boxes | You can select or clear check boxes that you use to set preferences. |
| Scroll bar | A Scroll bar is a vertical or horizontal bar at the side or bottom of a display area that is used to move around that area. |
| Browse | Browse refers to the window where you can browse through a list of folders and files. |
| Command button | A Command button refers to the usually rectangular button that carries out a command and may initiate immediate action. |
| Numeric keypad | You can use a Numeric keypad to enter numeric values. |
| Text keypad | You can use a Text keypad to enter text. |
| MP/GP knob | A line between the knob icon and the field indicates which knob you can turn on the oscilloscope to select a value. |
| F1 | F1 help opens help on a topic associated with the currently selected item in your software. |

Menus

The menu bar of TDSHT3 HDMI Compliance Test Software consists of the following menus:

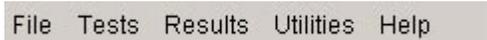


Figure 10: Menu bar

File menu

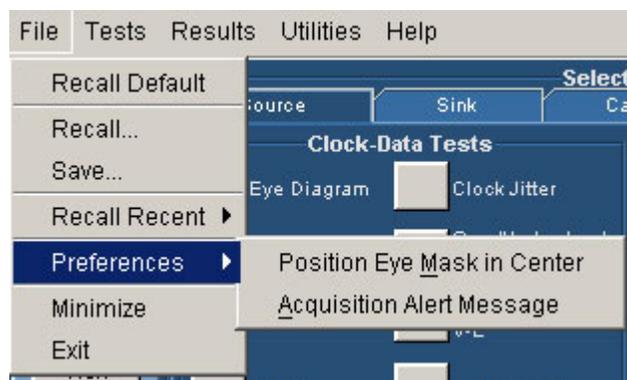


Figure 11: File menu

Table 6: File menu options

| Menu Selection | Description |
|----------------|---|
| Recall Default | Click File > Recall Default to recall the default settings for both the software and the oscilloscope. |
| Recall | Click File > Recall to recall the previously saved settings for the software from an .ini file. |
| Save | Click File > Save to save the software settings to an .ini file. |
| Recall Recent | Click File > Recall Recent to select among the recently saved and recalled setups. |
| Preferences | Click File > Preferences to select one of the following options. Click an option again to clear the selection. Position Eye Mask in Center Acquisition Alert Message Trigger (Rise/Fall Time or Over/Undershoot) |
| Minimize | Click File > Minimize to minimize the software window. |
| Exit | Click File > Exit to quit the software. |

Note: The File > Preferences > Trigger (Rise/Fall Time or Over/Undershoot) menu appears only on supported B-series oscilloscopes.

Tests menu

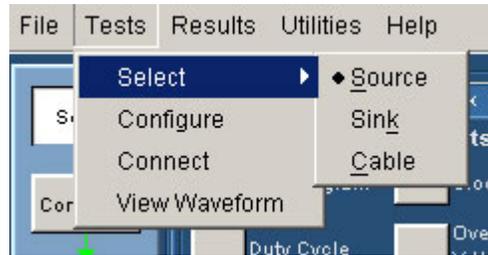


Figure 12: Tests menu

Table 7: Tests menu options

| Menu Selection | Description |
|----------------|---|
| Select | Click Tests > Select to display or modify the test selection for Source, Cable, or Sink in the client pane. |
| Configure | Click Tests > Configure to display or modify the configuration parameters for the selected test(s). |
| Connect | Click Tests > Connect to display the connection instructions for the selected test(s). |
| View Waveform | Click Tests > View Waveform to display a sample waveform or waveforms based on the settings for the selected test(s). |

Results menu



Figure 13: Results menu

Table 8: Results menu options

| Menu Selection | Description |
|----------------|---|
| Summary | Click Results > Summary to display the result summary of the last test(s) that you conducted. |
| Details | Click Results > Details to display the detailed results of the last test that was conducted. |

Utilities menu



Figure 14: Utilities menu

Table 9: Utilities menu options

| Menu Selection | Description |
|------------------|--|
| Report Generator | Click Utilities > Report Generator to open the Report Generator pane. |
| Deskew | Click Utilities > Deskew to open the deskew pane. The deskew pane allows you to compensate the skew between the oscilloscope channels. |

Help menu

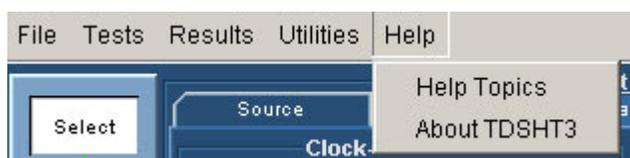


Figure 15: Help menu

Table 10: Help menu options

| Menu Selection | Description |
|----------------|--|
| Help Topics | Click Help > Help Topics to display the help file for the TDSHT3 HDMI Compliance Test Software. |
| About TDSHT3 | Click Help > About TDSHT3 to display a dialog box with information about the current TDSHT3 HDMI Compliance Test Software. |

Preferences

On the menu bar, click **File > Preferences** to select any of the options described in the following table. Click an option again to clear the selection.

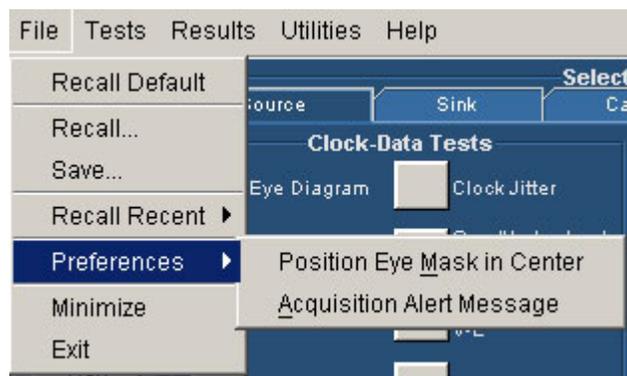


Figure 16: Preferences

Table 11: Preferences options

| Option | Description |
|---|---|
| Position Eye Mask in Center | Select this option to position the mask at the center of the eye diagram. Clear this option to position the mask to the left of the eye diagram. |
| Acquisition Alert Message | Select this option to receive an alert message that allows the software to use the custom oscilloscope setup. Clear this option to stop receiving the alert message. |
| Trigger (Rise/Fall Time or Over/Undershoot) | Select either Pulse Width or Edge Trigger for the Rise/Fall Time or the Over/Undershoot test. The default value is Edge Trigger. Select Pulse Width if the signal has very high inter-symbol interference. This option is available only on supported B-series oscilloscopes. |

Selection pane

The selection pane, which is located to the left of the software window, allows you to navigate through the software.

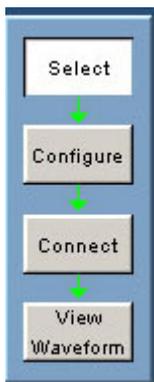


Figure 17: Selection pane

The following table lists the buttons and their task descriptions:

Table 12: Selection options

| Button Name | Description |
|---------------|---|
| Select | Click Tests > Select to display or modify the test selection for Source, Cable, or Sink in the client pane. |
| Configure | Click Tests > Configure to display or modify the configuration parameters for the selected test(s). |
| Connect | Click Tests > Connect to display the connection instructions for the selected test(s). |
| View Waveform | Click Tests > View Waveform to display a sample waveform or waveforms based on the settings for the selected test(s). |

Result pane

The result pane, which is located at the center of the software window, appears as shown in the following diagram:

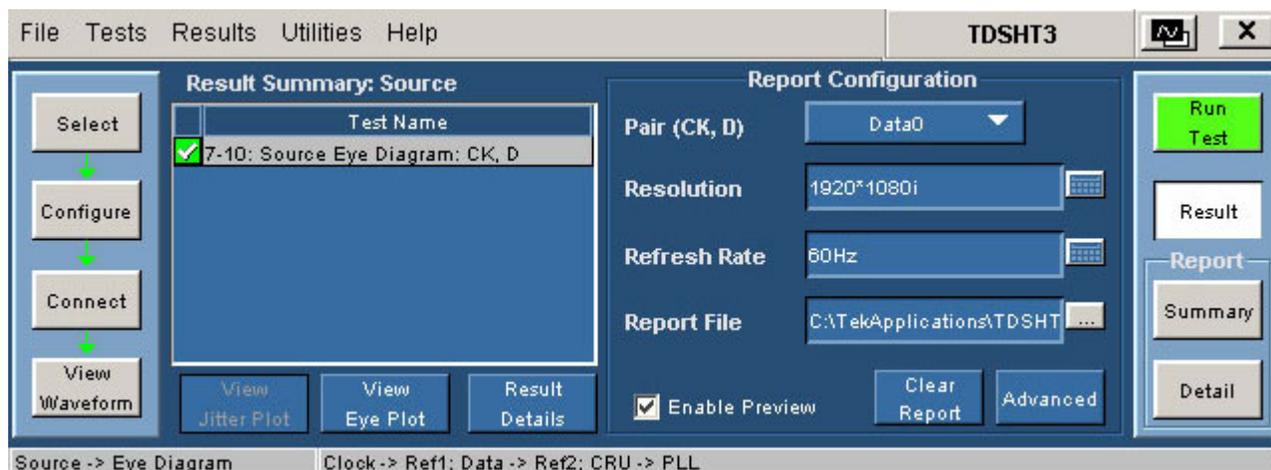


Figure 18: Result pane

The result pane includes the result summary pane and the report configuration pane.

Result Summary pane

The result summary pane displays the test results.

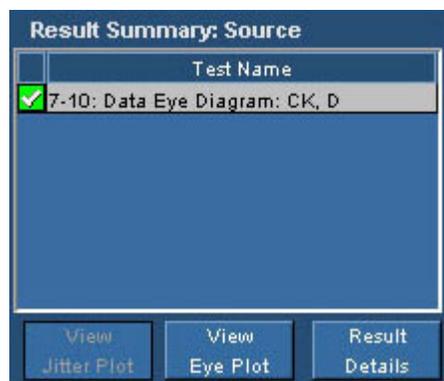


Figure 19: Result Summary pane

-  This icon indicates that the test has passed.
-  This icon indicates that the source eye diagram test has passed conditionally.
-  This icon indicates that the test has failed.
-  This icon indicates that the test could not be run due to an error.

Table 13: Result Summary options

| Option | Description |
|------------------|--|
| Status | The status icons display the status of the test as Pass, Conditional Pass (for the source eye diagram test), Fail, or Error. |
| Test Name | The Test Name box displays the test id, test name, and signal names - CK (Clock), D (Data). |
| View Jitter Plot | Click View Jitter Plot to display the jitter plot. This command is available if you have successfully run the clock jitter test. |
| View Eye Plot | Click View Eye Plot to display the eye plot. This command is available if you have successfully run the eye diagram test. |
| Result Details | Click Result Details to display the Result Details dialog box that shows the details of the test results categorized as test name, specification range, measured value, result, and remarks. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can also set a default report file.

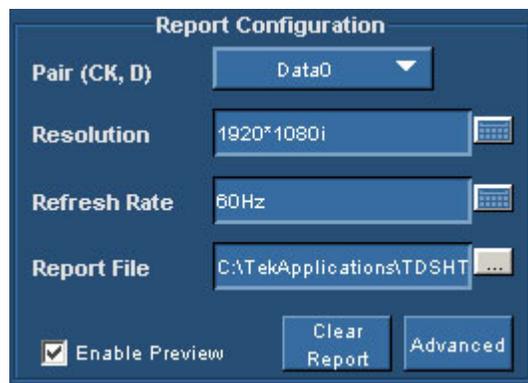


Figure 20: Report Configuration pane

In the report configuration pane, you can configure the following parameters:

Table 14: Report Configuration options

| Category | Description |
|----------------|--|
| Pair | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | In the Resolution box, type the resolution at which you conducted the test. Some examples are VGA, SVGA, XGA, SXGA, and so on. |
| Refresh Rate | In the Refresh Rate box, type the refresh rate at which you conducted the test. Some examples are 40 Hz, 43 Hz, 57 Hz, 60 Hz, and so on. |
| Report File | The Report File box allows you to specify the path and the file where you want to save the generated report. However, for the selected test, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the previously generated reports. |
| Advanced | Click Advanced to open the Advanced Report Configuration dialog box. |

Execution pane

The execution pane, which is located to the right of the software window, displays the **Run Test** and **Result** buttons. After you successfully run a test, the **Summary** and **Detail** buttons are available.



Figure 21: Execution pane

Click on each button to perform a particular task. The following table lists the buttons and their task descriptions:

Table 15: Execution options

| Button name | Description |
|-------------|--|
| Run Test | Click Run Test to run the selected test or tests. |
| Result | Click Result to display the result pane that shows the test results. |
| Summary | Click Summary to generate a report summary as a .csv file. |
| Detail | Click Detail to generate a report. The Report Viewer utility appears and displays the test results. The test results are displayed only if you have selected Enable Preview in the report configuration pane. Otherwise, the test results are stored in a file and the folder path of the stored file is shown in a message box. |

Note: The report details are real time. The results history is maintained as long as you do not change the device type. If you change the device type, then the history is cleared.

Status bar

At the bottom of the software window is the status bar, which displays the selected test and the important configuration parameters.

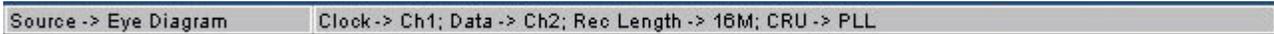


Figure 22: Status bar

General Purpose Knob

1. Click in any number box to display the connection to one of the general purpose knobs.
2. Turn the corresponding knob on the oscilloscope front panel to adjust the value for the selected parameter.
3. For better resolution, press the Fine button.

Enable Remote Control of Test Equipment

There are two methods to connect to AWG/DTG. One is the GPIB-USB method and the other, is the GPIB-ENET method.

The following section will guide you through the process of connecting the AWG, the DTG, and the digital oscilloscope used for Sink and Cable tests:

You will need Tektronix AWG710/B, Tektronix DTG5274, Tektronix supported oscilloscope, and National Instruments GPIB-USB-B with the included software, NI-488.2 for Windows.

1. Ensure that NI-VISA is NOT installed.
2. Install NI-488.2 for Windows (version 2.1 or later).

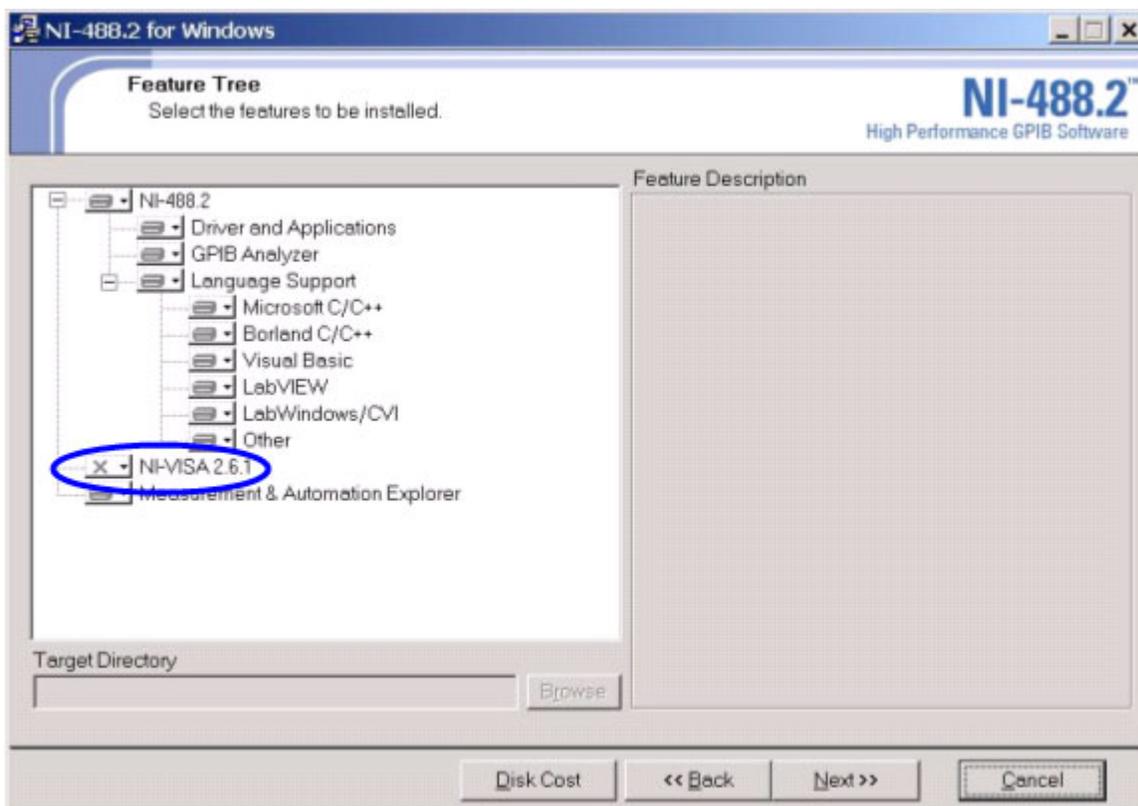


Figure 23: NI-488.2 for Windows

3. Install the Measurement & Automation Explorer software.
4. When prompted, enable the GPIB-USB interface.

Note: If you already have NI-488.2 installed on your oscilloscope, then ensure that you have the appropriate version and installation parameters. Otherwise, remove NI-488.2, and then reinstall the appropriate version.

5. Restart the oscilloscope.
6. Configure the DTG GPIB primary address to 1 and AWG GPIB primary address to 2.
7. Connect the USB-GPIB controller to the USB port on the oscilloscope (the TDS7000B rear panel is shown here). The oscilloscope operating system will detect the USB-GPIB controller and install the appropriate driver for it.

- Using GPIB cables, connect (stack) both the DTG and AWG GPIB ports to the GPIB port of the GPIB controller.

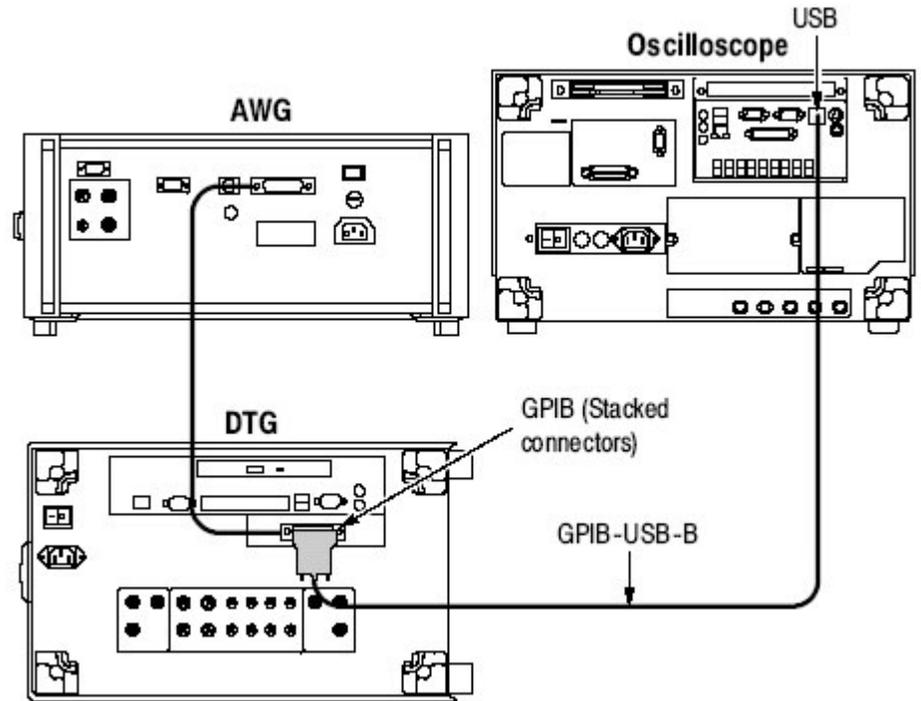


Figure 24: Connections for AWG/DTG (using GPIB-USB method)

9. Open the Measurement & Automation Explorer software that was installed with the NI-488.2 software.

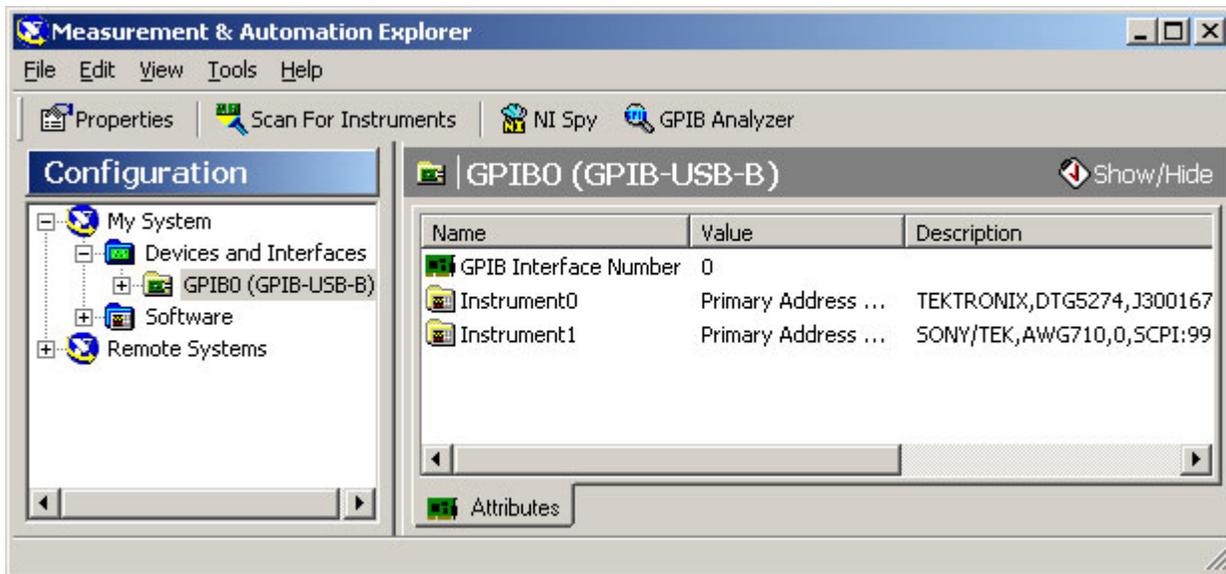


Figure 25: Measurement & Automation Explorer

10. In the configuration pane, look under Devices and Interfaces for the GPIB device.
11. Right-click the GPIB device and click **Scan for Instruments**.
12. Note the GPIB Instrument Number and the Primary Address to configure the instrument connection in the TDSHT3 HDMI Compliance Test Software.
13. Right-click the instrument, and then click **Communicate with Instrument**.
14. In the **NI-488.2 Communicator** dialog box, click **Query** and check that '*IDN?' displays a description of the correct equipment.
15. Start the TDSHT3 HDMI Compliance Test Software.
16. Click **Select**.
17. Click the **Sink** tab.

18. Select one of the differential tests, such as Jitter Tolerance.

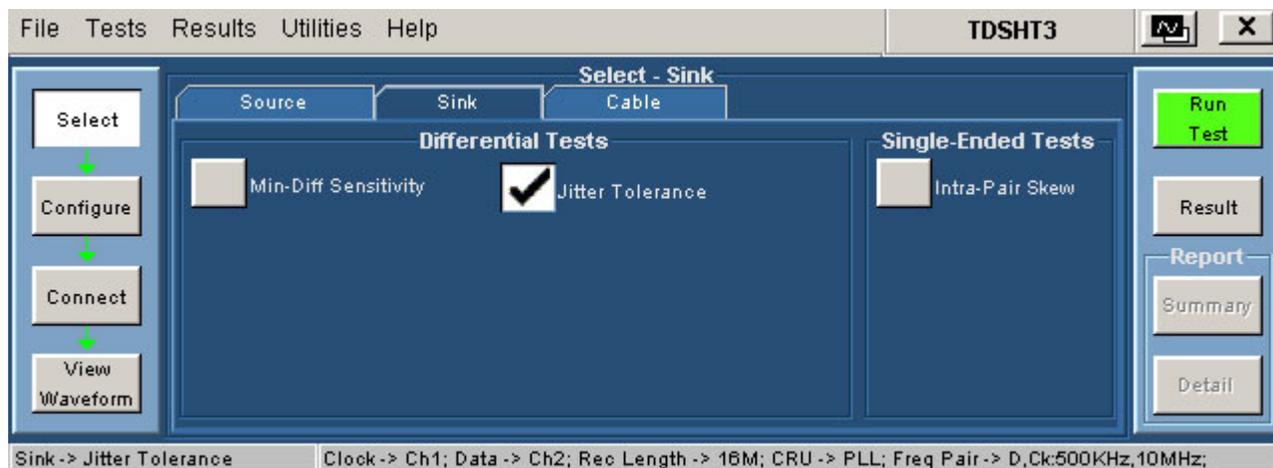


Figure 26: Jitter Tolerance (Sink test) Select pane

19. Click **Connect**.

20. Click **Signal Sources**. The **Signal Sources Setup** dialog box appears.



Figure 27: Signal Source Setup

21. In the **Signal Sources Setup** dialog box, click the **DTG** tab.

22. Configure the GPIB Board Type by using the GPIB Instrument Number that you noted in step 12.

23. Configure the Primary Address by using the address that you noted in step 12.

24. Leave the Secondary Address set to 0.

25. Click the **AWG** tab and repeat steps 22 through 24 for the AWG.
26. Click **Test Conn** and look for a message that the connection is successful.
27. This completes the GPIB hookup.

Configure New IP Address for GPIB-ENET

There are two methods to connect to AWG/DTG. One is the GPIB-USB method and the other, the GPIB-ENET method.

GPIB-ENET and GPIB-ENET/100 for Windows 3.1/95/98/ME/NT/2000/XP

1. Confirm that you have installed the latest NI-488.2 driver software for your device.
2. Connect your GPIB-ENET or GPIB-ENET/100 to an Ethernet network by using a category 5 Ethernet cable to connect the RJ-45 port on your hardware to an Ethernet hub. You could also connect the external hardware directly to your oscilloscope by using an Ethernet crossover cable.
3. Connect the power to your GPIB-ENET or GPIB-ENET/100 and turn it on. When you power on your GPIB-ENET, the POWER LED comes on immediately. The READY LED flashes while it completes its power-on self-test. When the test completes successfully and the IP address is assigned, the READY LED remains steady, indicating that the unit is ready to operate. To assign your IP address, continue to step 4.
4. Run the Measurement & Automation Explorer software from **Programs > National Instruments**.
5. Some devices are not Windows Plug and Play compatible. Hence, they do not automatically appear in the **Devices and Interfaces** list. Other devices may reside in another oscilloscope on your network. To add non Plug and Play or remote DAQ devices, right-click **Devices and Interfaces** in the configuration tree, and then click **Create New**. Follow the instructions in the wizard. Select GPIB-ENET/100 or GPIB-ENET interface according to the hardware.

How to Configure GPIB-ENET/100

1. Configure an existing device.

To configure an existing National Instruments device, right-click the device name in **Devices and Interfaces** in the configuration tree, and then click **Properties**. You can also configure existing device properties by clicking **Properties** in the toolbar.

2. To configure the network parameters of your GPIB-ENET/100, right-click your GPIB interface in the configuration tree, and click **Device Configuration**.
3. Click **Properties**. Configure the IP address as shown in the following image:

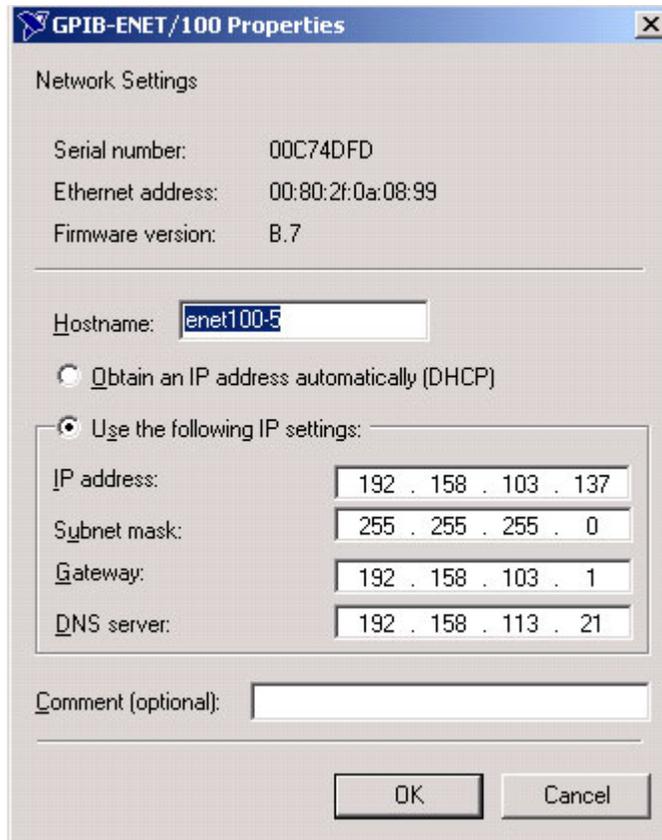


Figure 28: GPIB-ENET/100 Properties

4. After entering the IP settings, click **OK**. A message box appears as follows:

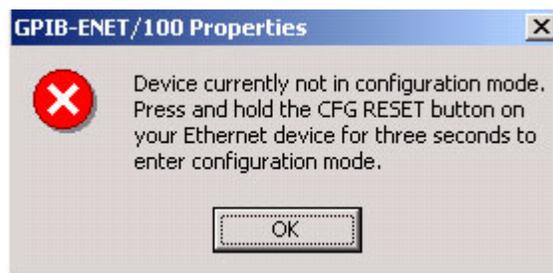


Figure 29: GPIB-ENET/100 Properties message box

5. After you reset the CFG in the ENET card, click **OK** in the **GPIB-ENET/100 Properties** message box. The software will configure and another message box appears.

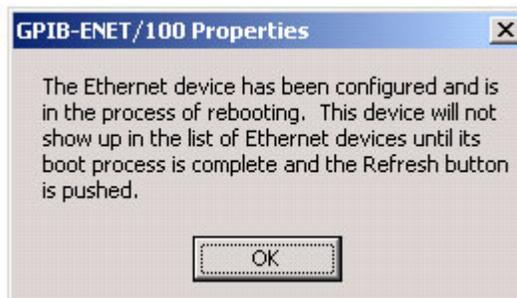


Figure 30: GPIB-ENET/100 Properties re-confirm message box

6. Click **OK**. The ENET card is configured.
7. Verify the configuration by pinging the IP address and through ICTA.

How to Configure GPIB-ENET (old card)

1. Right click **Devices and Interfaces**. Click **Assign IP Address**. A message box appears.



Figure 31: IP Assign Address message box

Note: The GPIB software installation is in the path C:\Program Files\National Instruments\NI-488.2\GPIB-ENET on the oscilloscope.

2. Run the Measurement & Automation Explorer software. Click **Assign IP Address**. A message box appears.

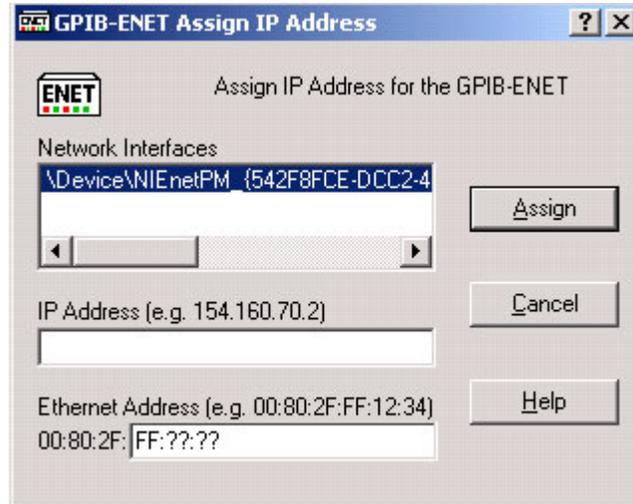


Figure 32: GPIB-ENET Assign IP Address message box

3. Enter the new IP Address and the Ethernet Address. Click **Assign**. A message box appears.

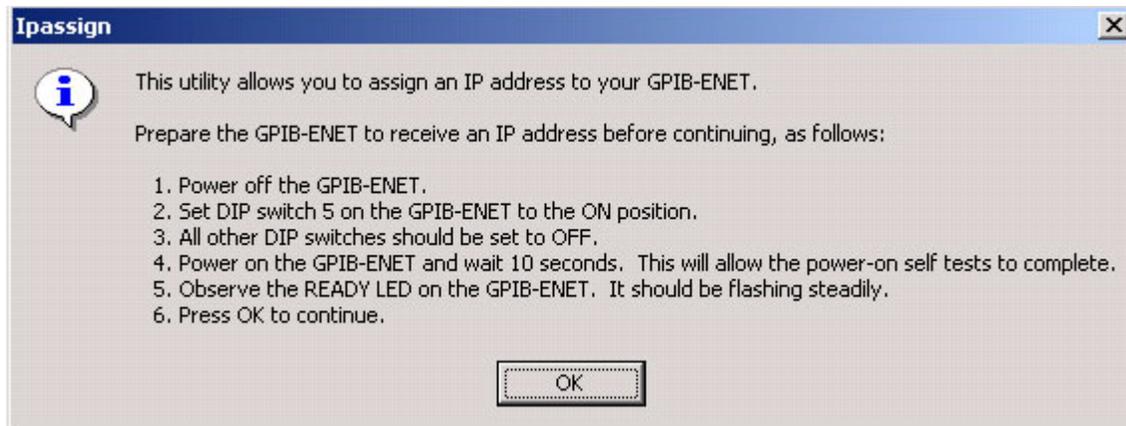


Figure 33: IPassign message box

4. Follow the instructions in the **Ipassign** message box. Click **OK**. Another message box appears.

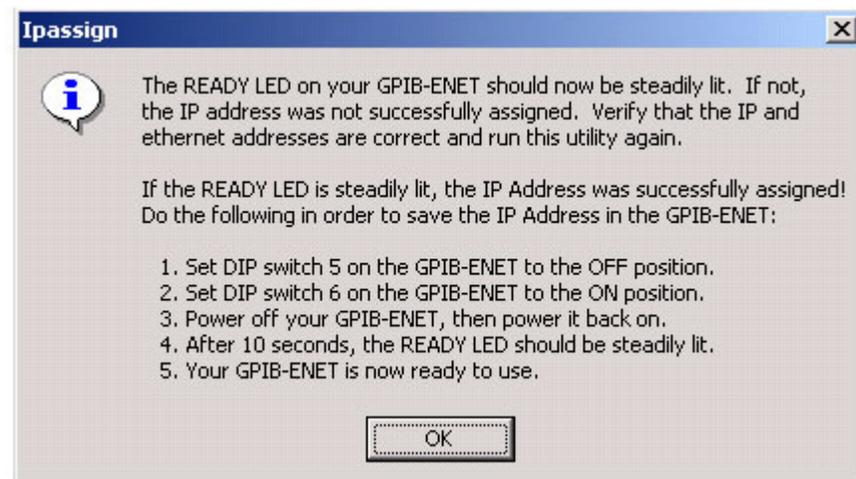


Figure 34: Ipassign re-confirm message box

5. Follow the instructions in the new **Ipassign** message box. Click **OK**.

Remote Control Caution

If you run the Sink or Cable tests, the **GPIB Bus Timing** dialog box appears.



Figure 35: GPIB Bus Timing dialog box

Click **OK** to continue if you are sure that the Bus Timing parameter is already set to 2 μ sec. Otherwise, click **Cancel** and follow the procedure outlined later to change the Bus Timing parameter manually.

Once you have changed the parameter, select the check box if you do not want the dialog box to appear again in the current session. However, if you click **File** >

Recall Default or you quit the software, then the dialog box appears again when you run the test.

When you install the remote control for the test equipment, the Measurement & Automation Explorer software will be installed on the oscilloscope. You can start the software by clicking **Start > Program Files > National Instruments > Measurement & Automation**.

To change the Bus Timing parameter, perform the following steps:

1. Start the Measurement & Automation Explorer software.
2. In the configuration pane, look under Devices and Interfaces for the GPIB device.
3. Right-click the GPIB device and click **Properties**. The **GPIB Configuration** dialog box appears.
4. In the **GPIB Configuration** dialog box, click the **Advanced** tab.
5. In the **Bus Timing** list, select 2 μ sec.

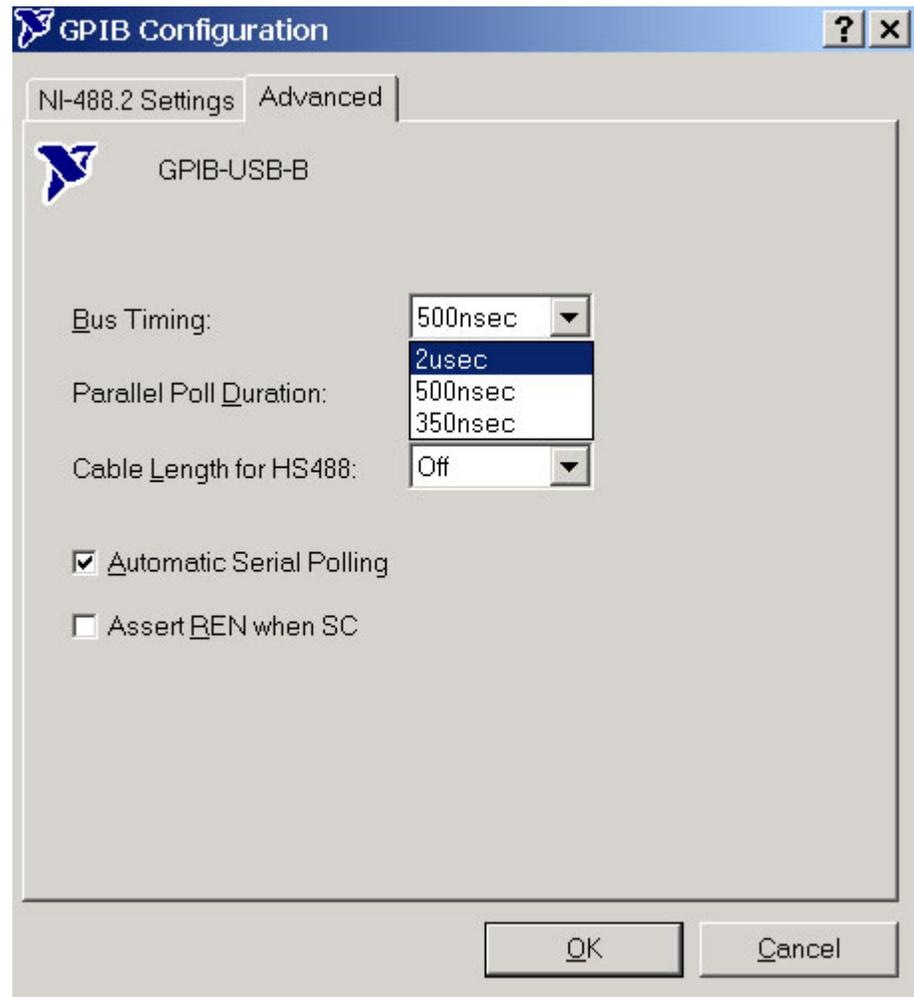


Figure 36: GPIB Configuration dialog box

6. Quit the TDSHT3 HDMI Compliance Test Software and restart the oscilloscope.

Remote GPIB Commands

The Remote General Purpose Interface Bus (RGPIB) is essentially another way of interfacing with the oscilloscope. It allows you to control much of the functionality of the oscilloscope as defined by the software, from a Remote GPIB controller.

You can use the following GPIB command to start the TDSHT3 HDMI Compliance Test Software:

```
application:activate "HDMI Compliance Test Software"
```

How to Set and Query

1. The command syntax for setting the value to the variable is:

```
VARIABLE:VALUE "<variable name>","<variable value>"
```

The arguments <variable name> and <variable value> are required in the order indicated.

2. The command syntax for querying the value of the variable is:

```
VARIABLE:VALUE? "<variable name>"
```

3. The command syntax to run the selected test is:

```
variable:value "sequencerState", "Sequencing"
```

The TDSHT3 HDMI Compliance Test Software will be remotely controllable for the following set of commands for (VARIABLE:VALUE):

Application

Table 16: Command Arguments and Queries (Application)

| Variable Name | Valid Values | Function (Set) | Query Form |
|---------------|--------------|---|---|
| Application | Exit | Set the value to quit running software. | Query to return the name of the currently running software. |
| Version | - | - | Query to return the version of the currently running software, for example, Version: 1.0.0. |

Sequencer

Table 17: Command Arguments and Queries (Sequencer)

| Variable Name | Valid Values | Function (Set) | Query Form |
|----------------|--|--------------------------|-----------------------------|
| sequencerState | {Sequencing}: to set {Ready, Sequencing}: returned on query | Set the sequencer state. | Return the sequencer state. |

Save/Recall

Table 18: Command Arguments and Queries (Save/Recall)

| Variable Name | Valid Values | Function (Set) | Query Form |
|---------------|---|-------------------------------------|---|
| Setup | {Default, Recall, Save} | Set the Save/Recall/Default action. | Default value for this variable is an empty string. Thus, the variable is set to selected value momentarily and after the task is completed, it returns to its default value. |
| recallName | Any string 1-8 chars, comprised of A-Z, 0-9 | Set the setup recall file name. | Return the setup recall file name. |
| saveName | Any string 1-8 chars, comprised of A-Z, 0-9 | Set the setup save file name. | Return the setup save file name. |

Report

Table 19: Command Arguments and Queries (Report)

| Variable Name | Valid Values | Function (Set) | Query Form |
|---------------|--------------|---|------------|
| reportSummary | Save | Save the report summary to a .csv file. | - |
| ReportDetail | Save | Save the report details to a .rpt file. | - |

Dialog Boxes

Result Details

After the test is complete, on the result pane, click **Result Details** to display the details of the result.

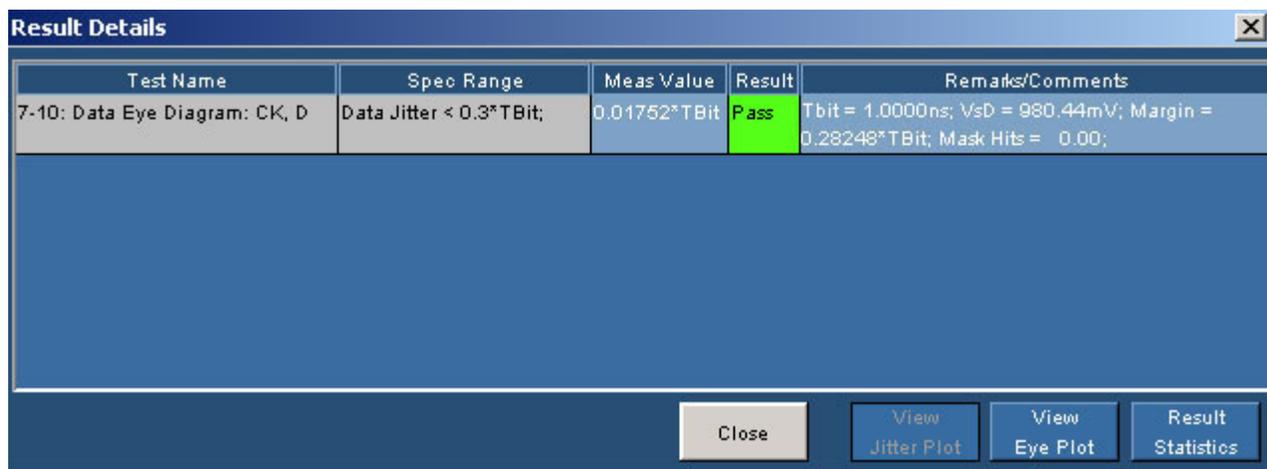


Figure 37: Result Details

Table 20: Result Details

| Option | Description |
|-------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal names - CK (Clock), D (Data). |
| Spec Range | The Spec Range box describes the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the results of Tbit, Vswing, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |
| View Jitter Plot | Click View Jitter Plot to display the jitter plot. This command is available if you have successfully run the clock jitter test. |
| View Eye Plot | Click View Eye Plot to display the eye plot. This command is available if you have successfully run the eye diagram test. |
| Result Statistics | Click Result Statistics to display statistics based on the tests. |

*Note: The parameters in the **Result Details** dialog box may change depending on the test that you run.*

Virtual Keyboard

Virtual Keyboard – Numeric

1. Click any number box to display the icon for the numeric keyboard.

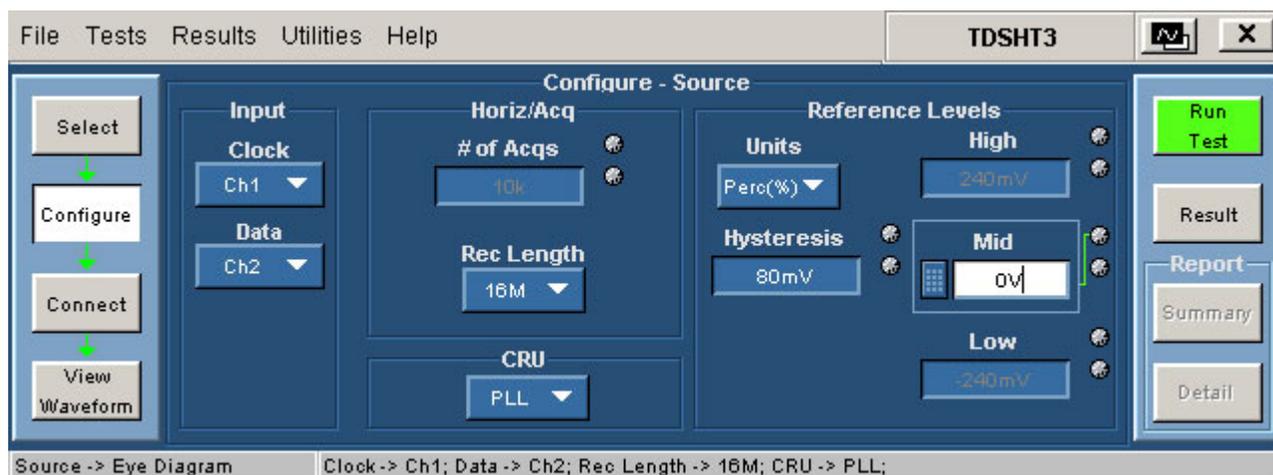


Figure 38: Configure Source

2. Click the icon to display the numeric keyboard.

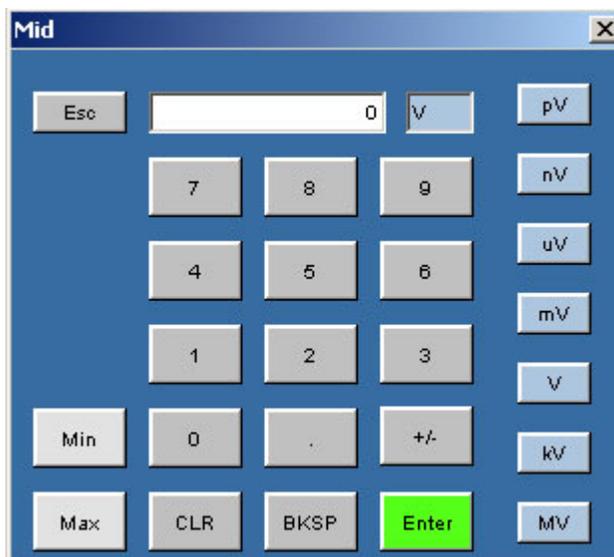


Figure 39: Numeric keyboard

3. Click the number keys to enter the desired value.
4. Select a unit measure.
5. Click **Enter** to confirm your entry. Selections are not effective until you click **Enter**.

Virtual Keyboard – Text

1. Click any text box to display the icon for the text keyboard.

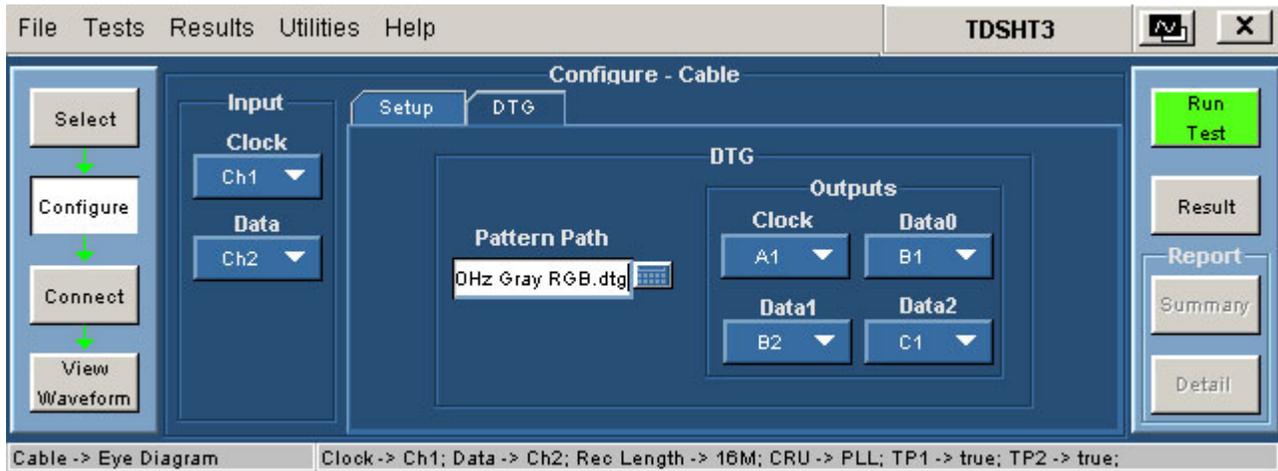


Figure 40: Configure Cable

2. Click the icon to display the text keyboard.

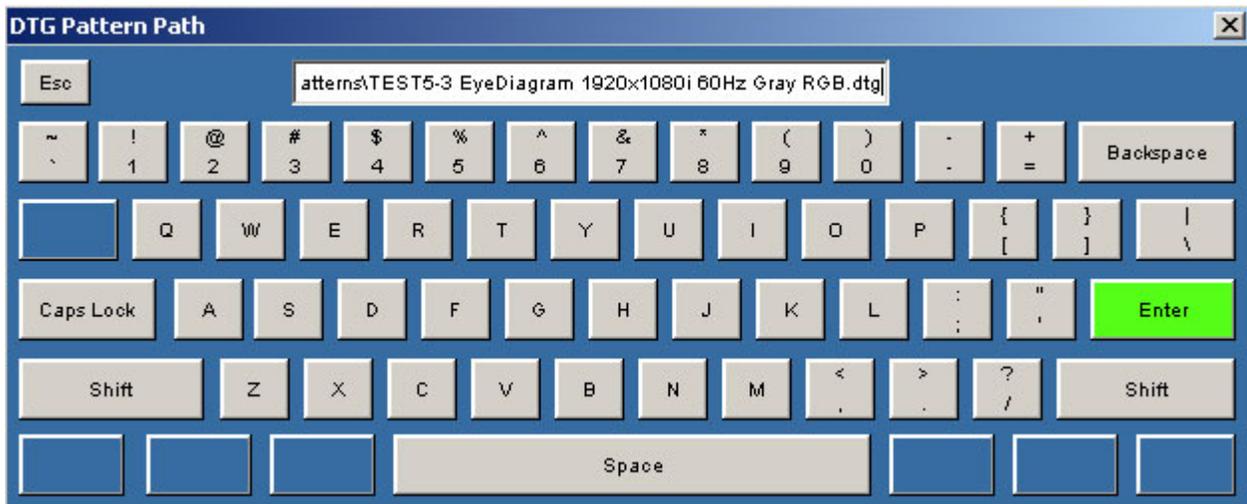


Figure 41: Text Keyboard

3. Use the text keyboard to enter the required text (such as a file name).
4. Click **Enter** to confirm your entry. Selections are not effective until you click **Enter**.

Report Configuration Advanced

In the report configuration pane, click **Advanced** to open the **Report Configuration Advanced** dialog box.



Figure 42: Advanced Report Configuration

In the **Report Configuration Advanced** dialog box, you can configure the following parameters:

Table 21: Report Configuration Advanced options

| Category | Description |
|--|---|
| Device ID | The Device ID box allows you to specify the DUT on which you conducted the test by printing the device id on the generated report. |
| Device Details | The Device Details box allows you to specify the DUT on which you conducted the test by printing the device details on the generated report. |
| Pair (Single-Ended) | The Pair (Single-Ended) list allows you to select the pair on which you conducted the single-ended test. |
| Pair (D, D) | The Pair (D, D) list allows you to select the pair on which you conducted the data-data test. |
| Use oscilloscope settings for image report | Select the Use oscilloscope settings for image export check box to use the current settings of the oscilloscope for image export. |

Exit

To quit the software:

- On the menu bar, click **File > Exit**.
- The **Exit** dialog box appears.



Figure 43: Exit

- Click either **Yes**, **No**, or **Cancel**. **Yes** is selected by default. While the software is running, it automatically changes some oscilloscope settings. When you quit the software, you can choose whether to retain these settings or restore the previous settings.

Note: Using other methods to quit the software may result in an abnormal termination of the software.

How to...

Calculate Tbit



Figure 44: Tbit pane

Tbit is the time that is required to transmit one bit of data. Tbit is one bit time at the specified pixel clock frequency ($= T_{\text{PIXEL}}/10$).

For all the tests that require clock, the software calculates Tbit. For all the other tests, you have an option of either recalculating Tbit or use the previous Tbit value for the test.

If you click **Re-calculate**, the software computes the specified number of averages of T_{PIXEL} and then calculates Tbit. If you use the existing Tbit value, then the software uses the previously calculated Tbit value or you can also again recalculate Tbit by using the Tbit pane.

To calculate Tbit for a measurement, use the Tbit pane. You can calculate Tbit for Duty Cycle, Rise Time, Fall Time, Over/Undershoot V-H, Over/Undershoot V-L, Inter-Pair Skew for Clock-Data Tests, Inter-Pair Skew for Data-Data Tests, Intra-Pair Skew, Low Amplitude +, and Low Amplitude – measurement if the clock is not connected.

To calculate Tbit

1. Set up the connections as shown in the following diagram:

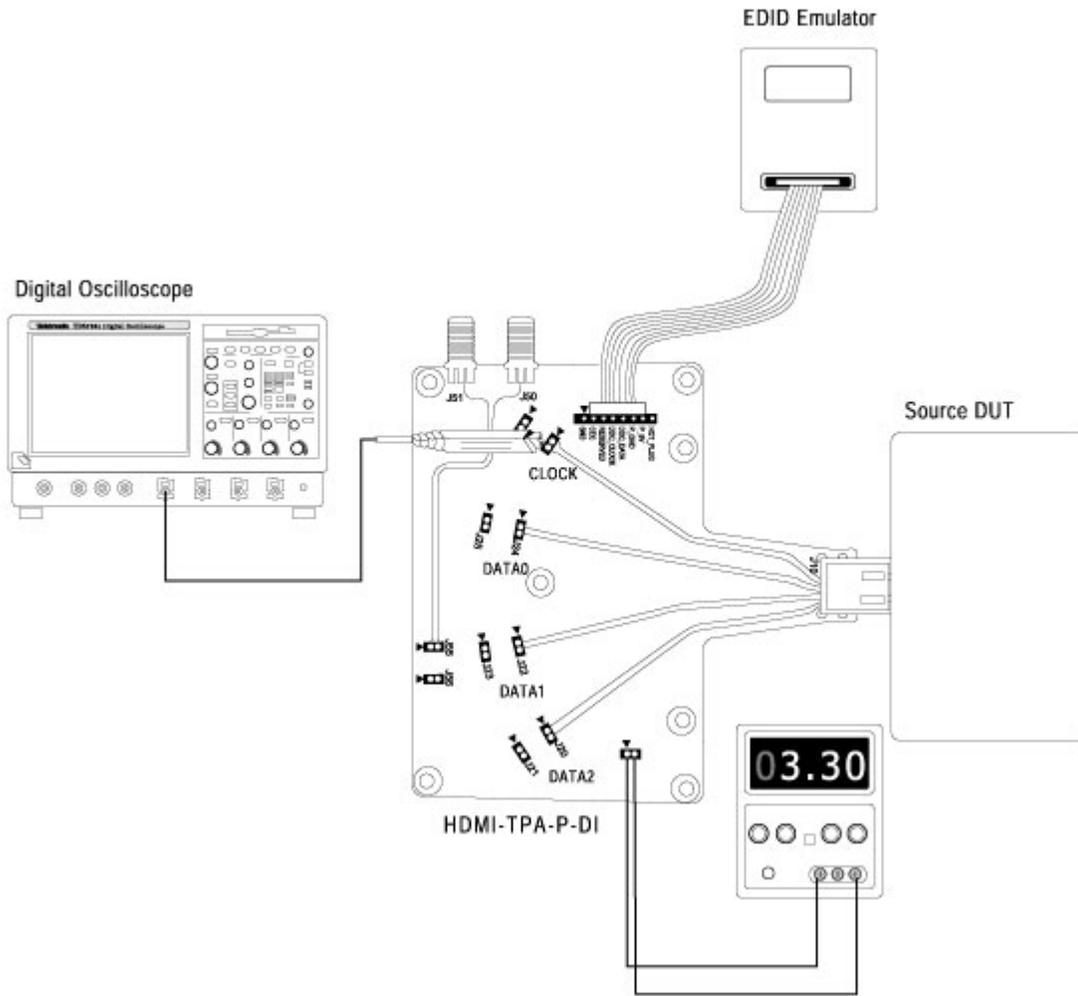


Figure 45: Connections to calculate Tbit

- Connect an TPA-P-DI adapter to a Source DUT HDMI output connector.
- Connect a power supply to a TPA board.
- Configure the Source DUT to output a video format with the required supported pixel clock frequency.
- Connect a TMD5 Clock to the configured oscilloscope channel by using a differential probe.

- In the tbit pane, you have the following options:

Table 22: Tbit pane configure options

| Configure Parameter | Description |
|---------------------|--|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

Note: Tbit value is used for oscilloscope setup and limit calculations. If the DUT's display resolution and the refresh rate changes, you have to recalculate Tbit.

Deskew

Deskew is recommended before you conduct any skew test. To ensure accurate results, deskew the test setup before you conduct the tests from your device under test.

- On the menu bar, click **Utilities > Deskew**.

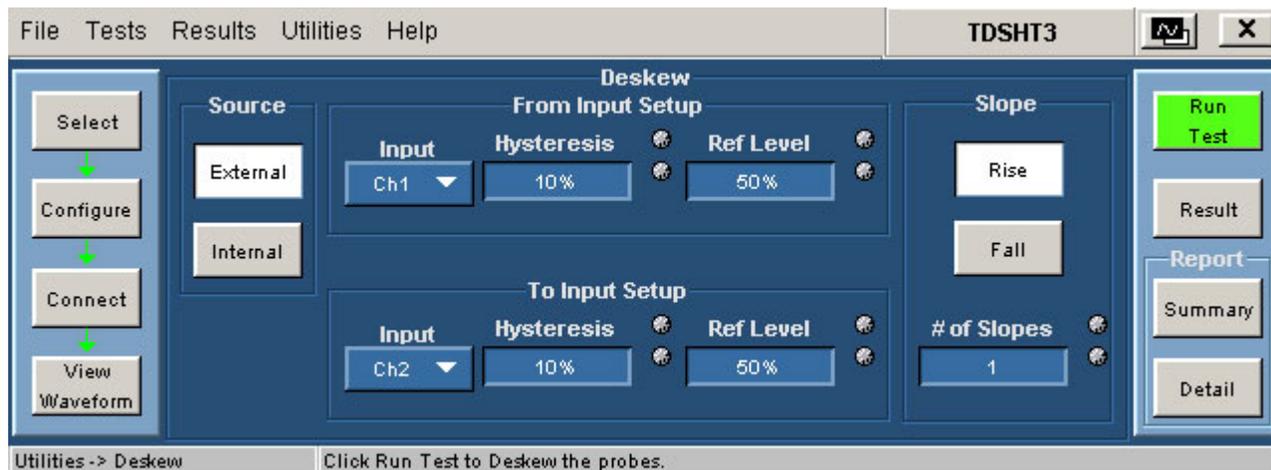


Figure 46: Utilities Deskew pane

- In the source pane, you have the following options:

Table 23: Utilities Deskew Source options

| Configure Parameter | Description |
|---------------------|---|
| External | Click External if you will use an external deskew fixture (such as the clock signal of DUT). |
| Internal | Click Internal to probe the compensation signal on an oscilloscope. |

- Select the input channels between which you want to perform the deskew operation. Hysteresis and Ref Level are available only for an external source.

- In the slope pane, you have the following options:

Table 24: Utilities Deskew Slope options

| Configure Parameter | Description |
|---------------------|--|
| Rise | Click Rise to calculate the average of the number of slopes and then set the skew for a rising pulse. |
| Fall | Click Fall to calculate the average of the number of slopes and then set the skew for a falling pulse. You do not have to calculate the average of the number of slopes for a falling pulse for an internal source. |
| # of Slopes | In the # of Slopes box, enter the required number of slopes to set the skew for either a rising pulse or a falling pulse. Ensure that the required number of slopes is present in the acquisition. |

- Click **Run Test** to deskew the probes.

Select Which Tests to Run

Source

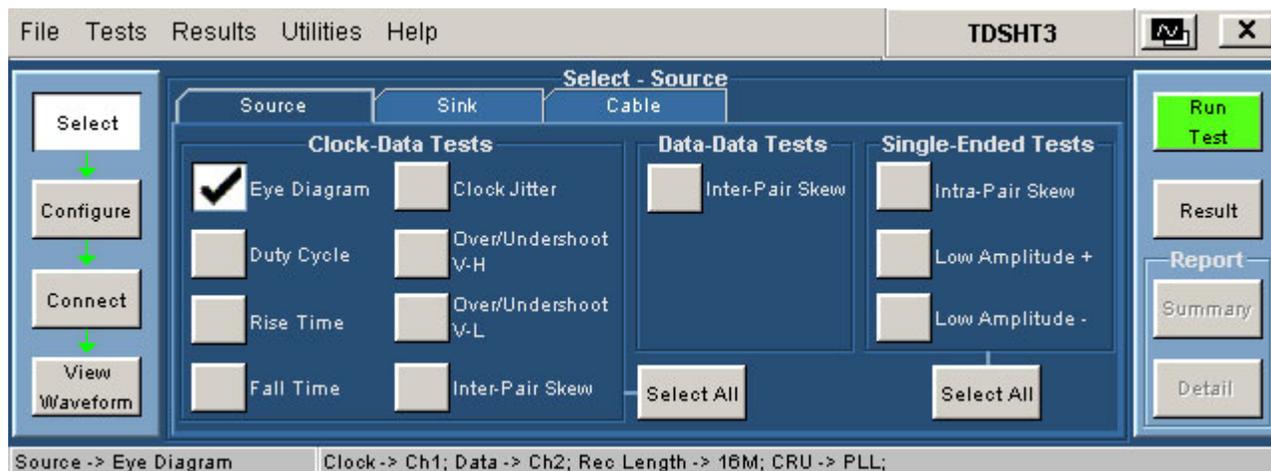


Figure 47: Select Source with Eye diagram test selected

The following table shows how to select the source test parameters:

Table 25: Select Source options

| Test type | How to select |
|---------------------|--|
| Source | Click Tests > Select > Source to select the source tab. |
| Eye Diagram | In the Source tab, select the Eye Diagram check box. |
| Duty Cycle | In the Source tab, select the Duty Cycle check box. |
| Rise Time | In the Source tab, select the Rise Time check box. |
| Fall Time | In the Source tab, select the Fall Time check box. |
| Clock Jitter | In the Source tab, select the Clock Jitter check box. |
| Over/Undershoot V-H | In the Source tab, select the Over/Undershoot V-H check box. |
| Over/Undershoot V-L | In the Source tab, select the Over/Undershoot V-L check box. |
| Inter-Pair Skew | In the Source tab, select the Inter-Pair Skew check box in either the clock-data tests pane or the data-data tests pane. |
| Intra-Pair Skew | In the Source tab, select the Intra-Pair Skew check box. |

Table 25: Select Source options (Contd.)

| Test type | How to select |
|-----------------|---|
| Low Amplitude + | In the Source tab, select the Low Amplitude + check box. |
| Low Amplitude - | In the Source tab, select the Low Amplitude - check box. |
| Select All | In the Source tab, click Select All to select multiple tests either for Clock-Data Tests or Single-Ended Tests. When you select more than one test, Select All changes to Clear All . |

Sink

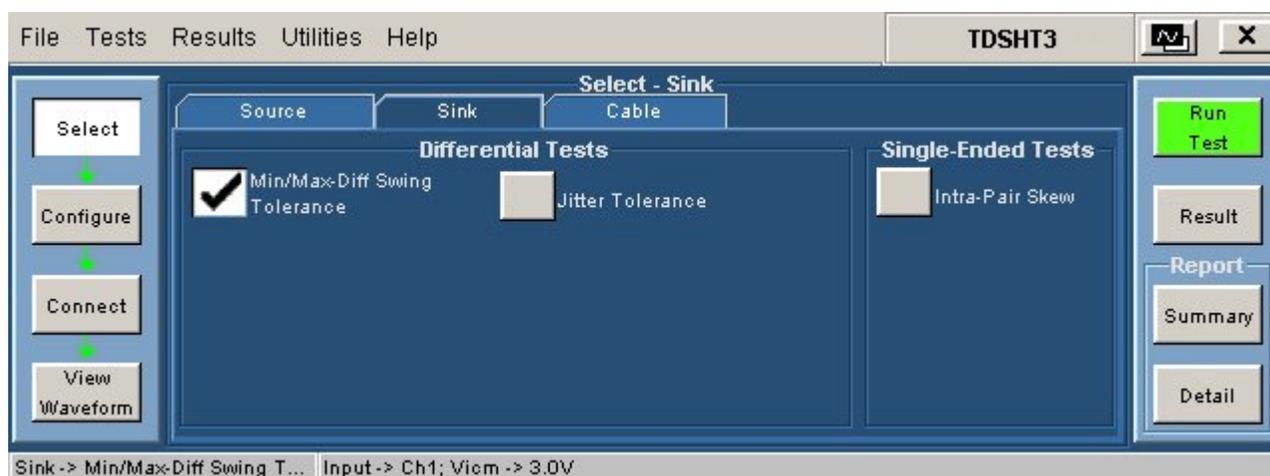


Figure 48: Select Sink with Min/Max-Diff Swing Tolerance test selected

The following table shows how to select the sink test parameters:

Table 26: Select Sink options

| Test type | How to select |
|------------------------------|---|
| Sink | Click Tests > Select > Sink to select the sink tab. |
| Min/Max-Diff Swing Tolerance | In the Sink tab, select the Min/Max-Diff Swing Tolerance check box. |
| Jitter Tolerance | In the Sink tab, select the Jitter Tolerance check box. |
| Intra-Pair Skew | In the Sink tab, select the Intra-Pair Skew check box. |

Cable

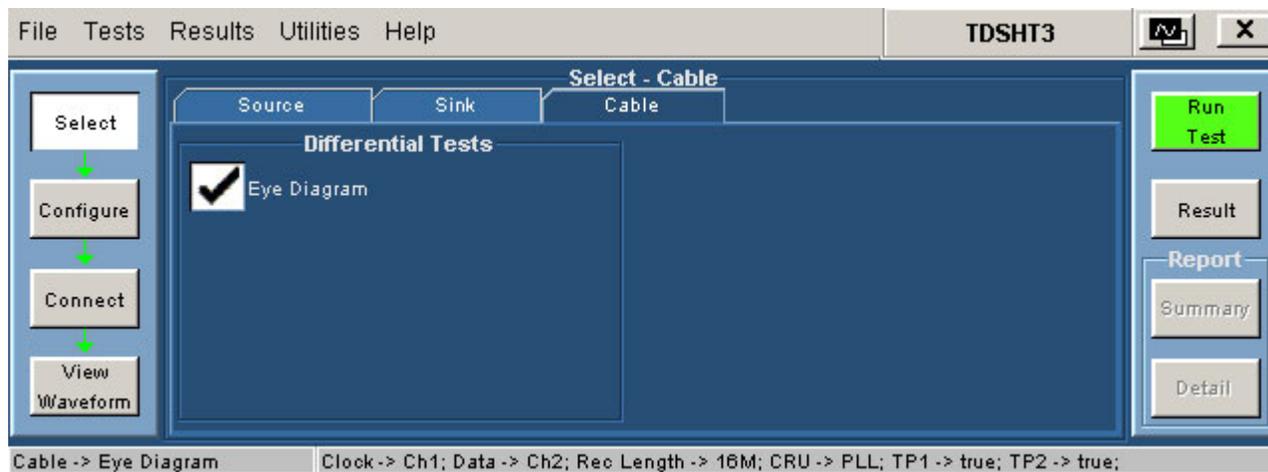


Figure 49: Select Cable with Eye Diagram test selected

The following table shows how to select the cable test parameters:

Table 27: Select Cable options

| Test Type | How to Select |
|-------------|---|
| Cable | Click Tests > Select > Cable to select the cable tab. |
| Eye Diagram | In the Cable tab, select the Eye Diagram check box. |

Configure

Source

On the menu bar, click **Tests > Configure** to configure the parameters for the selected test(s).

In the configure pane, you will see the factory default configuration for the test you selected. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings. For more information about configuration, click the Test help topic, and then go to the specific test.

The following table shows the parameters that you can configure for source (clock-data tests):

| | | | | Source Input | | | | | | | | | |
|--------|-------------------|---------------------|----------------|--------------|-------|------------|---------------|---------------|----------------|---------------|------|-----------|-------|
| Source | | | | | Clock | Hysteresis | Mid Ref Level | Low Ref Level | High Ref Level | Record Length | Tbit | # of Acqs | Units |
| | Clock-Data | | | | | | | | | | | | |
| | | Eye Diagram | Clock and Data | Yes | Yes | Yes | | | | Yes | | | Yes |
| | | Duty Cycle | Clock | | | Yes | | | | | Yes | Yes | Yes |
| | | Rise Time | Clock or Data | | | | Yes | Yes | | | Yes | Yes | Yes |
| | | Fall Time | Clock or Data | | | | Yes | Yes | | | Yes | Yes | Yes |
| | | Clock Jitter | Clock | Yes | Yes | Yes | | | | Yes | | | Yes |
| | | Over/Undershoot V-H | Clock or Data | | | | | | | | Yes | Yes | |
| | | Over/Undershoot V-L | Clock or Data | | | | | | | | Yes | Yes | |
| | | Inter-Pair Skew | Data and Clock | | Yes | Yes | | | | | Yes | | Yes |

Figure 50: Parameters for Source Clock-Data tests

The following table shows the parameters that you can configure for source (data-data tests):

| | | | | Source Input | | | | |
|--------|------------------|-----------------|-----------------------|--------------|------------|---------------|------|-------|
| Source | | | | | Hysteresis | Mid Ref Level | Tbit | Units |
| | Data-Data | | | | | | | |
| | | Inter-Pair Skew | Data+ and Data, Clock | Yes | Yes | Yes | Yes | Yes |

Figure 51: Parameters for Source Data-Data tests

The following table shows the parameters that you can configure for source (single-ended tests):

| | | | Source Input | Avcc | Tbit | # of Acqs |
|---------------|---------------------|-----------------|----------------------|------|------|-----------|
| Source | | | | | | |
| | Single-Ended | | | | | |
| | | Intra-Pair Skew | Data+ or Data-/Clock | | Yes | Yes |
| | | Low Amplitude + | Data+ or Data-/Clock | Yes | Yes | Yes |
| | | Low Amplitude - | Data+ or Data-/Clock | Yes | Yes | Yes |

Figure 52: Parameters for Source Single-Ended tests

Sink

On the menu bar, click **Tests > Configure** to configure the parameters for the selected test.

In the configure pane, you will see the factory default configuration for the test you selected. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings. For more information about configuration, click the Test help topic, and then go to the specific test.

The following table shows the parameters that you can configure for sink (differential tests):

| | | | Source Input | Clock | Hysteresis | Mid Ref Level | Record Length | Units | DTG Pattern Path | DTG Output | Vicm | Frequency Pair | DUT Freq (MHz) |
|-------------|---------------------|------------------------------|----------------|-------|------------|---------------|---------------|-------|------------------|------------|------|----------------|----------------|
| Sink | | | | | | | | | | | | | |
| | Differential | | | | | | | | | | | | |
| | | Min/Max-Diff Swing Tolerance | Data | | | | | | Yes | Yes | Yes | | |
| | | Jitter Tolerance | Clock and Data | Yes | Yes | Yes | Yes | Yes | Yes | Yes | | Yes | Yes |

Figure 53: Parameters for Sink Differential test

The following table shows the parameters that you can configure for sink (single-ended tests):

| | | | Source Input | Tbit | DTG Pattern Path | DTG Output |
|-------------|---------------------|-----------------|--------------|------|------------------|------------|
| Sink | | | | | | |
| | Single-Ended | | | | | |
| | | Intra-Pair Skew | Clock | Yes | Yes | Yes |

Figure 54: Parameters for Sink Single-Ended tests

Cable

On the menu bar, click **Tests > Configure** to configure the parameters for the selected test.

In the configure pane, you will see the factory default configuration for the test you selected. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings. For more information about configuration, click the Test help topic, and then go to the specific test.

The following table shows the parameters that you can configure for cable (differential tests):

| | | | Source Input | Clock | Hysteresis | Mid Ref Level | Record Length | Units | TP1-TP2 | DTG Pattern Path | DTG Output |
|--------------|---------------------|-------------|----------------|-------|------------|---------------|---------------|-------|---------|------------------|------------|
| Cable | | | | | | | | | | | |
| | Differential | | | | | | | | | | |
| | | Eye Diagram | Clock and Data | Yes | Yes | Yes | Yes | Yes | Yes | Yes | Yes |

Figure 55: Parameters for Cable Differential tests

Connect

Source – Eye Diagram

1. On the menu bar, click **Tests > Connect**.
2. Make the connections as follows:

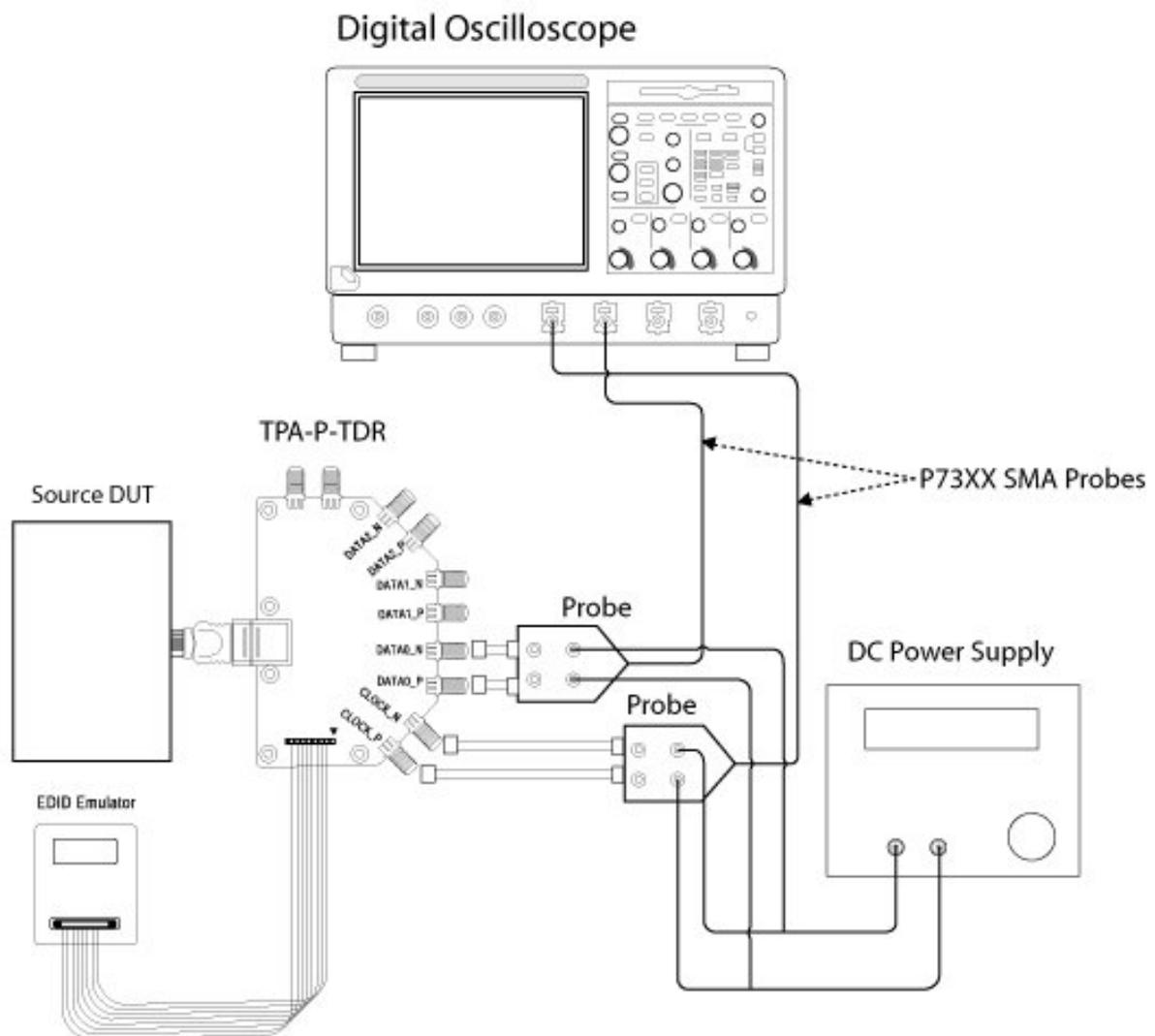


Figure 56: Connections for Source Eye Diagram

- Connect the HDMI output of the source DUT to the TPA-P-TDR adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Connect a TMDS Clock to the configured oscilloscope channel by using a SMA differential probe.
- Connect the TMDS_DATA pair on which you will conduct the test to the configured oscilloscope channel by using a SMA differential probe.
- Configure the Source DUT to output the required video format.

Source – Duty Cycle

1. On the menu bar, click **Tests > Connect**.
2. Make the connections as follows:

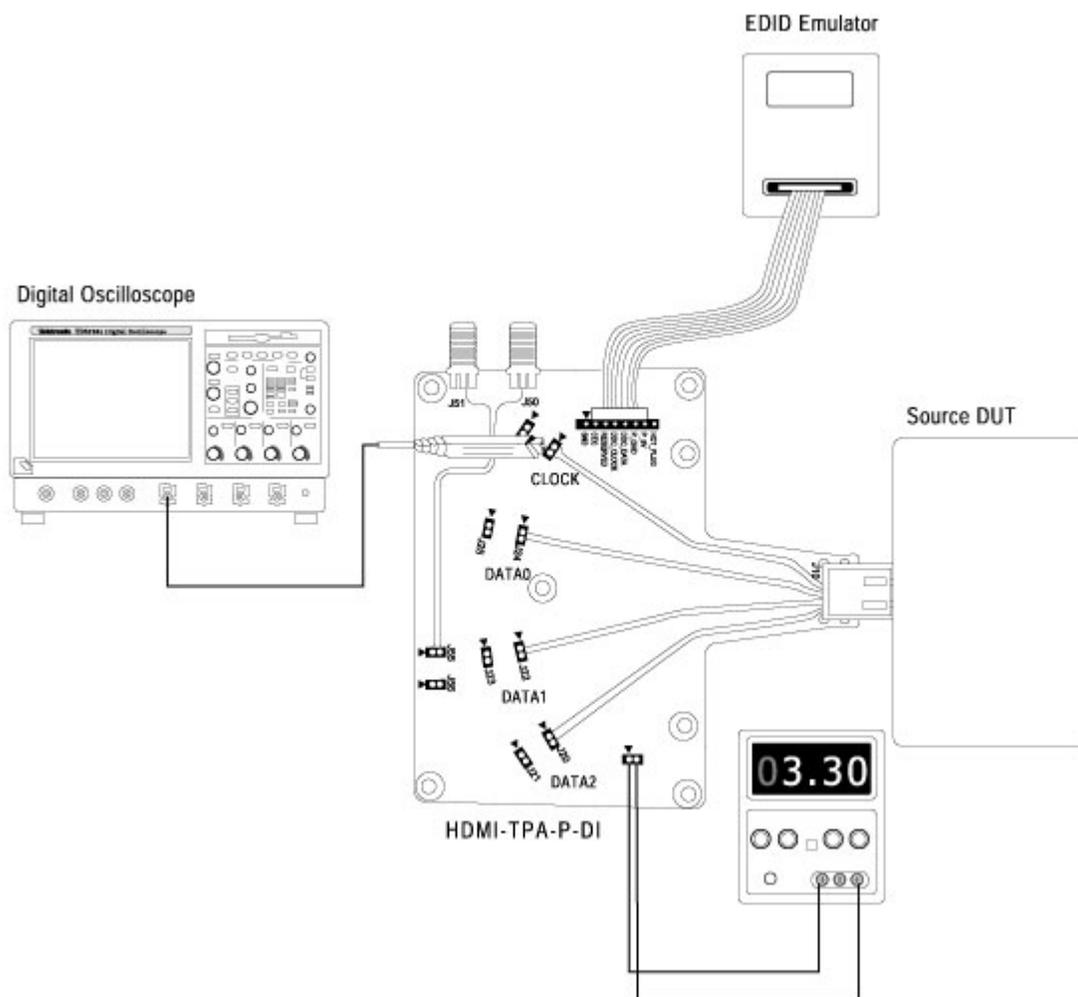


Figure 57: Connections for Source Duty Cycle

- Connect the HDMI output of the source DUT to the TPA-P-DI adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).

- Configure the Source DUT to output a video format with the required supported pixel clock frequency.
- Connect a TMDS Clock to the configured oscilloscope channel by using a differential probe.

Source – Rise Time

1. On the menu bar, click **Tests > Connect**.
2. Make the connections as follows:

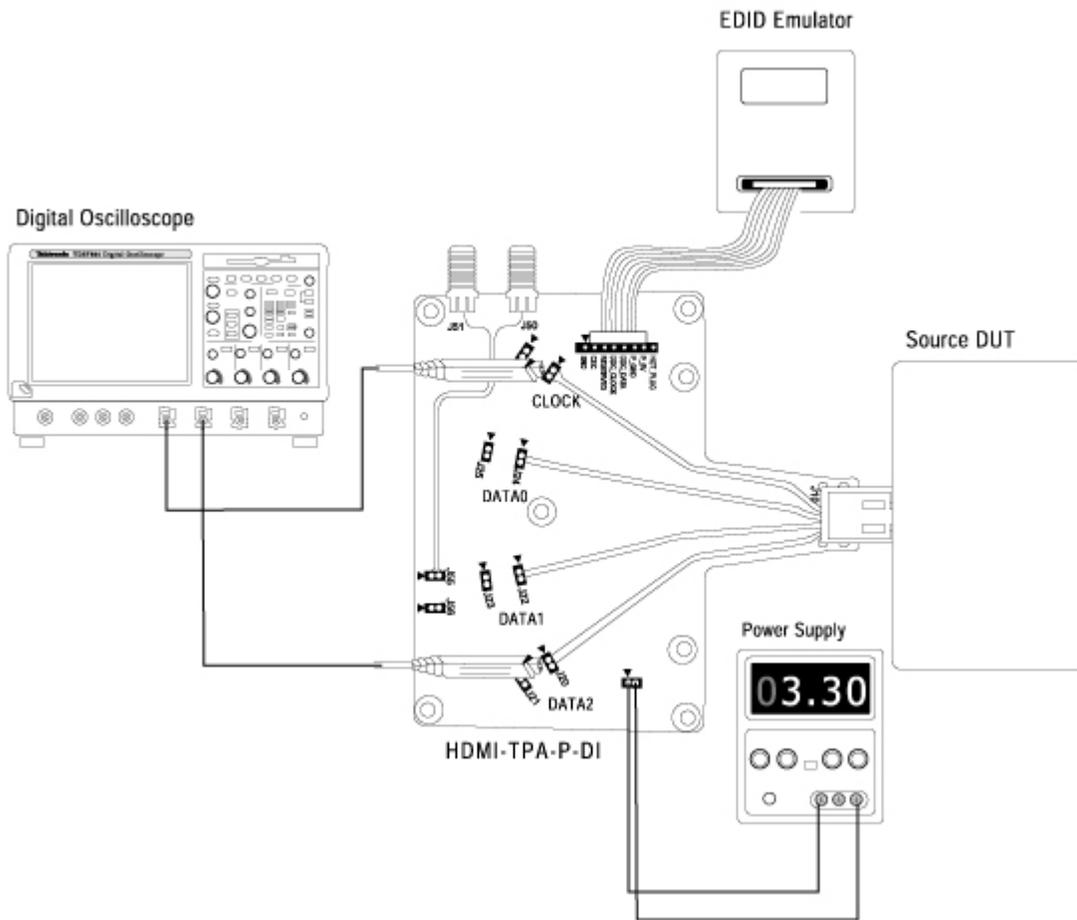


Figure 58: Connections for Source Rise Time

- Connect the HDMI output of the source DUT to the TPA-P-DI adapter.
 - Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
 - Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
 - Configure the Source DUT to output a video format with the required supported pixel clock frequency.

- Connect a differential probe to a TMDS_DATA/CLOCK.
- If you have selected 'Re-calculate Tbit' in the configuration pane, then connect the clock channel to the configured oscilloscope channel by using a second differential probe.

Source – Fall Time

1. On the menu bar, click **Tests > Connect**.
2. Make the connections as follows:

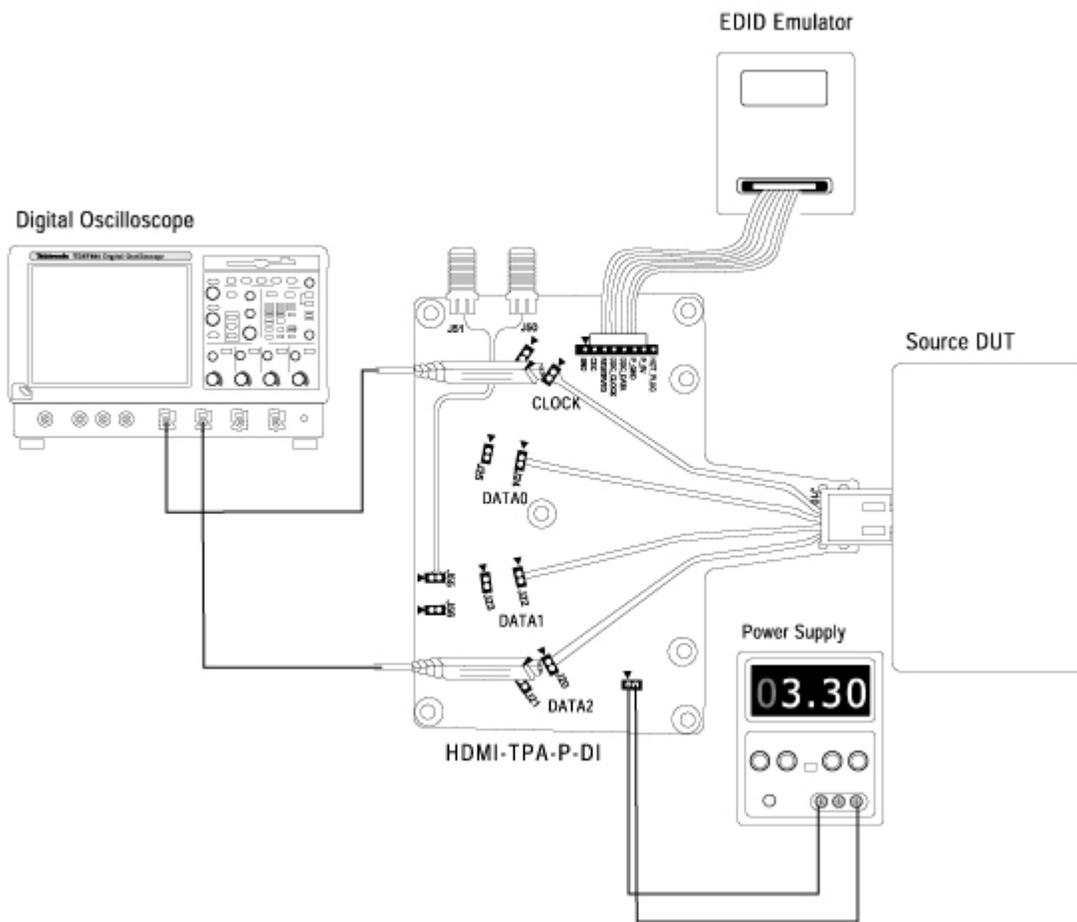


Figure 59: Connections for Source Fall Time

- Connect the HDMI output of the source DUT to the TPA-P-DI adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Configure the Source DUT to output a video format with the highest supported pixel clock frequency.

- Connect a differential probe to TMDS_DATA/CLOCK.
- If you have selected 'Re-calculate Tbit' in the configuration pane, then connect the clock channel to the configured oscilloscope channel by using a second differential probe.

Source – Clock Jitter

1. On the menu bar, click **Tests > Connect**.
2. Make the connections as follows:

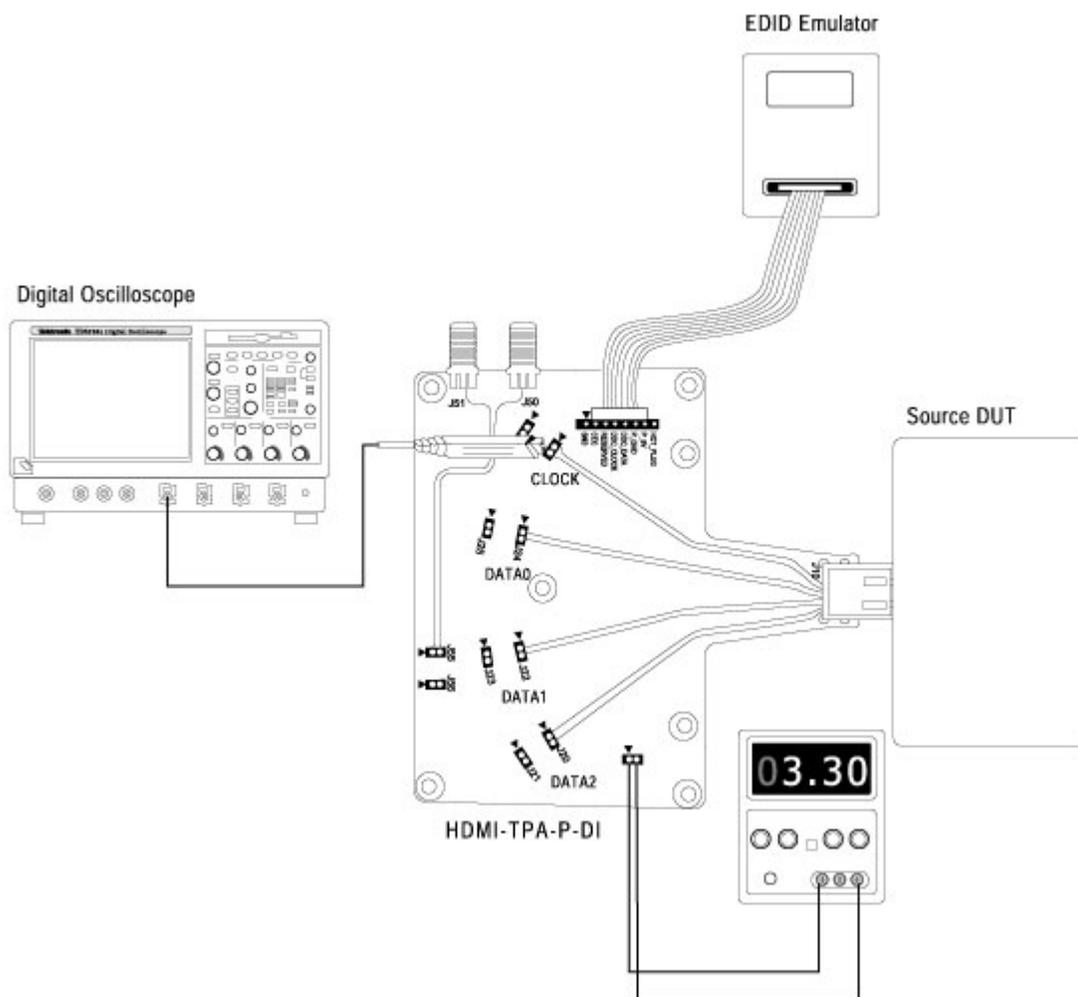


Figure 60: Connections for Source Clock Jitter

- Connect the HDMI output of the source DUT to the TPA-P-DI adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).

- Configure the Source DUT to output a video format with the required supported pixel clock frequency.
- Connect a TMDS Clock to the configured oscilloscope channel by using a differential probe.

Source – Over/Undershoot V-H (Voltage-High)

1. On the menu bar, click **Tests > Connect**.
2. Make the connections as follows:

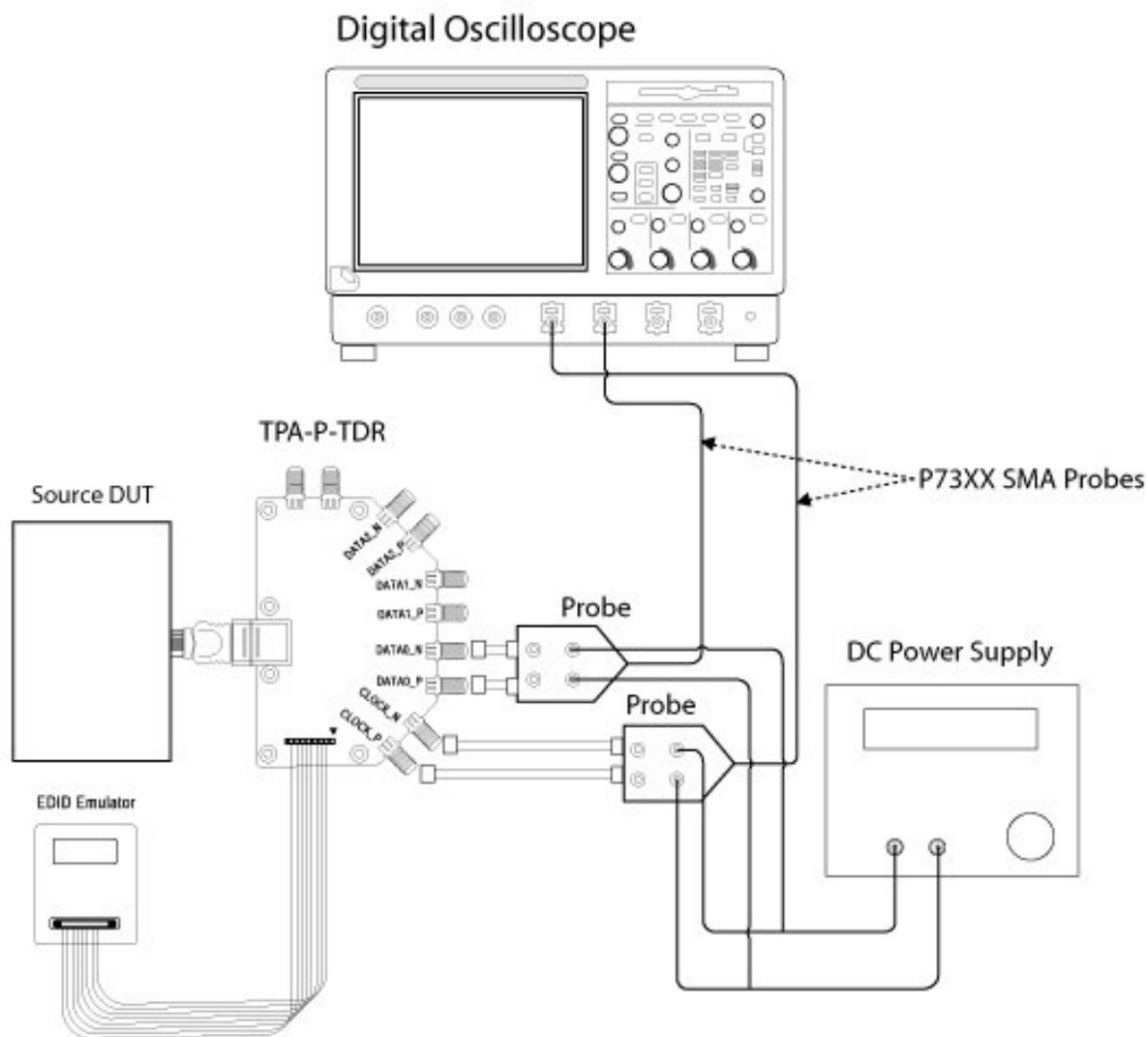


Figure 61: Connections for Source Over/Undershoot V-H

- Connect the HDMI output of the source DUT to the TPA-P-TDR adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.

- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Configure the Source DUT to output a video format with the required supported pixel clock frequency.
- Connect a SMA differential probe to TMDS_DATA/CLOCK.
- If you have selected 'Re-calculate Tbit' in the configuration pane, then connect the clock channel to the configured oscilloscope channel by using a SMA differential probe.

Source – Over/Undershoot V-L (Voltage-Low)

1. On the menu bar, click **Tests > Connect**.
2. Make the connections as follows:

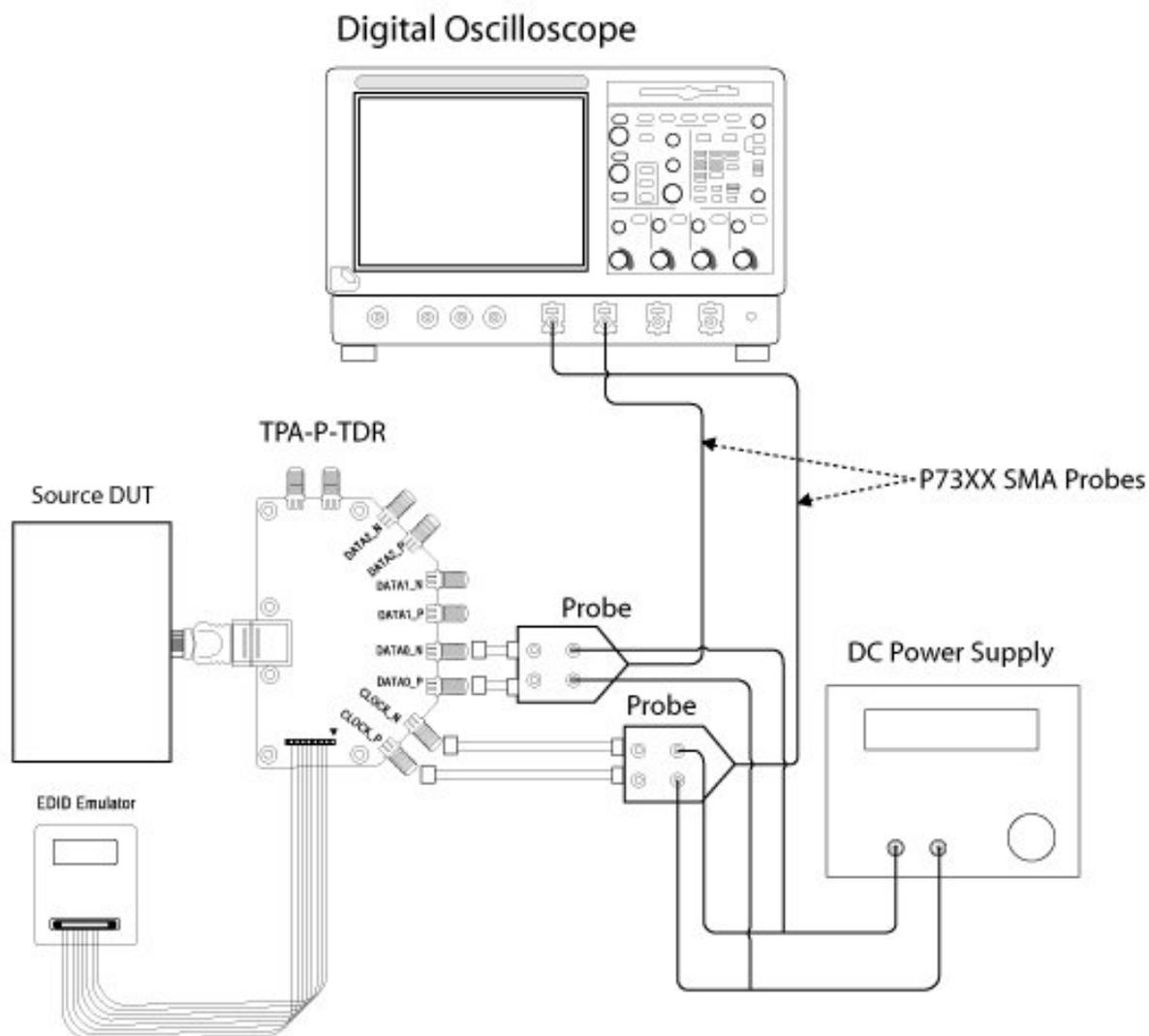


Figure 62: Connections for Source Over/Undershoot V-L

- Connect the HDMI output of the source DUT to the TPA-P-TDR adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.

- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Configure the Source DUT to output a video format with the required supported pixel clock frequency.
- Connect a SMA differential probe to TMDS_DATA/CLOCK.
- If you have selected 'Re-calculate Tbit' in the configuration pane, then connect the clock channel to the configured oscilloscope channel by using a SMA differential probe.

Source – Inter-Pair Skew for Clock-Data Tests

Note: The connection diagram shows both the probes connected to the data signals, instead of one probe being connected to clock signal and the other probe to the configured data signal on the fixture.

1. On the menu bar, click **Tests > Connect**.
2. Make the connections for Clock to Data Skew as follows:

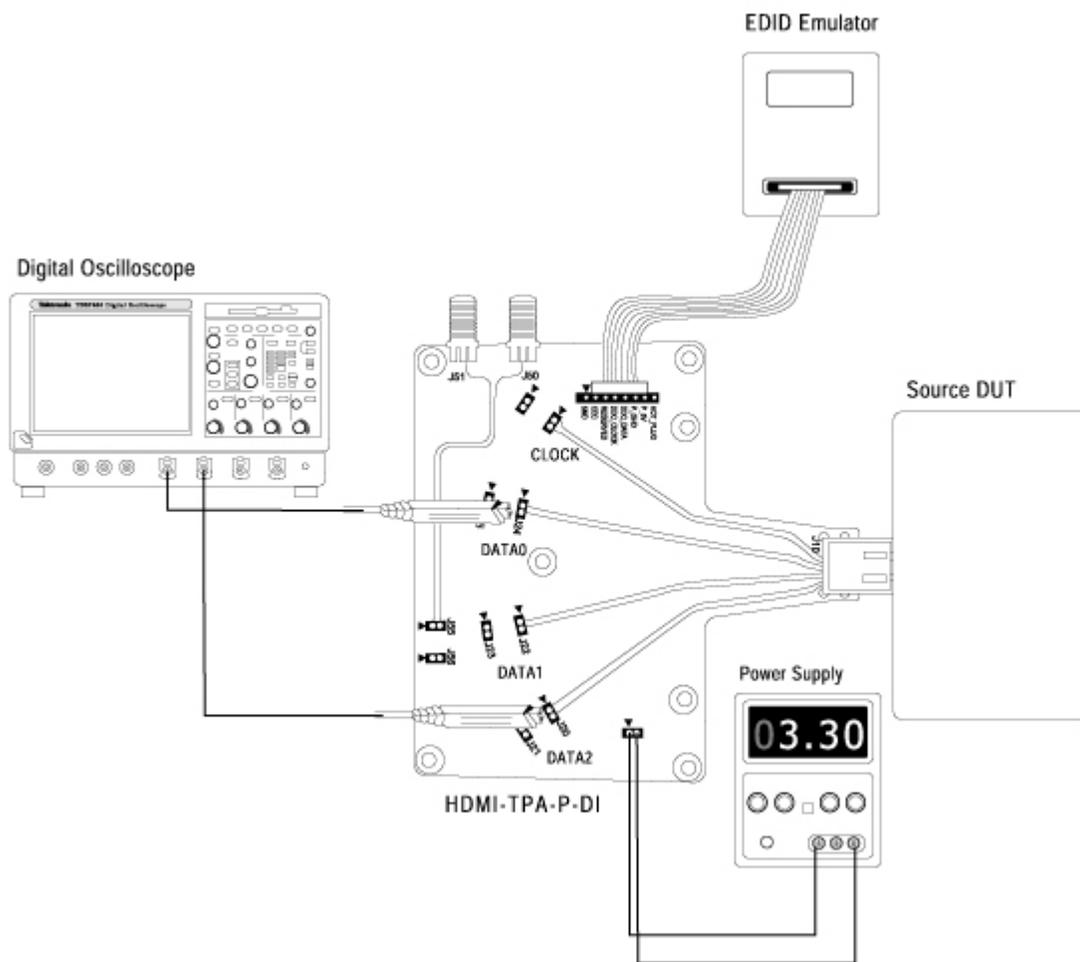


Figure 63: Connections for Inter-Pair Skew (Clock-Data)

Connect the HDMI output of the source DUT to the TPA-P-DI adapter.

- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Connect a TMDS Clock to the configured oscilloscope channel by using a differential probe.
- Connect the TMDS_DATA pair on which you will conduct the test to the configured oscilloscope channel by using a second differential probe.
- Configure the Source DUT to output the required video format.

Source – Clock-Data Tests Select All

1. On the menu bar, click **Tests > Connect**.
2. Make the connections as follows:

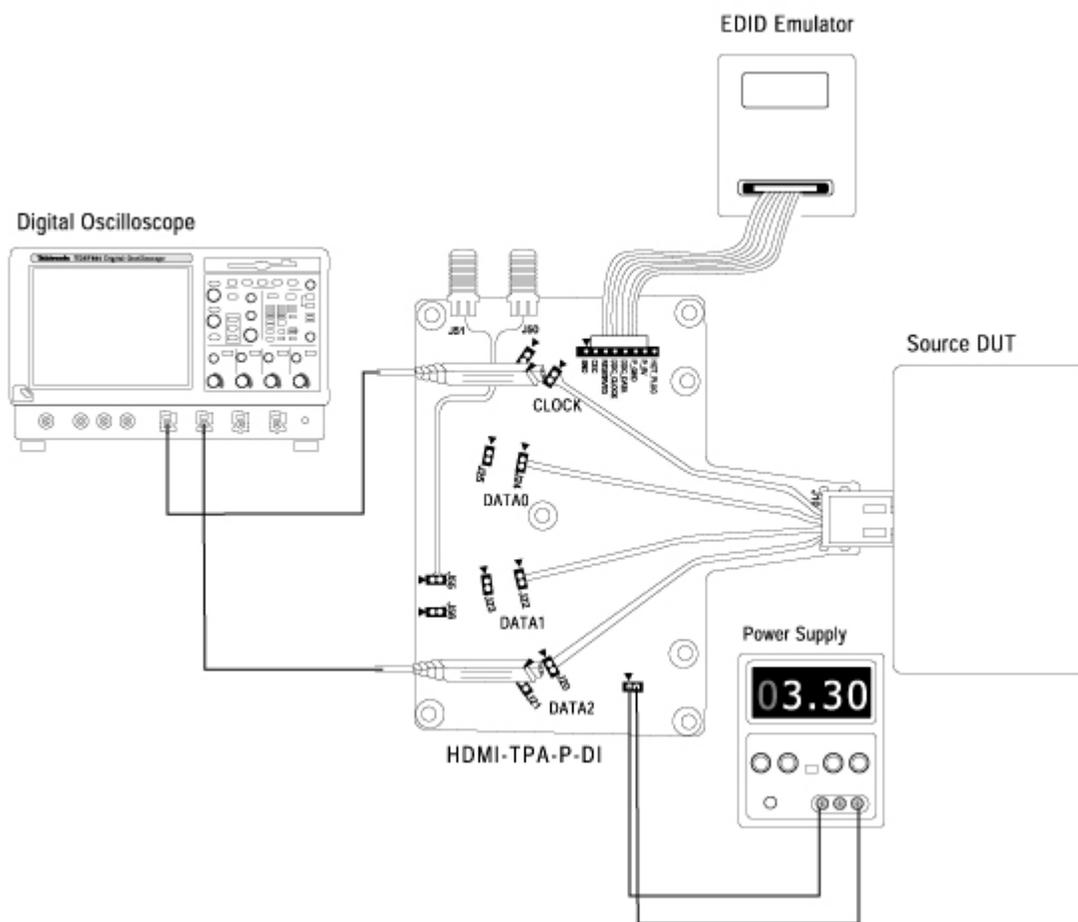


Figure 64: Connections for Source Clock-Data tests (with Select All option)

- Connect the HDMI output of the source DUT to the TPA-P-DI adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Connect a TMDS Clock to the configured oscilloscope channel by using a differential probe.

- Connect the TMDS_DATA pair on which you will conduct the test to the configured oscilloscope channel by using a second differential probe.
- Configure the Source DUT to output the required video format.

Note: For Single-Ended Tests Select All, use the Source Intra-Pair Skew connect procedure.

Source – Inter-Pair Skew for Data-Data Tests

On the menu bar, click **Tests > Connect**.

Setup 1: If you have selected 'Re-calculate Tbit' in the configuration pane

Make the connections as follows:

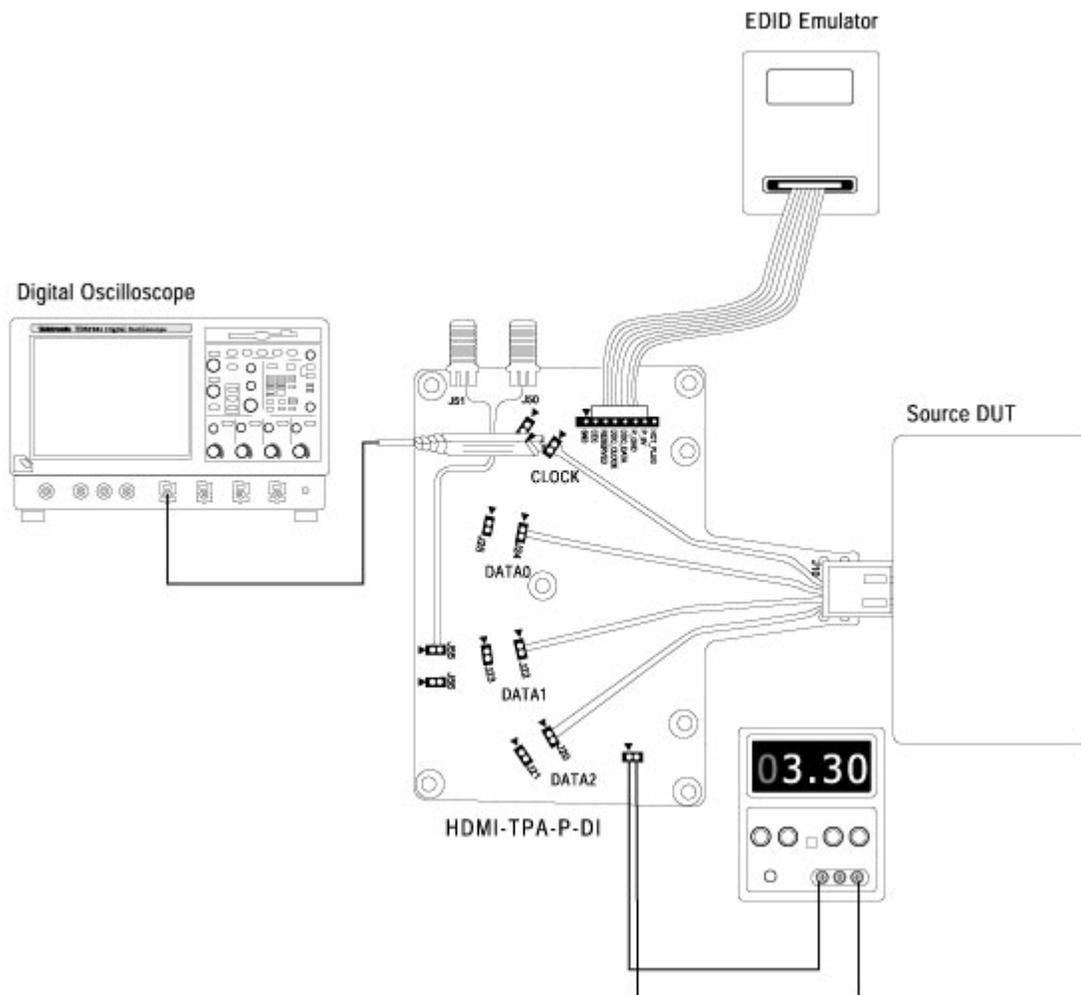


Figure 65: Connections for Inter-Pair Skew of Data-Data tests (with Re-calculate Tbit option selected)

- Connect the HDMI output of the source DUT to the TPA-P-DI adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.

- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Configure the Source DUT to output a video format with the required supported pixel clock frequency.
- Connect a TMDS Clock to the configured oscilloscope channel by using a differential probe.

Setup 2: If you have selected 'Existing Tbit' value or if you are calculating the inter-pair skew for data-data tests

Make the connections for Data to Data Skew as follows:

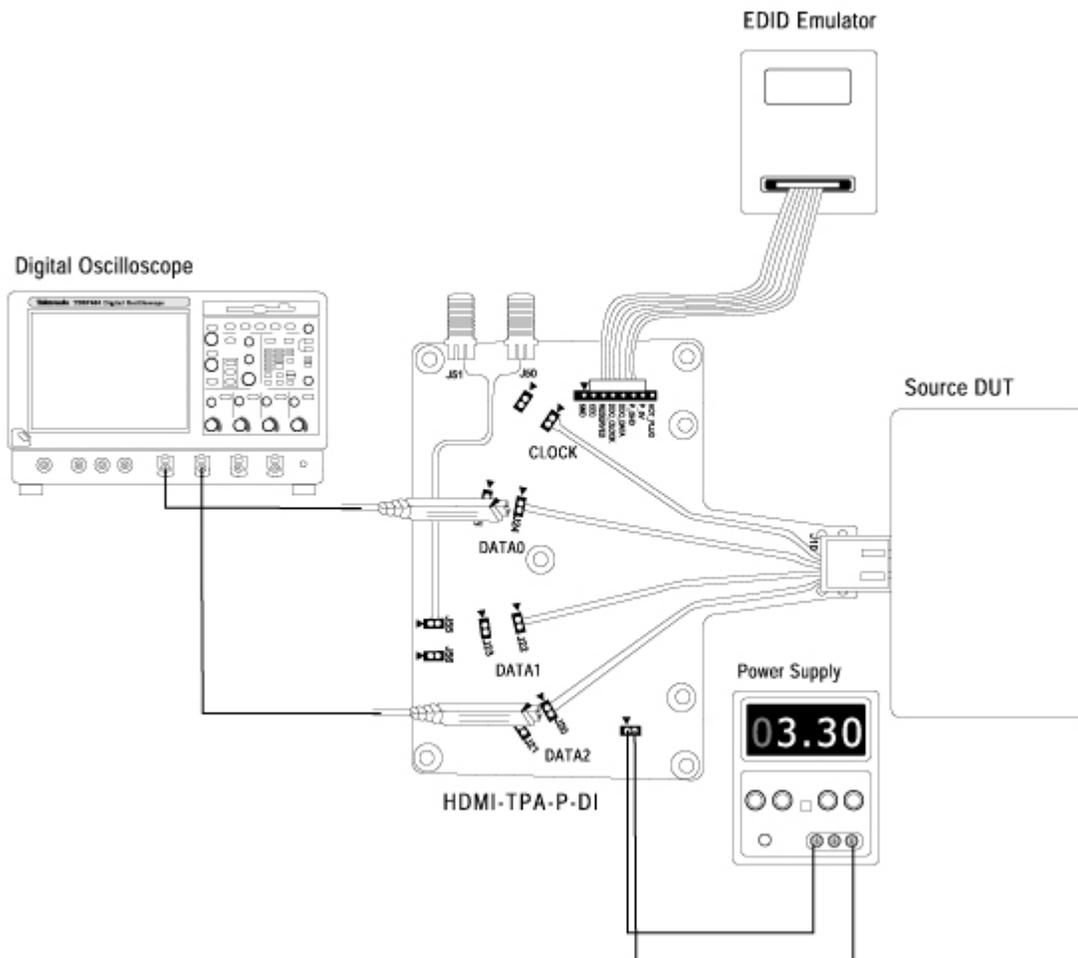


Figure 66: Connections for Source Inter-Pair Skew of Data-Data tests (with Existing Tbit option selected)

- Connect the HDMI output of the source DUT to the TPA-P-DI adapter.

- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Connect a TMDS_DATA<X> Clock to the configured oscilloscope channel by using a differential probe.
- Connect the TMDS_DATA<Y> pair on which you will conduct the test to the configured oscilloscope channel by using a second differential probe.
- Configure the Source DUT to output the required video format.

Source – Intra-Pair Skew

On the menu bar, click **Tests > Connect**.

Setup 1: If you have selected 'Re-calculate Tbit' in the configuration pane

Make the connections as follows:

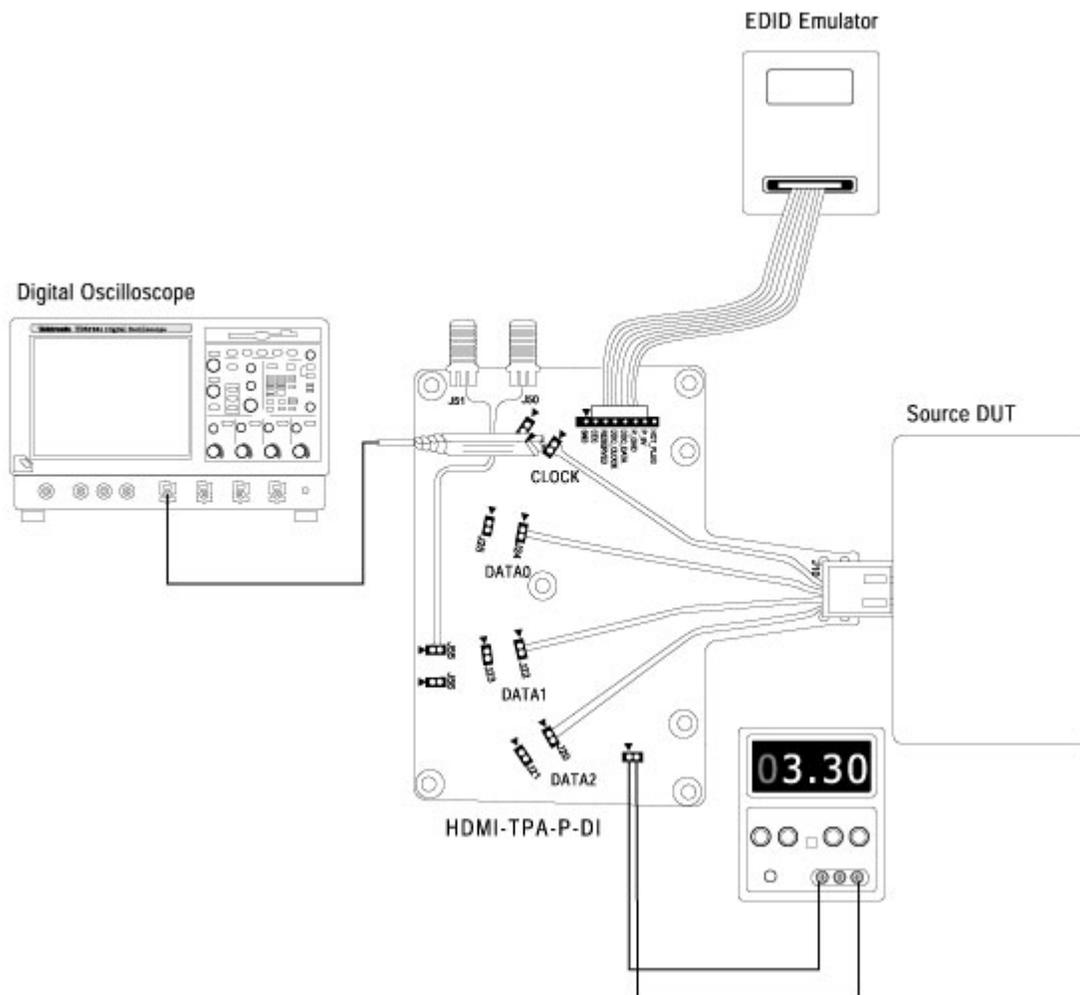


Figure 67: Connections for Source Intra-Pair Skew test (with Re-calculate Tbit option selected)

- Connect the HDMI output of the source DUT to the TPA-P-DI adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.

- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Configure the Source DUT to output a video format with the required supported pixel clock frequency.
- Connect a TMDS Clock to the configured oscilloscope channel by using a differential probe.

Setup 2: If you have selected 'Existing Tbit' value or if you are calculating the intra-pair skew

Make the connections as follows:

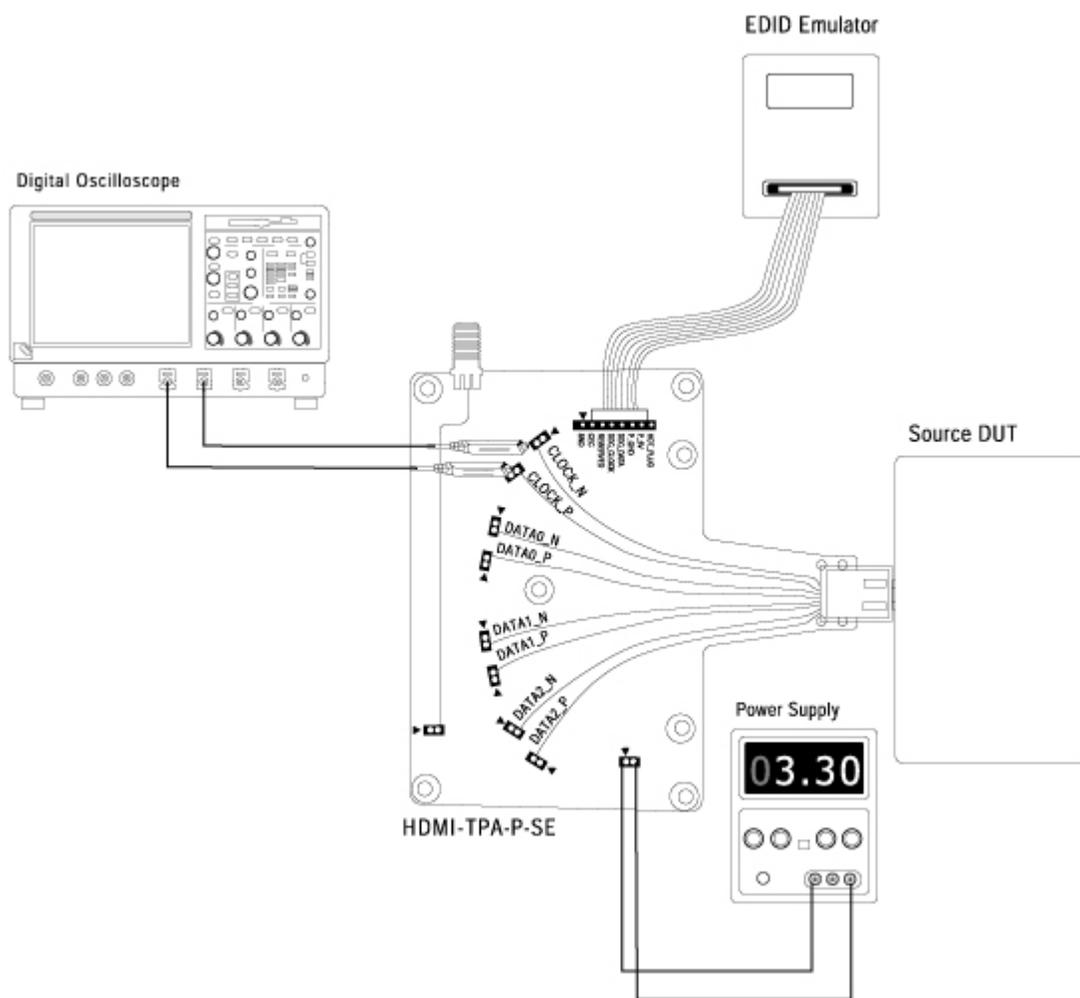


Figure 68: Connections for Source Intra-Pair Skew test (with Existing Tbit option selected)

- Connect the HDMI output of the source DUT to the TPA-P-SE adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Connect the first single-ended probe to TMDS_DATA<X>+/TMDS_CLOCK+.
- Connect the second single-ended probe to TMDS_DATA<X>- /TMDS_CLOCK+.
- Configure the Source DUT to output a video format with the required supported pixel clock frequency.

Source – Low Amplitude +

On the menu bar, click **Tests > Connect**.

Setup 1: If you have selected 'Re-calculate Tbit' in the configuration pane

Make the connections as follows:

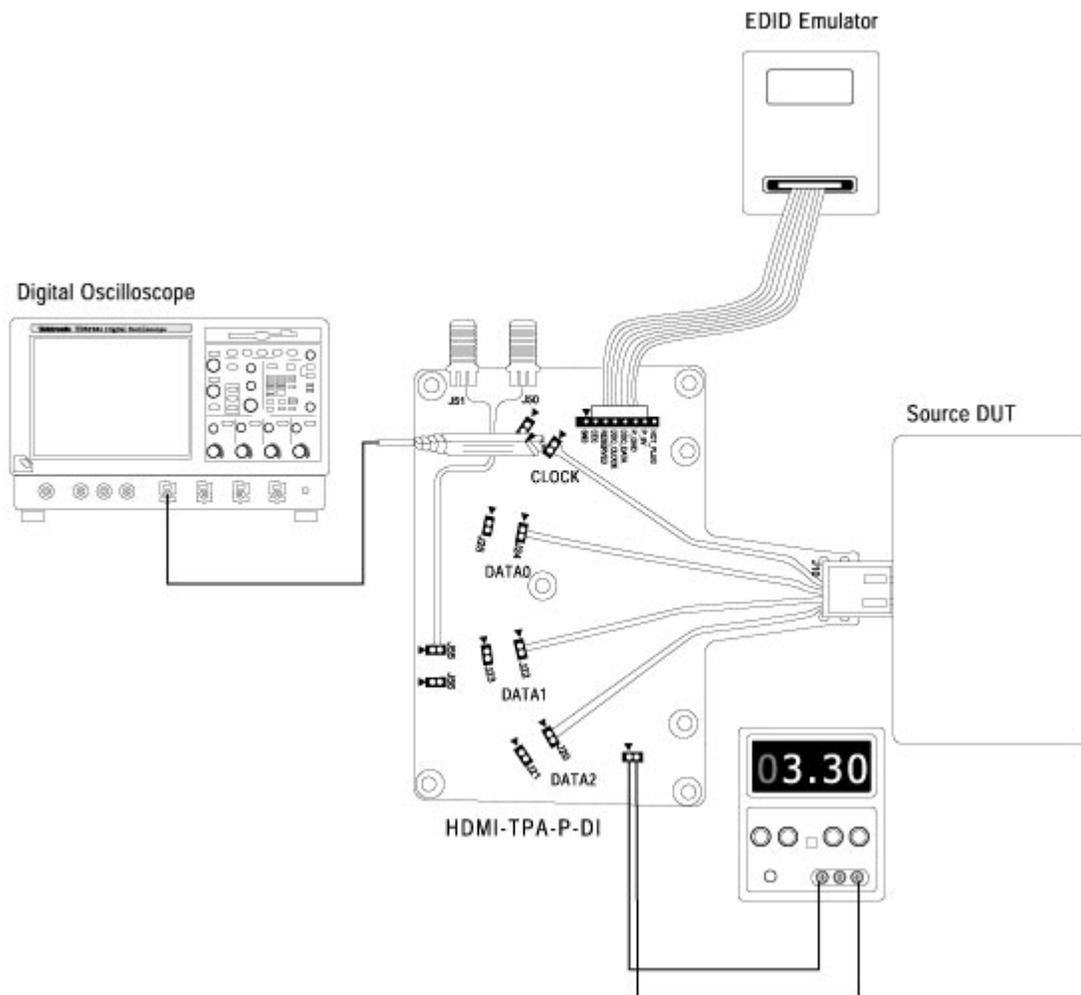


Figure 69: Connections for Low Amplitude + (with Re-calculate Tbit option selected)

- Connect the HDMI output of the source DUT to the TPA-P-DI adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.

- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Configure the Source DUT to output a video format with the required supported pixel clock frequency.
- Connect a TMDS Clock to the configured oscilloscope channel by using a differential probe.

Setup 2: If you have selected 'Existing Tbit' value or if you are calculating low amplitude

Make the connections as follows:

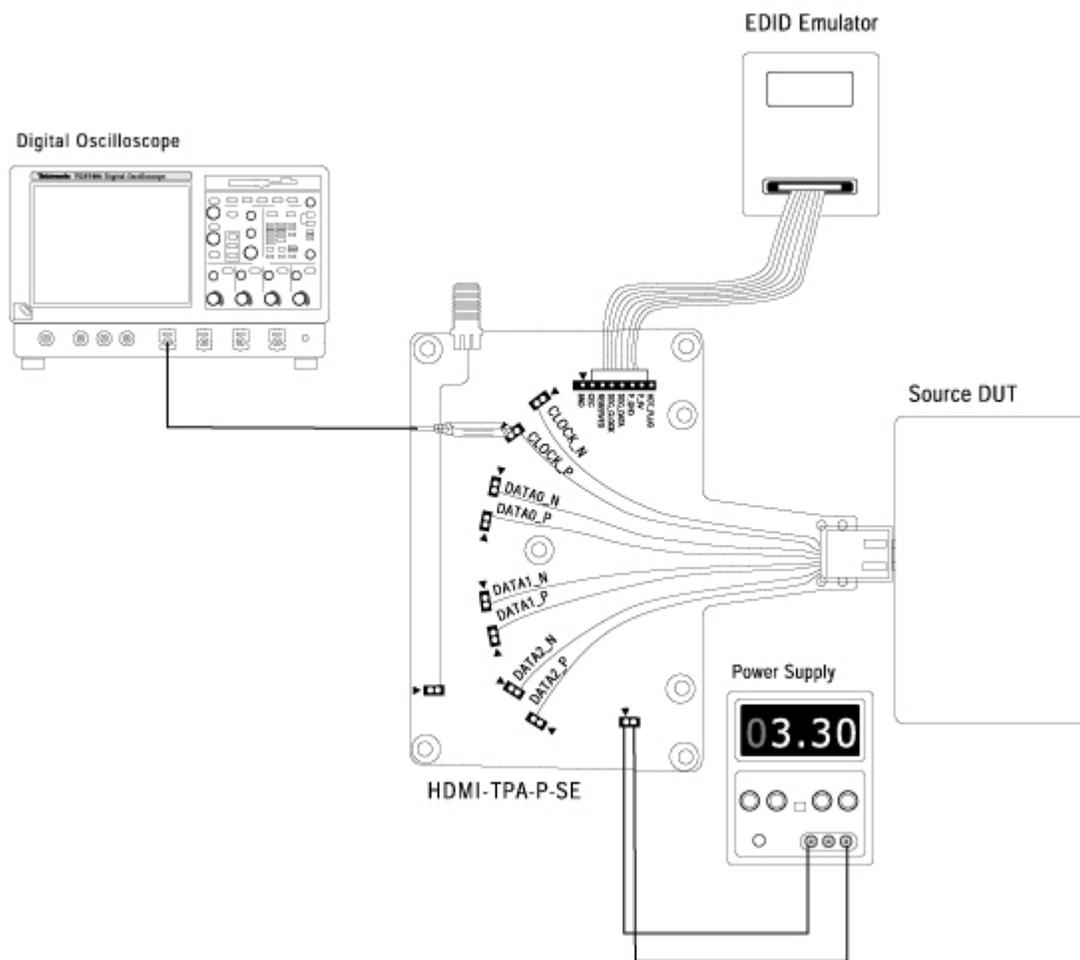


Figure 70: Connections for Low Amplitude + (with Existing Tbit option selected)

- Connect the HDMI output of the source DUT to the TPA-P-SE adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Connect the first single-ended probe to TMDS_DATA<X>+/TMDS_CLOCK+.
- Configure the Source DUT to output a video format with the required supported pixel clock frequency.

Source – Low Amplitude -

On the menu bar, click **Tests > Connect**.

Setup 1: If you have selected 'Re-calculate Tbit' in the configuration pane

Make the connections as follows:

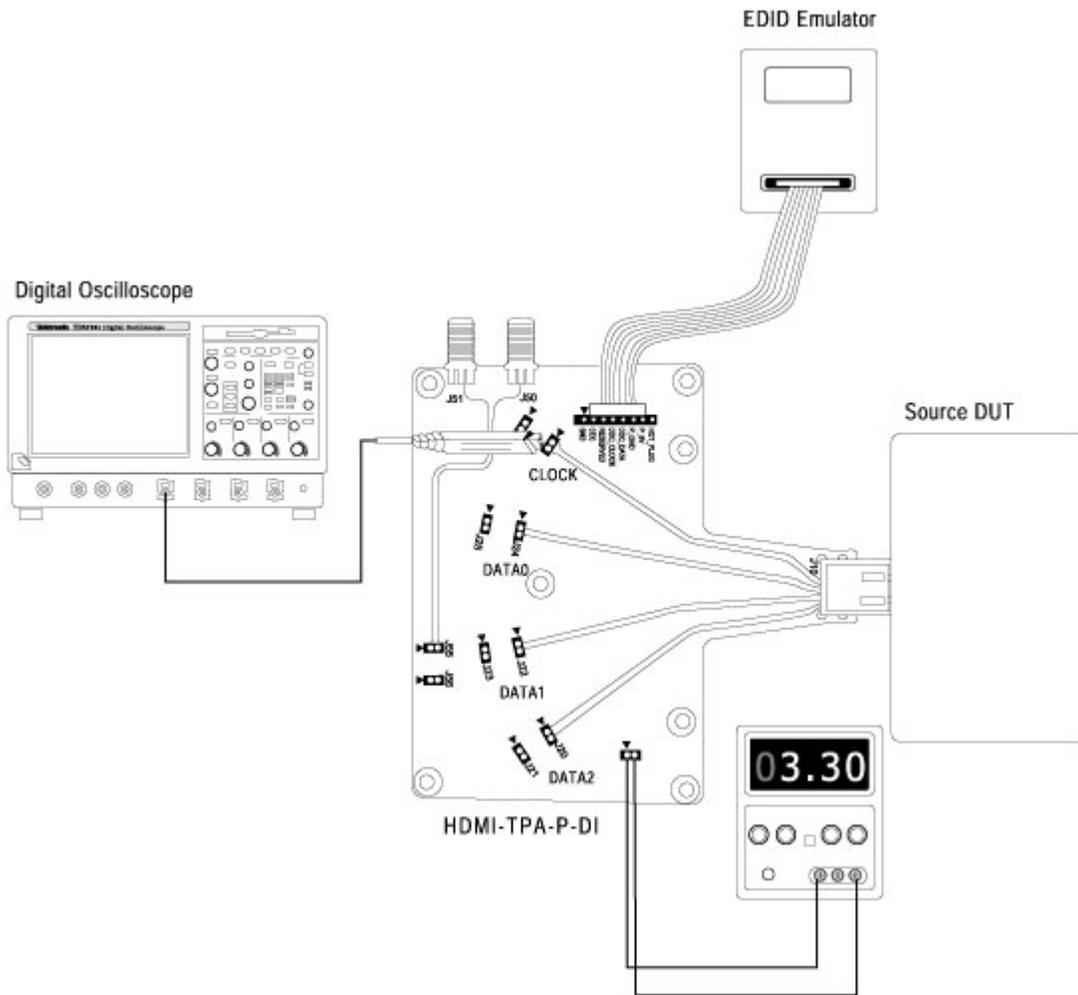


Figure 71: Connections for Low Amplitude - (with Re-calculate Tbit option selected)

- Connect the HDMI output of the source DUT to the TPA-P-DI adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).
- Configure the Source DUT to output a video format with the required supported pixel clock frequency.
- Connect a TMDS Clock to the configured oscilloscope channel by using a differential probe.

Setup 2: If you have selected 'Existing Tbit' value or if you are calculating low amplitude

Make the connections as follows:

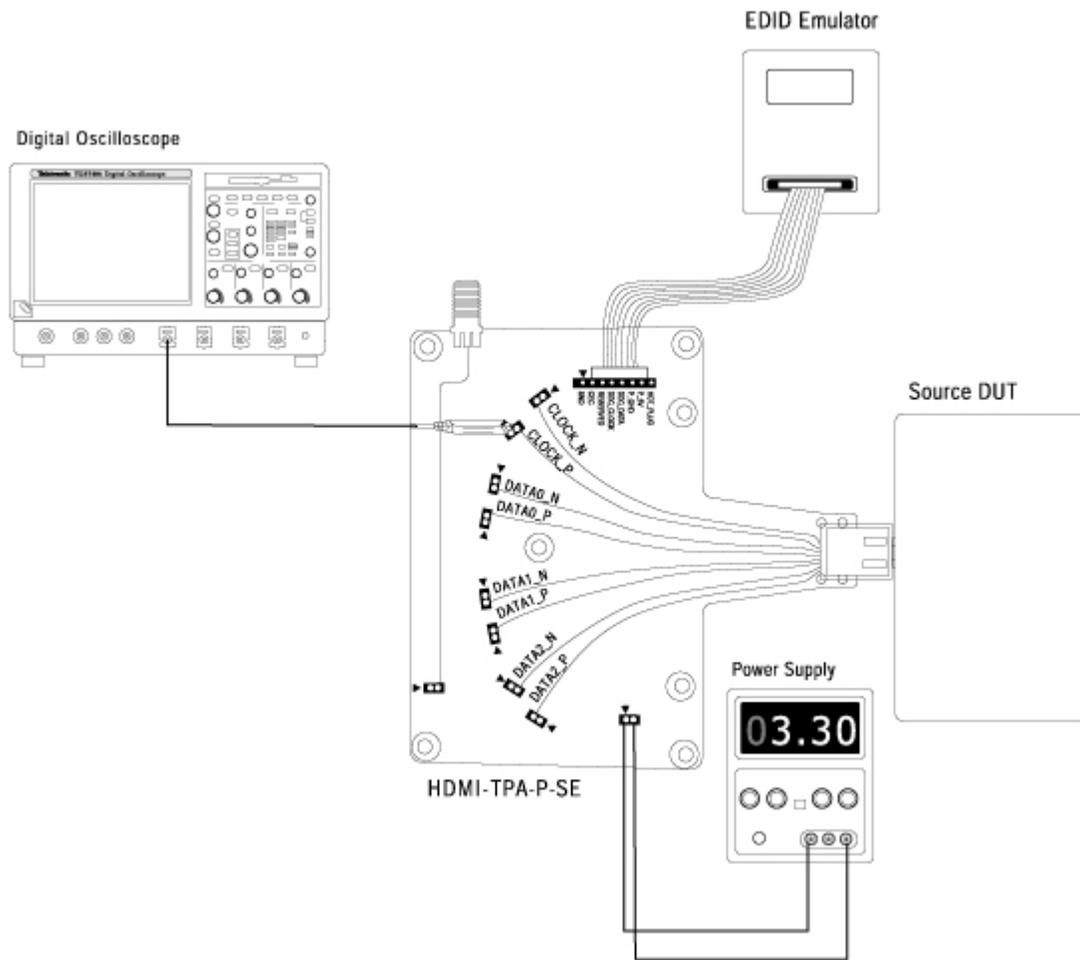


Figure 72: Connections for Low Amplitude - (with Existing Tbit option selected)

- Connect the HDMI output of the source DUT to the TPA-P-SE adapter.
- Connect a power supply to the TPA adapter and set the power supply to 3.30 V.
- Connect the EDID emulator to the TPA adapter and set the emulator for the required resolution (refer to the EDID emulator user manual).

- Connect the first single-ended probe to TMDS_DATA<X>+/TMDS_CLOCK+.
- Configure the Source DUT to output a video format with the required supported pixel clock frequency.

Sink – Min/Max-Diff Swing Tolerance

On the menu bar, click **Tests > Connect**.

Setup 1: To find the minimum swing voltage of the Sink DUT

Make the connections as follows:

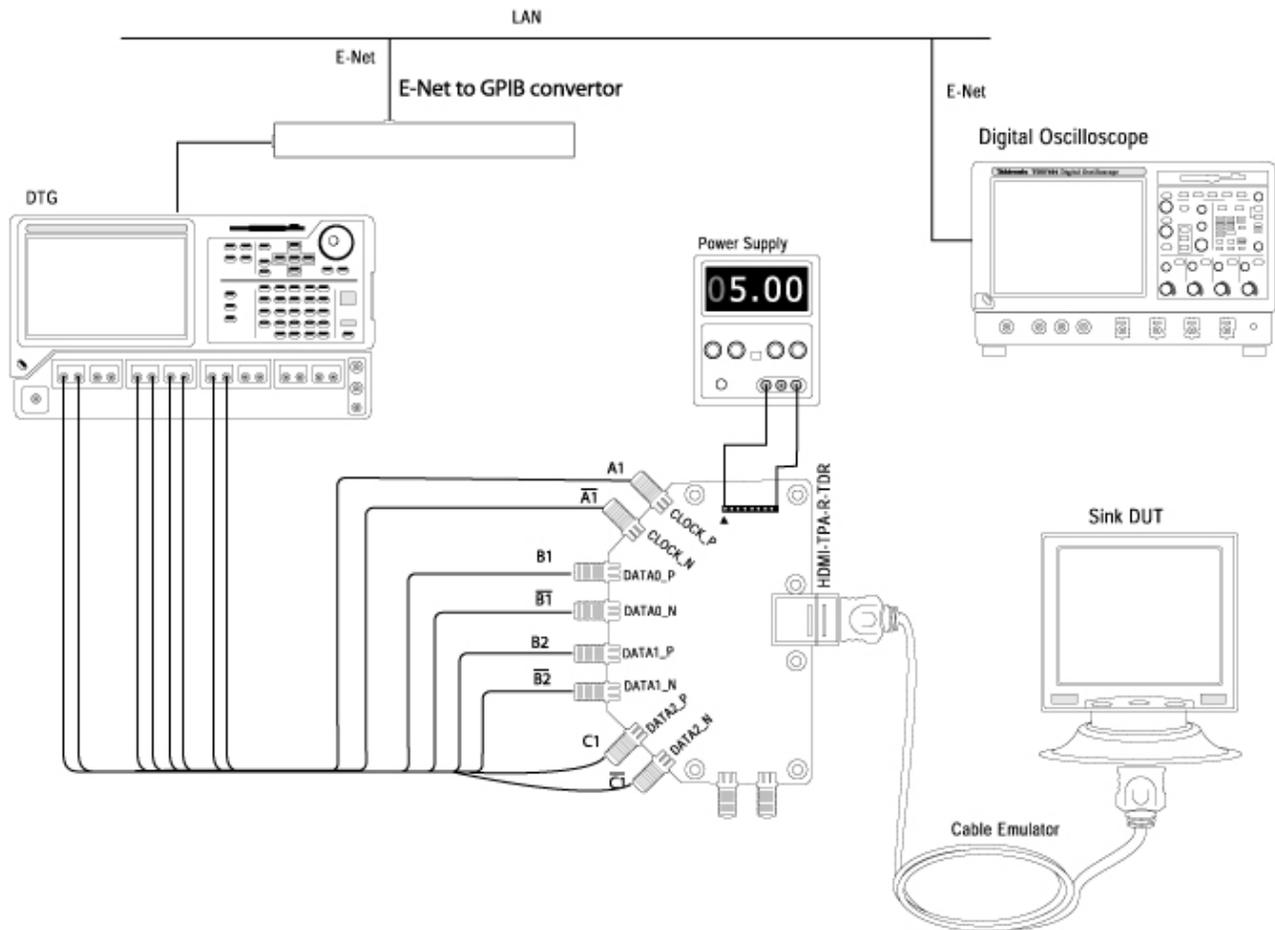


Figure 73: Connections for Min/Max-Diff Swing Tolerance (to find minimum swing voltage of the Sink DUT)

Note: Using the Cable Emulator/Cable is not mandatory. You can connect a TPA-P-TDR fixture directly to the DUT. If you find this inconvenient, then use the Cable Emulator/Cable to connect the DUT conveniently.

- Connect the DTG to the TPA-R-TDR by using eight one meter or one and a half meter SMA cables:
 - Module A, Channel 1+, 1-: Connect to CLOCK_P, and CLOCK_N
 - Module A, Channel 2+, 2-: No Connection
 - Module B, Channel 1+, 1-: Connect to DATA0_P and DATA0_N
 - Module B, Channel 2+, 2-: Connect to DATA1_P and DATA1_N
 - Module C, Channel 1+, 1-: Connect to DATA2_P and DATA2_N
 - Module C, Channel 2+, 2-: No Connection
- Connect the Cable Emulator from the TPA-R-TDR to the Sink DUT.
- Connect and configure the DC Power Supply to drive +5 V between +5 V Power (P_5V) and DDC/CEC Ground (P_GND) on the TPA-R-TDR.

Setup 2: To measure the minimum differential swing voltage by using an oscilloscope

Make the connections as follows:

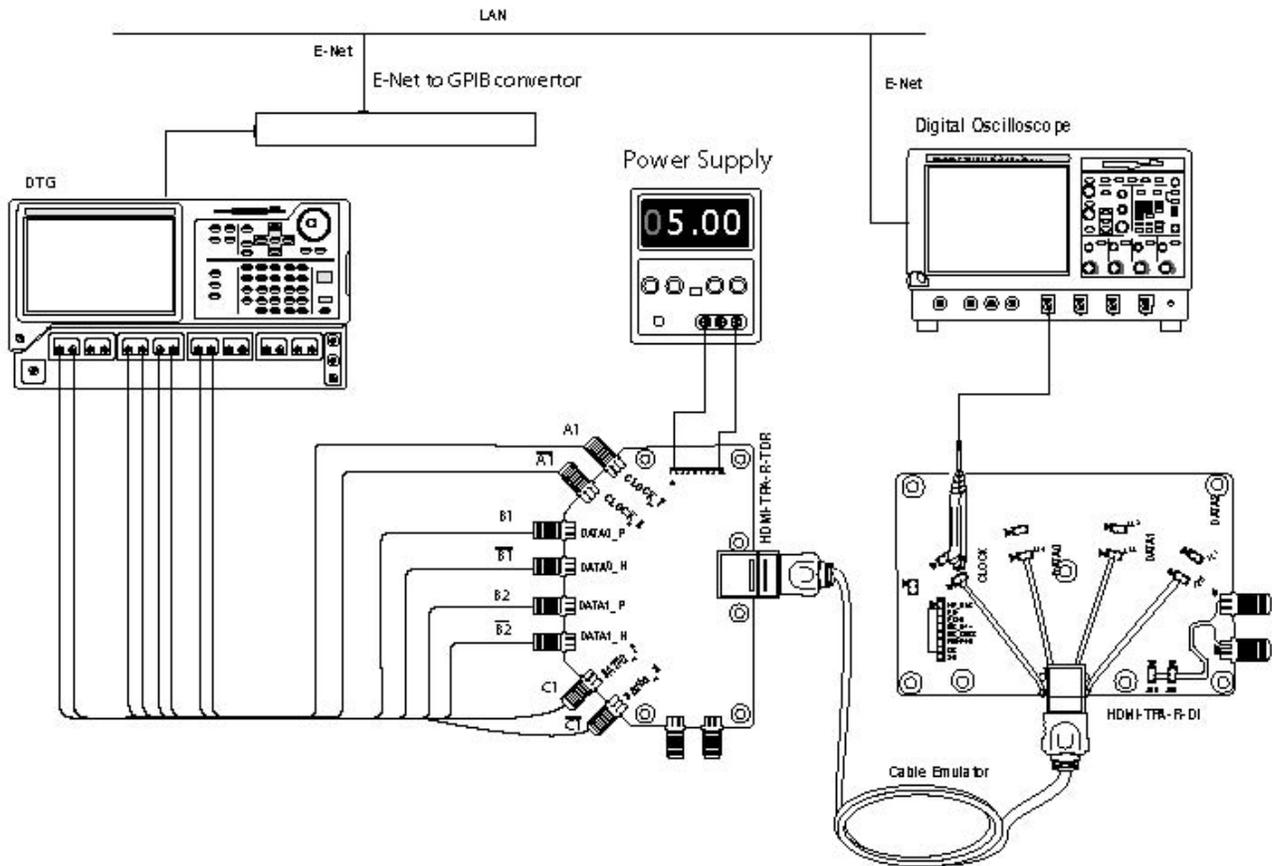


Figure 74: Connections for Min/Max-Diff Swing Tolerance (to measure the minimum differential swing voltage using an oscilloscope)

Note: Using the Cable Emulator/Cable is not mandatory. You can connect a TPA-P-TDR fixture directly to the DUT. If you find this inconvenient, then use the Cable Emulator/Cable to connect the DUT conveniently.

- Remove the Sink DUT from the Cable Emulator.
- Connect the TPA-R-DI test fixture at the end of the Cable Emulator.

- Connect a TMDS Clock/Data channel to the configured oscilloscope channel by using a differential probe.

Setup 3: To find the maximum swing voltage of the Sink DUT

1. Remove the TPA-R-DI text fixture at the end of the Cable Emulator.
2. Connect the Sink DUT to the Cable Emulator.

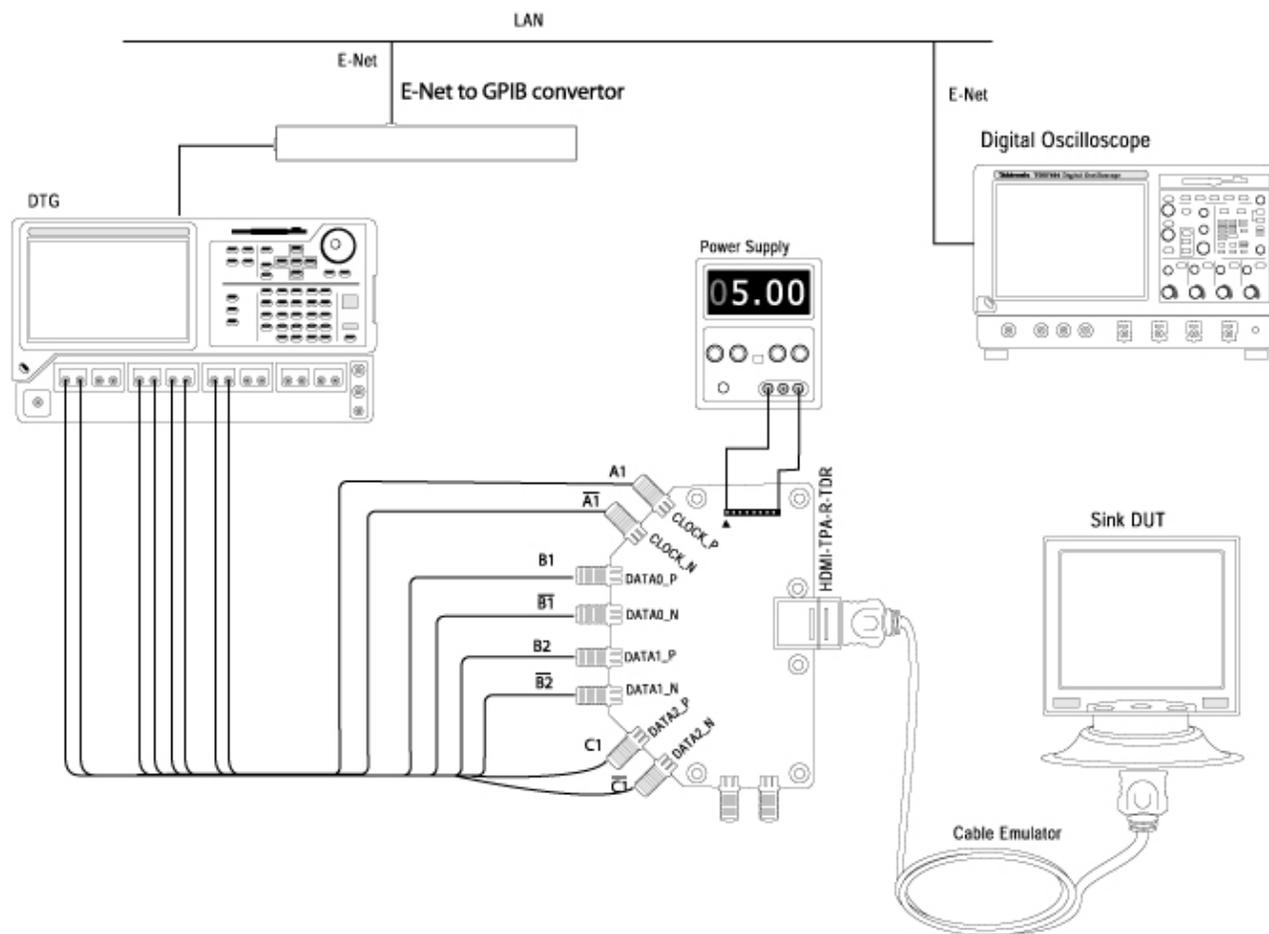


Figure 75: Connections for Min/Max-Diff Swing Tolerance (to find the maximum swing voltage of the Sink DUT)

Sink - Jitter Tolerance

On the menu bar, click **Tests > Connect**.

Setup 1: To find the device tolerance limit

Make the connections as follows:

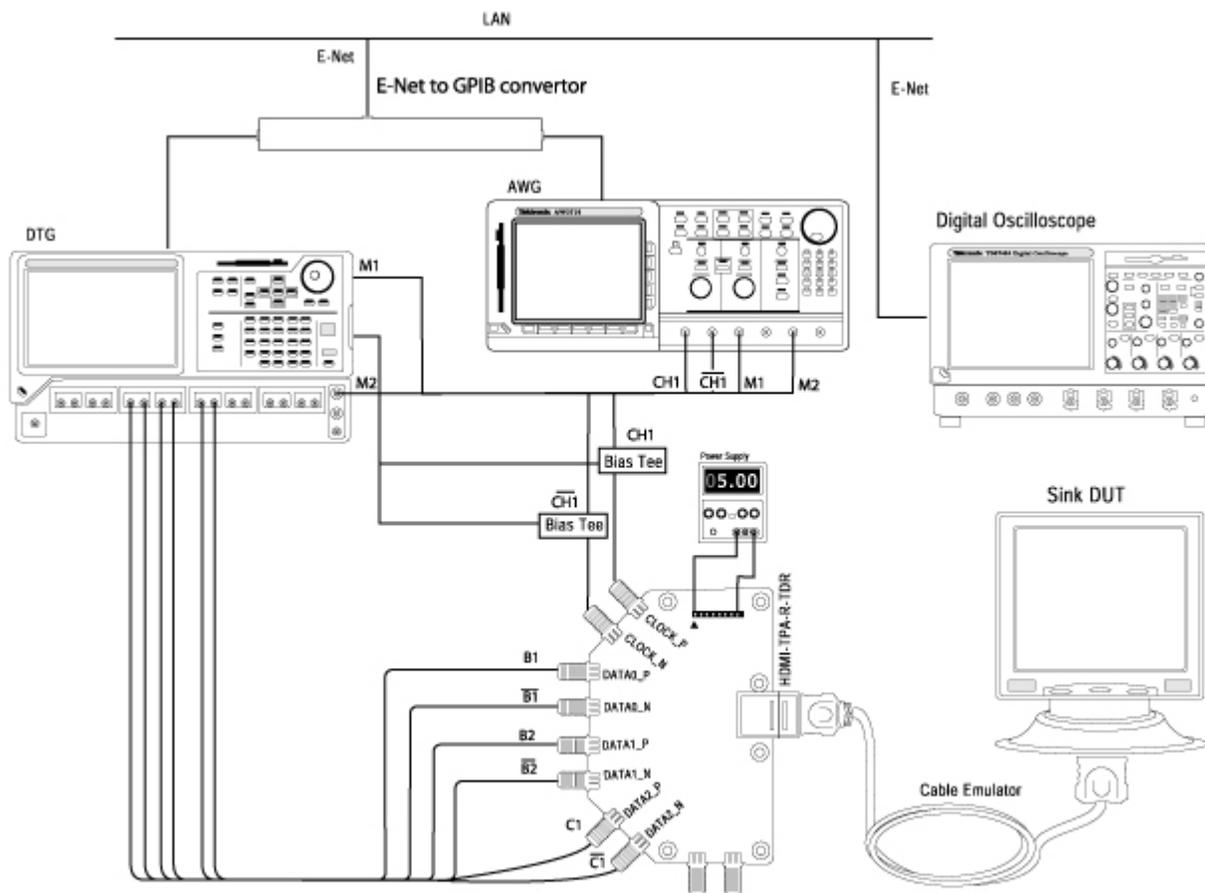


Figure 76: Connections for Jitter Tolerance (to find the device tolerance limit)

- Connect the DTG, AWG, Bias-Tees, and the TPA-R-TDR.
 - AWG Marker 1+ output to DTG External Clock input
 - AWG Marker 2+ output to DTG Trigger In
 - AWG Ch. 1+ output to Bias-Tee signal input (RF)
 - Bias-Tee signal output (RF and DC) to CLOCK_P

- DTG DC_OUT (1) to Bias-Tee DC-level input (DC)
- AWG Ch. 1- output to Bias-Tee signal input (RF)
 - Bias-Tee signal output (RF and DC) to CLOCK_N
 - DTG DC_OUT (2) to Bias-Tee DC-level input (DC)
- DTG Module A, Channel 1+, 1-: No Connection
- DTG Module A, Channel 2+, 2-: No Connection
- DTG Module B, Channel 1+, 1-: Connect to DATA0_P and DATA0_N
- DTG Module B, Channel 2+, 2-: Connect to DATA1_P and DATA1_N
- DTG Module C, Channel 1+, 1-: Connect to DATA2_P and DATA2_N
- DTG Module C, Channel 2+, 2-: No Connection
- Connect the TPA-R-TDR to the Sink DUT by using a Cable Emulator specified for tested pixel clock rate.
- Connect and configure the DC Power Supply to drive +5 V between +5 V Power (P_5V) and DDC/CEC Ground (P_GND) on the TPA-R-TDR.

Setup 2: To measure the parameters

Make the connections as follows:

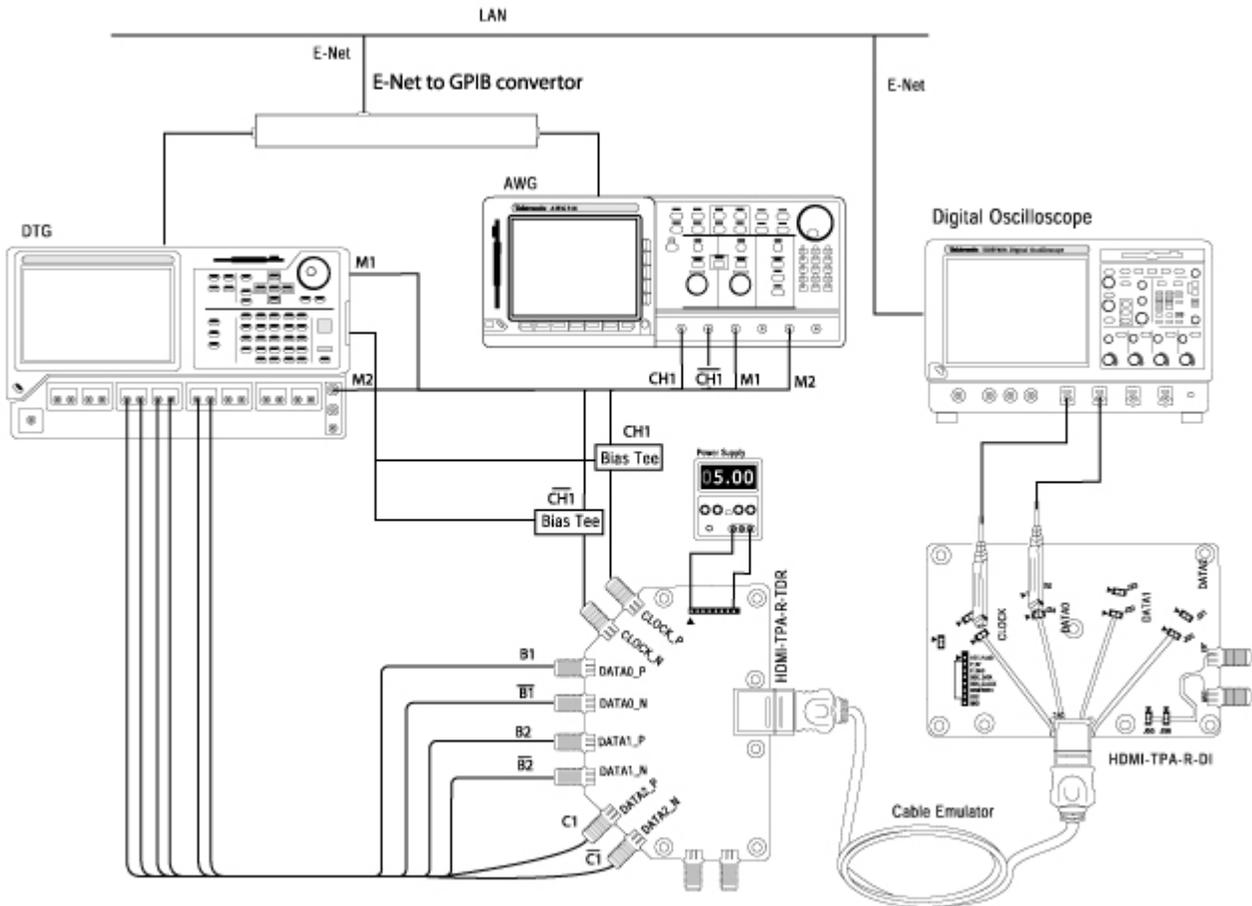


Figure 77: Connections for Jitter Tolerance (to measure the parameters)

- Remove the Sink DUT.
- Connect the TPA-R-DI test adaptor to a Cable Emulator.
- Connect a Clock to the configured oscilloscope channel by using a differential probe.
- Connect the DATA pair on which you will conduct the test to the configured oscilloscope channel by using a second differential probe.

Sink – Intra-Pair Skew

On the menu bar, click **Tests > Connect**.

***Note:** The procedure mentioned next is for the clock intra-pair skew test. For other pairs, interchange the connection of DATA<X>_P with CLOCK_P and DATA<X>_N with CLOCK_N. Make the appropriate changes in the configuration of the DTG Outputs accordingly.*

For example, to calculate the intra-pair skew of Data0:

Connect DATA0_P to Module A1+, DATA0_N to DTG Module A2+, CLOCK_P to Module B1+, and CLOCK_N to module B1-.

Setup 1: To measure Tbit

Make the connections as follows:

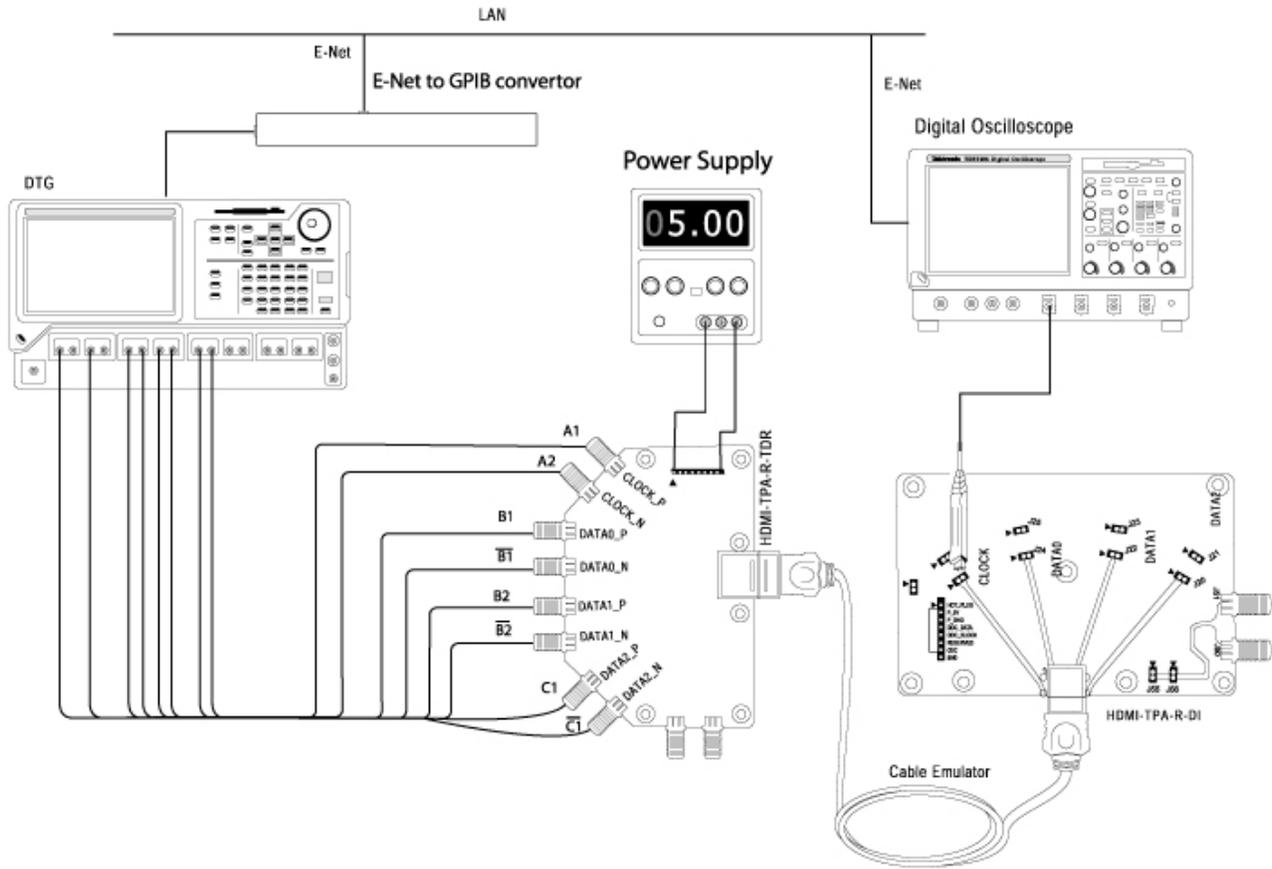


Figure 78: Connections for Sink Intra-Pair Skew (to measure Tbit)

Note: Using the Cable Emulator/Cable is not mandatory. You can connect a TPA-P-TDR fixture directly to the DUT. If you find this inconvenient, then use the Cable Emulator/Cable to connect the DUT conveniently.

- Connect the DTG to the TPA-R-TDR by using eight one meter (preferable) or one and a half meter SMA cables:
 - Module A, Channel 1+: Connect to CLOCK_P
 - Module A, Channel 1-: No Connection
 - Module A, Channel 2+: Connect to CLOCK_N
 - Module A, Channel 2-: No Connection
 - Module B, Channel 1+, 1-: Connect to DATA0_P and DATA0_N
 - Module B, Channel 2+, 2-: Connect to DATA1_P and DATA1_N
 - Module C, Channel 1+, 1-: Connect to DATA1_P and DATA1_N
 - Module C, Channel 2+, 2-: No Connection
- Connect the TPA-R-TDR to the Cable Emulator.
- Connect the TPA-R-DI to the Cable Emulator.
- Connect a Clock to the configured oscilloscope channel by using a differential probe.

Setup 2: To find intra-pair skew of the Sink DUT

Make the connections as follows:

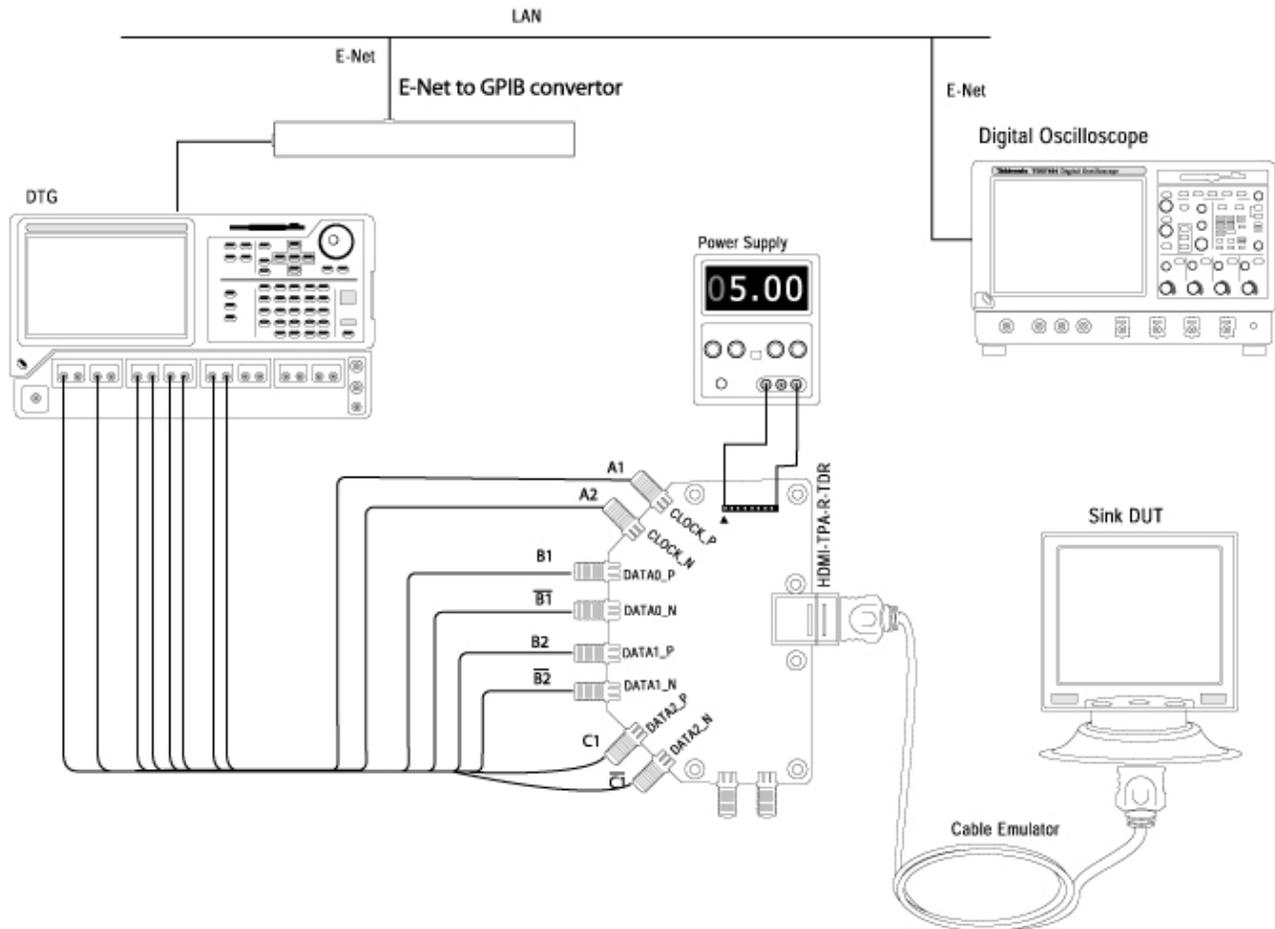


Figure 79: Connections for Sink Intra-Pair Skew (to find intra-pair skew of the sink DUT)

Note: Using the Cable Emulator/Cable is not mandatory. You can connect a TPA-P-TDR fixture directly to the DUT. If you find this inconvenient, then use the Cable Emulator/Cable to connect the DUT conveniently.

- Remove the TPA-R-DI test fixture from the Cable Emulator.
- Connect the Sink DUT to the Cable Emulator.
- Connect and configure the DC Power Supply to drive +5 V between +5 V Power (P_5V) and DDC/CEC Ground (P_GND) on the TPA-R-TDR.

Cable – Eye Diagram

On the menu bar, click **Tests > Connect**.

Setup diagram for TP1

Make the connections as follows:

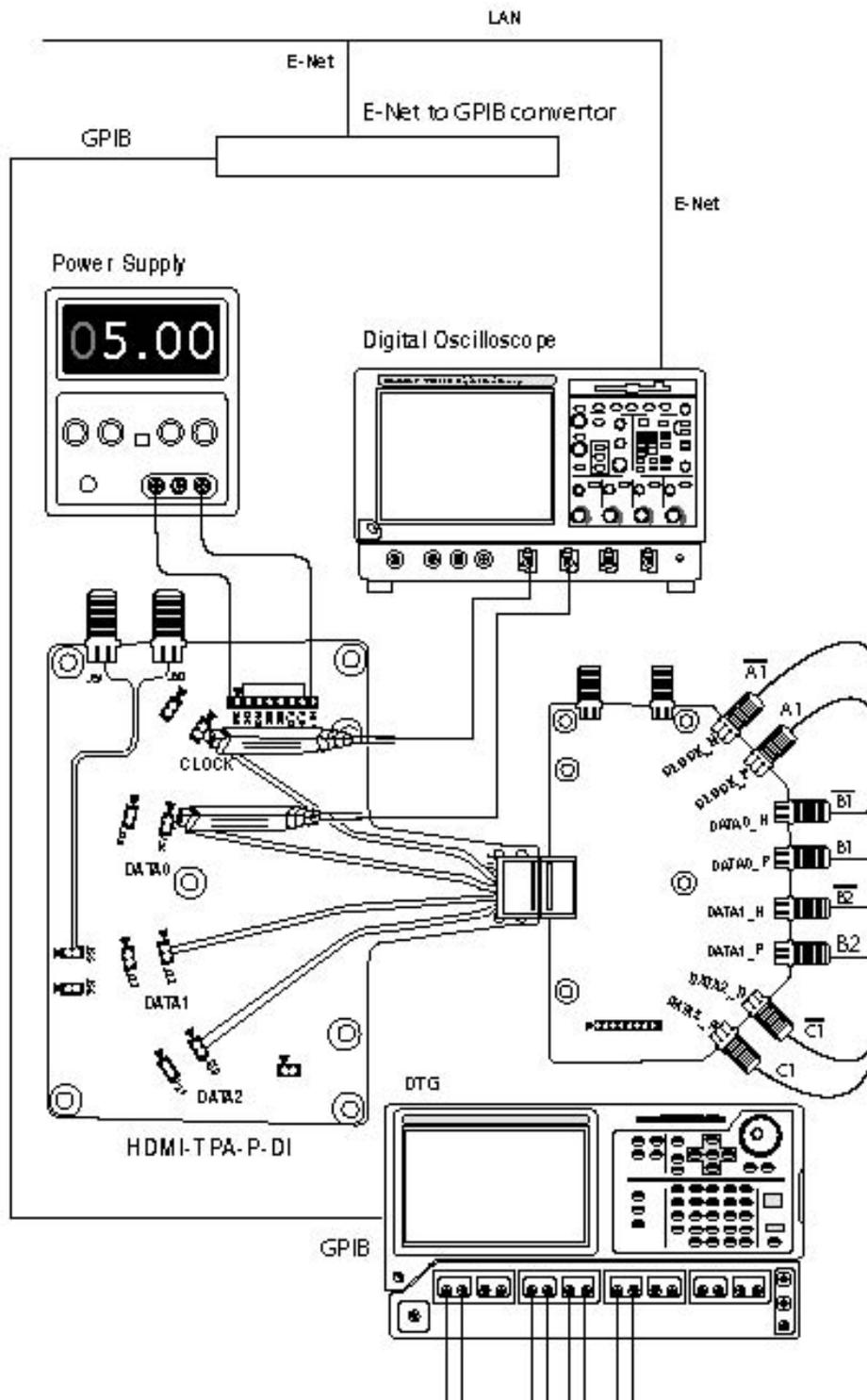


Figure 80: Connections for Cable Eye Diagram (Setup diagram for TP1)

- Connect the DTG to the 'input' TPA-P-TDR adapter by using eight one meter (preferable) or one and a half meter SMA cables:
 - Module A, Channel 1+, 1-: Connect to CLOCK_P and CLOCK_N
 - Module A, Channel 2+, 2-: No Connection
 - Module B, Channel 1+, 1-: Connect to DATA0_P and DATA0_N
 - Module B, Channel 2+, 2-: Connect to DATA1_P and DATA1_N
 - Module C, Channel 1+, 1-: Connect to DATA2_P and DATA2_N
 - Module C, Channel 2+, 2-: No Connection
- Connect the oscilloscope to the 'output' TPA-R-DI adapter by using two differential probes, and supply 3.3 V power.
- Connect a TMDS CLOCK to the configured oscilloscope channel by using a differential probe.
- Connect the TMDS_DATA pair on which you will conduct the test to the configured oscilloscope channel by using a second differential probe.

Setup diagram for TP2

Make the connections as follows:

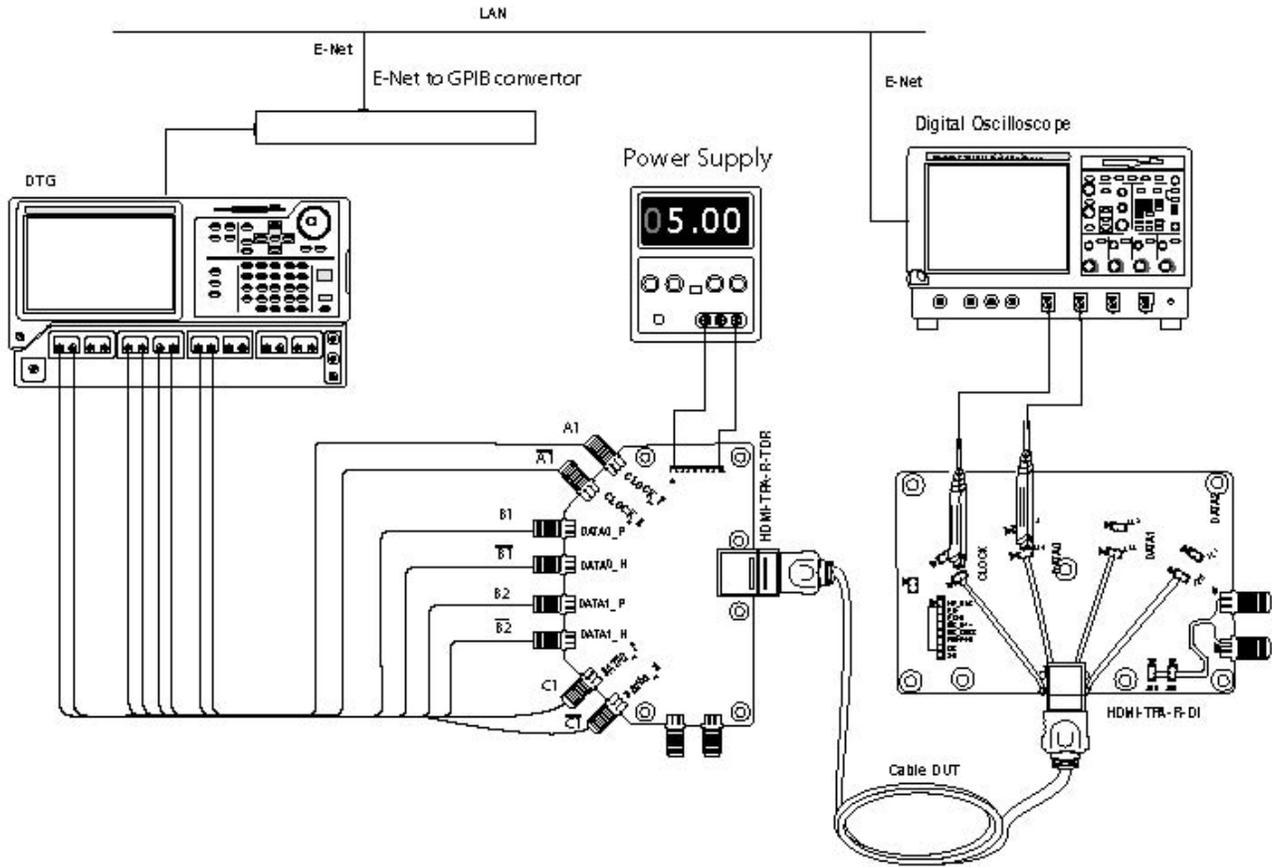


Figure 81: Connections for Cable Eye Diagram (Setup diagram for TP2)

- Remove the TPA-P-DI test adaptor.
- Connect the Cable DUT.

- Connect the TPA-R-DI test adaptor.
- Connect a TMDS CLOCK to the configured oscilloscope channel by using a differential probe.
- Connect the TMDS_DATA pair on which you will conduct the test to the configured oscilloscope channel by using a second differential probe.

View Waveform

Source – Eye Diagram

Click **View Waveform** to display the input signals Clock and Data as follows:

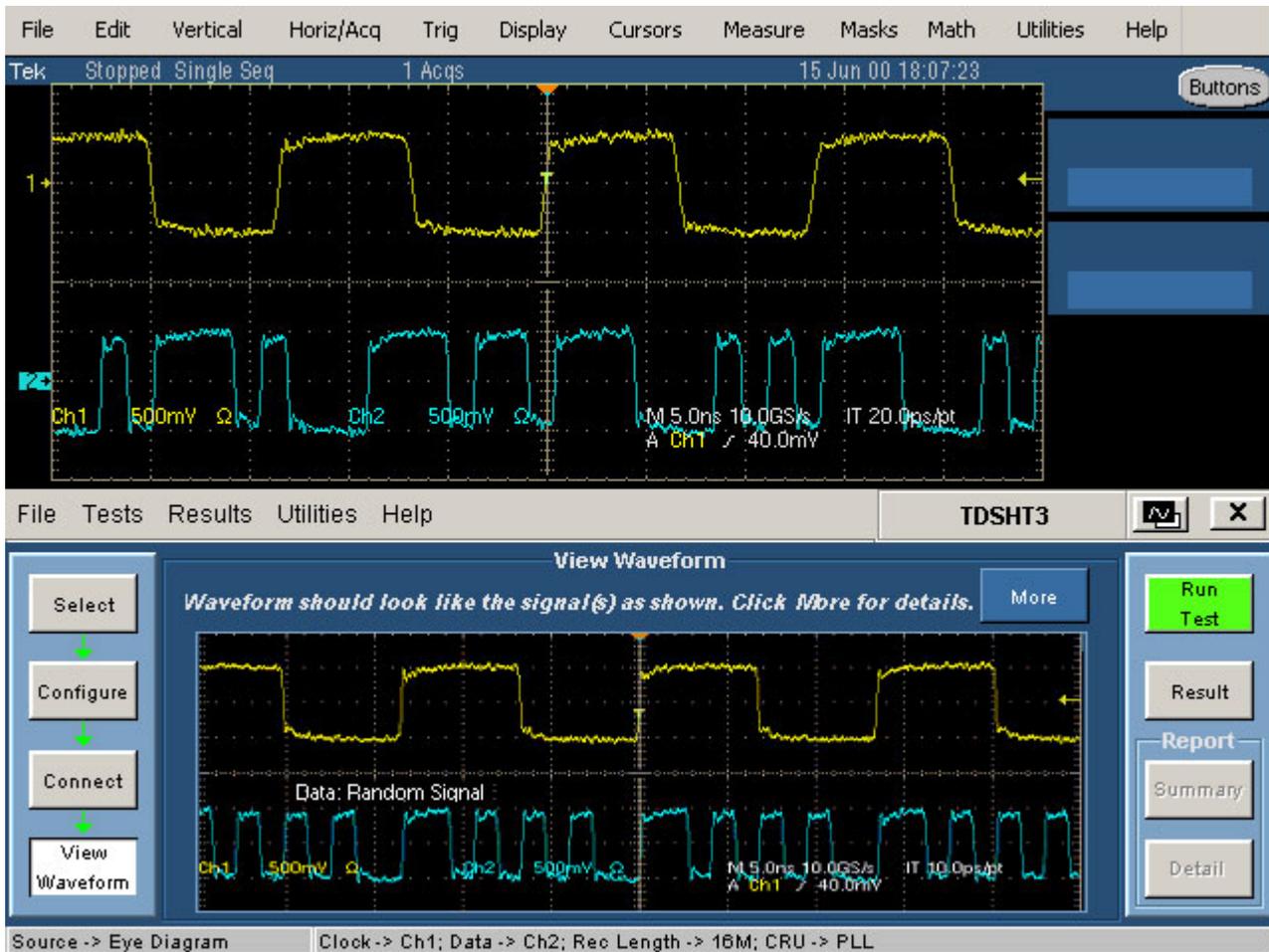


Figure 82: Waveform of Source Eye Diagram

Source – Duty Cycle

Click **View Waveform** to display the Clock signal as follows:

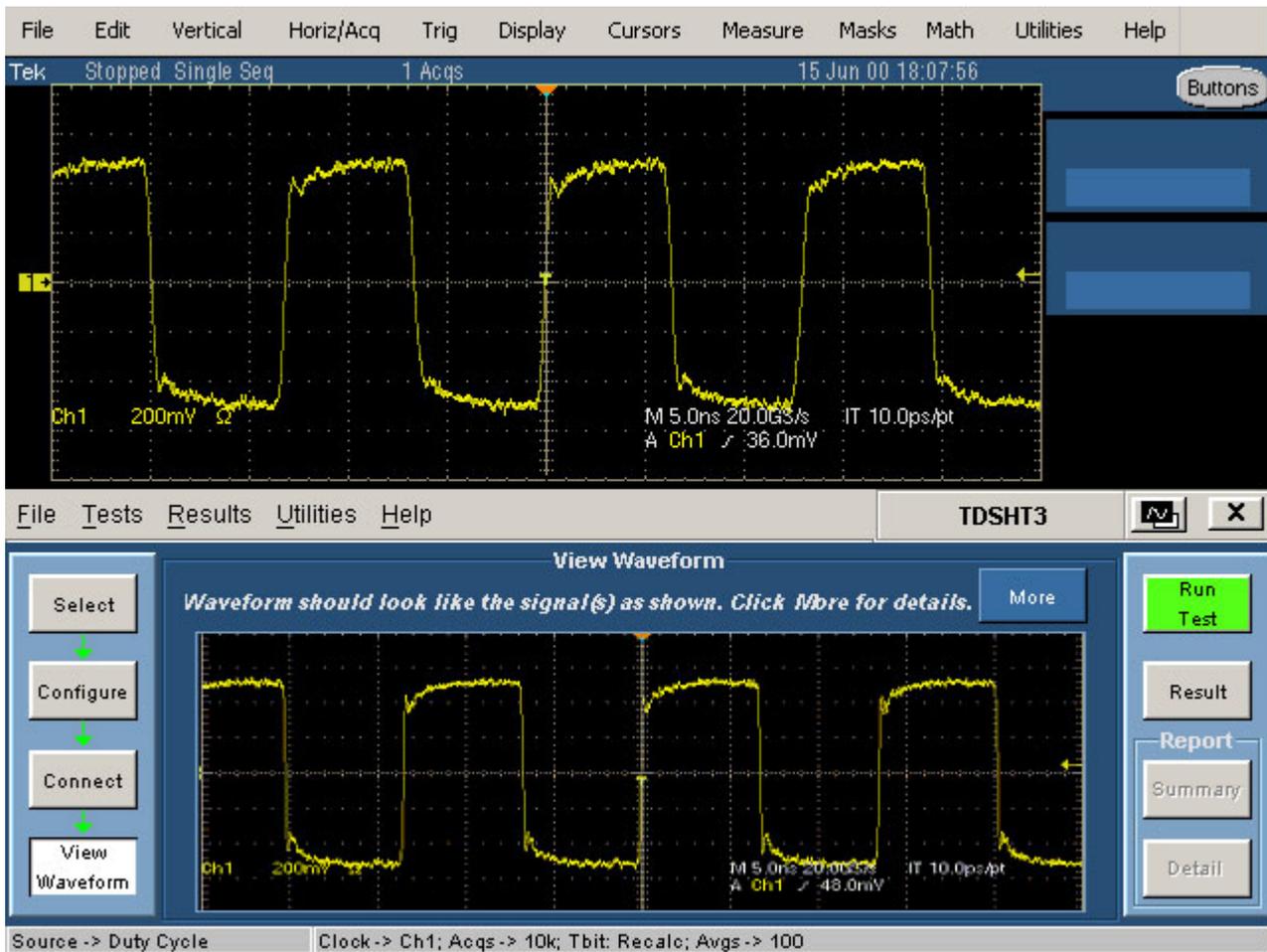


Figure 83: Waveform of Duty Cycle

Source – Rise Time

Click **View Waveform** to display the input signals Clock or Data as follows:

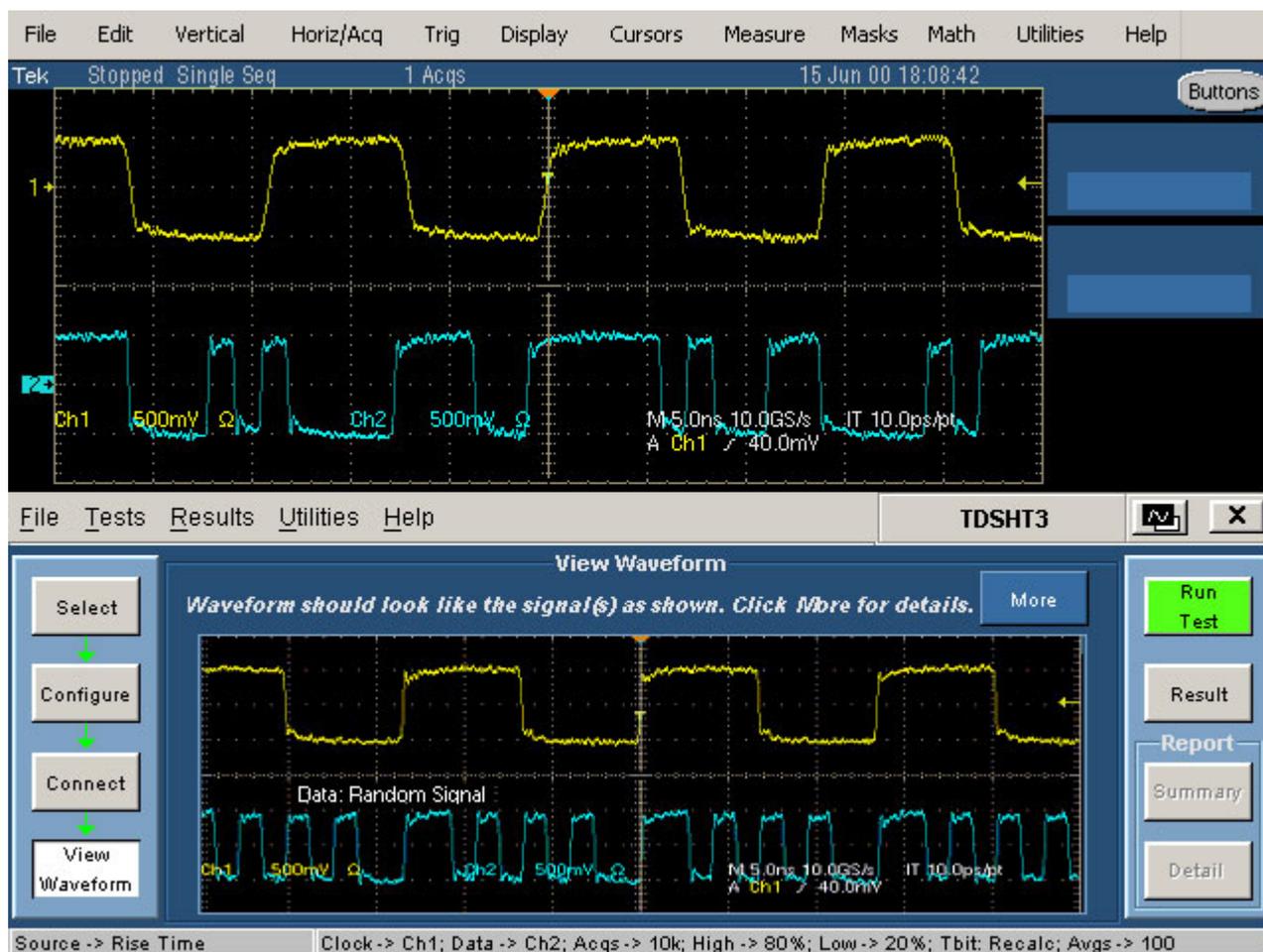


Figure 84: Waveform of Rise Time

Source – Fall Time

Click **View Waveform** to display the input signals Clock or Data as follows:

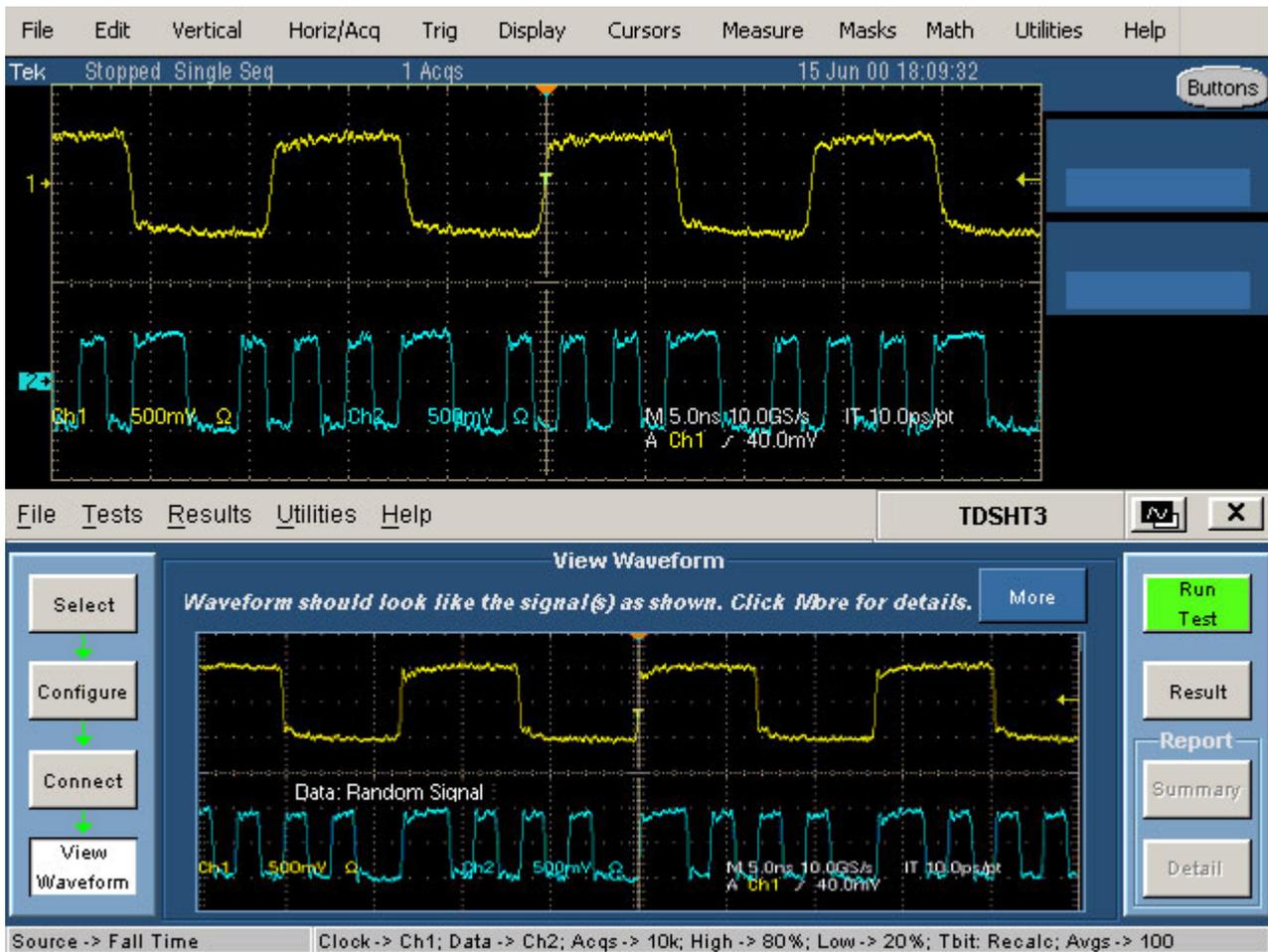


Figure 85: Waveform of Fall Time

Source – Clock Jitter

Click **View Waveform** to display the Clock signal as follows:

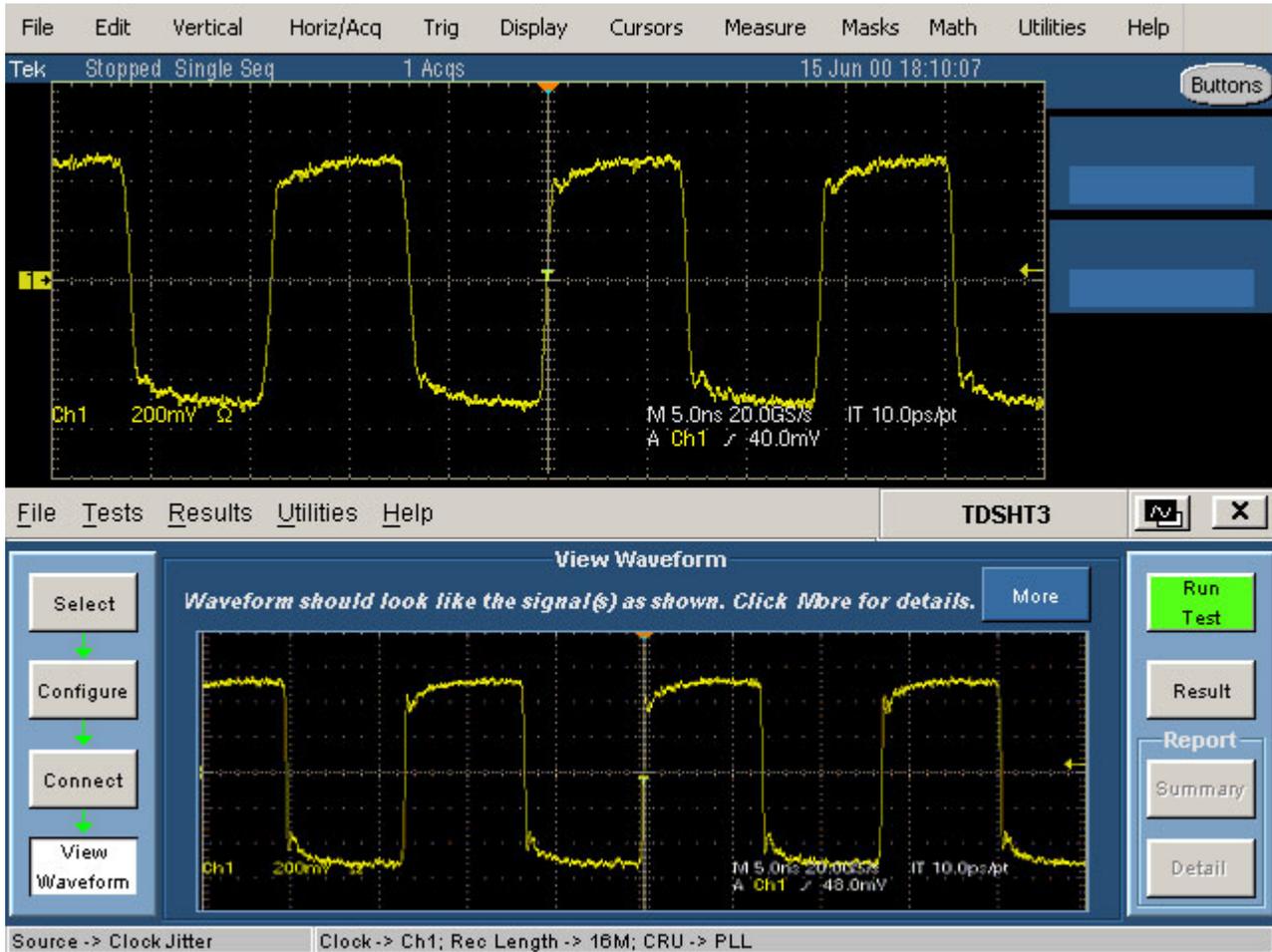


Figure 86: Waveform of Clock Jitter

Source – Over/Undershoot V-H (Voltage-High)

Click **View Waveform** to display the input signals Clock or Data as follows:

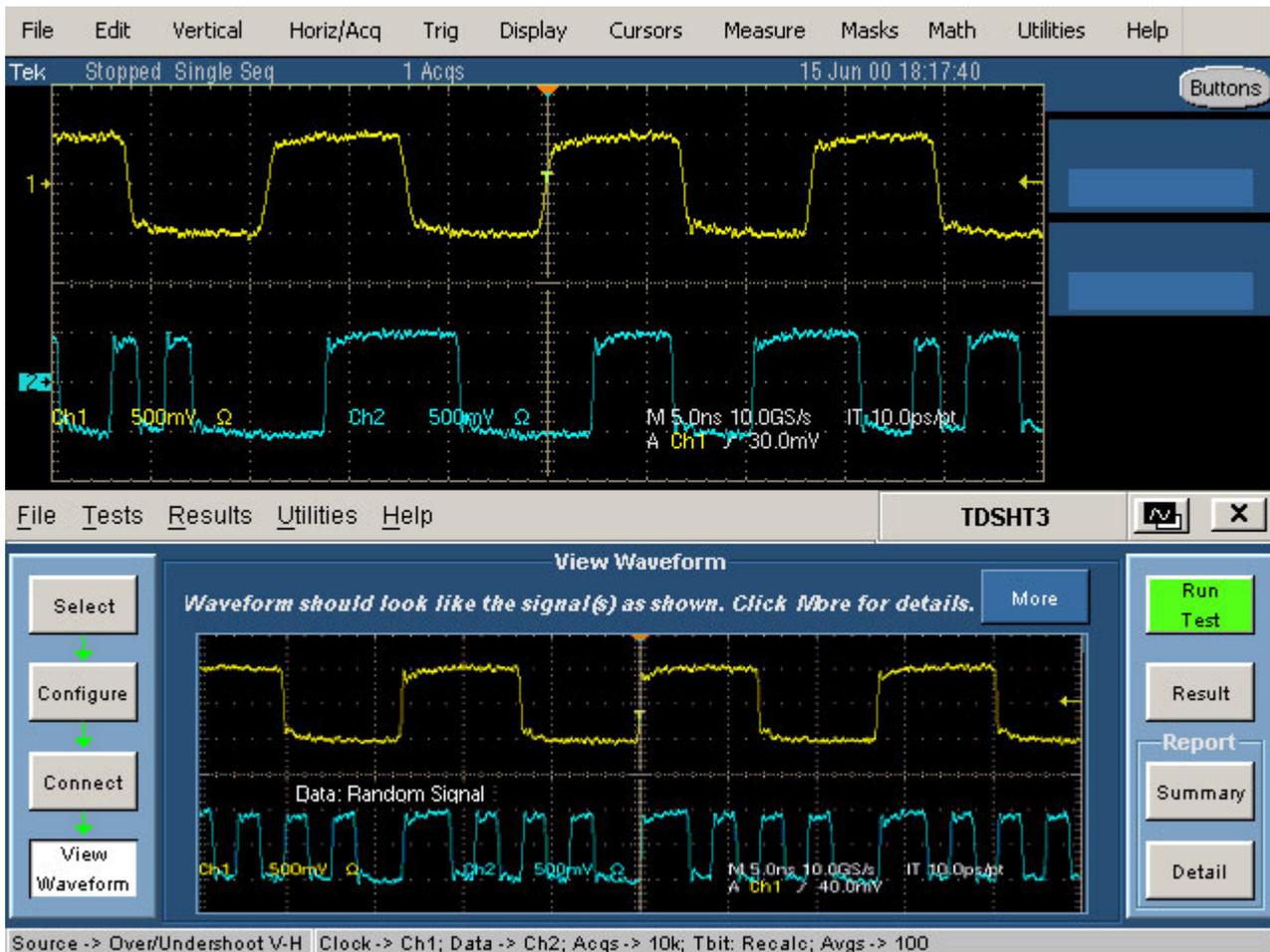


Figure 87: Waveform of Over/Undershoot V-H

Source – Over/Undershoot V-L (Voltage-Low)

Click **View Waveform** to display the input signals Clock or Data as follows:

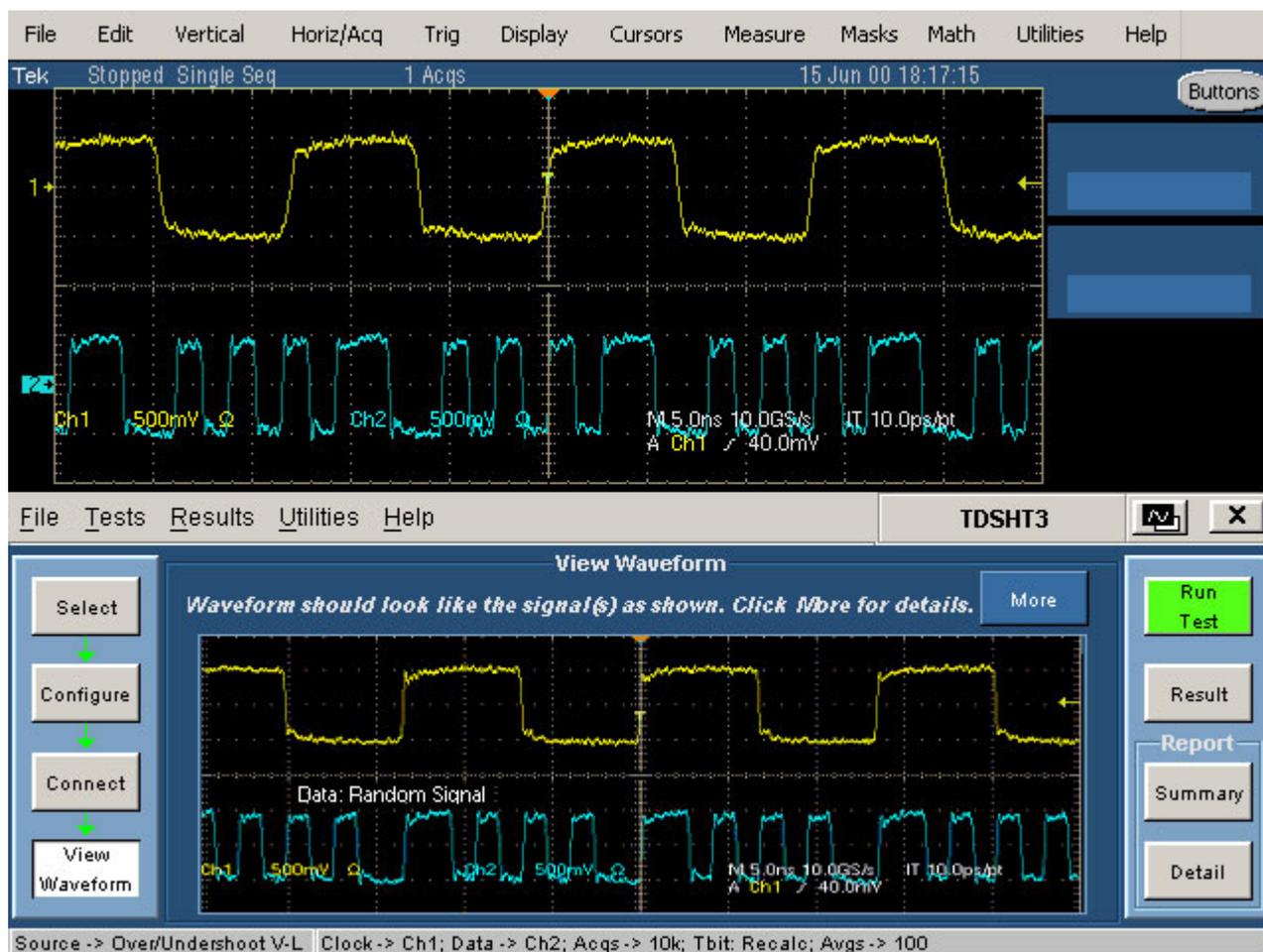


Figure 88: Waveform of Over/Undershoot V-L

Source – Inter-Pair Skew for Clock-Data Tests

Click **View Waveform** to display the input signals Clock and Data as follows:

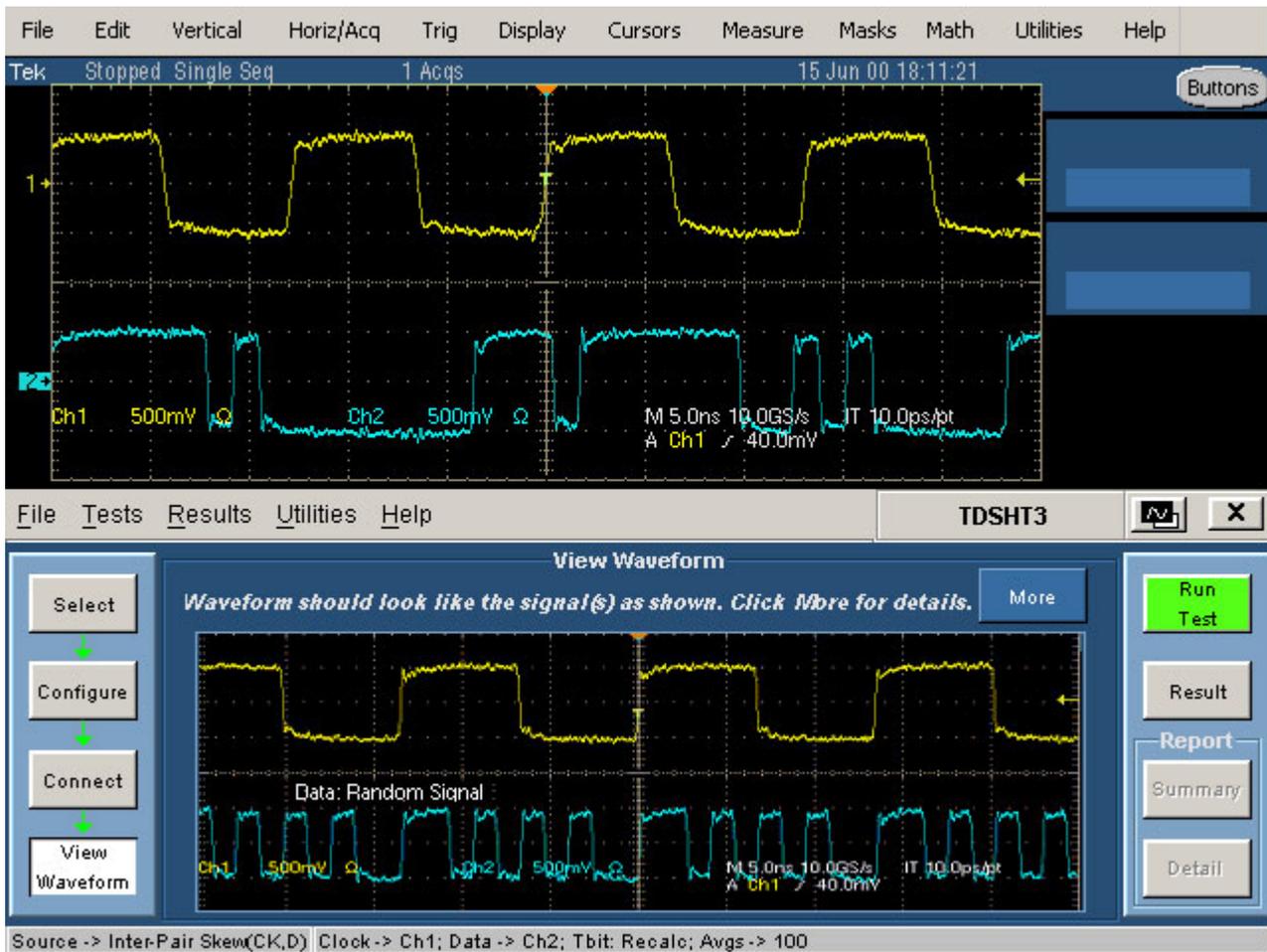


Figure 89: Waveform of Inter-Pair Skew (Clock-Data)

Source – Clock-Data Tests Select All

Click **View Waveform** to display the input signals Clock and Data as follows:

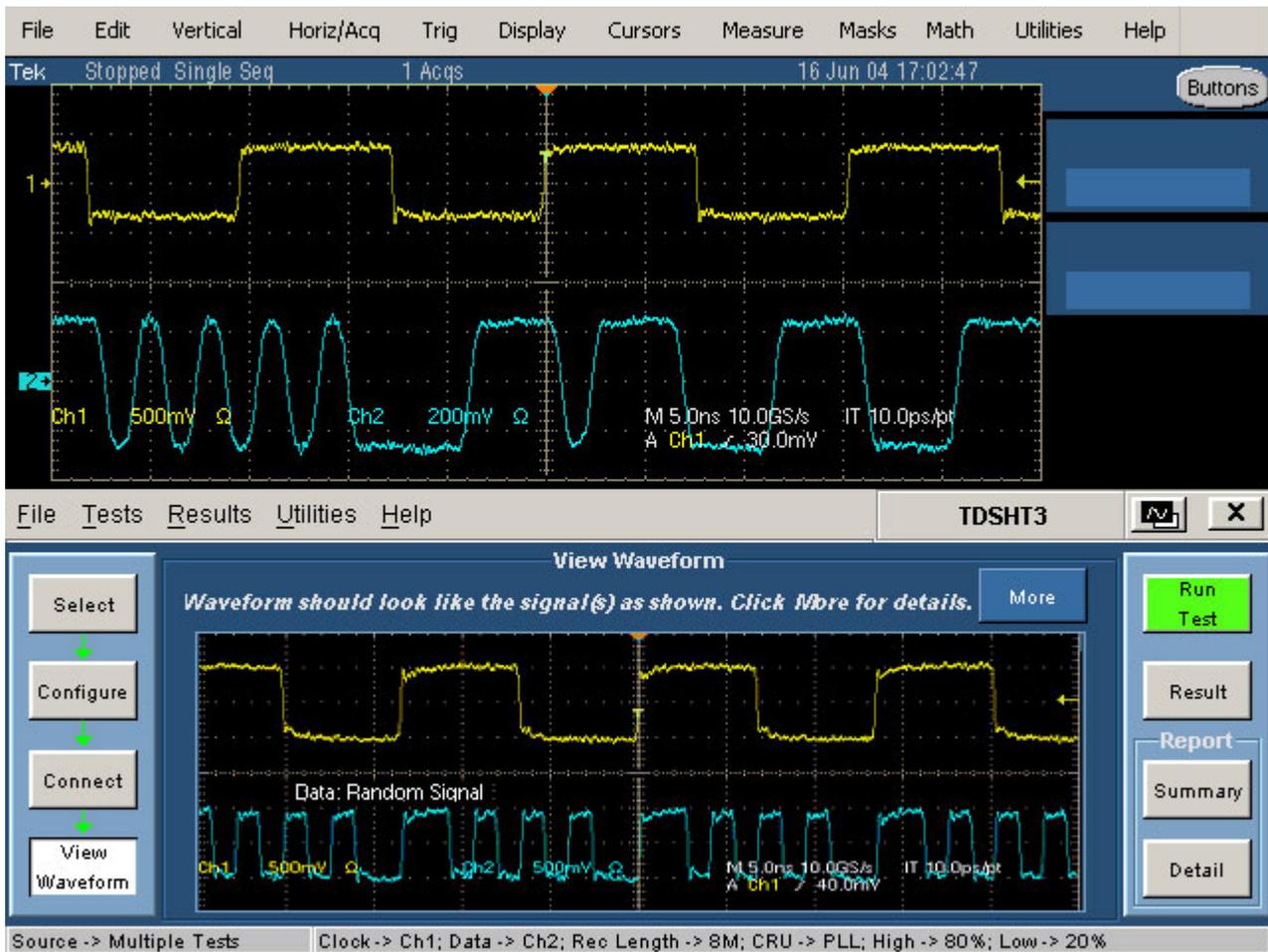


Figure 90: Waveform of Source Multiple Tests

Source – Inter-Pair Skew for Data-Data Tests

Click **View Waveform** to display the input signals Data+ and Data, Click as follows:

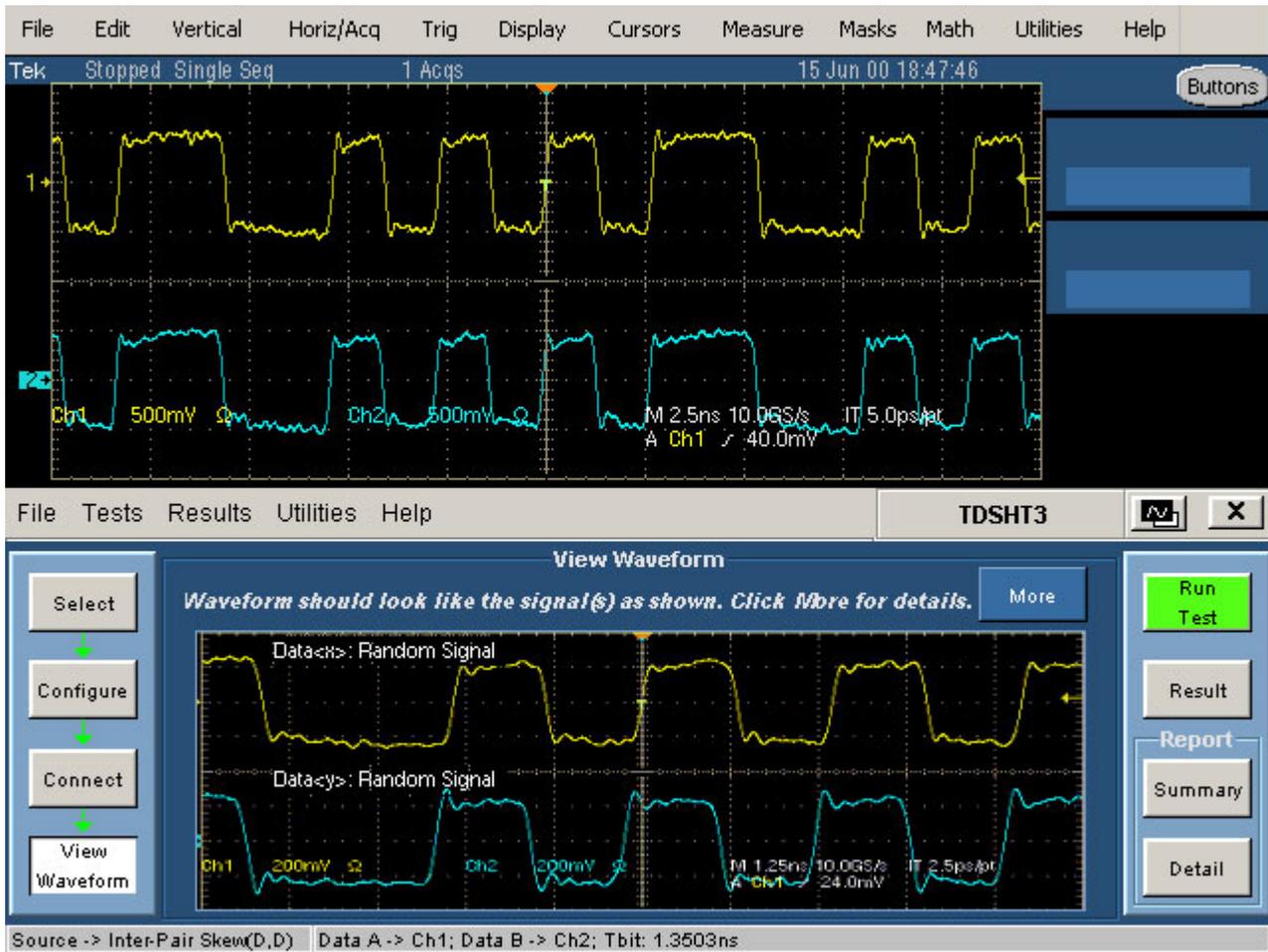


Figure 91: Waveform of Inter-Pair Skew (Data-Data)

Source – Intra-Pair Skew

Click **View Waveform** to display the input signals Data+ or Data-/Clock as follows:

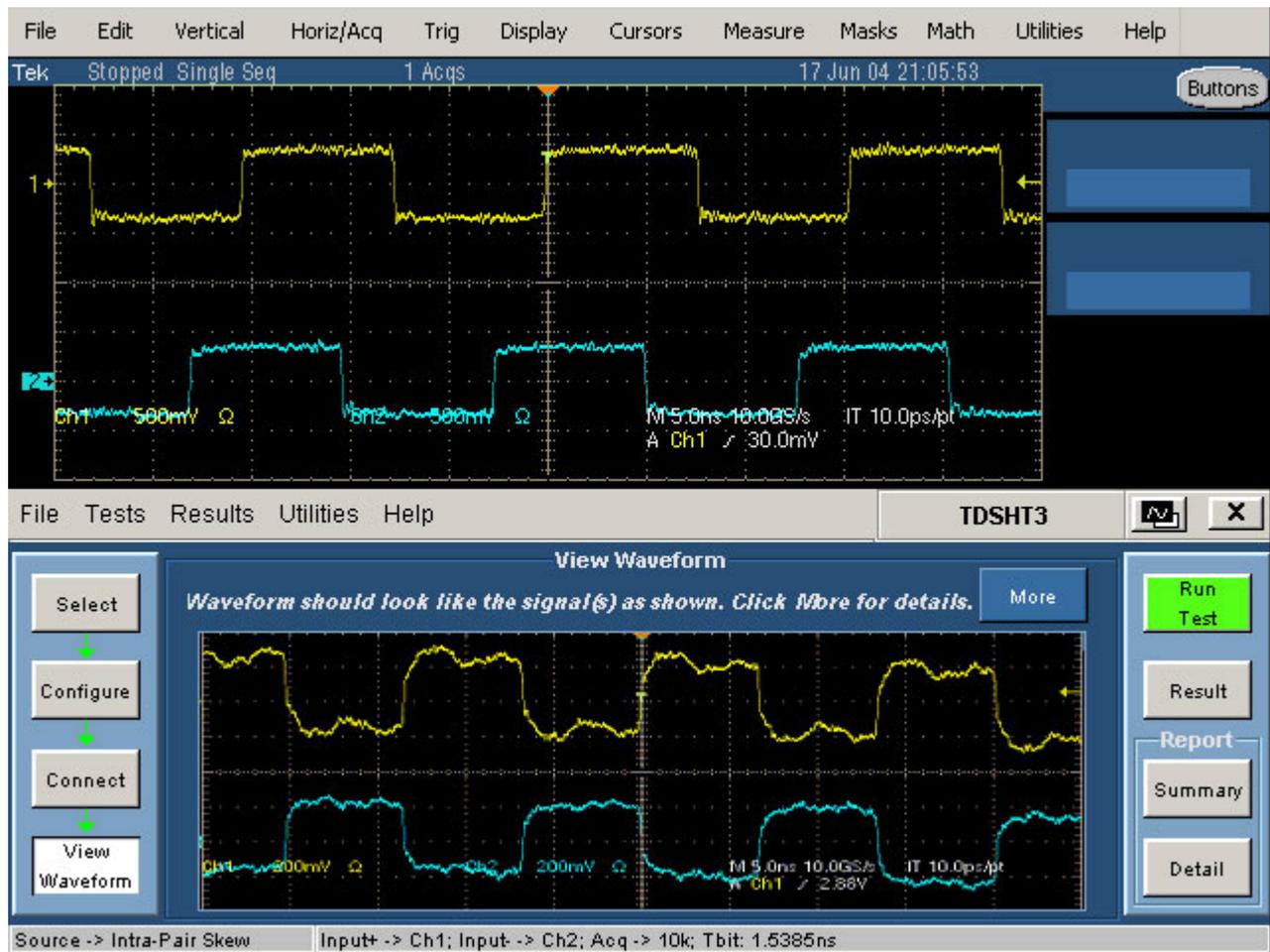


Figure 92: Waveform of Source Intra-Pair Skew

Source – Low Amplitude +

Click **View Waveform** to display the input signals Data+ or Data-/Clock as follows:

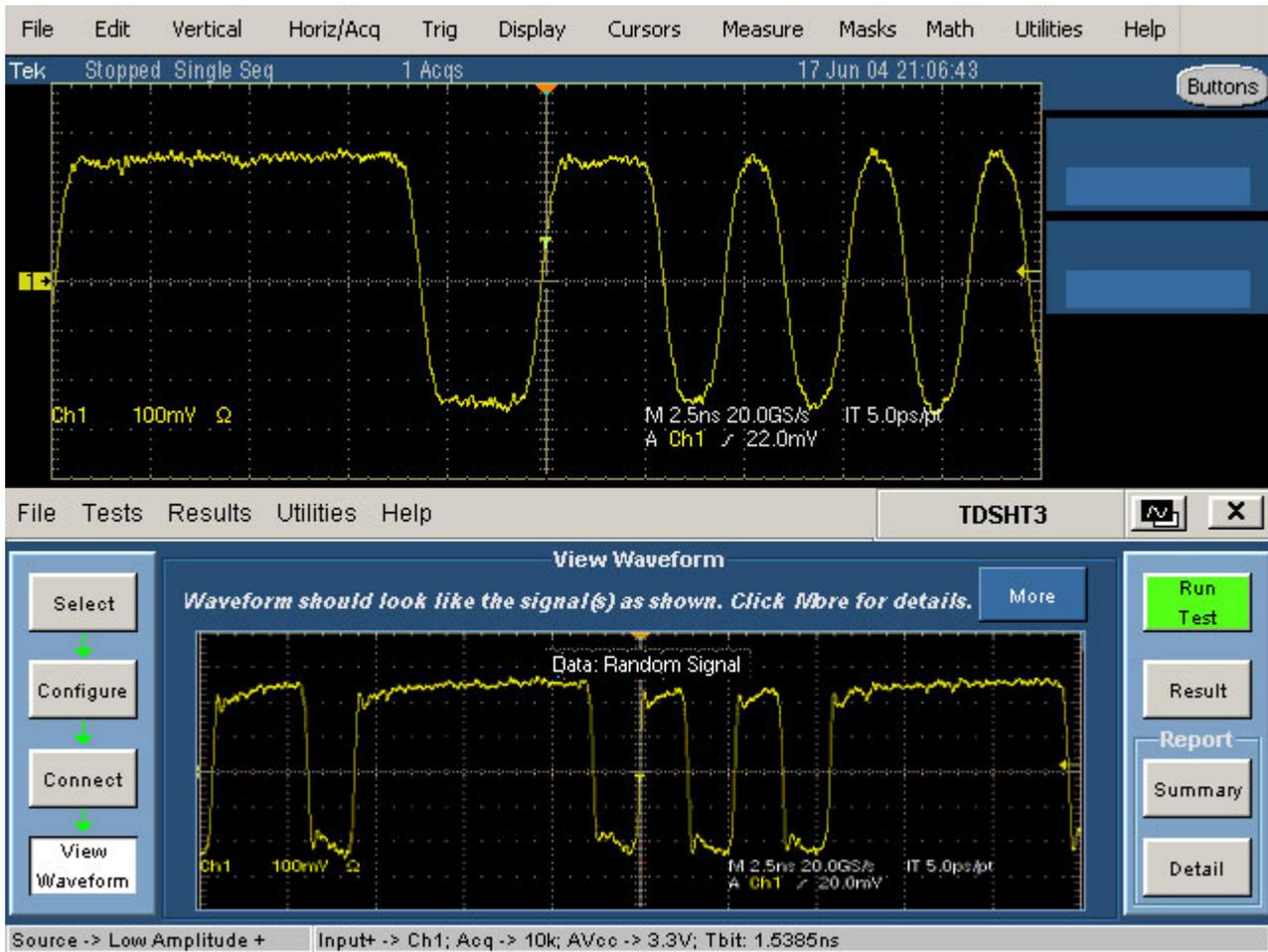


Figure 93: Waveform of Low Amplitude +

Source – Low Amplitude -

Click **View Waveform** to display the input signals Data+ or Data-/Clock as follows:

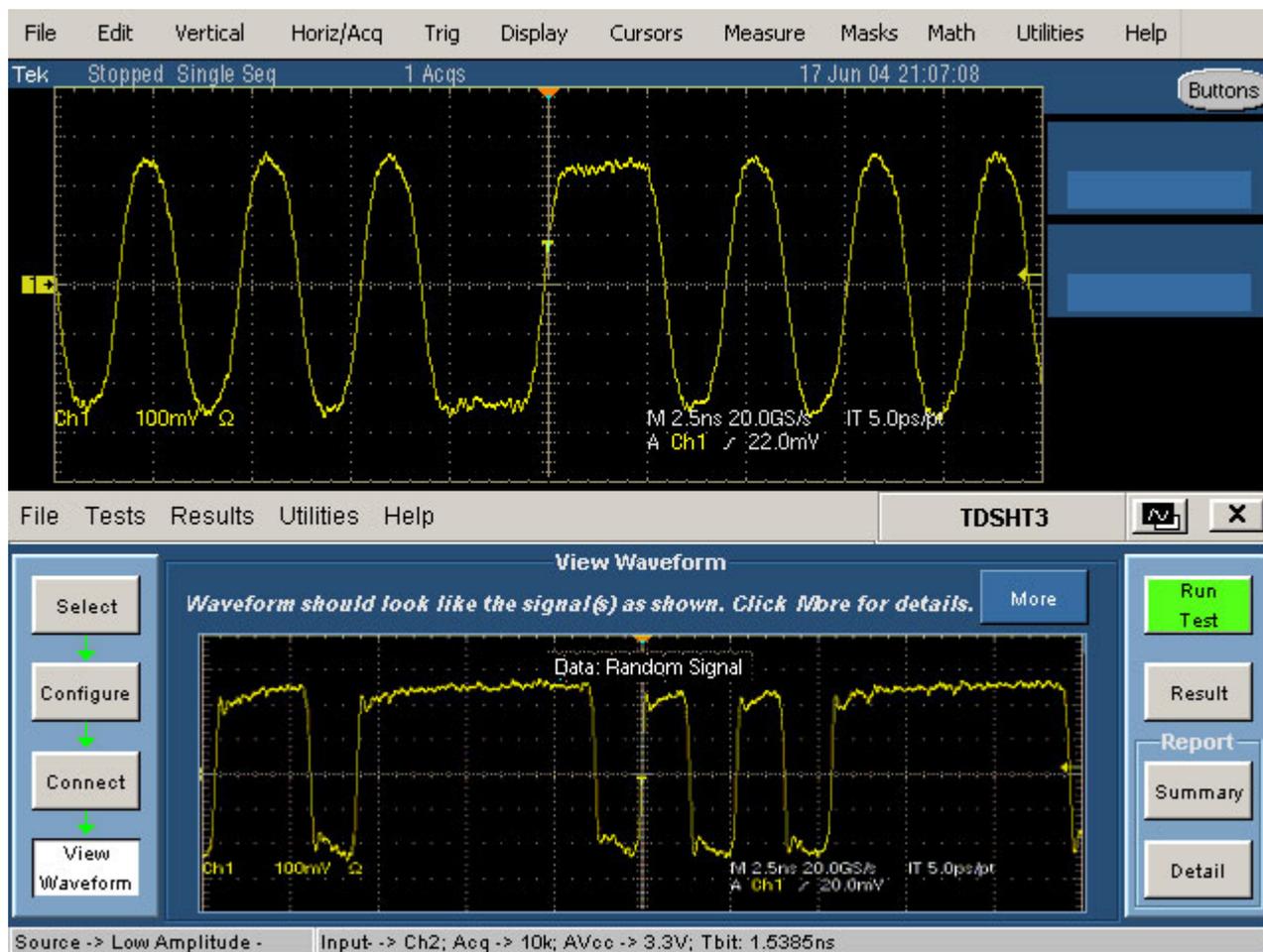


Figure 94: Waveform of Low Amplitude -

Sink – Min/Max-Diff Swing Tolerance

Because no signal is connected to the oscilloscope, you cannot view the waveform for the min/max-diff swing tolerance test.

Sink – Jitter Tolerance

Because no signal is connected to the oscilloscope, you cannot view the waveform for the jitter tolerance test.

Sink – Intra-Pair Skew

If you have selected re-calculate Tbit, then click **View Waveform** to display the Clock signal as follows:

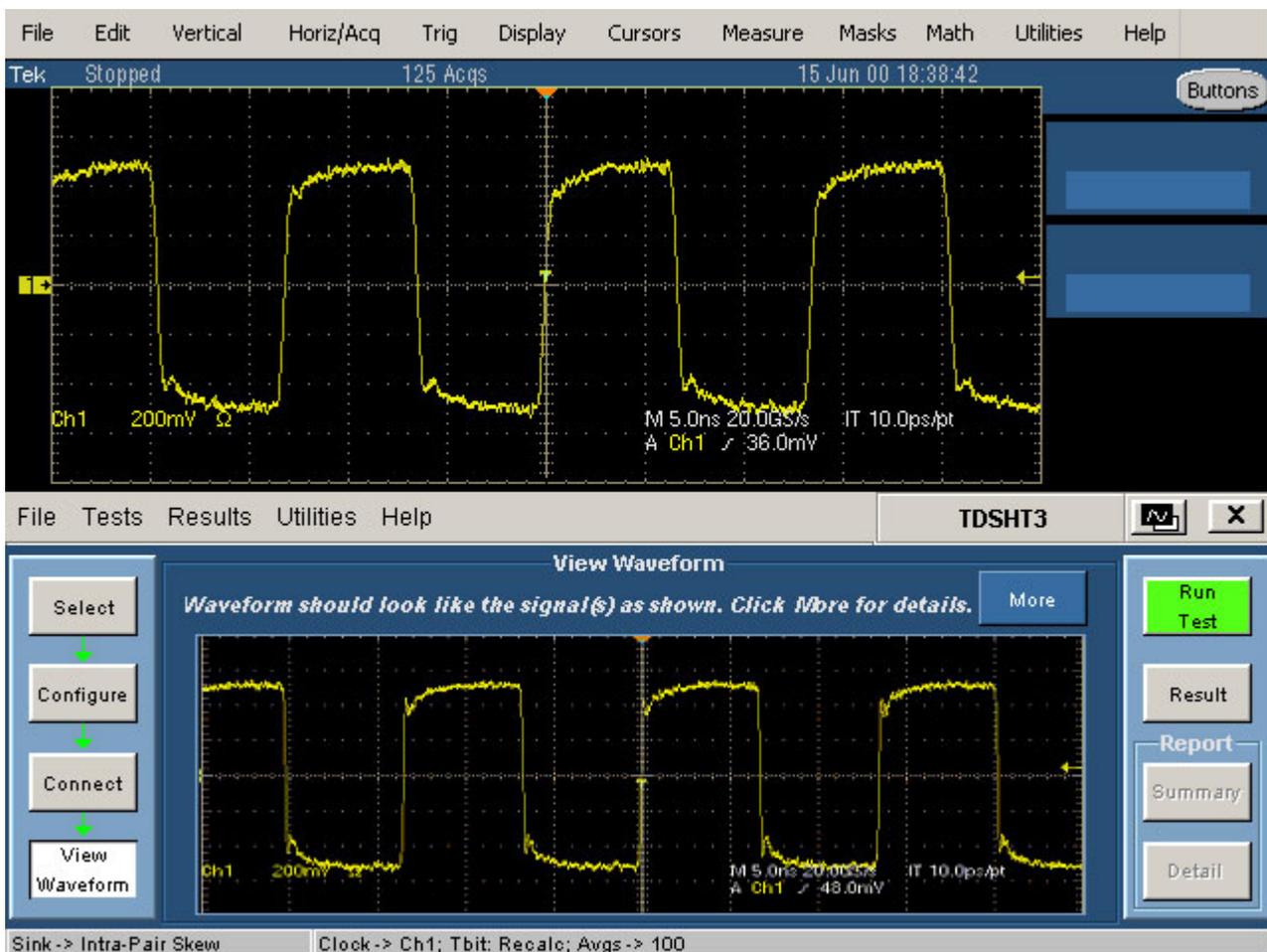


Figure 95: Waveform of Sink Intra-Pair Skew

Cable – Eye Diagram

Because no signal is connected to the oscilloscope, you cannot view the waveform for the eye diagram test.

Test

Source – Eye Diagram

This test allows you to confirm that the differential signal on each TMDS differential data pair has an 'eye opening' (region of valid data) which meets or exceeds the limits on eye opening in the specification.

You will need one supported oscilloscope, two differential probes, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-DI fixture.

1. On the menu bar, click **Tests > Select > Source**.
2. In the clock-data tests pane, select the **Eye Diagram** check box.

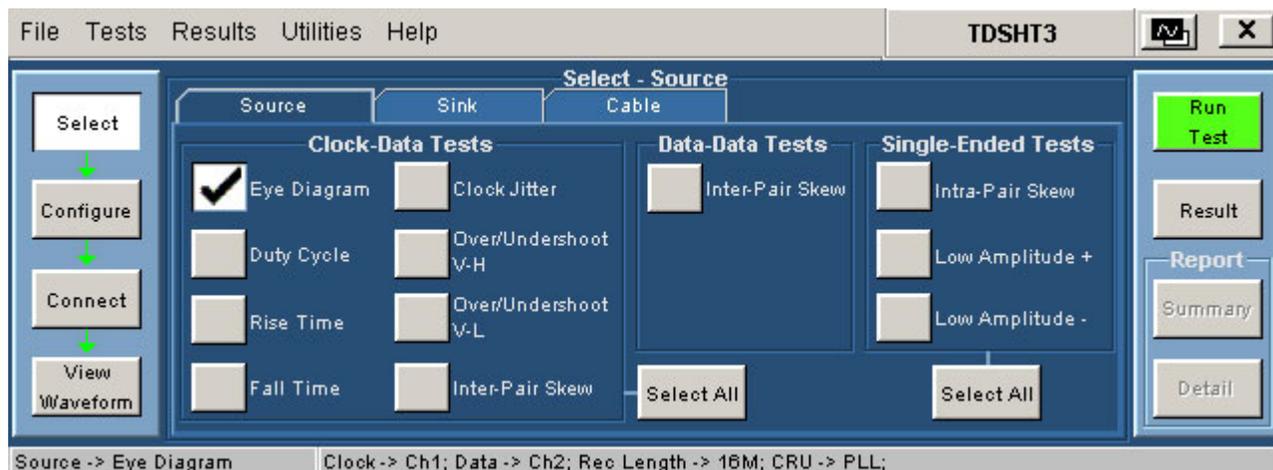


Figure 96: Select Source with Eye Diagram test selected

- To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

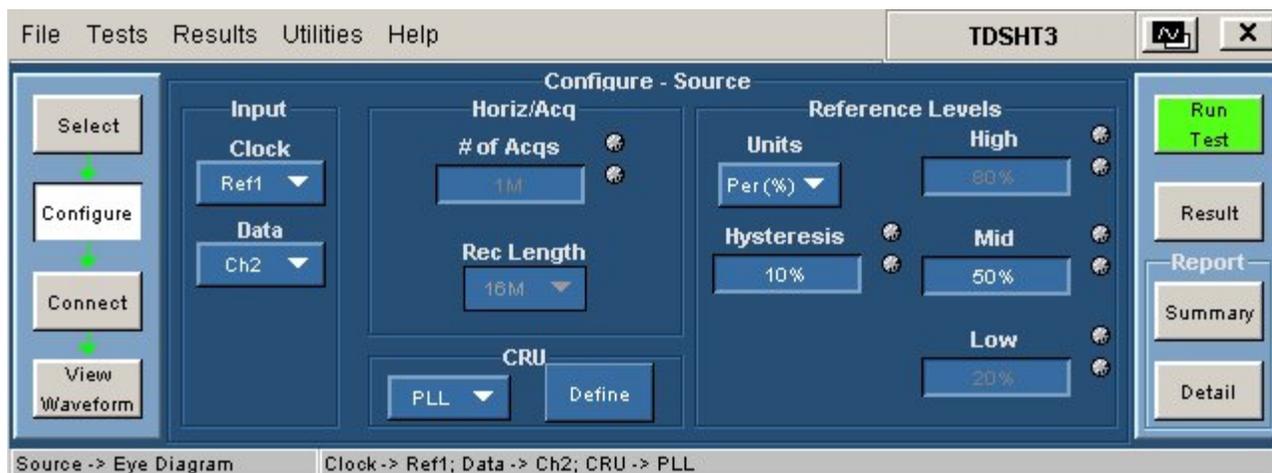


Figure 97: Configure Source for Eye Diagram

- In the input pane, you have the following options:

Table 28: Input options for Eye Diagram

| Configure Parameter | Description |
|---------------------|--|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, Ch4, Ref1, Ref2, Ref3, and Ref4. |
| Data | Data indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, Ch4, Ref1, Ref2, Ref3, and Ref4. |

- In the horiz/acq pane, you have the following option:

Table 29: Horiz/Acq options for Eye Diagram

| Configure Parameter | Description |
|---------------------|--|
| Record Length | In the Rec Length box, enter the desired record length value for the eye tests. |

6. In the CRU pane, you have the following option:

Table 30: CRU options for Eye Diagram

| Configure Parameter | Description |
|---------------------|---|
| CRU | The CRU list allows you to configure the CRU. The available choices are PLL, Raw, and Ideal. The default value is first order PLL and is used for compliance testing. Raw and Ideal are used for analysis. |
| Define | The Define is available only when PLL is selected. |

7. In the reference levels pane, you have the following options:

Table 31: Reference Levels options for Eye Diagram

| Configure Parameter | Description |
|---------------------|--|
| Units | The Units list allows you to set the reference level units to either Per (%) or Abs. Per (%) indicates that the reference levels are a percentage of the Vswing value. Abs indicates that the reference levels are absolute voltage values. |
| Hysteresis | In the Hysteresis box, enter the desired hysteresis percent value. The default value is 10 percent. The hysteresis range is between 2 percent and 10 percent. |
| Mid | In the Mid box, enter the desired mid reference voltage value. The default value is 50 percent. |

8. To connect the DUT, click **Tests > Connect**.

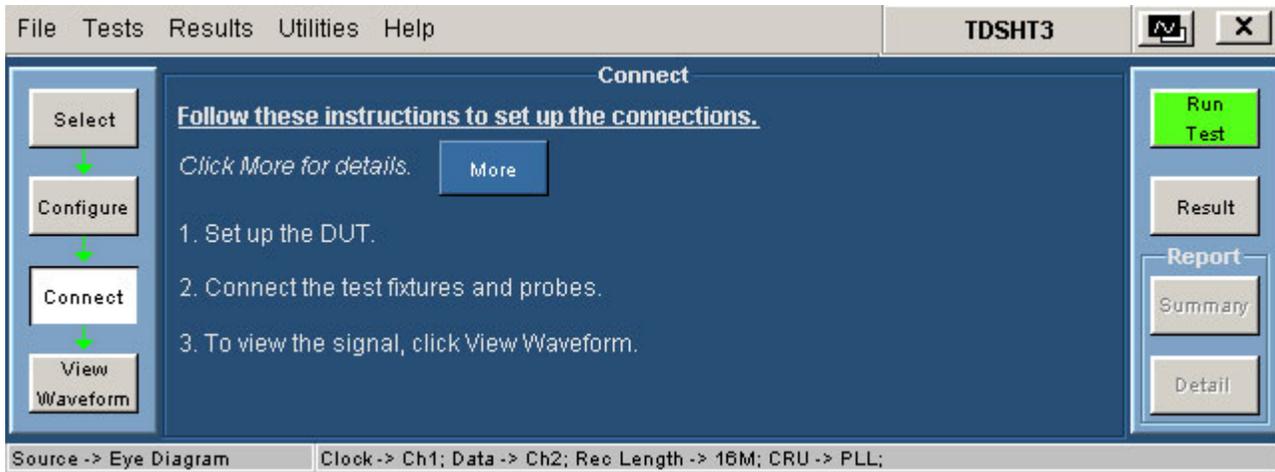


Figure 98: Connect pane for Source Eye Diagram

9. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections.

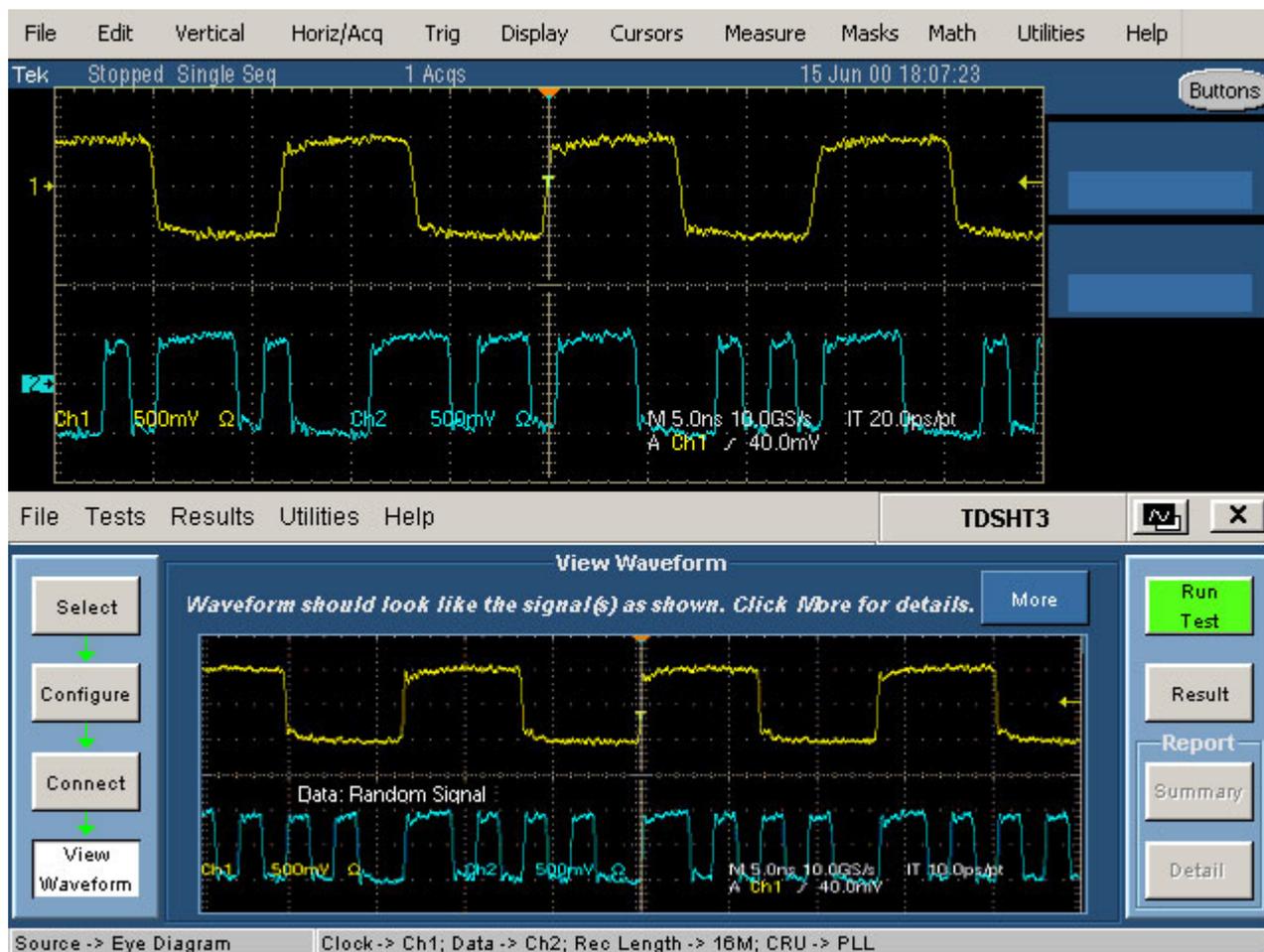


Figure 99: Waveform of Source Eye Diagram

10. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

11. If you have run the eye diagram test successfully, the software makes **Result** available automatically and displays the eye diagram plot. A warning message box may also appear. For more information on the eye diagram plot, refer to the online help. For more information on the message box, refer to the online help.

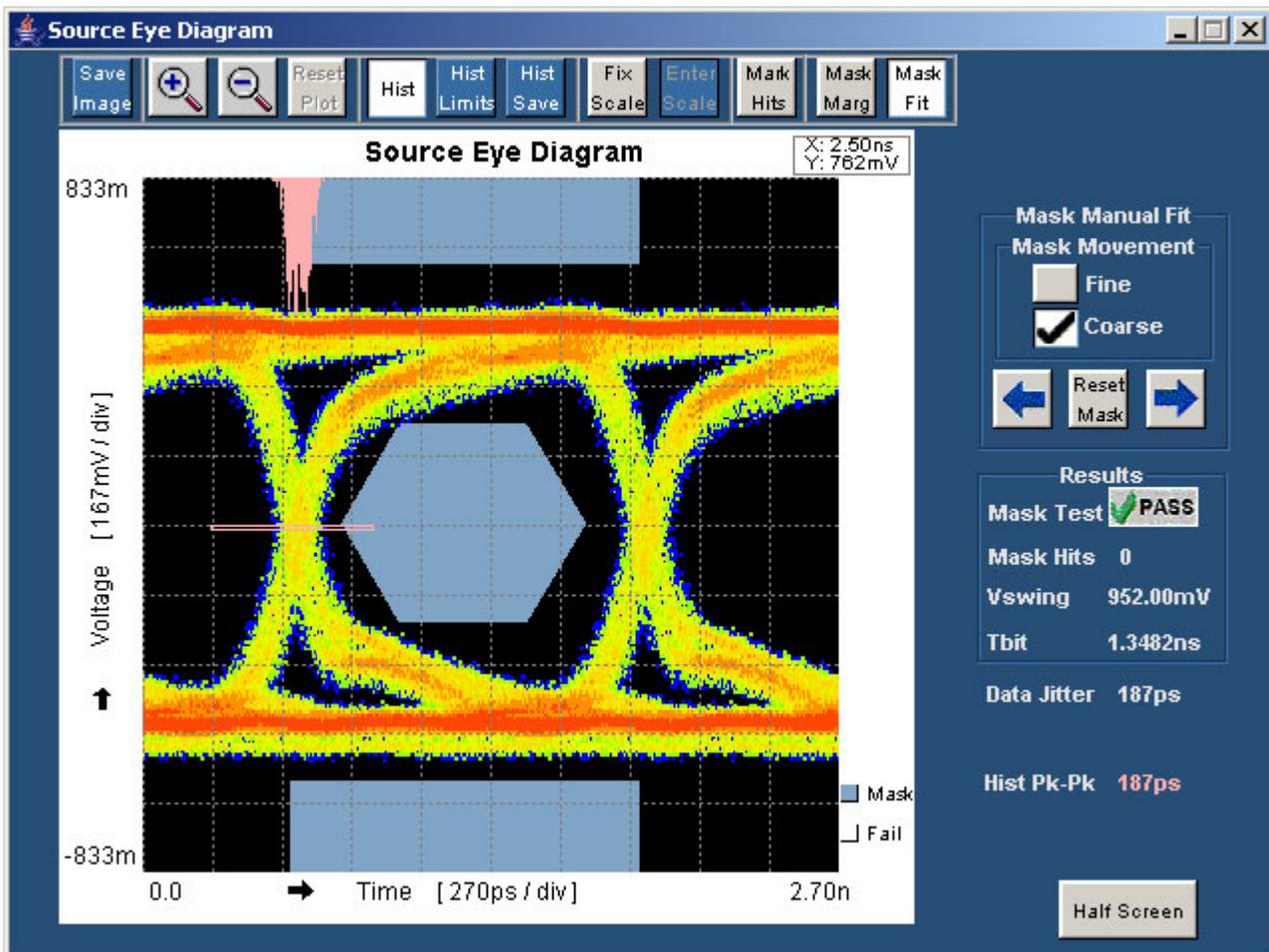


Figure 100: Source Eye Diagram plot

12. Click **Half Screen** to view the eye diagram plot in half screen. You can also view both the result summary of the test and the report configuration in the result pane as shown in the following diagram. For more information on result summary and report configuration, refer to the online help.

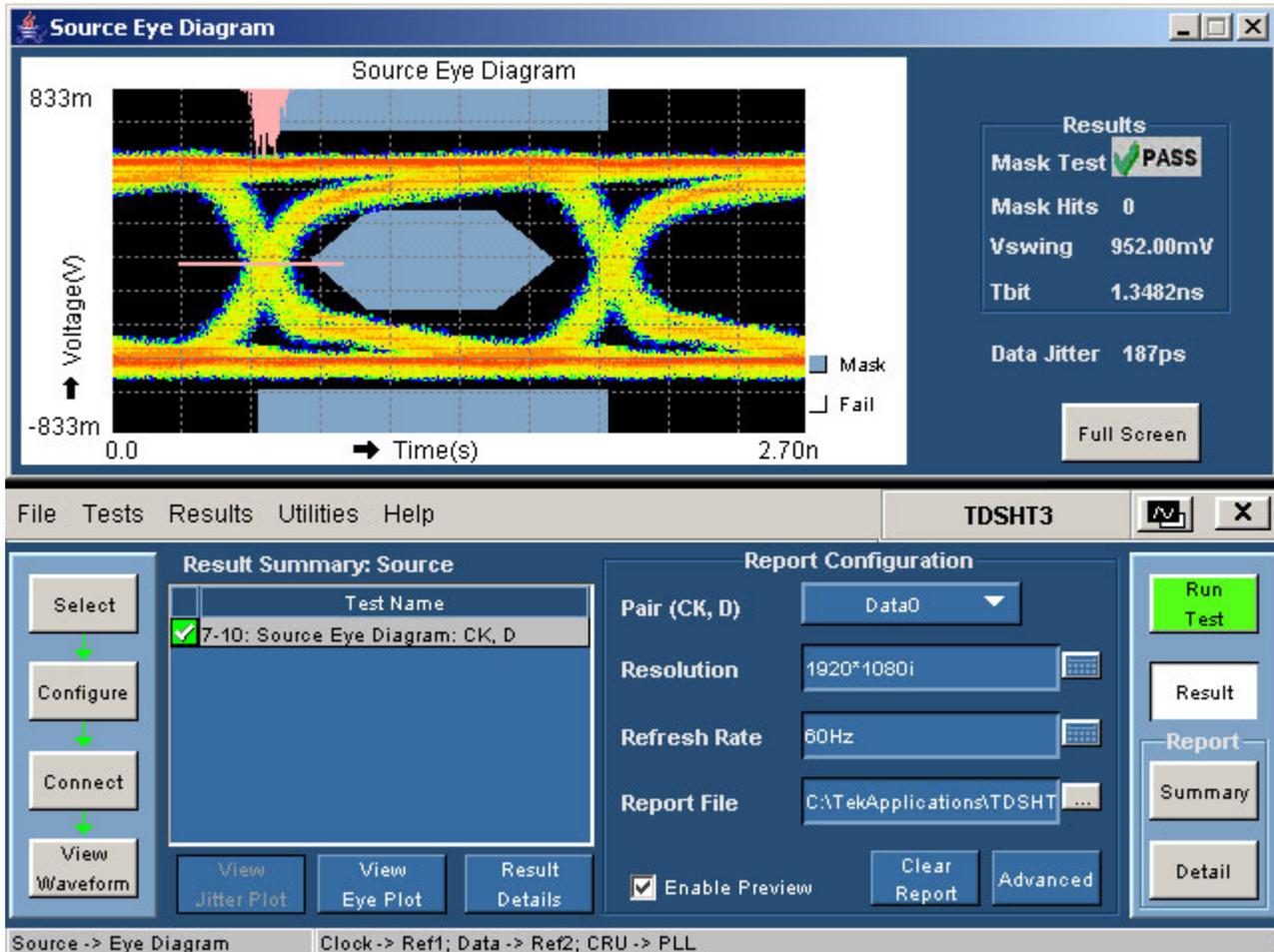


Figure 101: Waveform of Source Eye Diagram plot and Result

- In the result summary pane, click **Result Details** to display the details of the result. For more information on the result details, refer to the online help.

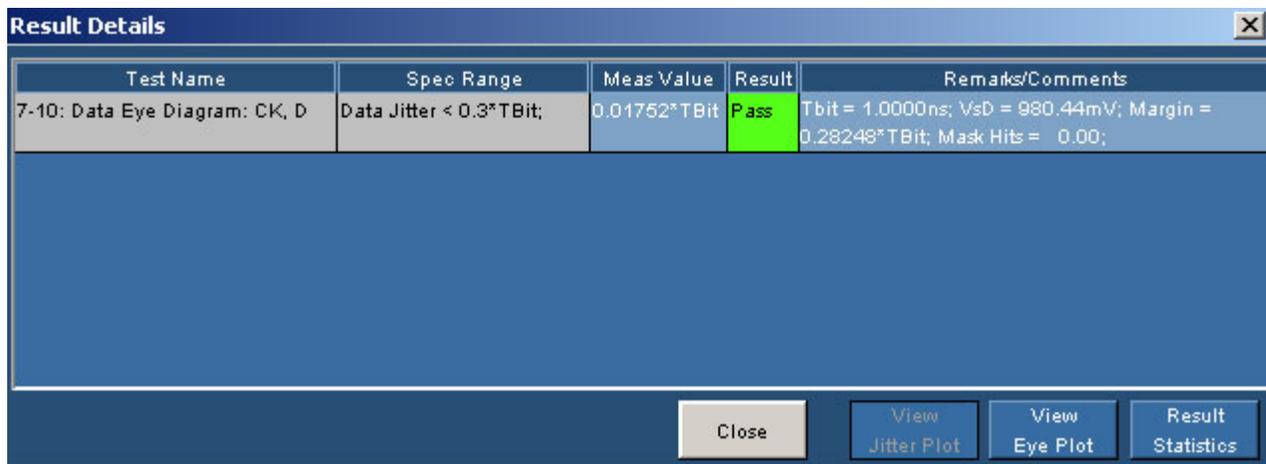


Figure 102: Result Details for Source Eye Diagram

- In the **Result Details** dialog box, click **Result Statistics** to display statistics based on the tests. For more information on result statistics, refer to the online help.

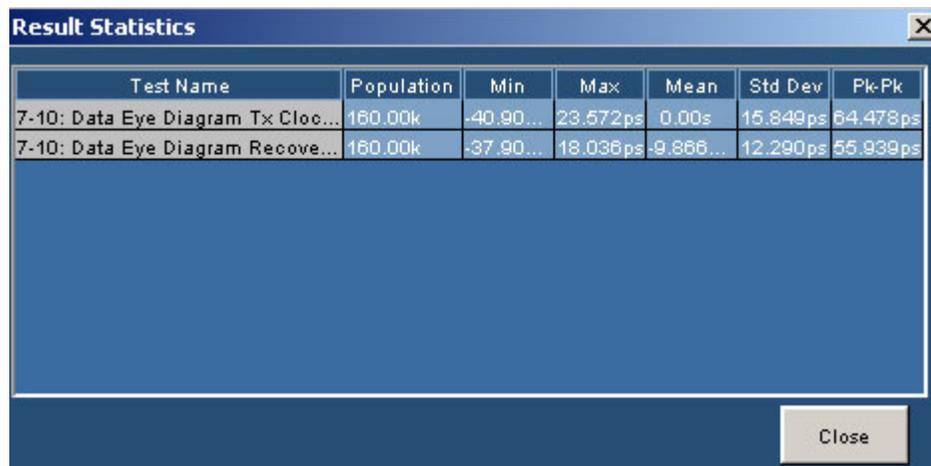


Figure 103: Result Statistics for Source Eye Diagram

Source – Duty Cycle

This test allows you to confirm that the duty cycle of the differential TMDS clock does not exceed the limits allowed by the specification.

You will need one supported oscilloscope, one differential probe, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-DI fixture.

1. On the menu bar, click **Tests > Select > Source**.
2. In the clock-data tests pane, select the **Duty Cycle** check box.

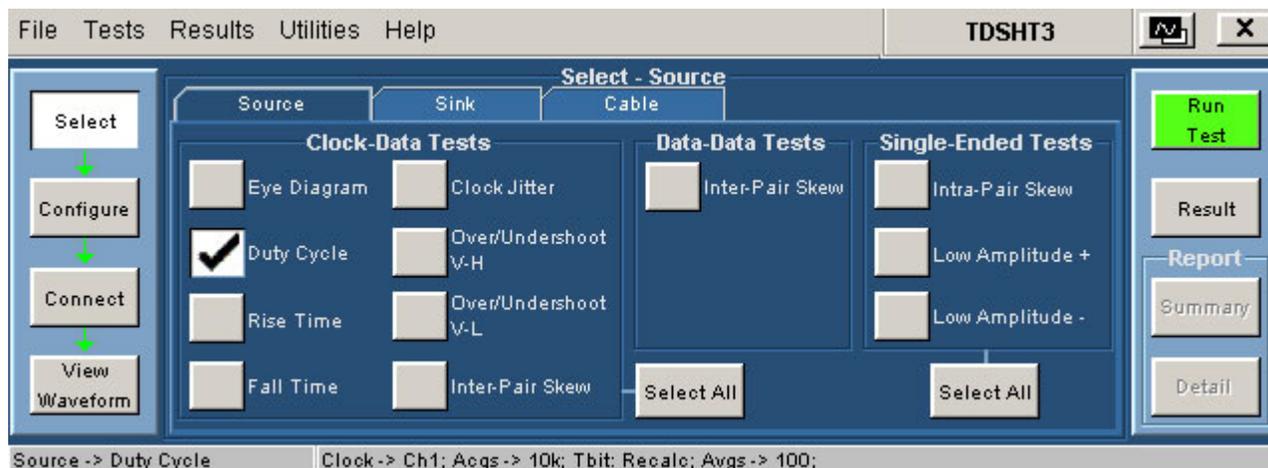


Figure 104: Select Source with Duty Cycle test selected

3. To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

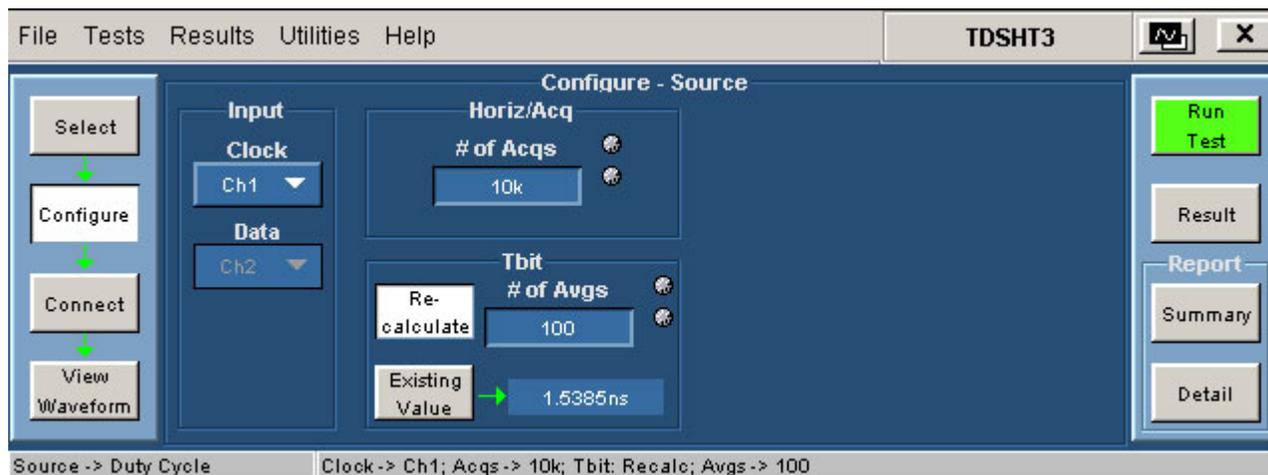


Figure 105: Configure Source for Duty Cycle

4. In the input pane, you have the following option:

Table 32: Input options for Duty Cycle

| Configure Parameter | Description |
|---------------------|--|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

5. In the horiz/acq pane, you have the following option:

Table 33: Horiz/Acq options for Duty Cycle

| Configure Parameter | Description |
|---------------------|--|
| # of Acqs | In the # of Acqs box, enter the desired number of acquisitions that are required for the test. The default value is 10 K. |

6. In the tbit pane, you have the following options:

Table 34: Tbit options for Duty Cycle

| Configure Parameter | Description |
|---------------------|---|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

7. To connect the DUT, click **Tests > Connect**.

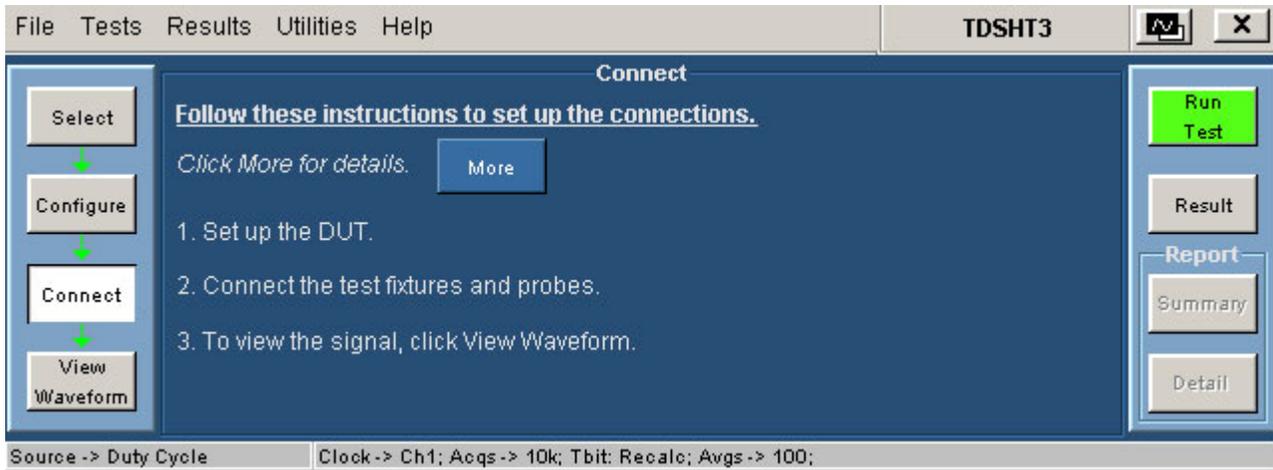


Figure 106: Connect pane for Duty Cycle

8. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections.

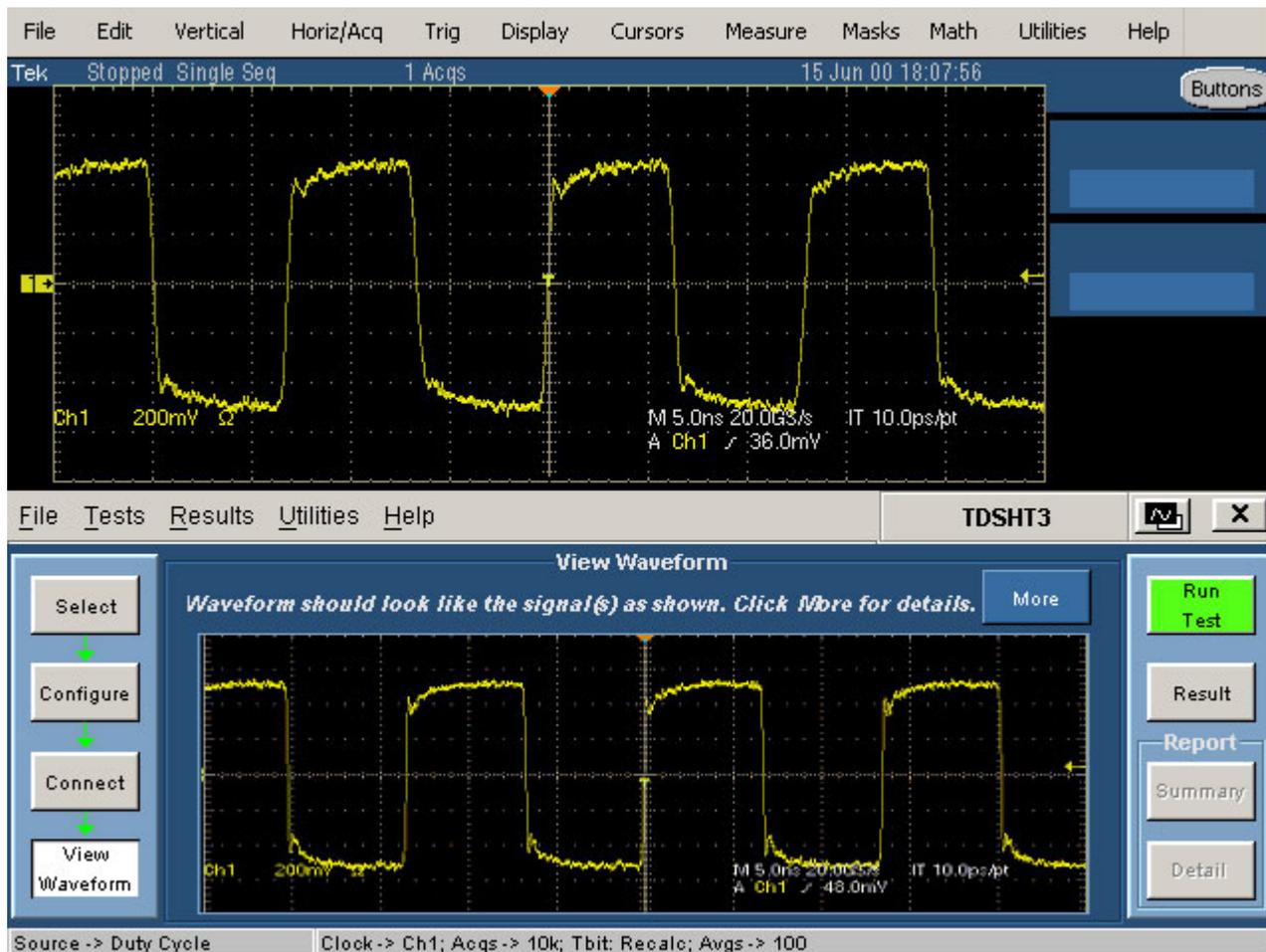


Figure 107: Waveform of Duty Cycle

9. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

- The software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

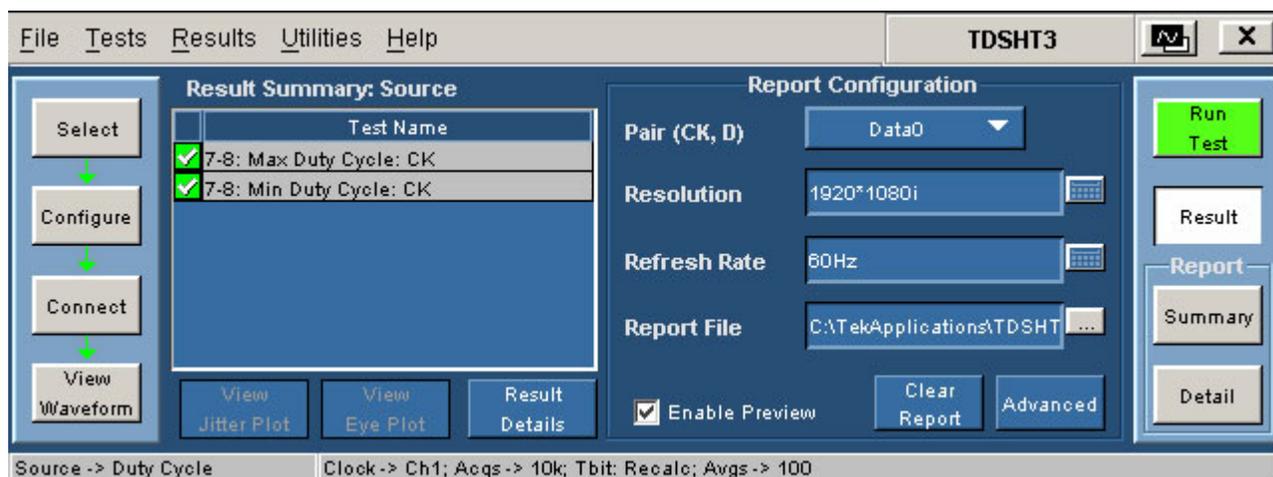


Figure 108: Result for Duty Cycle

Table 35: Result options for Duty Cycle

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

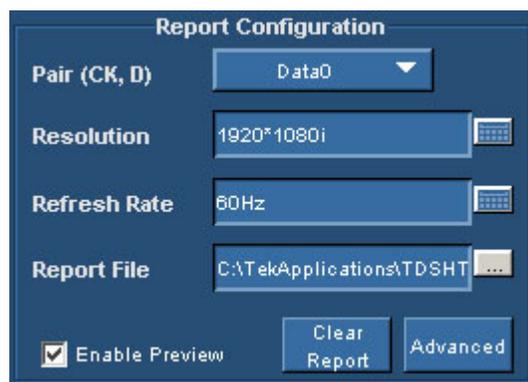


Figure 109: Report Configuration for Duty Cycle

In the report configuration pane, you can configure the following parameters:

Table 36: Report Configuration options for Duty Cycle

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

11. In the result summary pane, click **Result Details** to display the details of the result.



Figure 110: Result Details for Duty Cycle

Table 37: Result Details options for Duty Cycle

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |

Source – Rise Time

This test allows you to confirm that the rise times on the TMDS differential signals fall within the limits of the specification.

You will need one supported oscilloscope, one differential probe, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-DI fixture.

1. On the menu bar, click **Tests > Select > Source**.
2. In the clock-data tests pane, select the **Rise Time** check box.

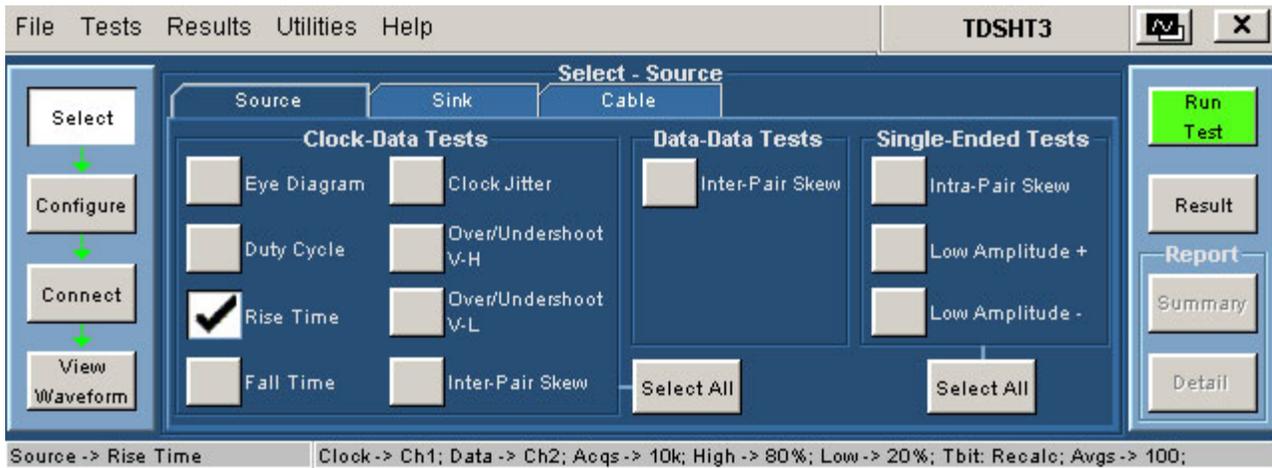


Figure 111: Select Source with Rise Time test selected

3. To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

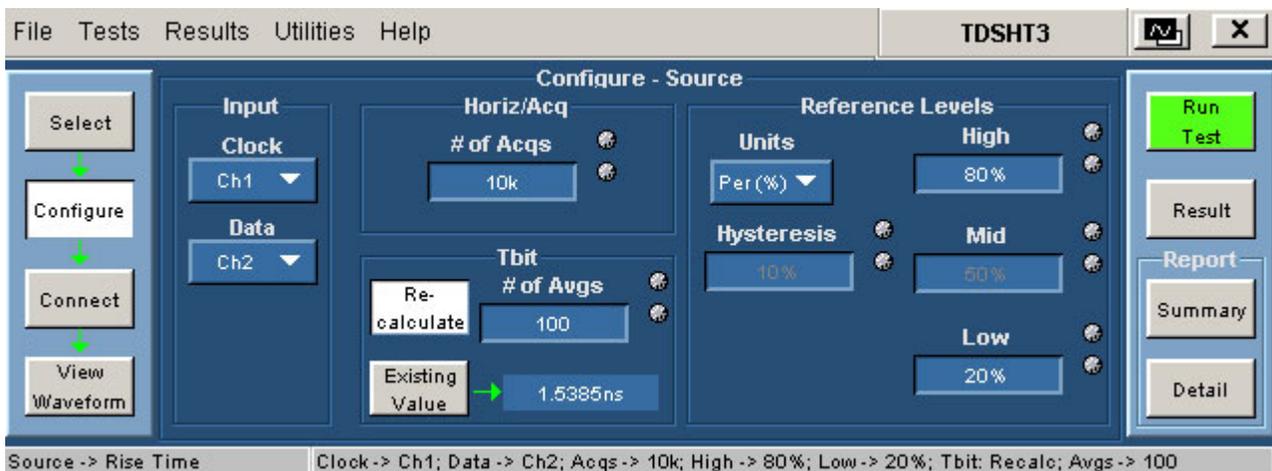


Figure 112: Configure Source for Rise Time

4. In the input pane, you have the following options:

Table 38: Input options for Rise Time

| Configure Parameter | Description |
|---------------------|--|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, Ch4, and Not Conn. |
| Data | Data indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, Ch4, and Not Conn. |

5. In the horiz/acq pane, you have the following option:

Table 39: Horiz/Acq options for Rise Time

| Configure Parameter | Description |
|---------------------|--|
| # of Acqs | In the # of Acqs box, enter the desired number of acquisitions that are required for the test. The default value is 10 K. |

6. In the tbit pane, you have the following options:

Table 40: Tbit options for Rise Time

| Configure Parameter | Description |
|---------------------|---|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

7. In the reference levels pane, you have the following options:

Table 41: Reference Levels options for Rise Time

| Configure Parameter | Description |
|---------------------|--|
| Units | The Units list allows you to set the reference level units to either Per (%) or Abs. Per (%) indicates that the reference levels are a percentage of the Vswing value. Abs indicates that the reference levels are absolute voltage values. |
| Hysteresis | In the Hysteresis box, enter the desired hysteresis percent value. The default value is 10 percent. |
| High | In the High box, enter the desired high reference voltage value. The default value is 80 percent. |
| Mid | In the Mid box, enter the desired mid reference voltage value. The default value is 50 percent. |
| Low | In the Low box, enter the desired low reference voltage value. The default value is 20 percent. |

8. To connect the DUT, click **Tests > Connect**.

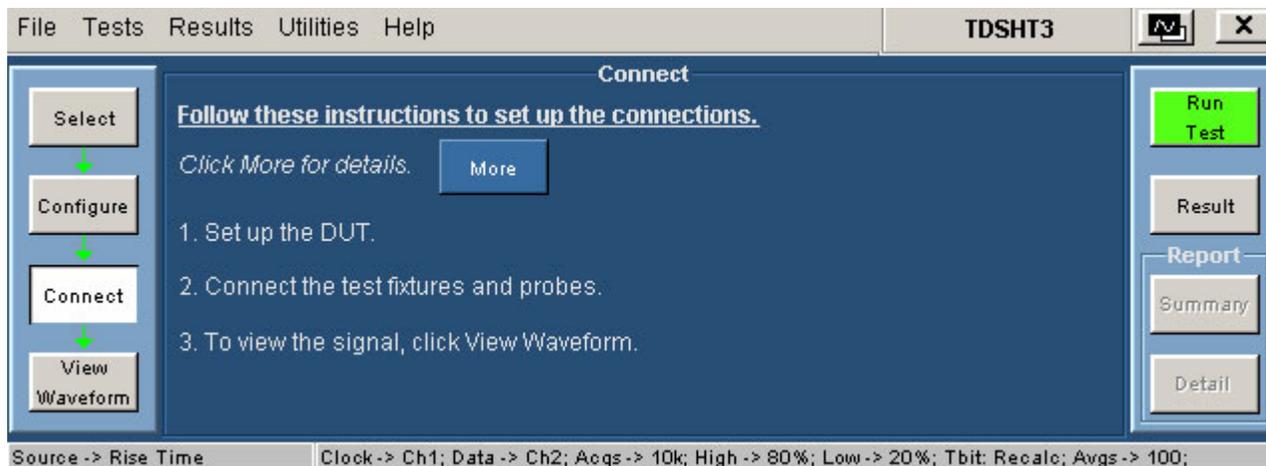


Figure 113: Connect pane for Rise Time

9. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections.

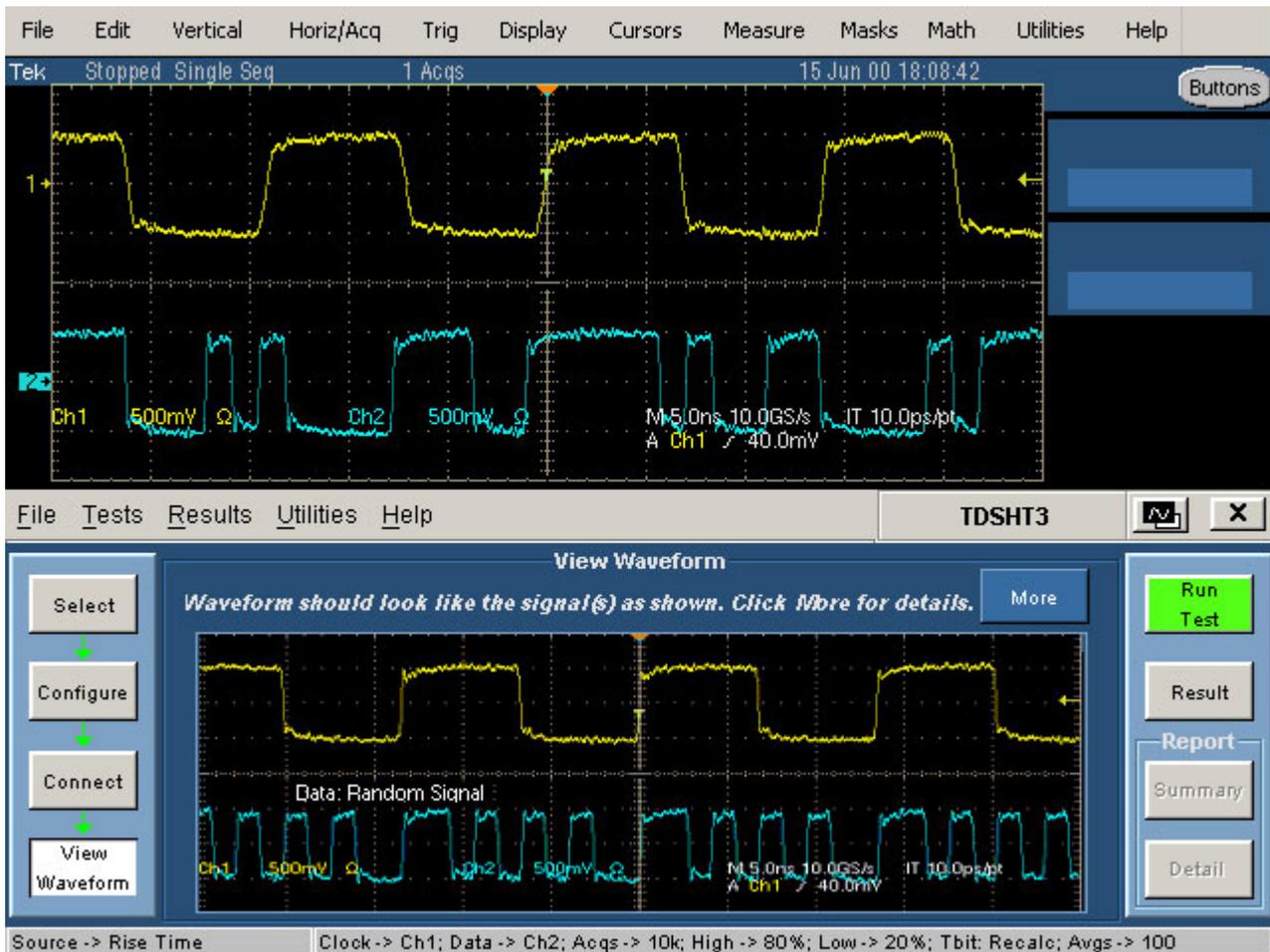


Figure 114: Waveform of Rise Time

10. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

11. The software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

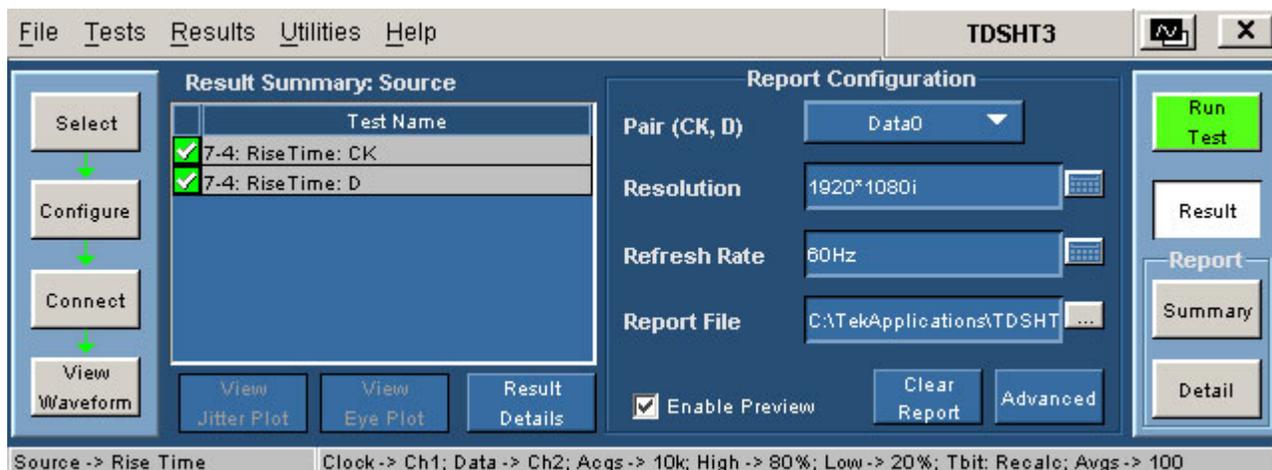


Figure 115: Result for Rise Time

Table 42: Result options for Rise Time

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

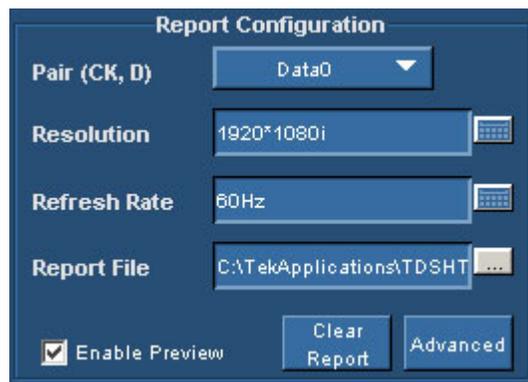


Figure 116: Report Configuration for Rise Time

In the report configuration pane, you can configure the following parameters:

Table 43: Report Configuration options for Rise Time

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

- In the result summary pane, click **Result Details** to display the details of the result.



Figure 117: Result Details for Rise Time

Table 44: Result Details for Rise Time

| Option | Description |
|-------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Spec Range | The Spec Range box displays the lower limit and upper limit of the rise time test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |
| Result Statistics | Click Result Statistics to display statistics based on the tests. |

- In the **Result Details** dialog box, click **Result Statistics** to display statistics based on the tests.

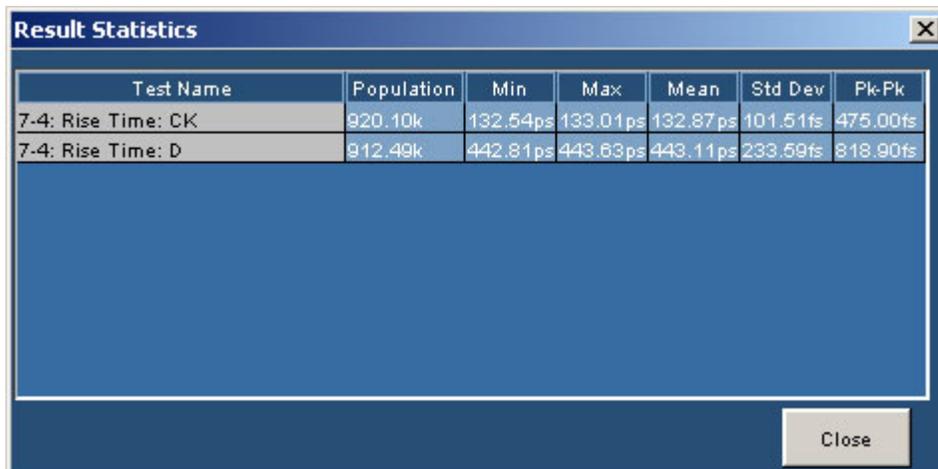


Figure 118: Result Statistics for Rise Time

The software calculates statistics for each selected test, and logs the statistics on a cycle-by-cycle basis in a large waveform. The standard statistics are for the Maximum, Minimum, Mean, Standard Deviation, and Population.

Table 45: Result Statistics for Rise Time test

| Option | Description |
|------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal names - CK (Clock), D (Data). |
| Population | The software calculates this statistic by using the following equation: Population (X) = N |
| Min | The software calculates this statistic by using the following equation: Min (X) = Lowest value of X |
| Max | The software calculates this statistic by using the following equation: Max (X) = Highest value of X |
| Mean | The software calculates this statistic by using the following equation: $Mean (X) = \bar{X} = \frac{1}{N} \sum_{n=1}^N X_n$ |
| Std Dev | The software calculates this statistic by using the following equation: $Standard Deviation (X) = \sigma_x = \sqrt{\frac{1}{(N-1)} \sum_{n=1}^N (X_n - \bar{X})^2}$ |

Table 45: Result Statistics for Rise Time test (Contd.)

| Option | Description |
|--------|--|
| PK-Pk | The software calculates this statistic by using the following equation: $X_{ppn} = \text{Max}(X) - \text{Min}(X)$ |
| Close | Click Close to quit the Result Statistics dialog box. |

Source – Fall Time

This test allows you to confirm that the fall times on the TMDS differential signals fall within the limits of the specification.

You will need one supported oscilloscope, one differential probe, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-DI fixture.

1. On the menu bar, click **Tests > Select > Source**.
2. In the clock-data tests pane, select the **Fall Time** check box.

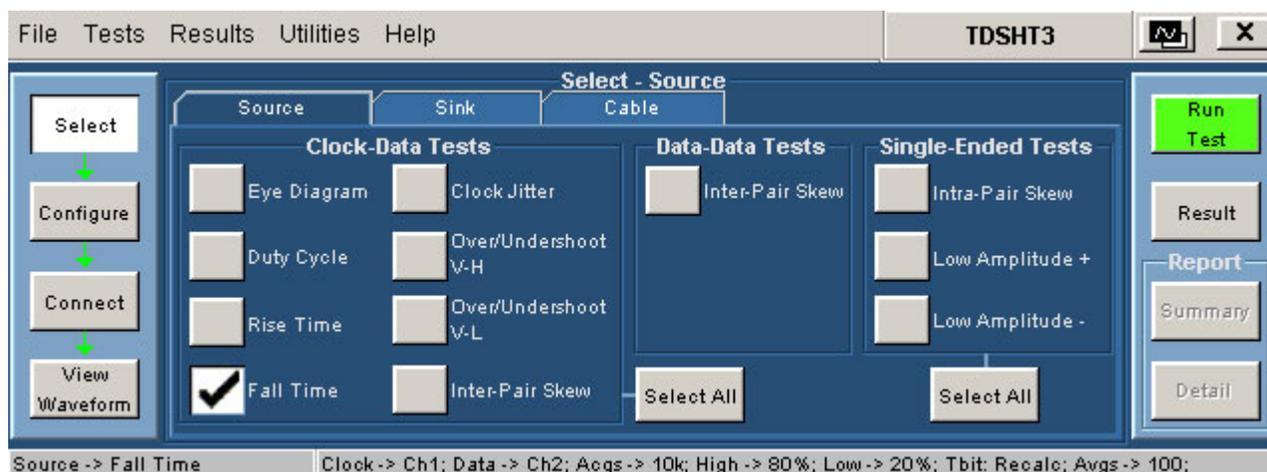


Figure 119: Select Source with Fall Time test selected

- To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

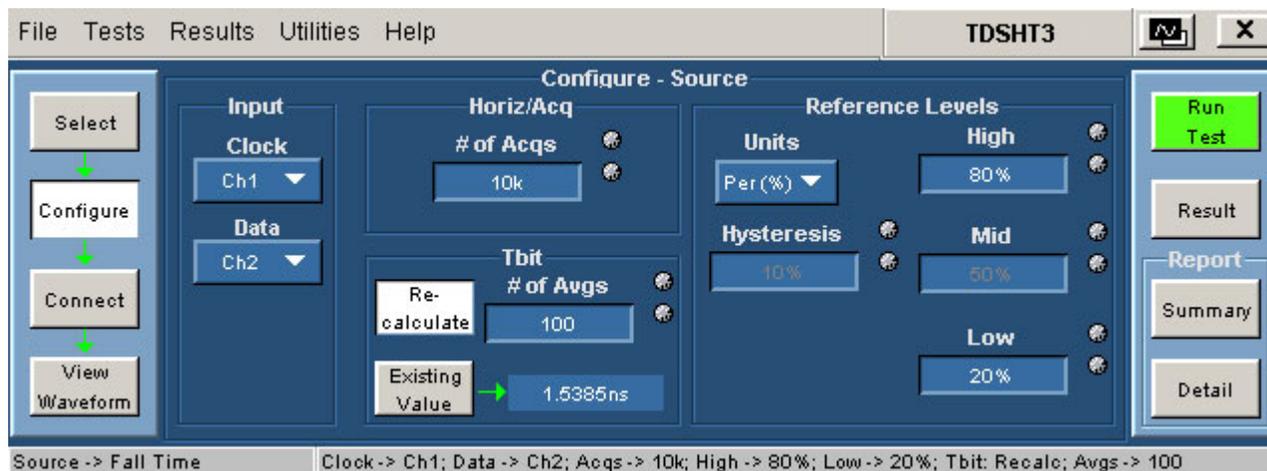


Figure 120: Configure Source for Fall Time

- In the input pane, you have the following options:

Table 46: Input options for Fall Time

| Configure Parameter | Description |
|---------------------|--|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, Ch4, and Not Conn. |
| Data | Data indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, Ch4, and Not Conn. |

- In the horiz/acq pane, you have the following option:

Table 47: Horiz/Acq options for Fall Time

| Configure Parameter | Description |
|---------------------|--|
| # of Acqs | In the # of Acqs box, enter the desired number of acquisitions that are required for the test. The default value is 10 K. |

6. In the tbit pane, you have the following options:

Table 48: Tbit options for Fall Time

| Configure Parameter | Description |
|---------------------|---|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

7. In the reference levels pane, you have the following options:

Table 49: Reference Levels options for Fall Time

| Configure Parameter | Description |
|---------------------|--|
| Units | The Units list allows you to set the reference level units to either Per (%) or Abs. Per (%) indicates that the reference levels are a percentage of the Vswing value. Abs indicates that the reference levels are absolute voltage values. |
| Hysteresis | In the Hysteresis box, enter the desired hysteresis percent value. The default value is 10 percent. |
| High | In the High box, enter the desired high reference voltage value. The default value is 80 percent. |
| Mid | In the Mid box, enter the desired mid reference voltage value. The default value is 50 percent. |
| Low | In the Low box, enter the desired low reference voltage value. The default value is 20 percent. |

8. To connect the DUT, click **Tests > Connect**.

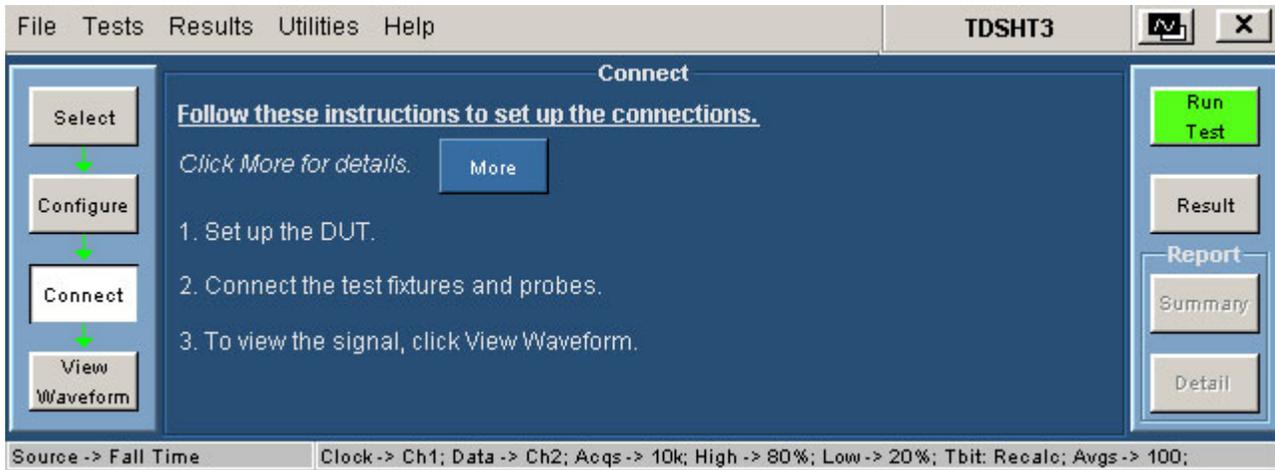


Figure 121: Connect pane for Fall Time

9. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections.

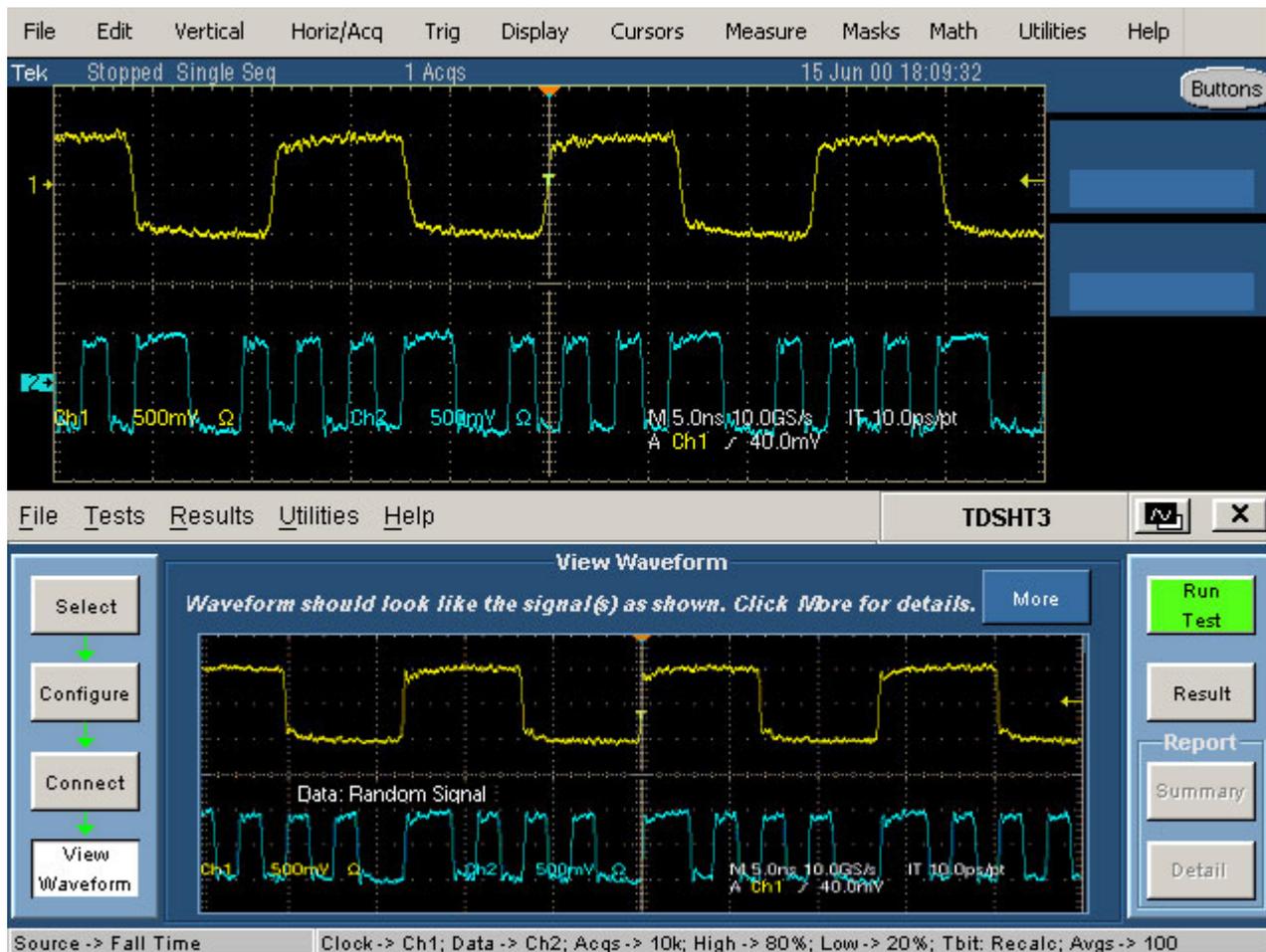


Figure 122: Waveform of Fall Time

10. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

- The software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

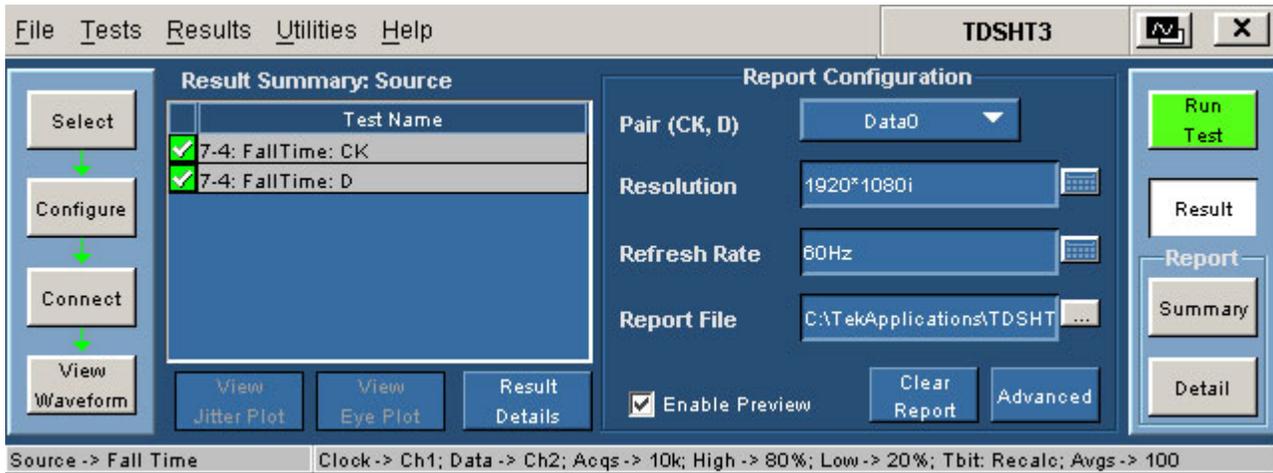


Figure 123: Result for Fall Time

Table 50: Results for Fall Time test

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

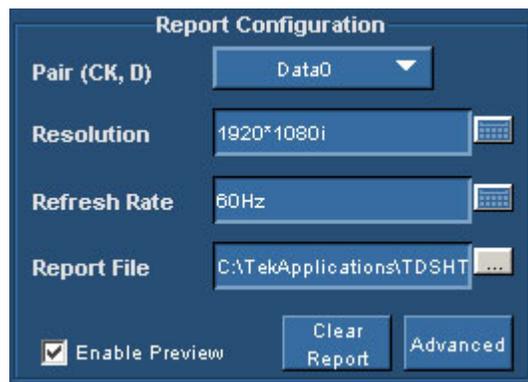


Figure 124: Report Configuration for Fall Time

In the report configuration pane, you can configure the following parameters:

Table 51: Report Configuration options for Fall Time

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

- In the result summary pane, click **Result Details** to display the details of the result.



Figure 125: Result Details for Fall Time

Table 52: Result Details for Fall Time

| Option | Description |
|-------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Spec Range | The Spec Range box displays the lower limit and upper limit of the fall time test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |
| Result Statistics | Click Result Statistics to display statistics based on the tests. |

- In the **Result Details** dialog box, click **Result Statistics** to display statistics based on the tests.

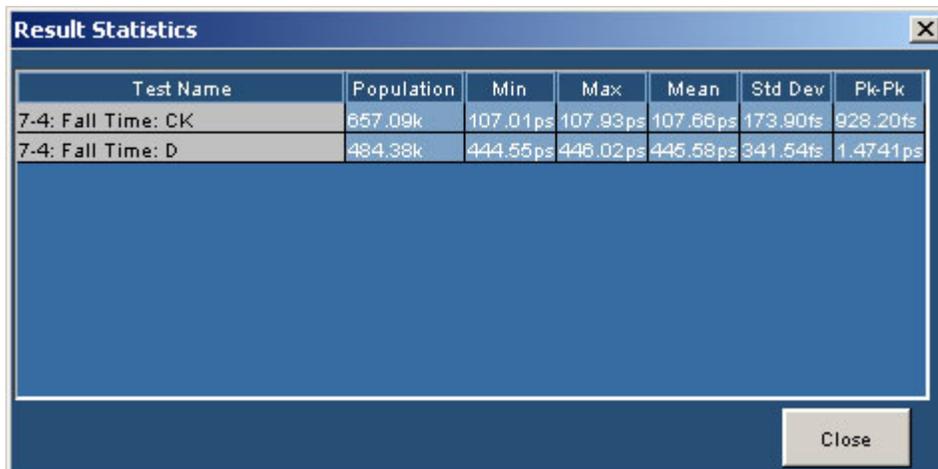


Figure 126: Result Statistics for Fall Time

The software calculates statistics for each selected test, and logs the statistics on a cycle-by-cycle basis in a large waveform. The standard statistics are for the Maximum, Minimum, Mean, Standard Deviation, and Population.

Table 53: Result Statistics for Fall Time

| Option | Description |
|------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal names - CK (Clock), D (Data). |
| Population | The software calculates this statistic by using the following equation: Population (X) = N |
| Min | The software calculates this statistic by using the following equation: Min (X) = Lowest value of X |
| Max | The software calculates this statistic by using the following equation: Max (X) = Highest value of X |
| Mean | The software calculates this statistic by using the following equation: $Mean (X) = \bar{X} = \frac{1}{N} \sum_{n=1}^N X_n$ |
| Std Dev | The software calculates this statistic by using the following equation: $Standard Deviation (X) = \sigma_x = \sqrt{\frac{1}{(N-1)} \sum_{n=1}^N (X_n - \bar{X})^2}$ |

Table 53: Result Statistics for Fall Time (Contd.)

| Option | Description |
|--------|--|
| PK-Pk | The software calculates this statistic by using the following equation: $X_{ppn} = \text{Max}(X) - \text{Min}(X)$ |
| Close | Click Close to quit the Result Statistics dialog box. |

Source – Clock Jitter

This test allows you to confirm that the TMDS clock does not carry excessive jitter.

You will need one supported oscilloscope, one differential probe, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-DI fixture.

1. On the menu bar, click **Tests > Select > Source**.
2. In the clock-data tests pane, select the **Clock Jitter** check box.

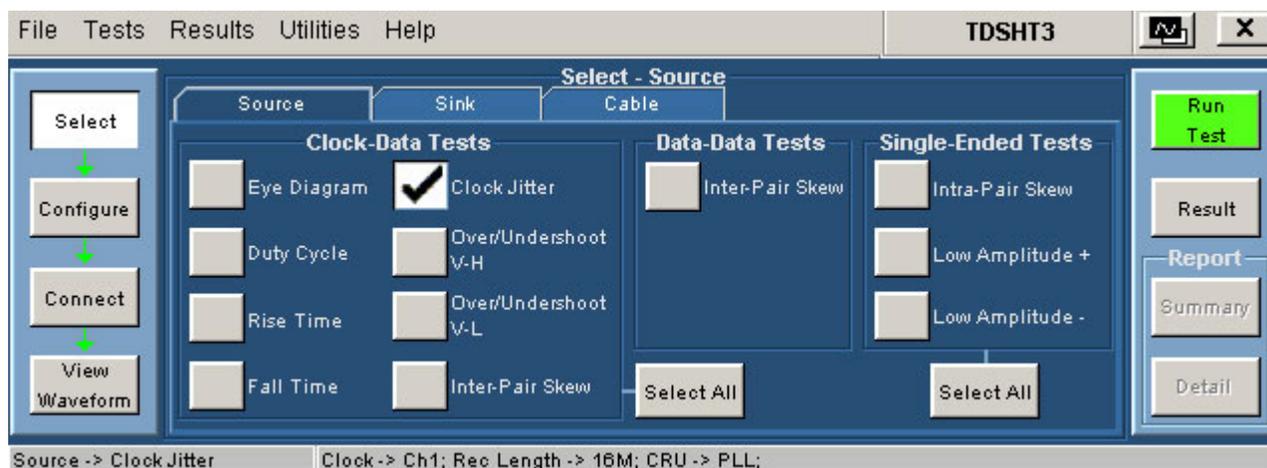


Figure 127: Select Source with Clock Jitter test selected

- To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

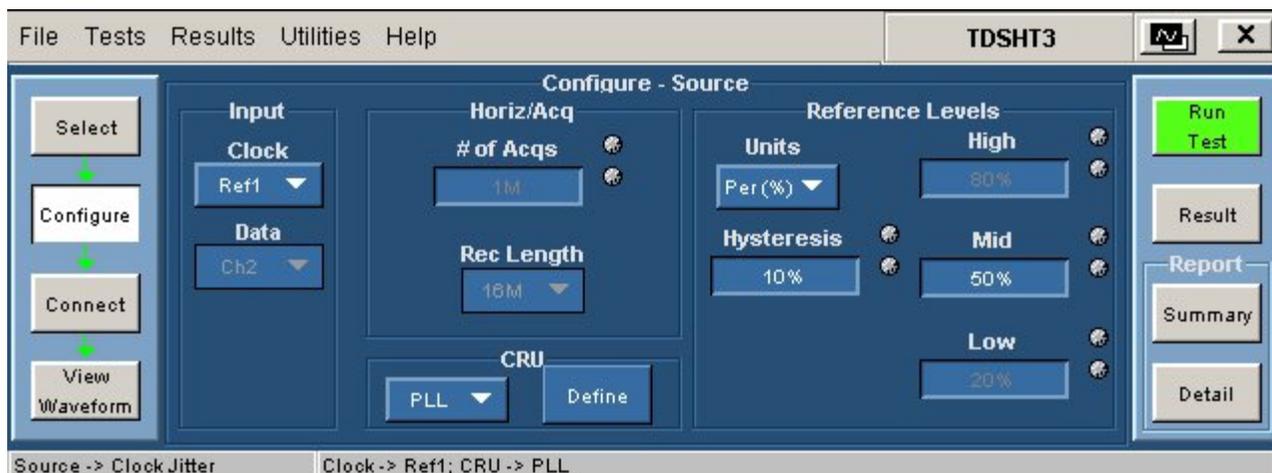


Figure 128: Configure Source for Clock Jitter

- In the input pane, you have the following option:

Table 54: Input options for Clock Jitter

| Configure Parameter | Description |
|---------------------|---|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, Ch4, Ref1, Ref2, Ref3, and Ref4. |

- In the horiz/acq pane, you have the following option:

Table 55: Horiz/ options for Clock Jitter

| Configure Parameter | Description |
|---------------------|---|
| Record Length | In the Rec Length box, enter the desired record length value for the clock jitter tests. |

6. In the CRU pane, you have the following option:

Table 56: CRU options for Clock Jitter

| Configure Parameter | Description |
|---------------------|---|
| CRU | The CRU list allows you to configure the CRU. The available choices are PLL, Raw, and Ideal. The default value is first order PLL and is used for compliance testing. Raw and Ideal are used for analysis. |
| Define | The Define is available only when PLL is selected. |

7. In the reference levels pane, you have the following options:

Table 57: Reference Levels options for Clock Jitter

| Configure Parameter | Description |
|---------------------|--|
| Units | The Units list allows you to set the reference level units to either Per (%) or Abs. Per (%) indicates that the reference levels are a percentage of the Vswing value. Abs indicates that the reference levels are absolute voltage values. |
| Hysteresis | In the Hysteresis box, enter the desired hysteresis percent value. The default value is 10 percent. The hysteresis range is between 2 percent and 10 percent. |
| Mid | In the Mid box, enter the desired mid reference voltage value. The default value is 50 percent. |

8. To connect the DUT, click **Tests > Connect**.

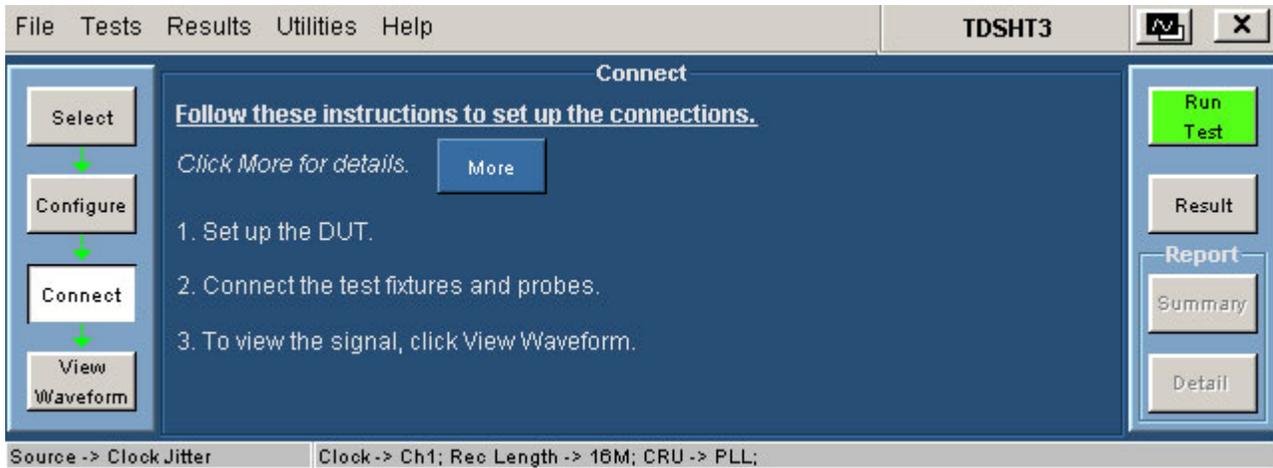


Figure 129: Connect pane for Clock Jitter

9. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections.

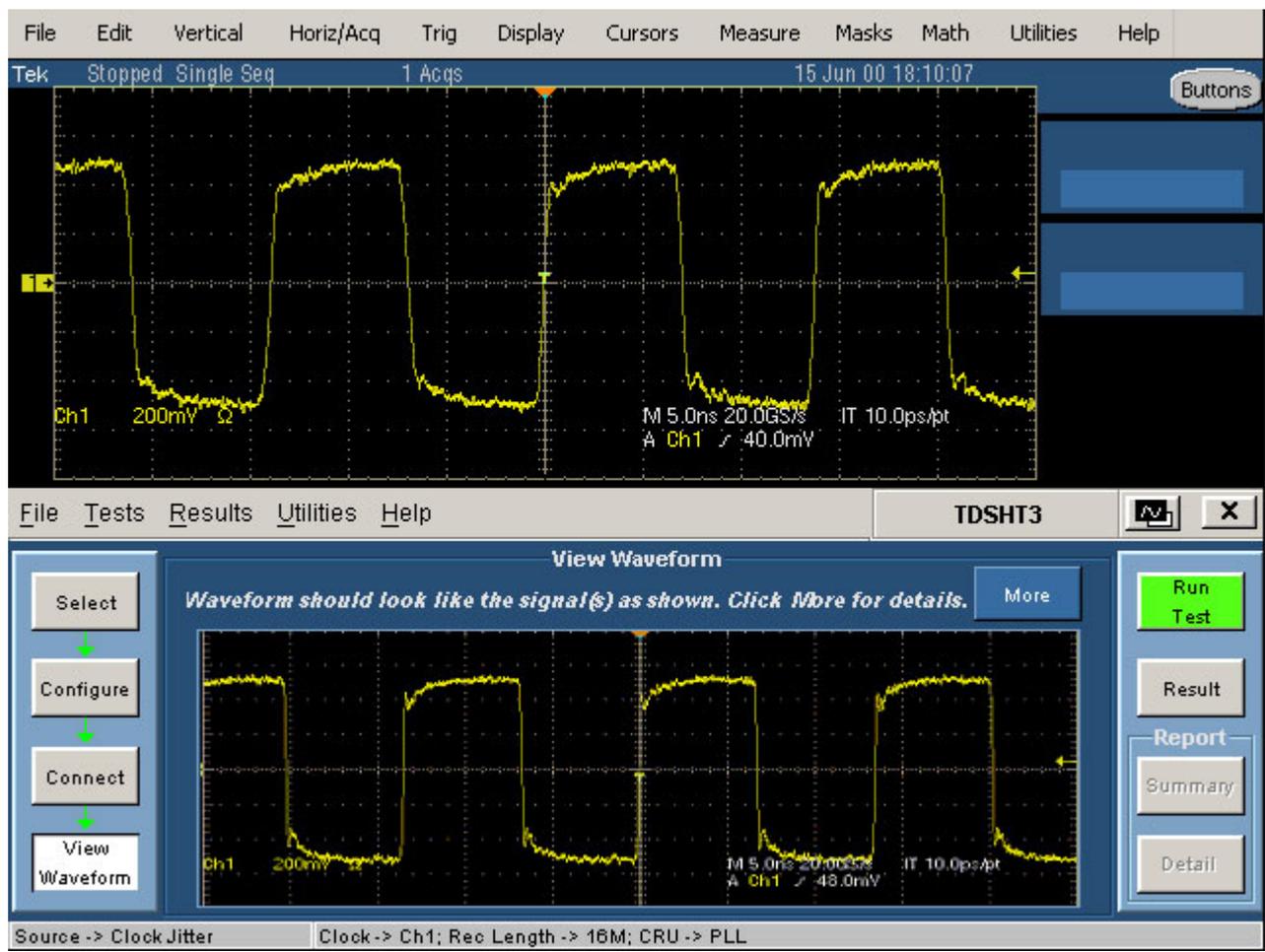


Figure 130: Waveform of Clock Jitter

10. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

11. If you have run the clock jitter test successfully, the software makes **Result** available automatically and displays the clock jitter plot. For more information on the clock jitter plot, refer to the online help.

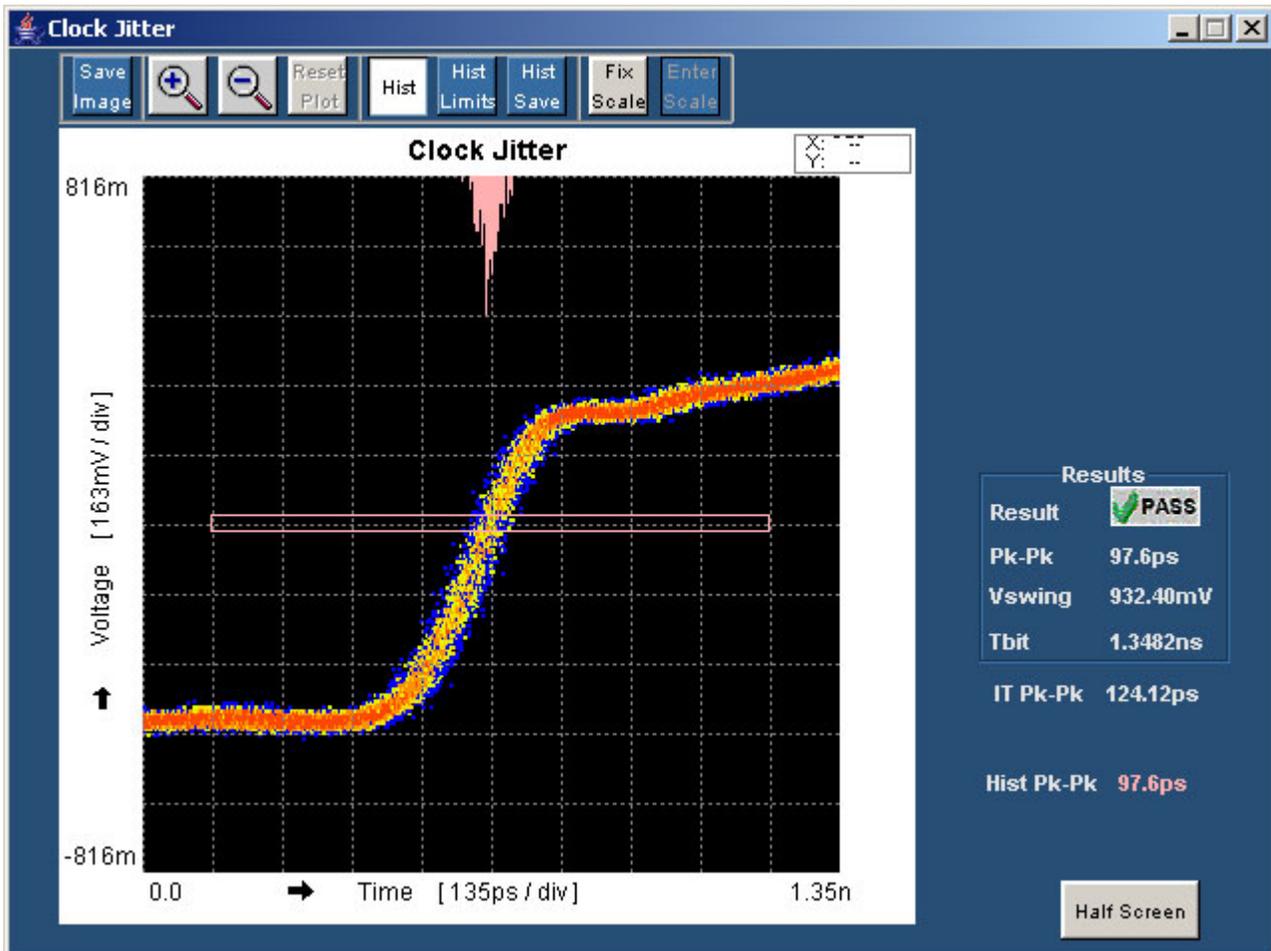


Figure 131: Clock Jitter plot

12. Click **Half Screen** to view the clock jitter plot in half screen. You can also view both the result summary of the test and the report configuration in the result pane as shown in the following diagram. For more information on result summary and report configuration, refer to the online help.

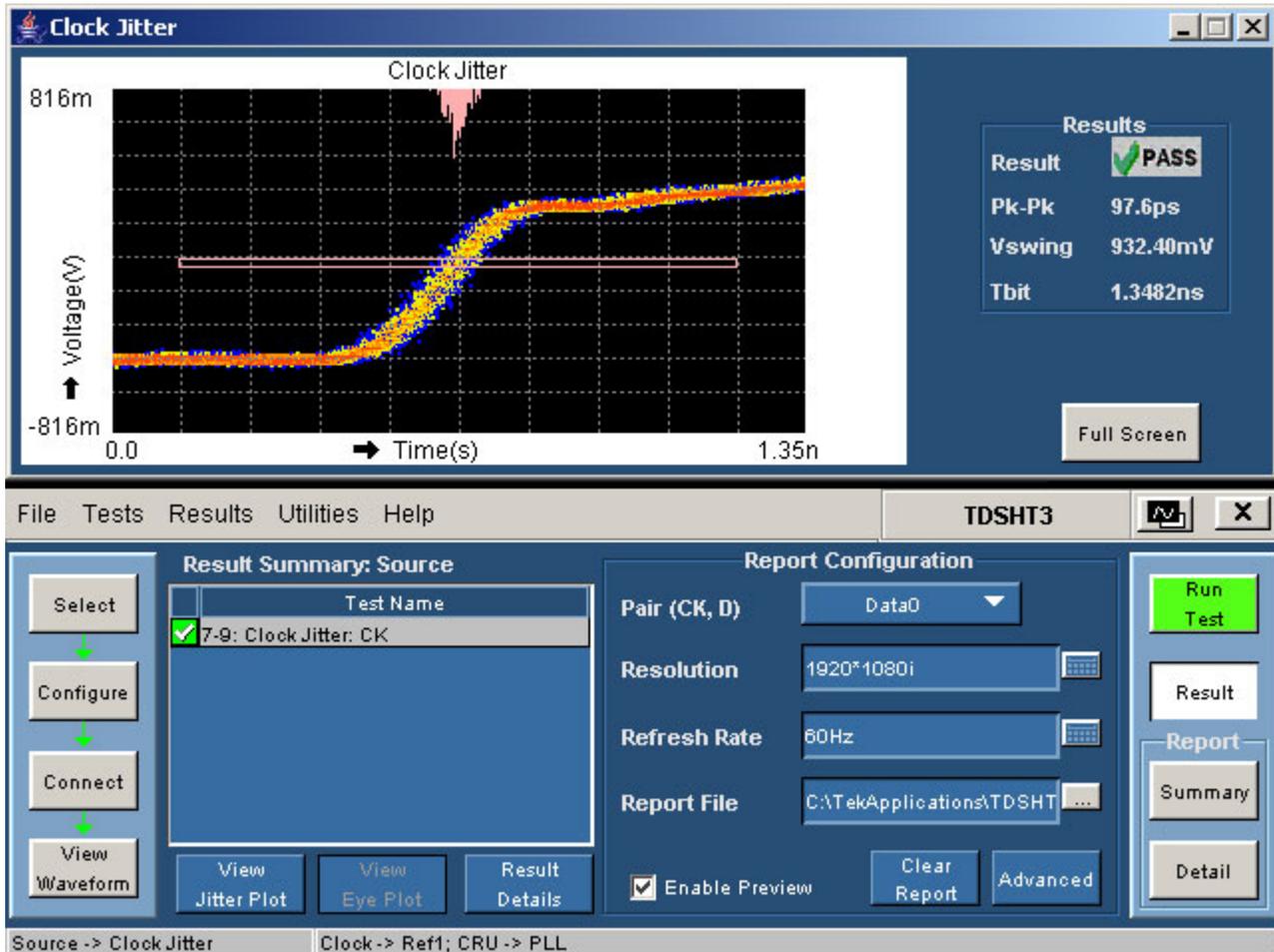


Figure 132: Source Clock Jitter plot and Result

- In the result summary pane, click **Result Details** to display the details of the result. For more information on the result details, refer to the online help.



Figure 133: Result Details for Clock Jitter

- In the **Result Details** dialog box, click **Result Statistics** to display statistics based on the tests. For more information on result statistics, refer to the online help.

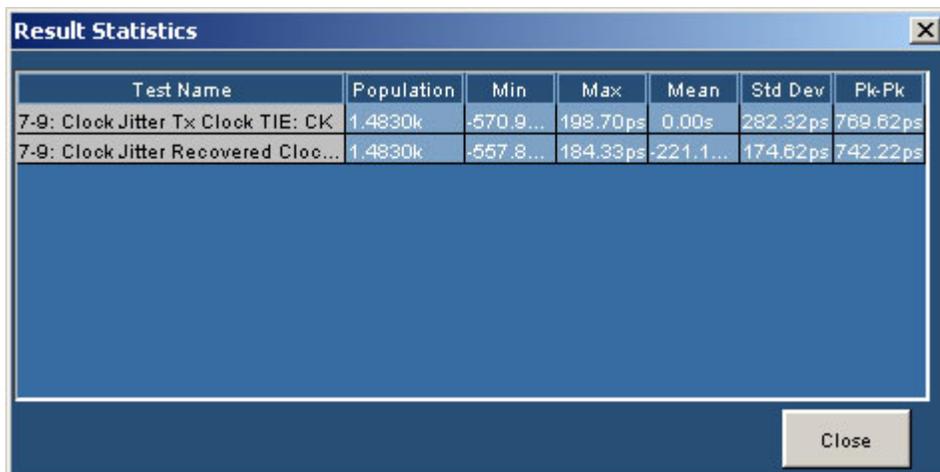


Figure 134: Result Statistics for Clock Jitter

Source – Over/Undershoot V-H (Voltage-High)

This test allows you to confirm that the differential TMDS signals do not have overshoot or undershoot beyond that allowed by the specified limits.

You will need one supported oscilloscope, one differential probe, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-DI fixture.

1. On the menu bar, click **Tests > Select > Source**.
2. In the clock-data tests pane, select the **Over/Undershoot V-H** check box.

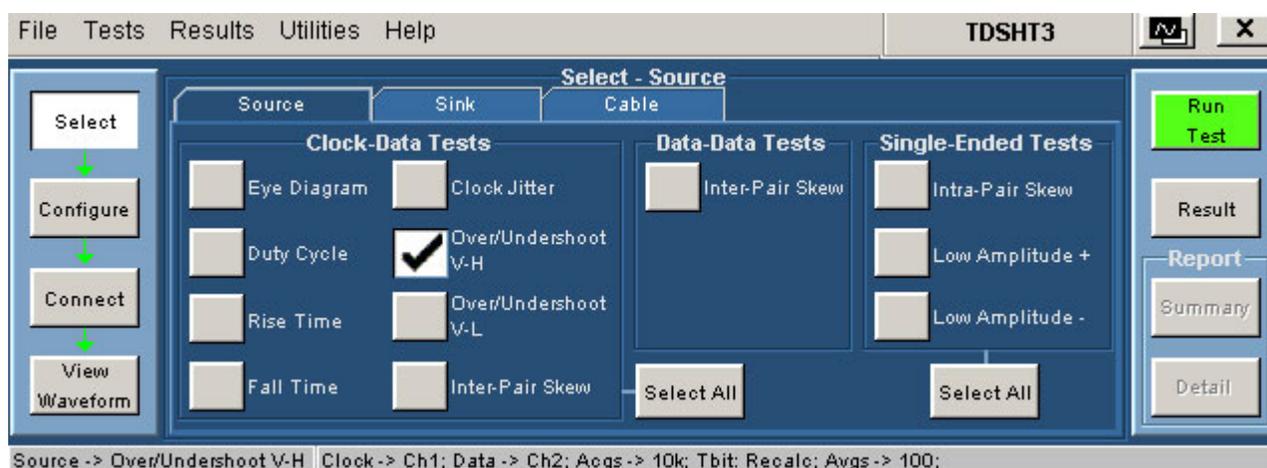


Figure 135: Select Source with Over/Undershoot V-H test selected

3. To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

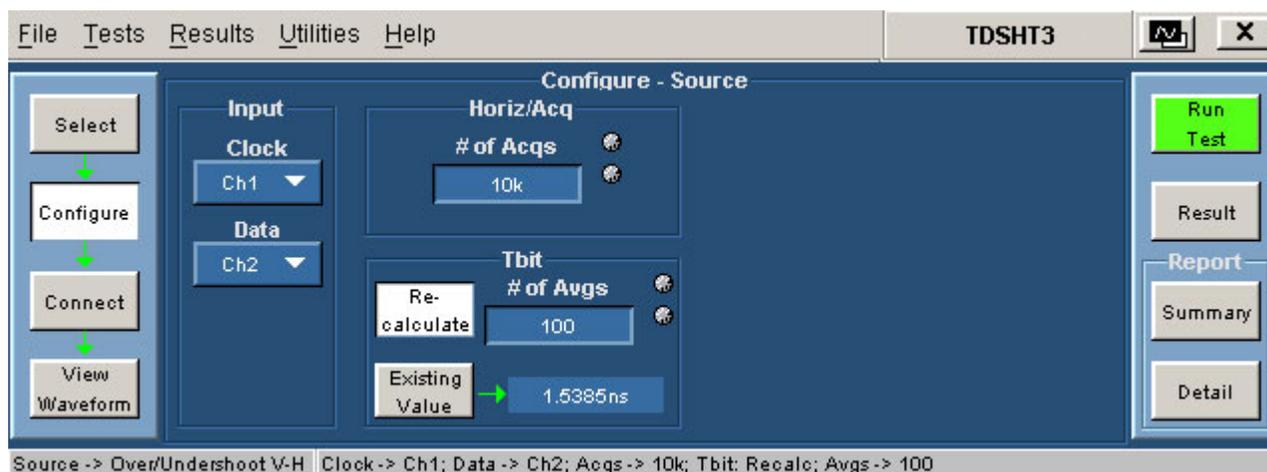


Figure 136: Configure Source for Over/Undershoot V-H

- In the input pane, you have the following options:

Table 58: Input options for Over/Undershoot V-H

| Configure Parameter | Description |
|---------------------|--|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, Ch4, and Not Conn. |
| Data | Data indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, Ch4, and Not Conn. |

- In the Horiz/Acq pane, you have the following option:

Table 59: Horiz/Acq options for Over/Undershoot V-H

| Configure Parameter | Description |
|---------------------|--|
| # of Acqs | In the # of Acqs box, enter the desired number of acquisitions that are required for the test. The default value is 10 K. |

- In the tbit pane, you have the following options:

Table 60: Tbit options for Over/Undershoot V-H

| Configure Parameter | Description |
|---------------------|--|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

- To connect the DUT, click **Tests > Connect**.



Figure 137: Connect pane for Over/Undershoot V-H

- Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections.

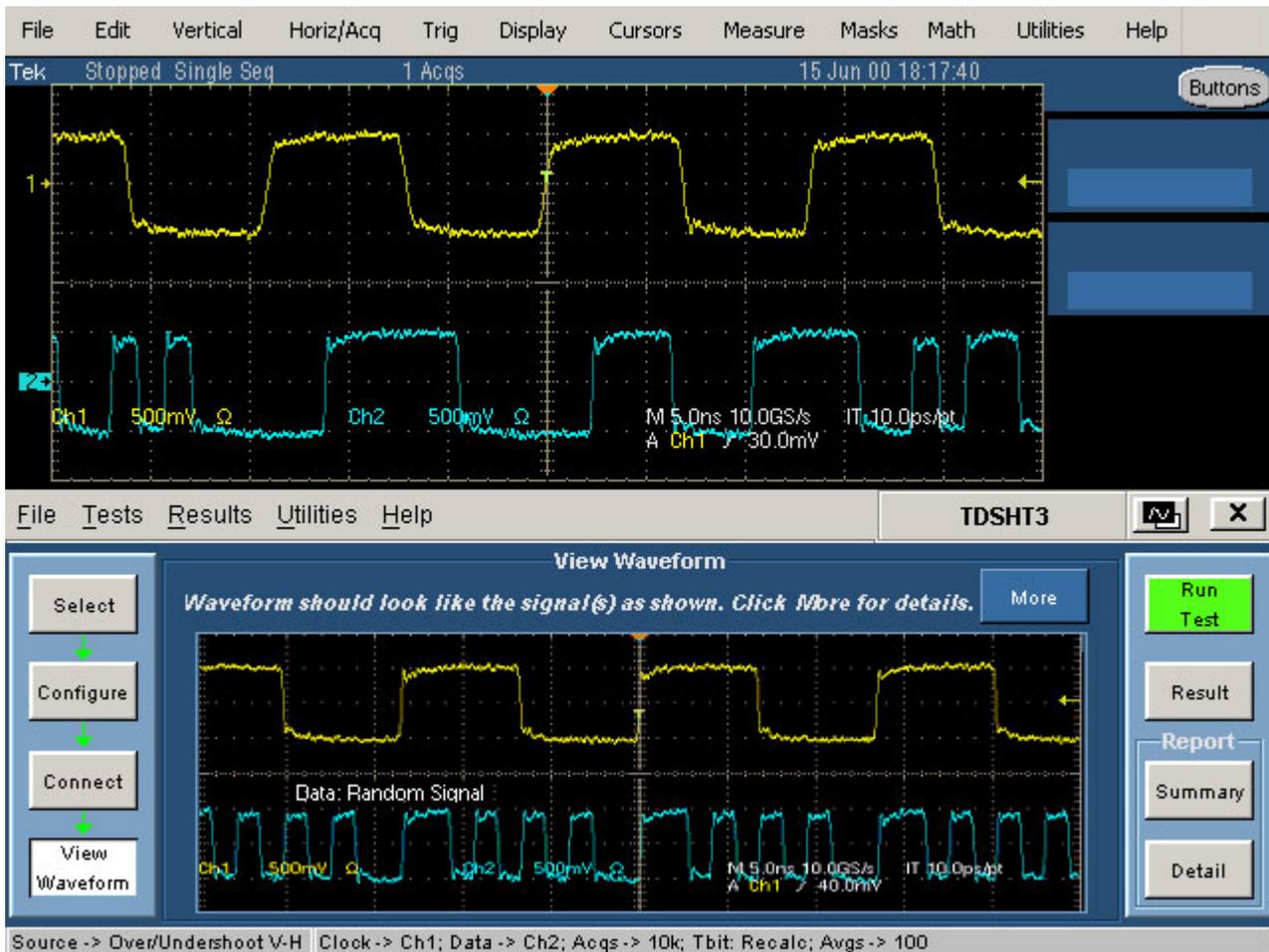


Figure 138: Waveform of Over/Undershoot V-H

9. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

- The software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

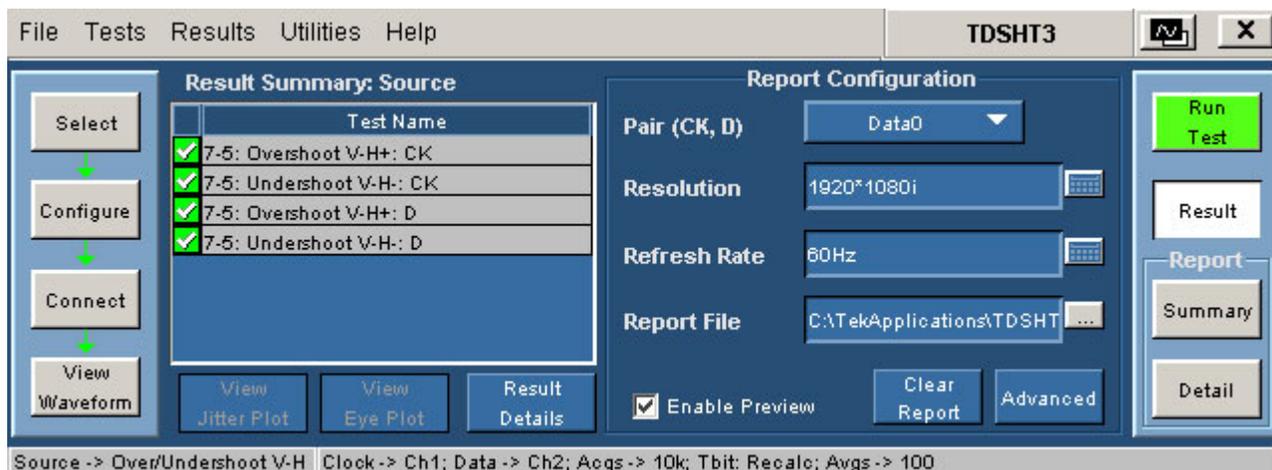


Figure 139: Result for Over/Undershoot V-H

Table 61: Result for Over/Undershoot V-H

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

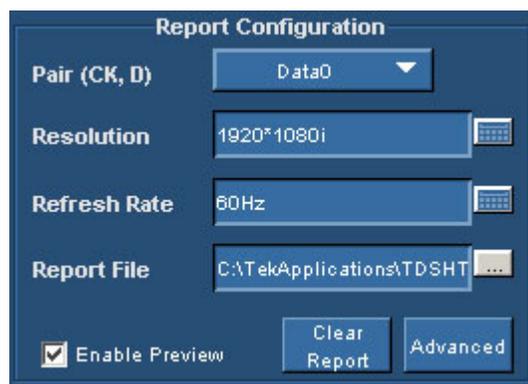


Figure 140: Report Configuration for Over/Undershoot V-H

In the report configuration pane, you can configure the following parameters:

Table 62: Report Configuration options for Over/Undershoot V-H

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

11. In the result summary pane, click **Result Details** to display the details of the result.

| Test Name | Spec Range | Meas Value | Result | Remarks/Comments |
|-------------------------|---------------------|------------|--------|---|
| 7-5: Overshoot V-H+: CK | Overshoot < 15.0%; | 2.85% | Pass | Tbit = 1.9999ns; Vh - Vl = 685.00mV; Margin = 12.15%; |
| 7-5: Undershoot V-H: CK | Undershoot < 25.0%; | 3.8% | Pass | Tbit = 1.9999ns; Vh - Vl = 685.00mV; Margin = 21.2%; |
| 7-5: Overshoot V-H+: D | Overshoot < 15.0%; | 2.27% | Pass | Tbit = 1.9999ns; Vh - Vl = 510.60mV; Margin = 12.73%; |
| 7-5: Undershoot V-H: D | Undershoot < 25.0%; | 6.5% | Pass | Tbit = 1.9999ns; Vh - Vl = 510.60mV; Margin = 18.5%; |

Figure 141: Result Details for Over/Undershoot V-H

Table 63: Result Details for Over/Undershoot V-H

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |

Source – Over/Undershoot V-L (Voltage-Low)

This test allows you to confirm that the differential TMDS signals do not have overshoot or undershoot beyond that allowed by the specified limits.

You will need one supported oscilloscope, one differential probe, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-DI fixture.

1. On the menu bar, click **Tests > Select > Source**.

- In the clock-data tests pane, select the **Over/Undershoot V-L** check box.

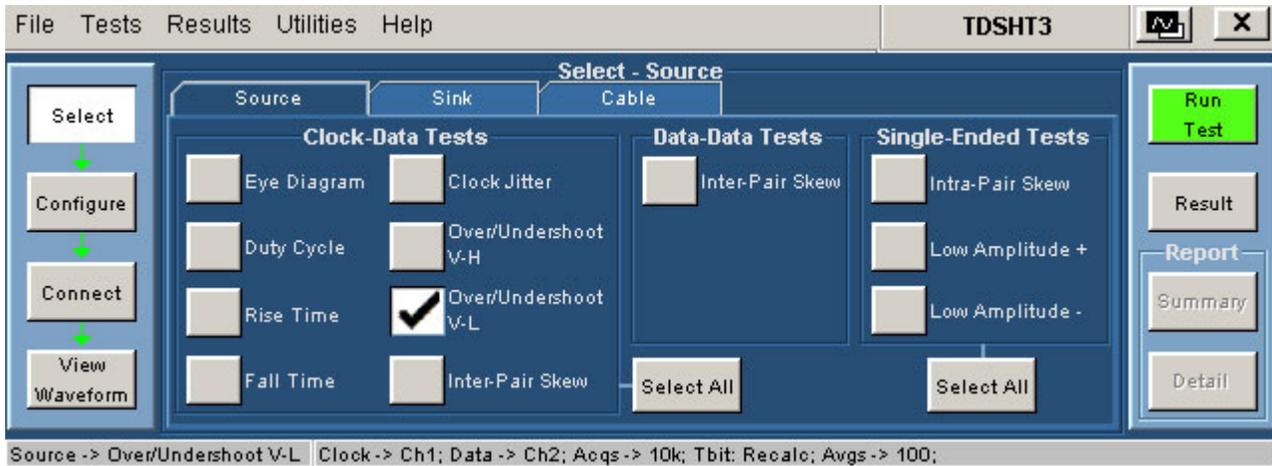


Figure 142: Select Source for Over/Undershoot V-L

- To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

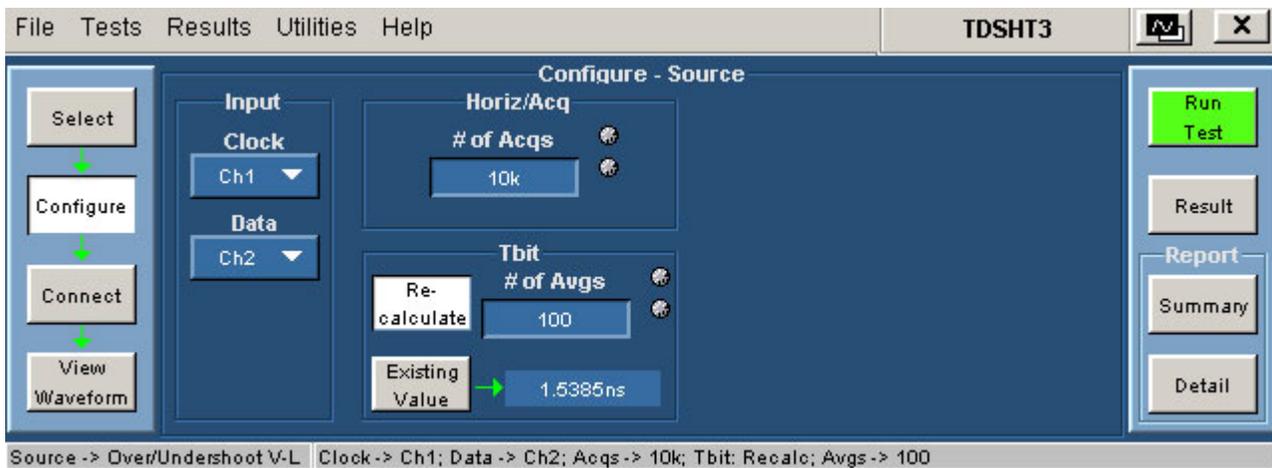


Figure 143: Configure Source for Over/Undershoot V-L

4. In the Input pane, you have the following options:

Table 64: Input options for Over/Undershoot V-L

| Configure Parameter | Description |
|---------------------|--|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, Ch4, and Not Conn. |
| Data | Data indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, Ch4, and Not Conn. |

5. In the Horiz/Acq pane, you have the following option:

Table 65: Horiz/Acq options for Over/Undershoot V-L

| Configure Parameter | Description |
|---------------------|--|
| # of Acqs | In the # of Acqs box, enter the desired number of acquisitions that are required for the test. The default value is 10 K. |

6. In the Tbit pane, you have the following options:

Table 66: Tbit options for Over/Undershoot V-L

| Configure Parameter | Description |
|---------------------|---|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

7. To connect the DUT, click **Tests > Connect**.

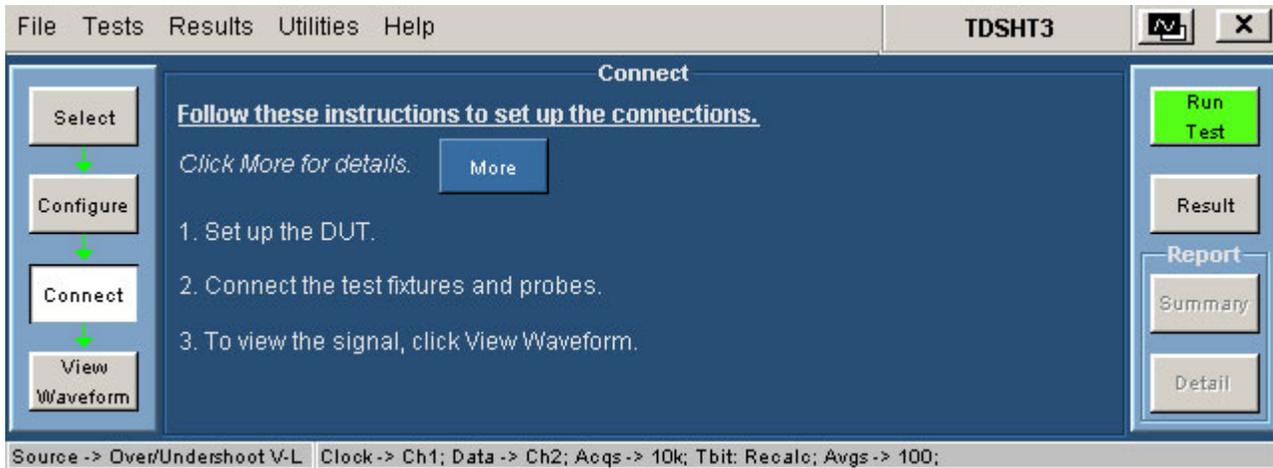


Figure 144: Connect pane for Over/Undershoot V-L

8. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections.

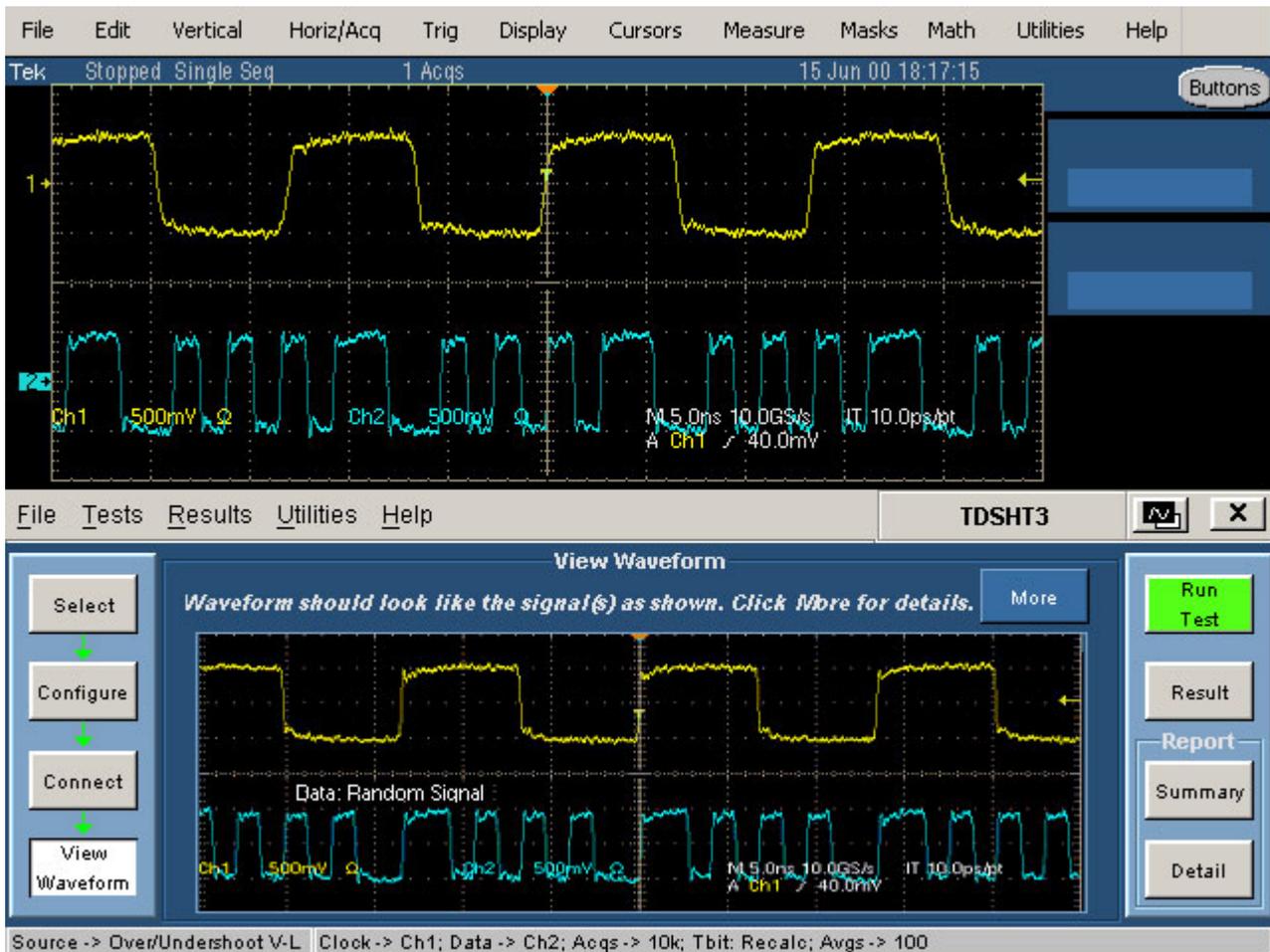


Figure 145: Waveform of Over/Undershoot V-L

9. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

- The software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

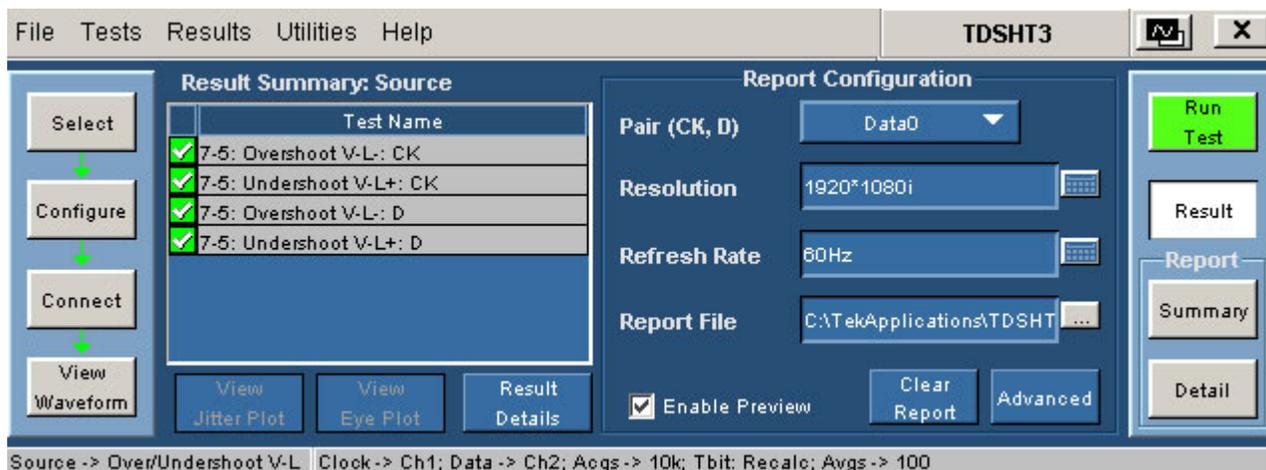


Figure 146: Result for Over/Undershoot V-L

Table 67: Result for Over/Undershoot V-L

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

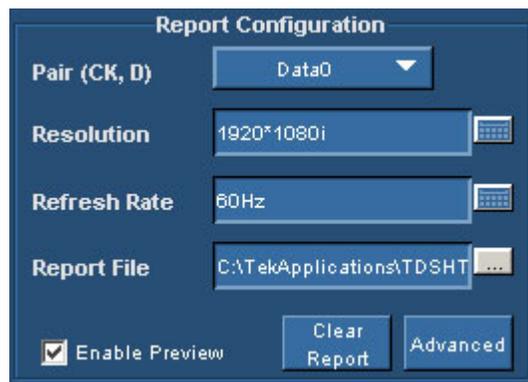


Figure 147: Report Configuration for Over/Undershoot V-L

In the report configuration pane, you can configure the following parameters:

Table 68: Report Configuration options for Over/Undershoot V-L

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

11. In the result summary pane, click **Result Details** to display the details of the result.

| Test Name | Spec Range | Meas Value | Result | Remarks/Comments |
|-------------------------|---------------------|------------|--------|---|
| 7-5: Overshoot V-L: CK | Overshoot < 15.0%; | 3.22% | Pass | Tbit = 2.0000ns; Vh - Vl = 685.00mV; Margin = 11.78%; |
| 7-5: Undershoot V-L: CK | Undershoot < 25.0%; | 5.03% | Pass | Tbit = 2.0000ns; Vh - Vl = 685.00mV; Margin = 19.97%; |
| 7-5: Overshoot V-L: D | Overshoot < 15.0%; | 2.15% | Pass | Tbit = 2.0000ns; Vh - Vl = 512.40mV; Margin = 12.85%; |
| 7-5: Undershoot V-L: D | Undershoot < 25.0%; | 4.91% | Pass | Tbit = 2.0000ns; Vh - Vl = 512.40mV; Margin = 20.09%; |

Buttons: Close, View Jitter Plot, View Eye Plot, Result Statistics

Figure 148: Result Details for Over/Undershoot V-L

Table 69: Result Details for Over/Undershoot V-L

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |

Source – Inter-Pair Skew for Clock-Data Tests

This test allows you to confirm that any skew between the differential pairs in the TMDS portion of the HDMI link does not exceed the limits in the specification.

You will need one supported oscilloscope, two differential probes, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-DI fixture.

Note: Deskew is recommended before you conduct any skew test.

1. On the menu bar, click **Tests > Select > Source**.

- In the clock-data tests pane, select the **Inter-Pair Skew** check box.

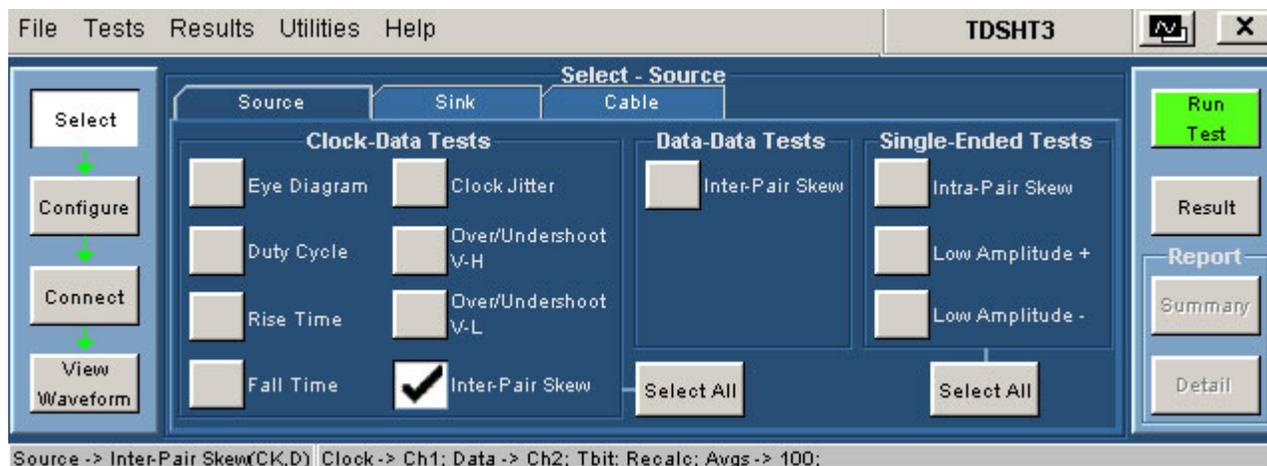


Figure 149: Select Source with Inter-pair Skew (Clock-Data) test selected

- To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

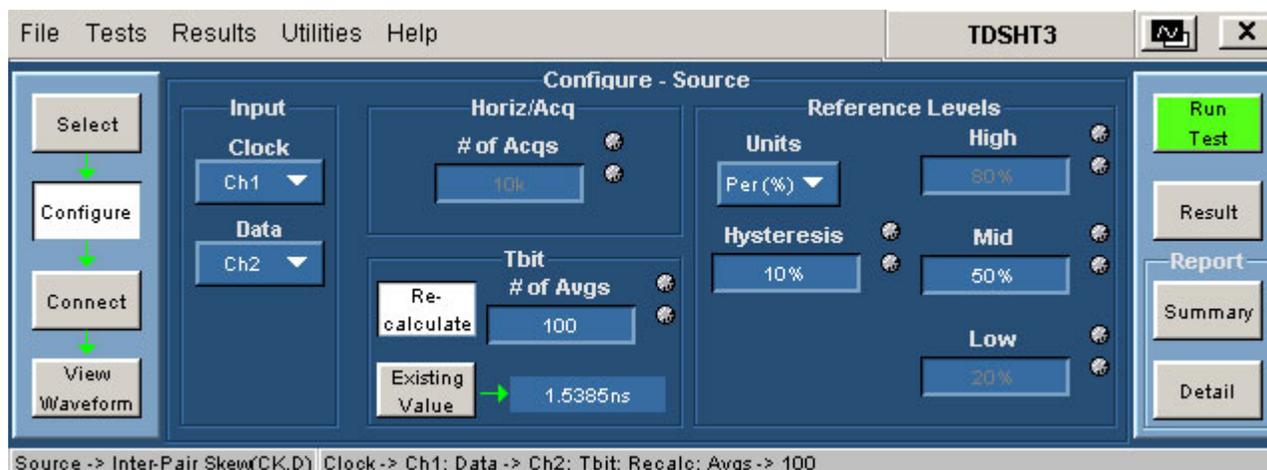


Figure 150: Configure Source for Inter-pair Skew (Clock-Data)

- In the Input pane, you have the following options:

Table 70: Input options for Inter-pair Skew (Clock-Data)

| Configure Parameter | Description |
|---------------------|--|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, and Ch4. |
| Data | Data indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

- In the Tbit pane, you have the following options:

Table 71: Tbit options for Inter-pair Skew (Clock-Data)

| Configure Parameter | Description |
|---------------------|---|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

- In the reference levels pane, you have the following options:

Table 72: Reference Levels options for Inter-pair Skew (Clock-Data)

| Configure Parameter | Description |
|---------------------|--|
| Units | The Units list allows you to set the reference level units to either Per (%) or Abs. Per (%) indicates that the reference levels are a percentage of the Vswing value. Abs indicates that the reference levels are absolute voltage values. |
| Hysteresis | In the Hysteresis box, enter the desired hysteresis percent value. The default value is 10 percent. |
| Mid | In the Mid box, enter the desired mid reference voltage value. The default value is 50 percent. |

- To connect the DUT, click **Tests > Connect**. Click **Deskew** to deskew the test setup.

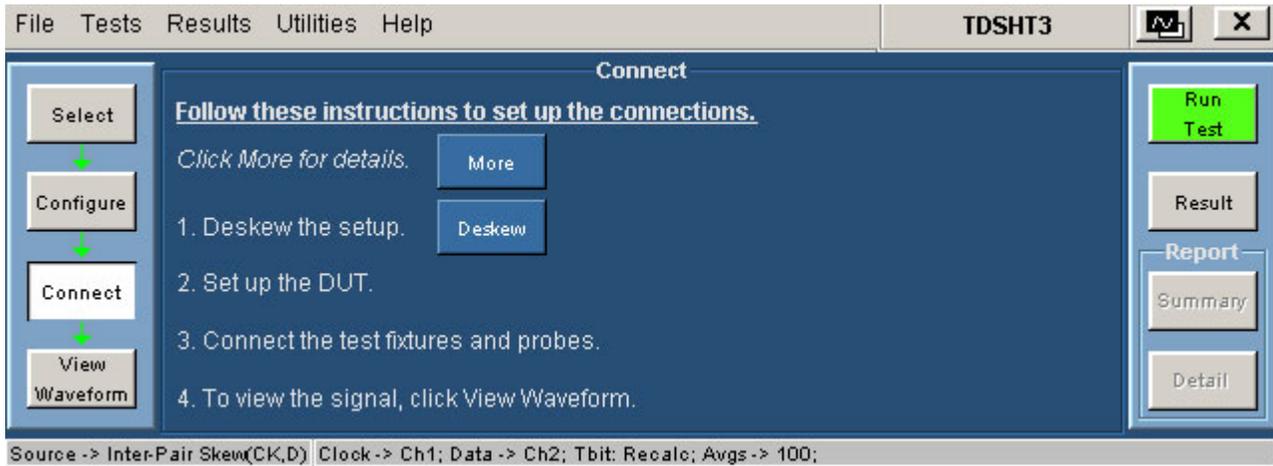


Figure 151: Connect pane for Inter-pair Skew (Clock-Data)

8. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections.

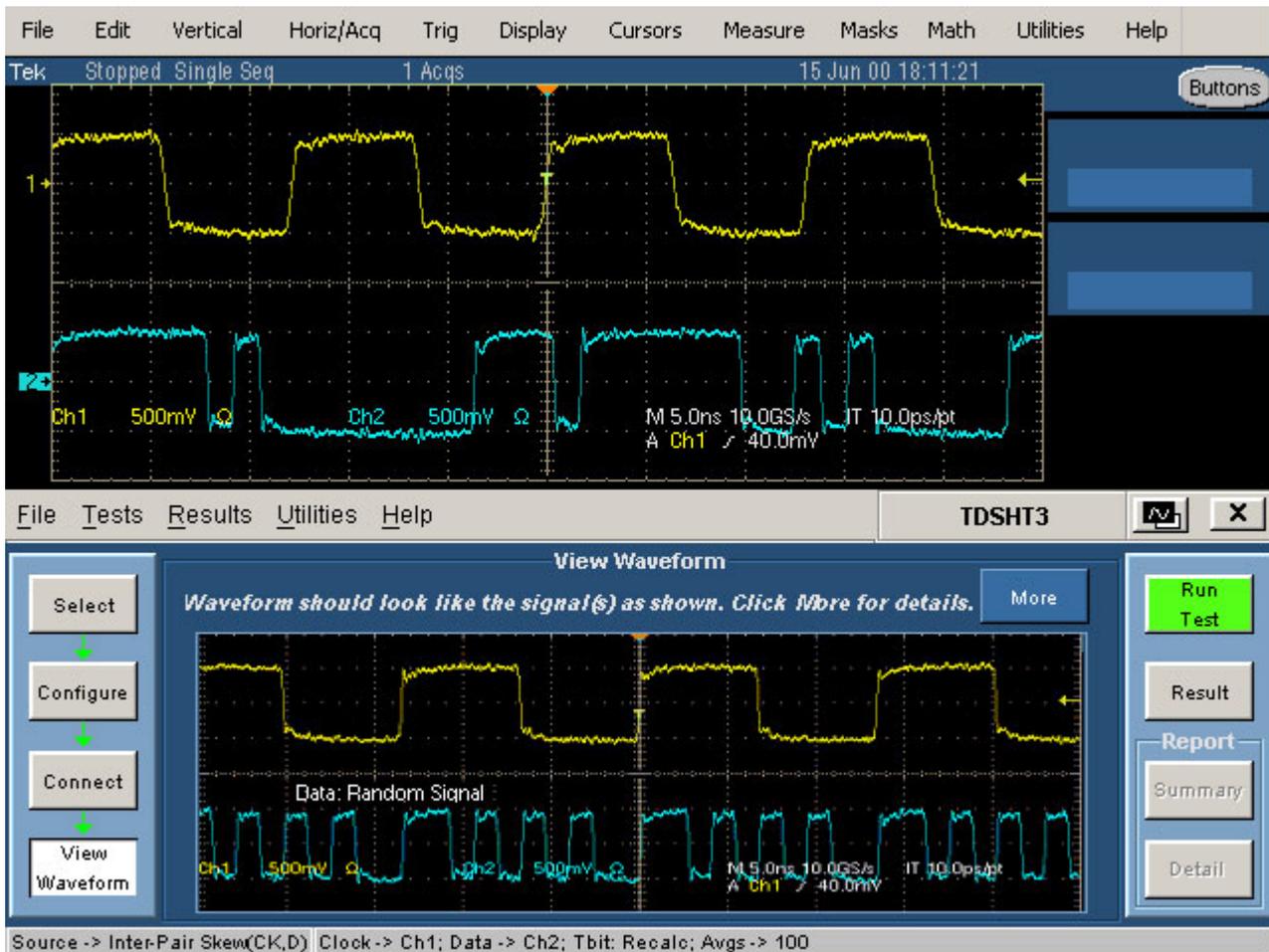


Figure 152: Waveform of Inter-pair Skew (Clock-Data)

9. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

- The software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

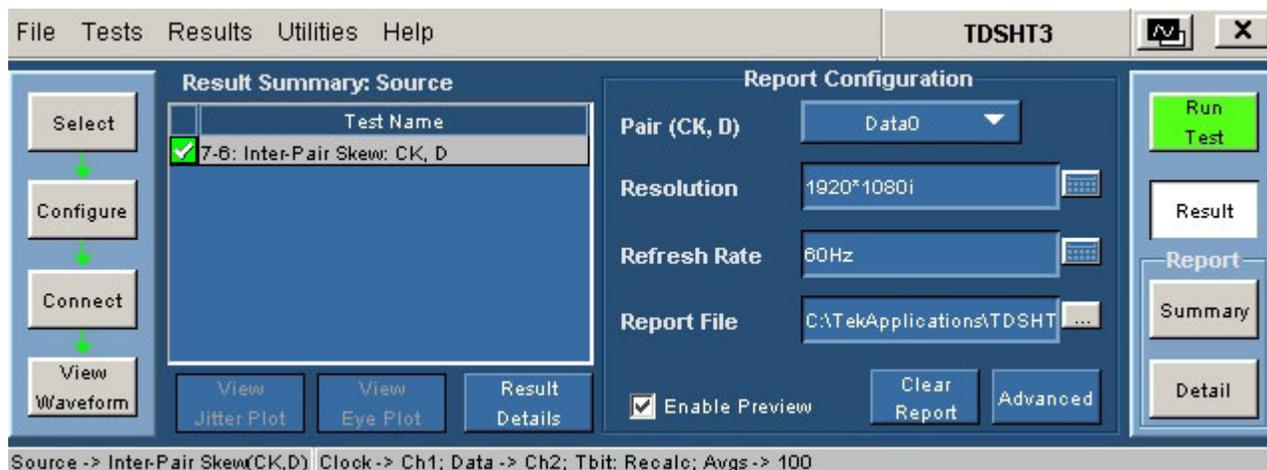


Figure 153: Result for Inter-pair Skew (Clock-Data)

Table 73: Result for Inter-pair Skew (Clock-Data)

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

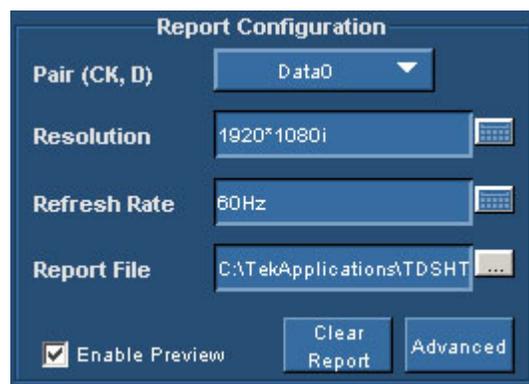


Figure 154: Report Configuration for Inter-pair Skew (Clock-Data)

In the report configuration pane, you can configure the following parameters:

Table 74: Report Configuration options for Inter-pair Skew (Clock-Data)

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

11. In the result summary pane, click **Result Details** to display the details of the result.



Figure 155: Result Details for Inter-pair Skew (Clock-Data)

Table 75: Result Details for Inter-pair Skew (Clock-Data)

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |

Source – Clock-Data Tests Select All

This option enables you to run the eye diagram, duty cycle, rise time, fall time, clock jitter, over/undershoot v-h, over/undershoot v-l, and inter-pair skew test simultaneously.

You will need one supported oscilloscope, two differential probes, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-DI fixture.

1. On the menu bar, click **Tests > Select > Source**.

- In the clock-data tests pane, click **Select All**.

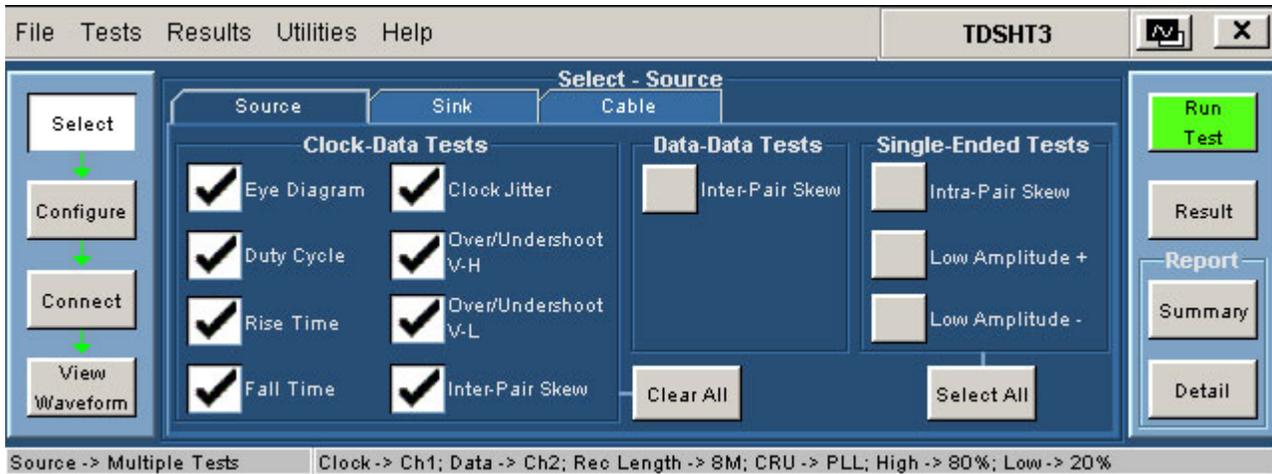


Figure 156: Select Source with Multiple tests selected

- To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

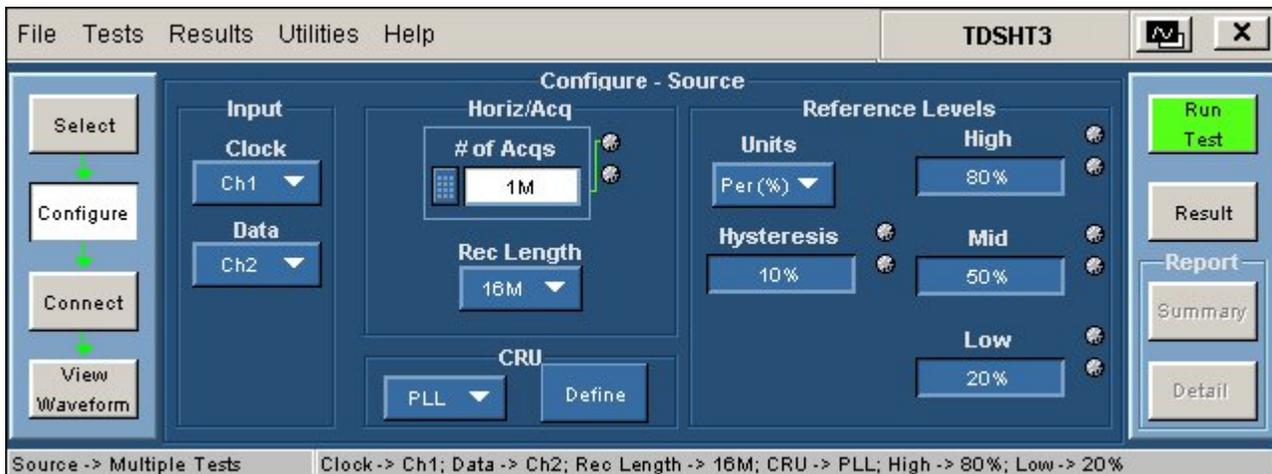


Figure 157: Configure Source for Source Multiple Tests selected

4. In the input pane, you have the following options:

Table 76: Input options for Source Multiple Tests

| Configure Parameter | Description |
|---------------------|--|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, and Ch4. |
| Data | Data indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

5. In the horiz/acq pane, you have the following options:

Table 77: Horiz/acq options for Source Multiple Tests

| Configure Parameter | Description |
|---------------------|--|
| # of Acqs | The # of Acqs box displays the number of acquisitions that are required for the test. The default value is 10k. |
| Record Length | In the Rec Length box, enter the desired record length value for all the selected tests. |

6. In the CRU pane, you have the following option:

Table 78: CRU options for Source Multiple Tests

| Configure Parameter | Description |
|---------------------|---|
| CRU | The CRU list allows you to configure the CRU. The available choices are PLL, Raw, and Ideal. The default value is first order PLL and is used for compliance testing. Raw and Ideal are used for analysis. |
| Define | The Define is available only when PLL is selected. |

7. In the reference levels pane, you have the following options:

Table 79: Reference Levels options for Source Multiple Tests

| Configure Parameter | Description |
|---------------------|--|
| Units | The Units list allows you to set the reference level units to either Per (%) or Abs. Per (%) indicates that the reference levels are a percentage of the Vswing value. Abs indicates that the reference levels are absolute voltage values. |
| Hysteresis | In the Hysteresis box, enter the desired hysteresis percent value. The default value is 10 percent. The hysteresis range is between 2 percent and 10 percent. |
| High | The High box displays the high reference voltage value. The default value is 80 percent. |
| Mid | In the Mid box, enter the desired mid reference voltage value. The default value is 50 percent. |
| Low | The Low box displays the low reference voltage value. The default value is 20 percent. |

8. To connect the DUT, click **Tests > Connect**.

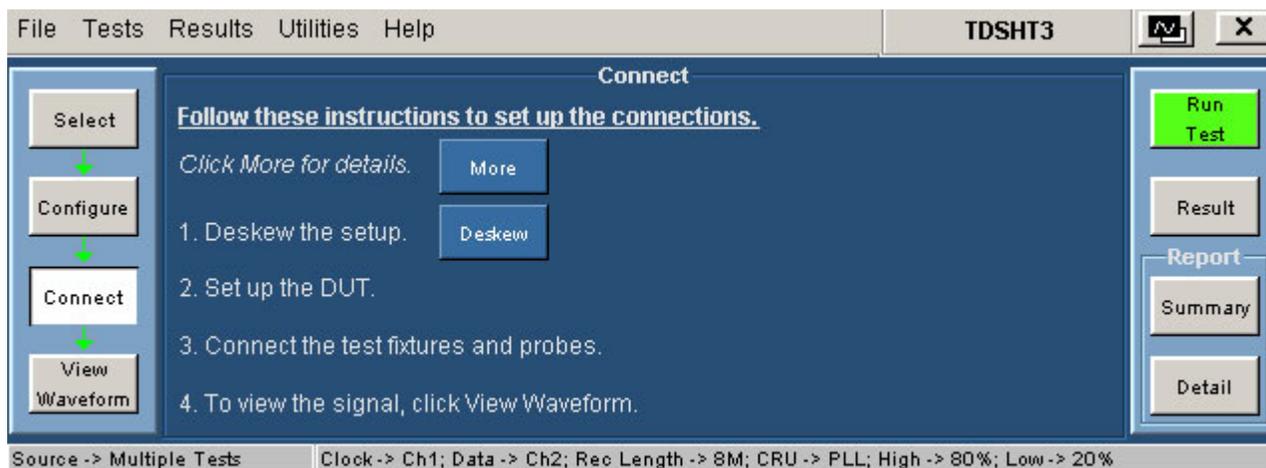


Figure 158: Connect pane for Source Multiple Tests selected

9. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections.

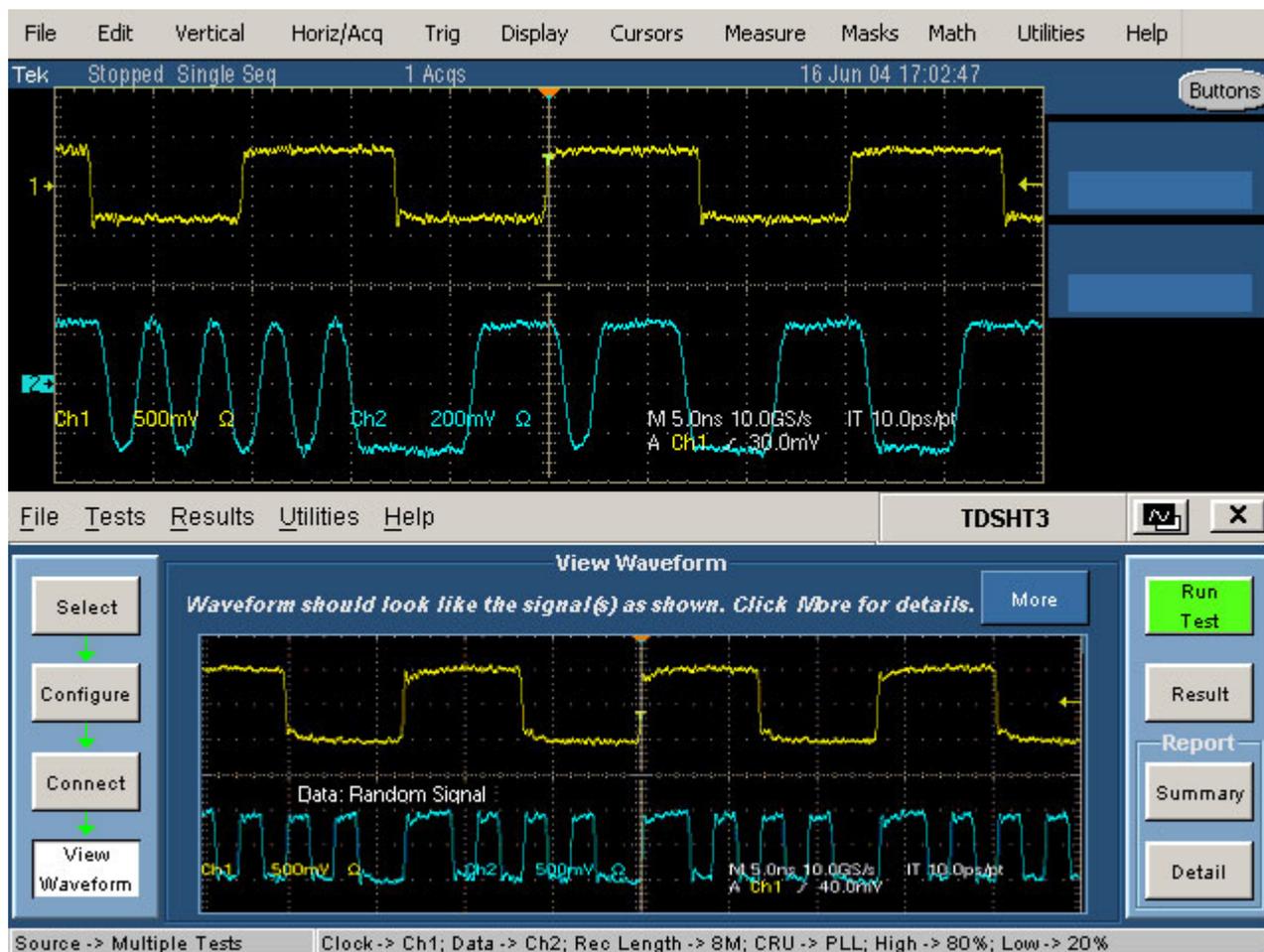


Figure 159: Waveform of Source Multiple Tests selected

10. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

11. If you have run the tests successfully, the software makes **Result** available automatically and displays the eye diagram plot and the clock jitter plot. For more information on the plots, refer to the online help. You can also view both the result summary of the test and the report configuration in the result pane as shown in the following diagram:

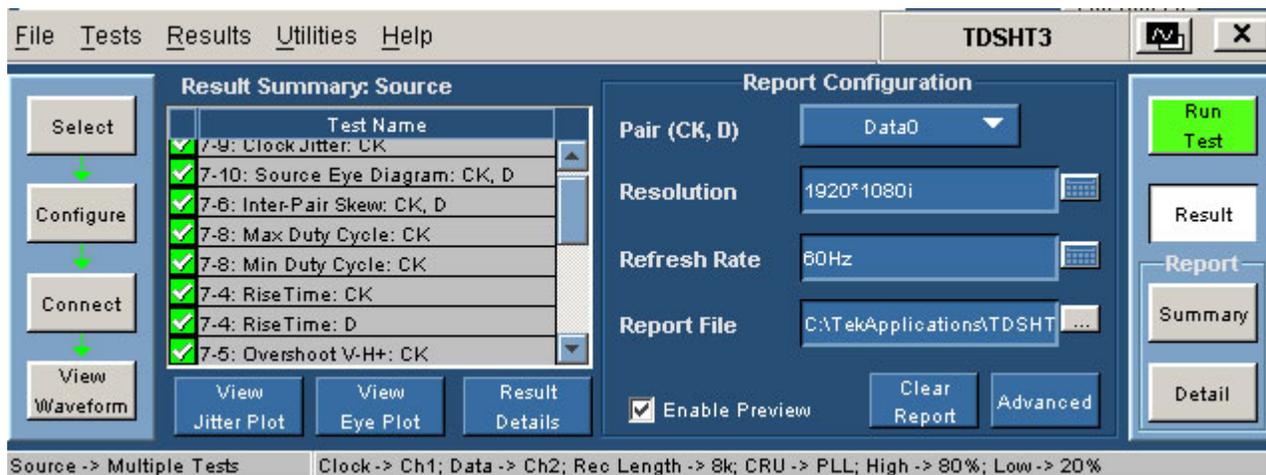


Figure 160: Result for Source Multiple Tests selected

Table 80: Result for Source Multiple Tests selected

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal names - CK (Clock), D (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| View Jitter Plot | Click View Jitter Plot to view the jitter plot for the clock jitter test. |
| View Eye Plot | Click View Eye Plot to view the eye plot for the eye diagram test. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

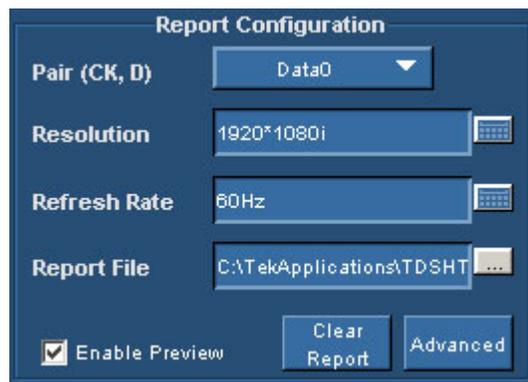


Figure 161: Report Configuration pane for Source Multiple Tests

In the report configuration pane, you can configure the following parameters:

Table 81: Report Configuration options for Source Multiple Tests

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

12. In the result summary pane, click **Result Details** to display the details of the result.



Figure 162: Result Details for Source Multiple Tests

Table 82: Result Details for Source Multiple Tests

| Option | Description |
|-------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |
| View Jitter Plot | Click View Jitter Plot to display the jitter plot for the clock jitter test. |
| View Eye Plot | Click View Eye Plot to display the eye plot for the eye diagram test. |
| Result Statistics | Click Result Statistics to display statistics based on the tests. |

- In the **Result Details** dialog box, click **Result Statistics** to display statistics based on the tests.

| Test Name | Population | Min | Max | Mean | Std Dev | Pk-Pk |
|-------------------------------------|------------|-----------|----------|-----------|----------|----------|
| 7-9: Clock Jitter Tx Clock TIE: CK | 52.000 | -21.13... | 12.480ps | 0.00s | 7.9029ps | 33.616ps |
| 7-9: Clock Jitter Recovered Cloc... | 52.000 | -9.224... | 5.1142ps | -3.755... | 3.5109ps | 14.339ps |
| 7-10: Source Eye Diagram Tx Cl... | 52.000 | -21.13... | 12.480ps | 0.00s | 7.9029ps | 33.616ps |
| 7-10: Source Eye Diagram Reco... | 52.000 | -9.224... | 5.1142ps | -3.755... | 3.5109ps | 14.339ps |
| 7-4: Rise Time: CK | 661.95k | 127.15ps | 128.43ps | 128.00ps | 387.37fs | 1.2843ps |
| 7-4: Rise Time: D | 880.54k | 430.29ps | 432.95ps | 430.95ps | 562.07fs | 2.6550ps |
| 7-4: Fall Time: CK | 662.78k | 104.12ps | 106.02ps | 104.39ps | 418.69fs | 1.9065ps |
| 7-4: Fall Time: D | 896.58k | 434.74ps | 438.05ps | 435.38ps | 704.15fs | 3.3080ps |

Figure 163: Result Details for Source Multiple Tests

The software calculates statistics for each selected test, and logs the statistics on a cycle-by-cycle basis in a large waveform. The standard statistics are for the Maximum, Minimum, Mean, Standard Deviation, and Population.

Table 83: Result Details for Source Multiple Tests

| Option | Description |
|------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal names - CK (Clock), D (Data). |
| Population | The software calculates this statistic by using the following equation: Population (X) = N |
| Min | The software calculates this statistic by using the following equation: Min (X) = Lowest value of X |
| Max | The software calculates this statistic by using the following equation: Max (X) = Highest value of X |
| Mean | The software calculates this statistic by using the following equation: $Mean (X) = \bar{X} = \frac{1}{N} \sum_{n=1}^N X_n$ |
| Std Dev | The software calculates this statistic by using the following equation: $Standard Deviation (X) = \sigma_x = \sqrt{\frac{1}{(N-1)} \sum_{n=1}^N (X_n - \bar{X})^2}$ |

Table 83: Result Details for Source Multiple Tests (Contd.)

| Option | Description |
|--------|--|
| Pk-Pk | The software calculates this statistic by using the following equation: $X_{ppn} = \text{Max}(X) - \text{Min}(X)$ |
| Close | Click Close to quit the Result Statistics dialog box. |

Note: Perform similar steps as mentioned in this procedure to test Single-Ended Select All.

Source – Inter-Pair Skew for Data-Data Tests

This test allows you to confirm that any skew between the differential pairs in the TMDS portion of the HDMI link does not exceed the limits in the specification.

You will need one supported oscilloscope, two differential probes, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-DI fixture.

Note: Deskew is recommended before you conduct any skew test.

1. On the menu bar, click **Tests > Select > Source**.
2. In the data-data tests pane, select the **Inter-Pair Skew** check box.

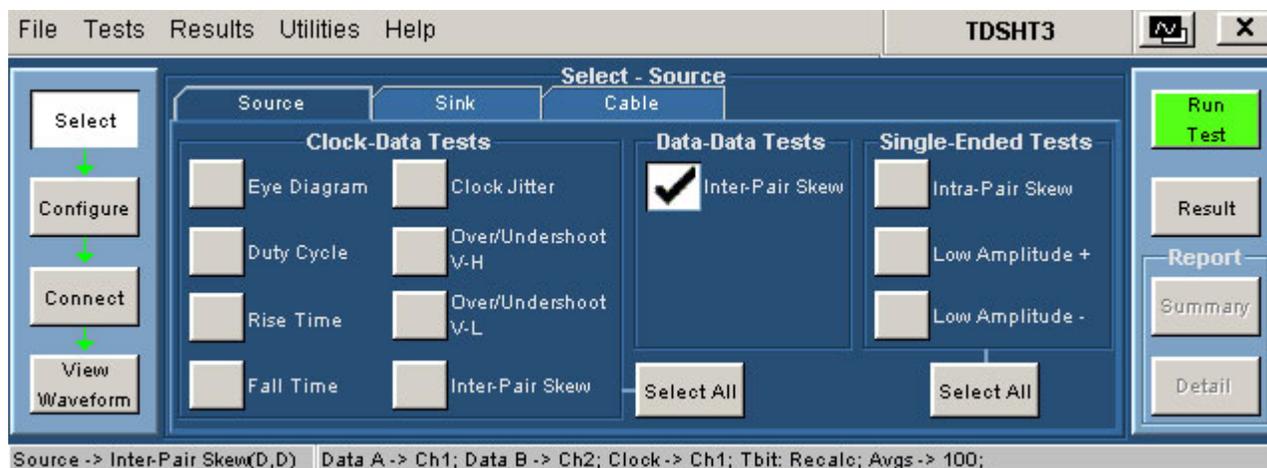


Figure 164: Select Source with Inter-Pair Skew (Data-Data) test selected

- To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

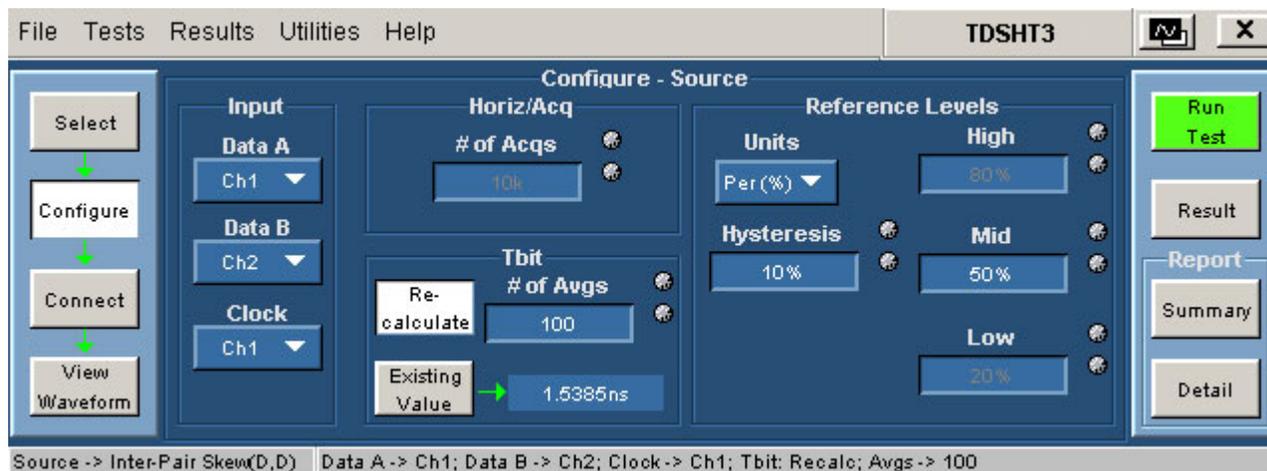


Figure 165: Configure Source for Inter-Pair Skew (Data-Data)

- In the Input pane, you have the following options:

Table 84: Input options for Inter-Pair Skew (Data-Data)

| Configure Parameter | Description |
|---------------------|--|
| Data A | Data A indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, and Ch4. |
| Data B | Data B indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, and Ch4. |
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

5. In the Tbit pane, you have the following options:

Table 85: Tbit options for Inter-Pair Skew (Data-Data)

| Configure Parameter | Description |
|---------------------|---|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

6. In the reference levels pane, you have the following options:

Table 86: Reference Levels options for Inter-Pair Skew (Data-Data)

| Configure Parameter | Description |
|---------------------|--|
| Units | The Units list allows you to set the reference level units to either Per (%) or Abs. Per (%) indicates that the reference levels are a percentage of the Vswing value. Abs indicates that the reference levels are absolute voltage values. |
| Hysteresis | In the Hysteresis box, enter the desired hysteresis percent value. The default value is 10 percent. |
| Mid | In the Mid box, enter the desired mid reference voltage value. The default value is 50 percent. |

7. To connect the DUT, click **Tests > Connect**.

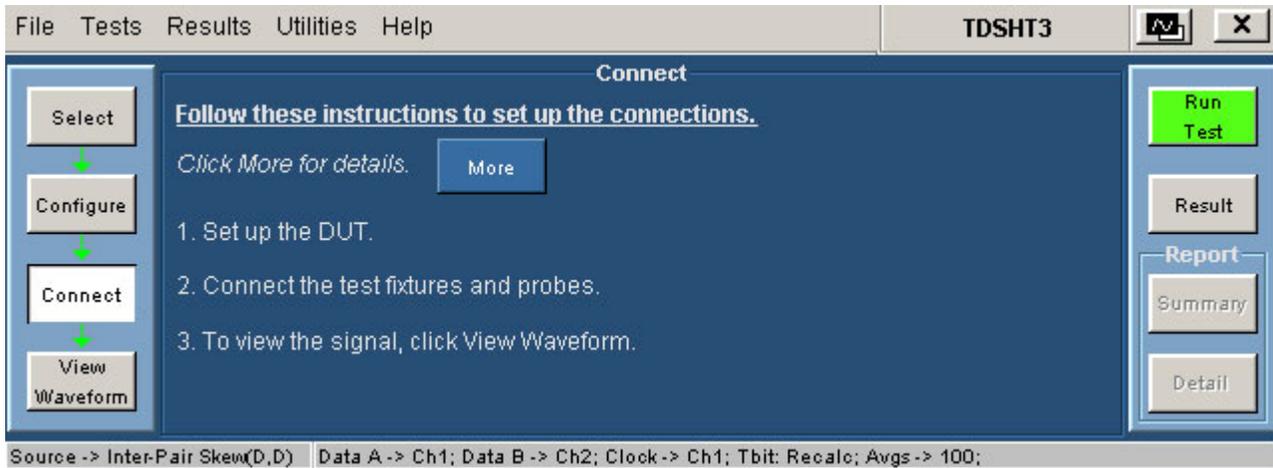


Figure 166: Connect pane for Inter-Pair Skew (Data-Data)

8. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections. The waveform shown here is for the re-calculate Tbit option. Click **Run Test** to run the test. The **Confirm** dialog box appears. Click **Continue** to continue to run the test. Go to step 10.

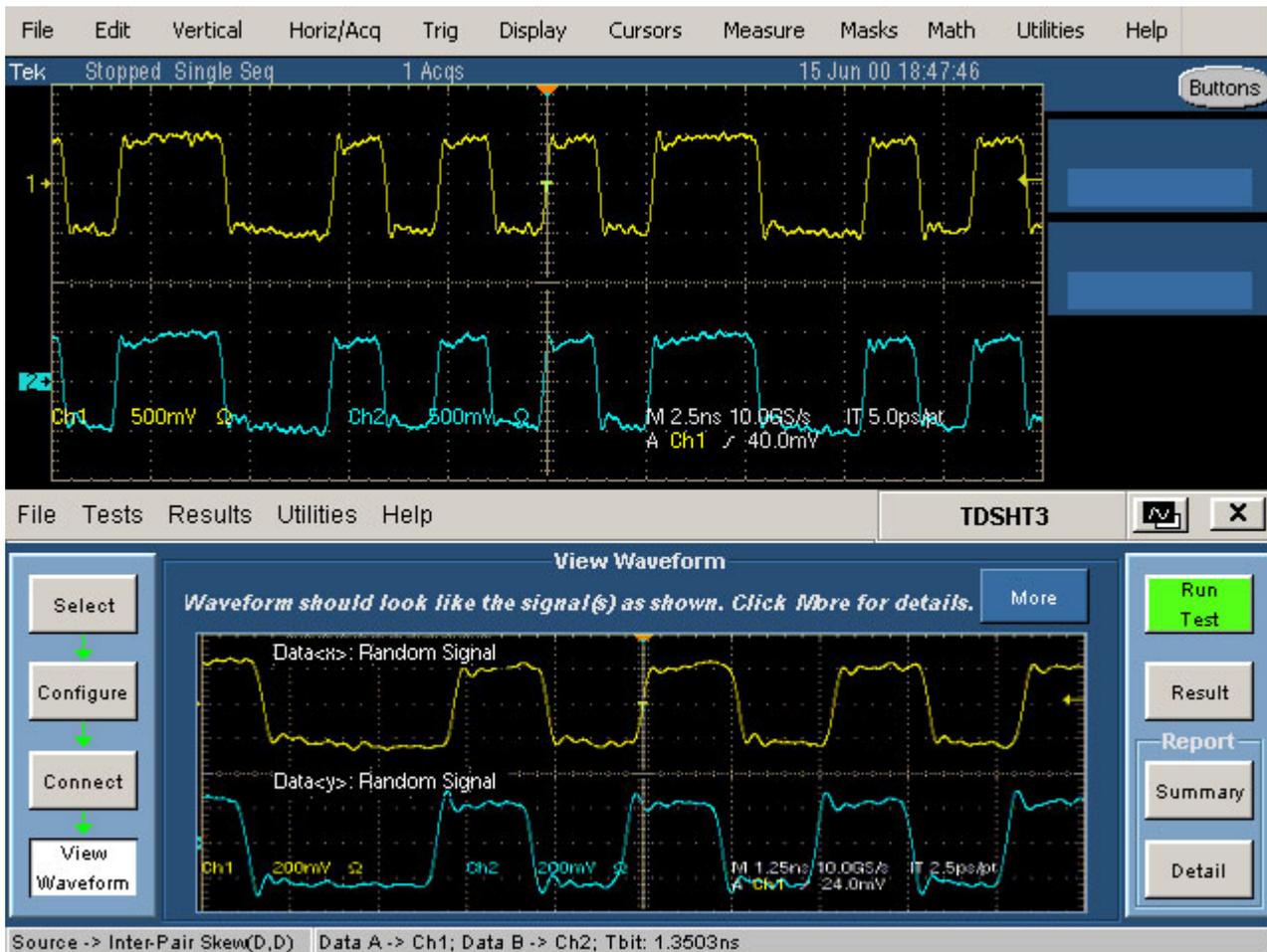


Figure 167: Waveform of Inter-Pair Skew (Data-Data)

9. If you have selected existing Tbit value, then click **View Waveform** to get a different waveform on your display. Ensure that your signal in the oscilloscope display is similar to the sample signal.
10. Click **Run Test** to run the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

- The software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

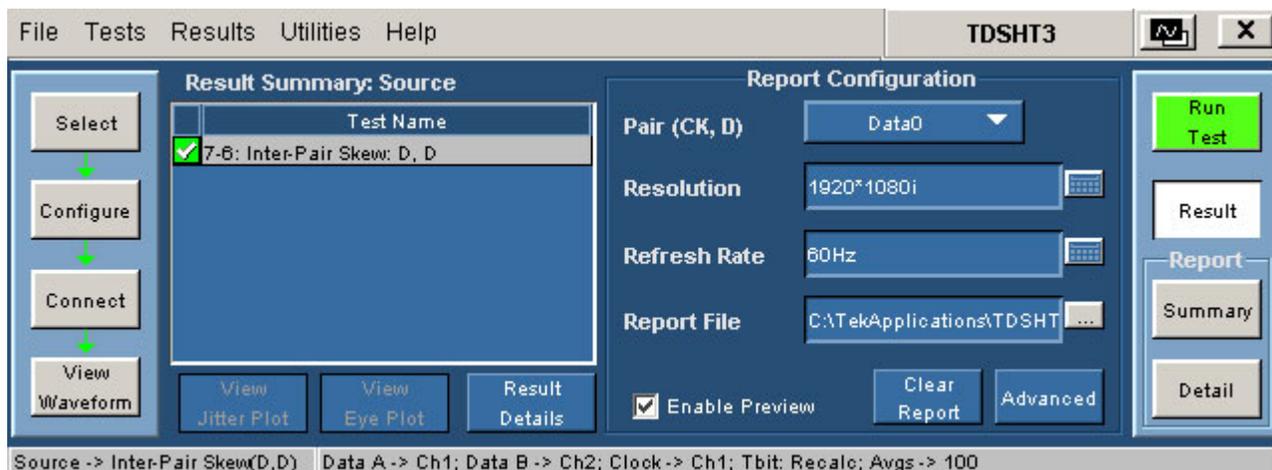


Figure 168: Result for Inter-Pair Skew (Data-Data)

Table 87: Result for Inter-Pair Skew (Data-Data Tests)

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - D (Data), D (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

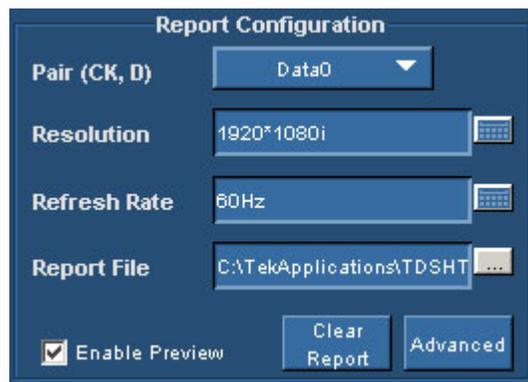


Figure 169: Report Configuration pane for Inter-Pair Skew (Data-Data)

In the report configuration pane, you can configure the following parameters:

Table 88: Report Configuration options for Inter-Pair Skew (Data-Data)

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

12. In the result summary pane, click **Result Details** to display the details of the result.



Figure 170: Result Details for Inter-Pair Skew (Data-Data)

Table 89: Result Details for Inter-Pair Skew (Data-Data)

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - D (Data), D (Data). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |

Source – Intra-Pair Skew

This test allows you to confirm that any skew within any one differential pair in the TMDS portion of the HDMI link does not exceed the limits in the specification.

You will need one supported oscilloscope, two single-ended probes, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-SE fixture.

Note: Deskew is recommended before you conduct any skew test.

1. On the menu bar, click **Tests > Select > Source**.
2. In the single-ended tests pane, select the **Intra-Pair Skew** check box.

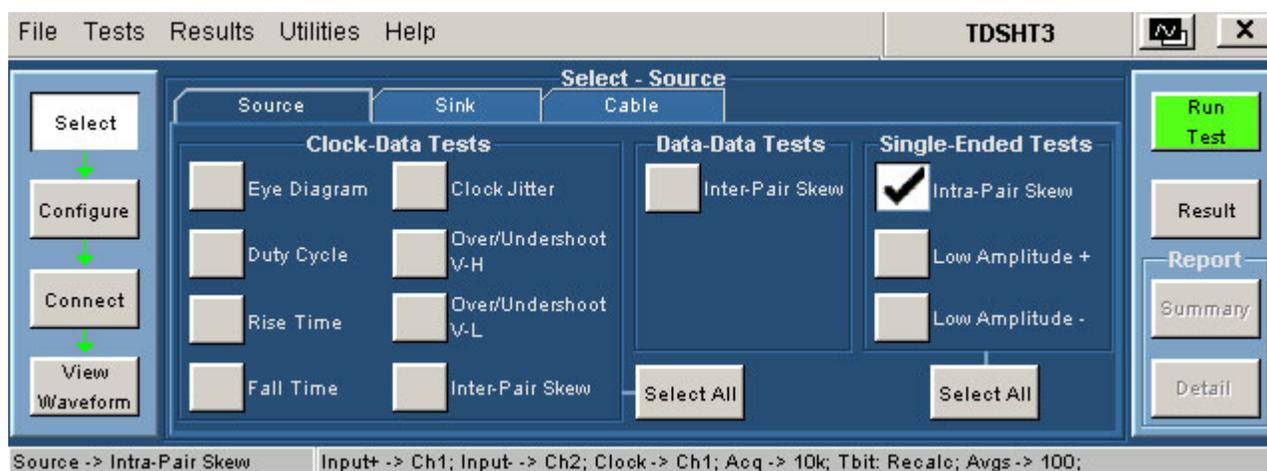


Figure 171: Select Source with Source Intra-Pair Skew test selected

3. To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

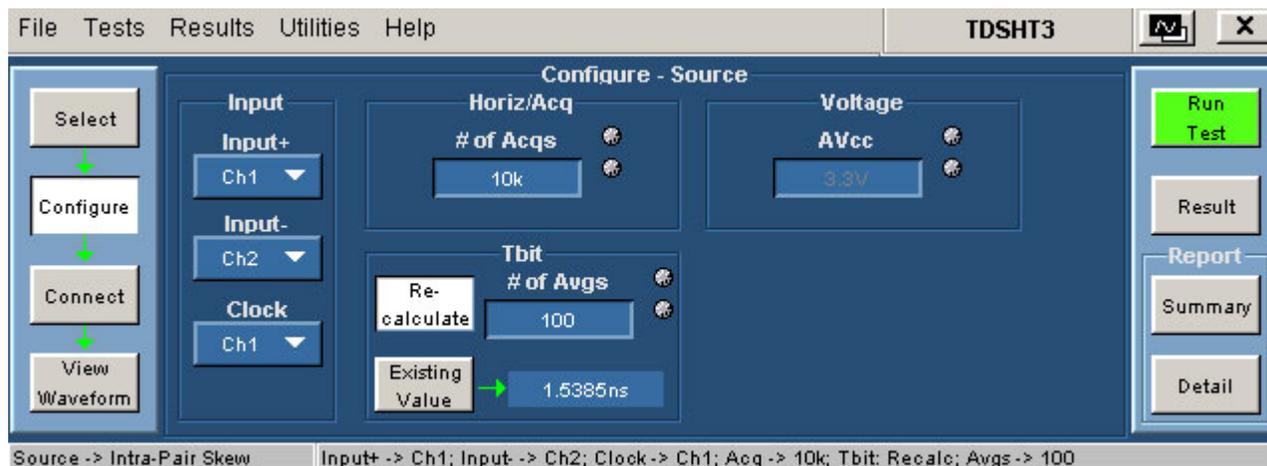


Figure 172: Configure Source for Intra-Pair Skew

- In the input pane, you have the following options:

Table 90: Input options for Source Intra-Pair Skew

| Configure Parameter | Description |
|---------------------|--|
| Input | Input+ indicates the oscilloscope channel to which you will connect the positive input. The available choices are Ch1, Ch2, Ch3, and Ch4. |
| Input | Input- indicates the oscilloscope channel to which you will connect the negative input. The available choices are Ch1, Ch2, Ch3, and Ch4. |
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

- In the horiz/acq pane, you have the following option:

Table 91: Horiz/Acq option for Source Intra-Pair Skew

| Configure Parameter | Description |
|---------------------|--|
| # of Acqs | In the # of Acqs box, enter the desired number of acquisitions that are required for the test. The default value is 10 K. |

6. In the Tbit pane, you have the following options:

Table 92: Tbit options for Source Intra-Pair Skew

| Configure Parameter | Description |
|---------------------|--|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

7. To connect the DUT, click **Tests > Connect**.

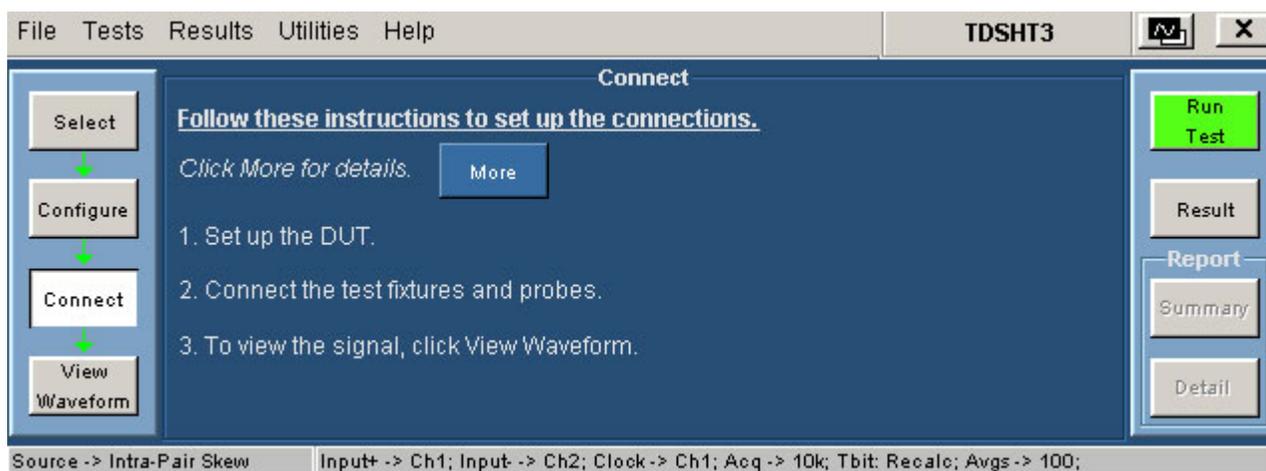


Figure 173: Connect pane for Source Intra-Pair Skew

8. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections. The waveform shown here is for the re-calculate Tbit option. Click **Run Test** to run the test. The **Confirm** dialog box appears. Click **Continue** to continue to run the test. Go to step 10.

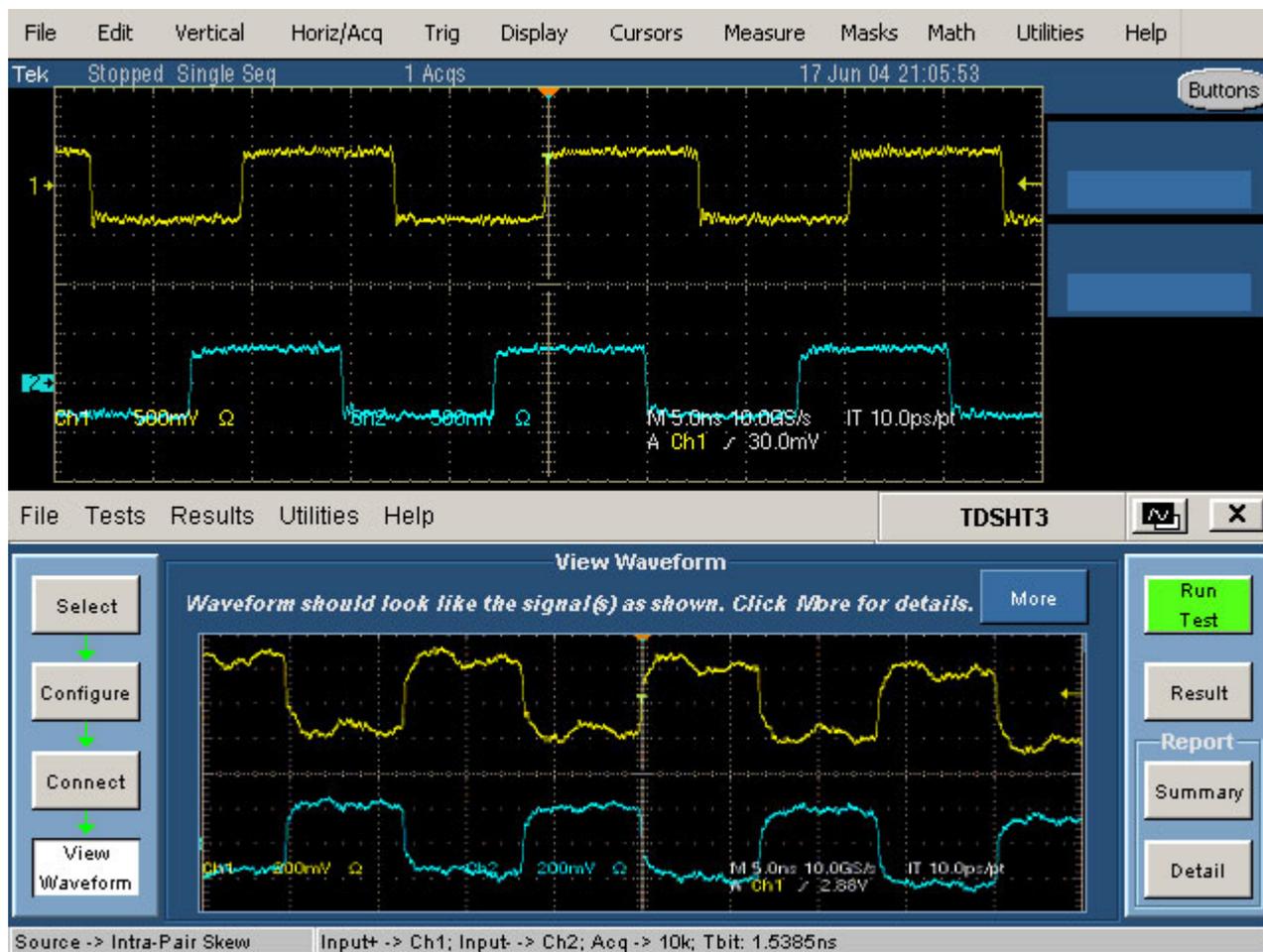


Figure 174: Waveform of Source Intra-Pair Skew

9. If you have selected existing Tbit value, then click **View Waveform** to get a different waveform on your display. Ensure that your signal in the oscilloscope display is similar to the sample signal.
10. Click **Run Test** to run the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

- The software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

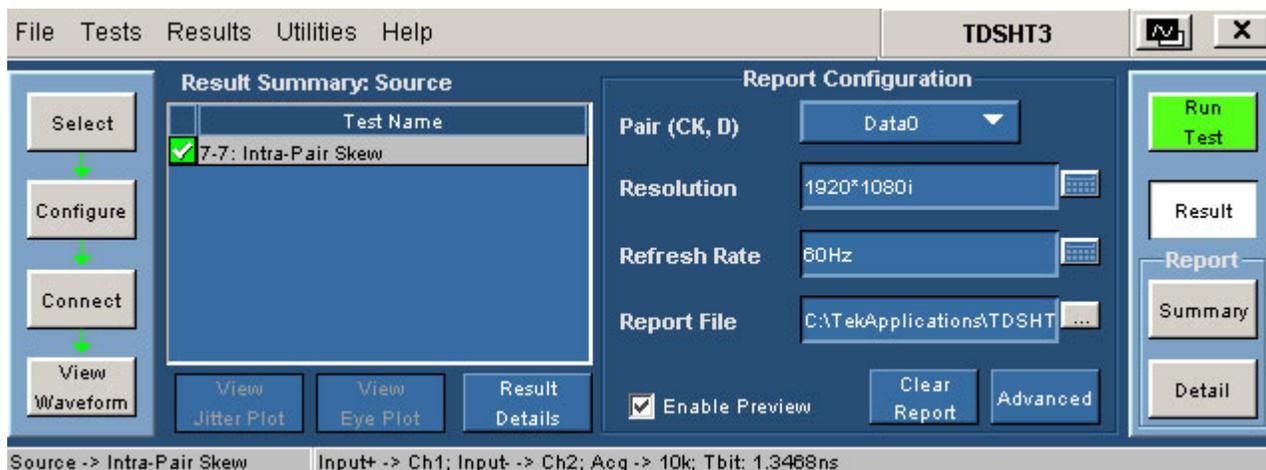


Figure 175: Result for Source Intra-Pair Skew

Table 93: Result for Source Intra-Pair Skew

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - D0+ (Data), D0- (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

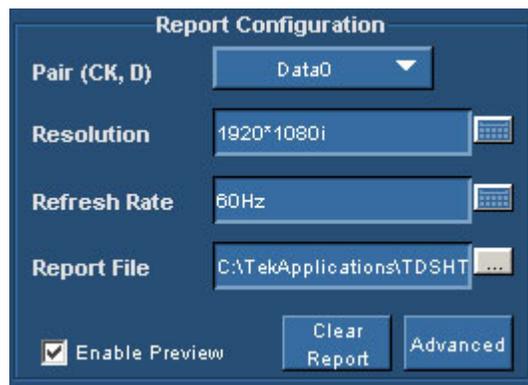


Figure 176: Report Configuration for Source Intra-Pair Skew

In the report configuration pane, you can configure the following parameters:

Table 94: Report Configuration options for Source Intra-Pair Skew

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

- In the result summary pane, click **Result Details** to display the details of the result.

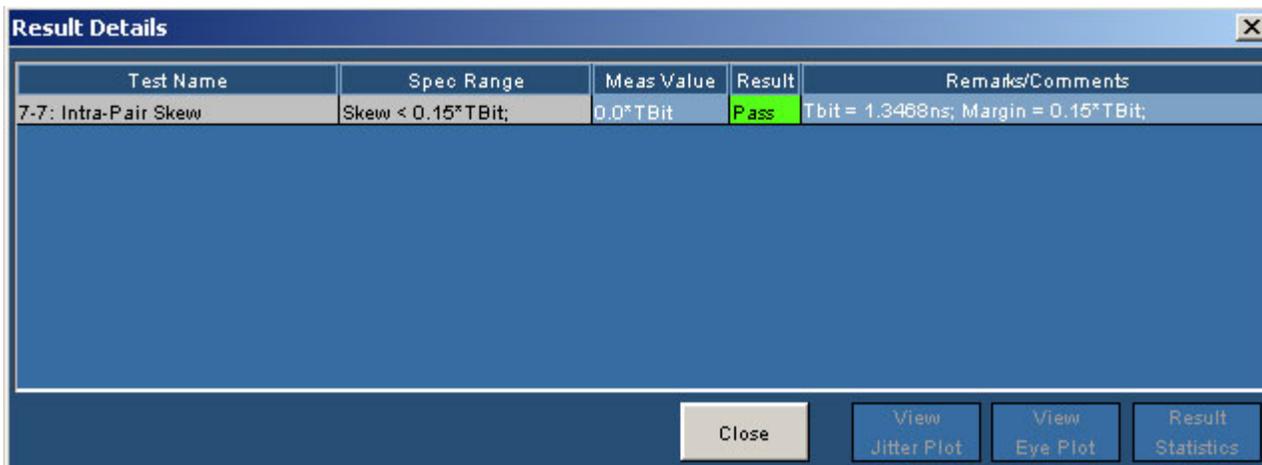


Figure 177: Result Details for Source Intra-Pair Skew

Table 95: Result Details for Source Intra-Pair Skew

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - D0+ (Data), D0- (Data). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |

Source – Low Amplitude +

This test allows you to confirm that DC voltage levels on the HDMI link are within specified limits for each TMDS signal.

You will need one supported oscilloscope, one single-ended probe, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-SE fixture.

- On the menu bar, click **Tests > Select > Source**.
- In the single-ended tests pane, select the **Low Amplitude +** check box.

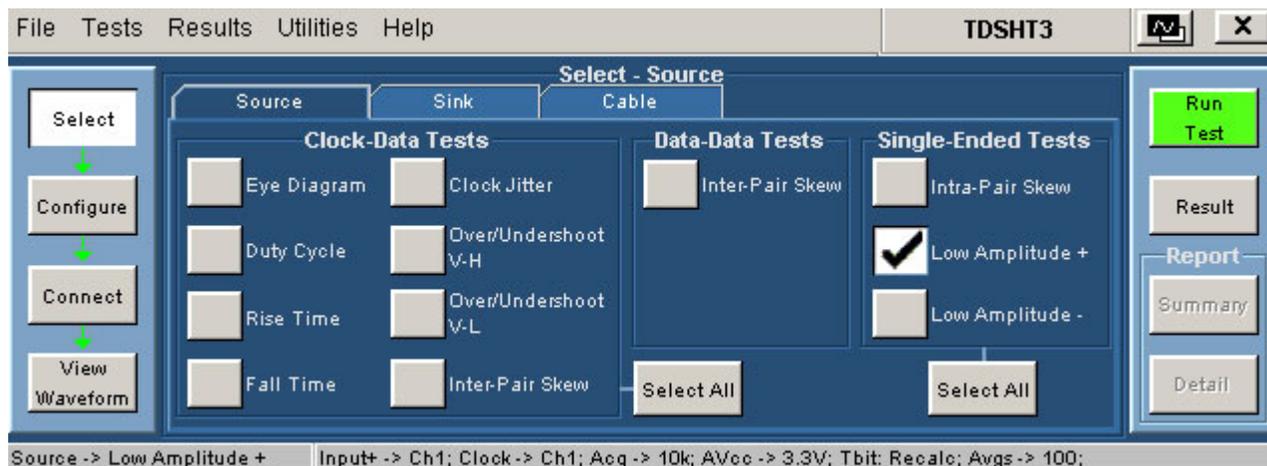


Figure 178: Select Source with Low Amplitude + test selected

3. To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

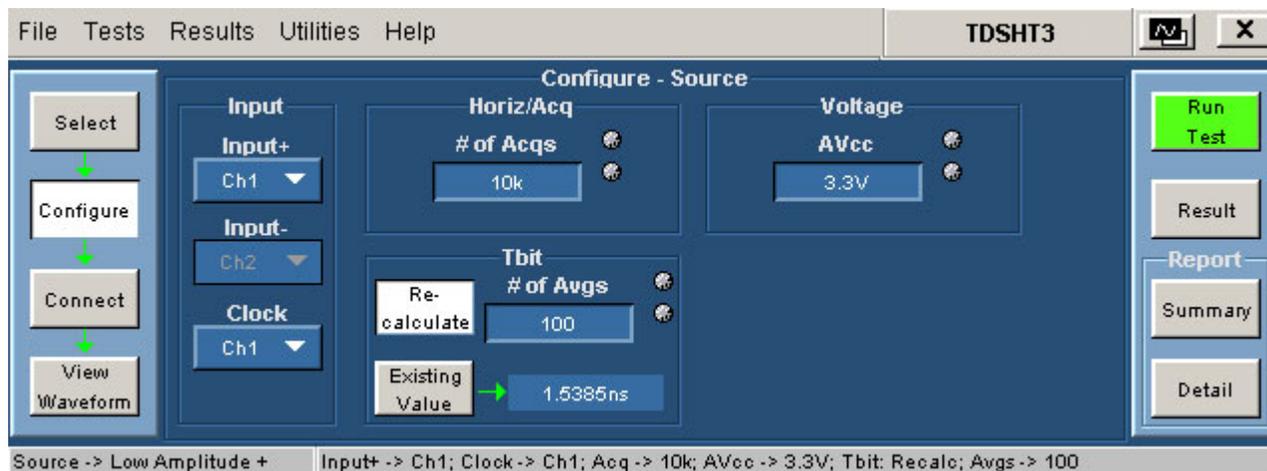


Figure 179: Configure Source for Low Amplitude +

4. In the input pane, you have the following options:

Table 96: Input options for Low Amplitude +

| Configure Parameter | Description |
|---------------------|--|
| Input+ | Input+ indicates the oscilloscope channel to which you will connect the positive input. The available choices are Ch1, Ch2, Ch3, and Ch4. |
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

5. In the horiz/acq pane, you have the following option:

Table 97: Horiz/Acq option for Low Amplitude +

| Configure Parameter | Description |
|---------------------|--|
| # of Acqs | In the # of Acqs box, enter the desired number of acquisitions that are required for the test. The default value is 10 K. |

6. In the Tbit pane, you have the following options:

Table 98: Tbit options for Low Amplitude +

| Configure Parameter | Description |
|---------------------|---|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

7. In the voltage pane, you have the following option:

Table 99: Voltage option for Low Amplitude +

| Configure Parameter | Description |
|---------------------|--|
| AVcc | In the AVcc box, enter the desired voltage value. The default value is 3.3 V. |

8. To connect the DUT, click **Tests > Connect**.

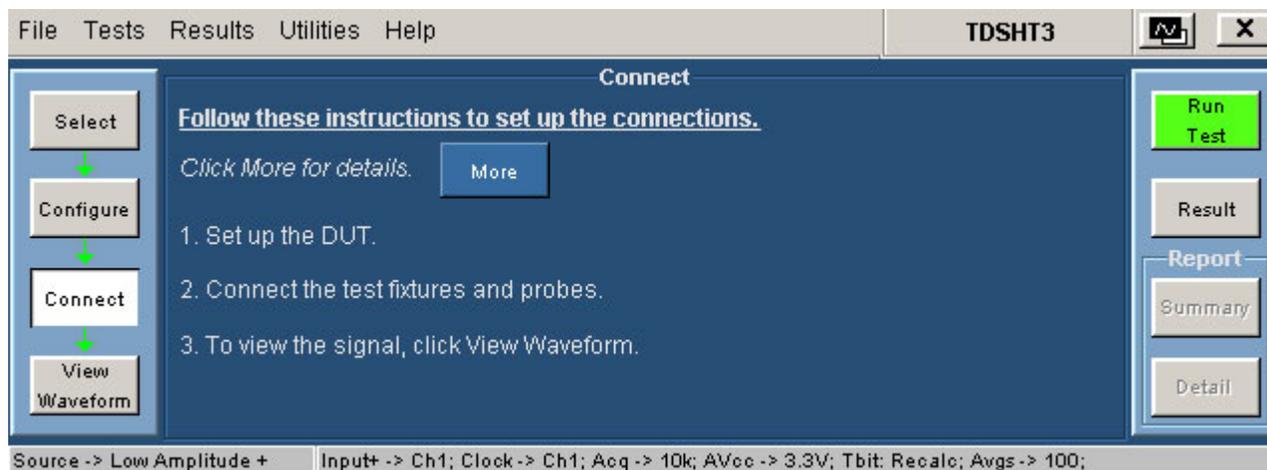


Figure 180: Connect pane for Low Amplitude +

9. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections. The waveform shown here is for the re-calculate Tbit option. Click **Run Test** to run the test. The **Confirm** dialog box appears. Click **Continue** to continue to run the test. Go to step 11.

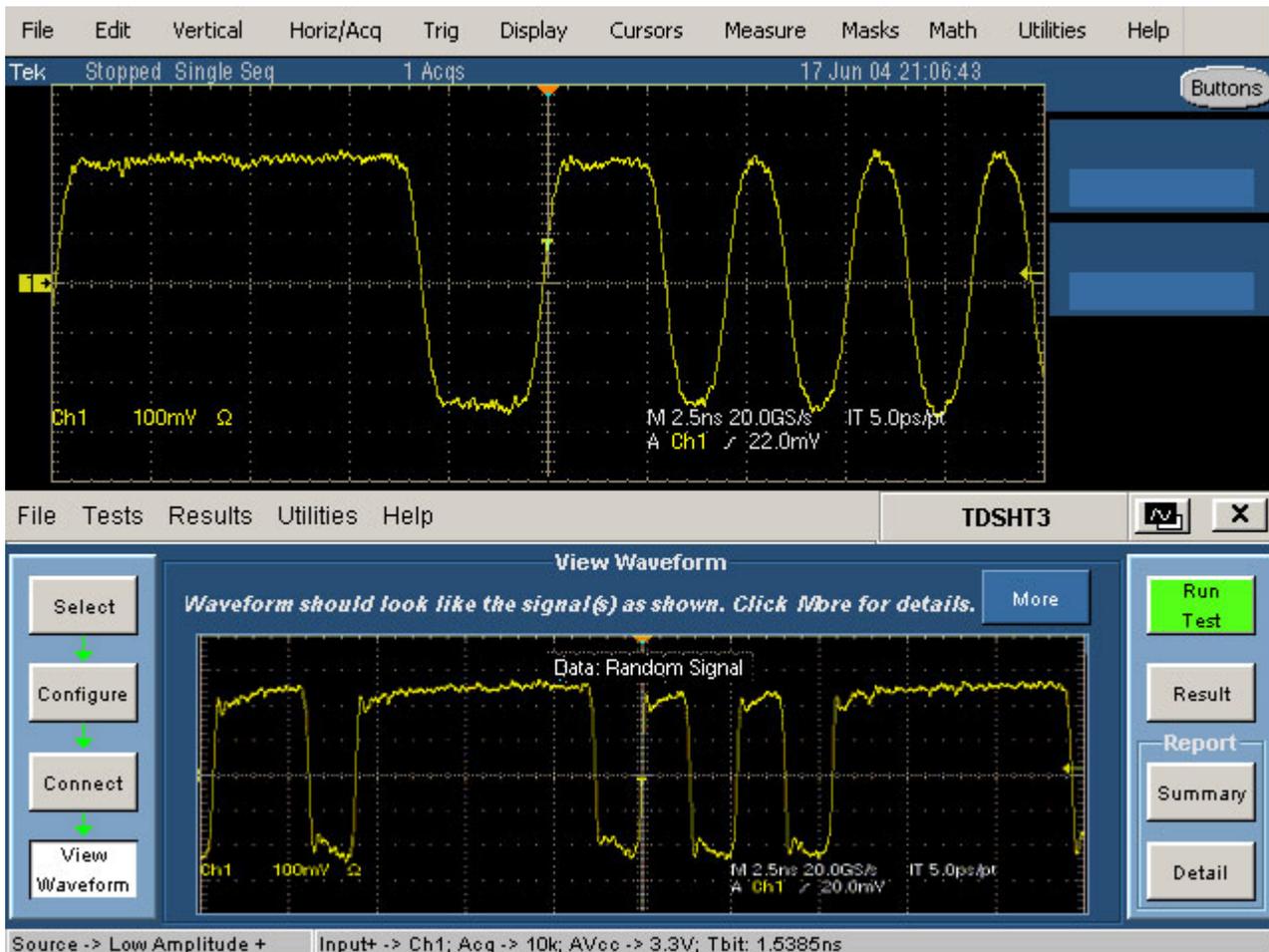


Figure 181: Waveform of Source - Low Amplitude + test

10. If you have selected existing Tbit value, then click **View Waveform** to get a different waveform on your display. Ensure that your signal in the oscilloscope display is similar to the sample signal.
11. Click **Run Test** to run the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

12. The software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

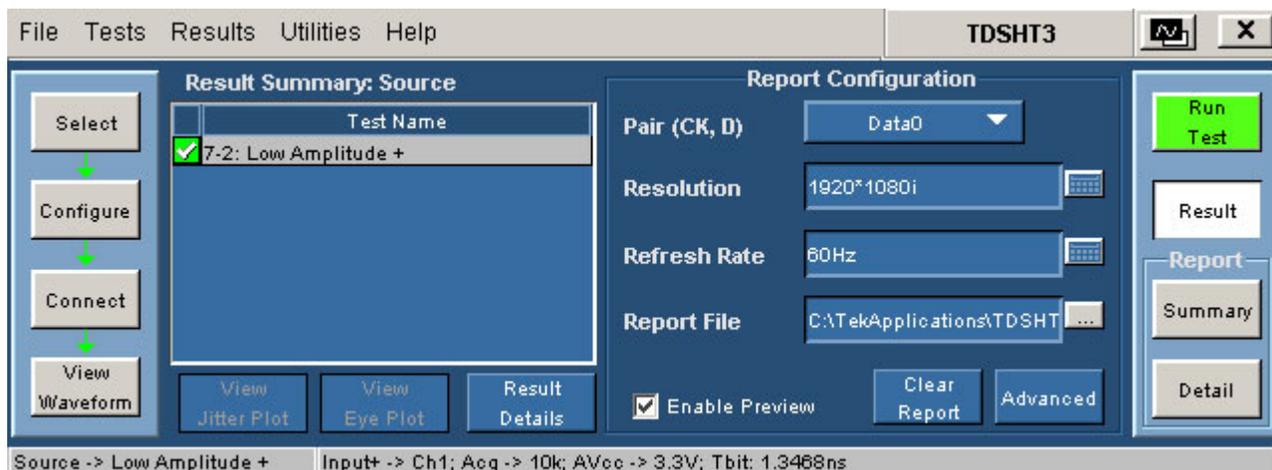


Figure 182: Result for Low Amplitude +

Table 100: Result for Low Amplitude +

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - D0+ (Data), CK (Clock). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

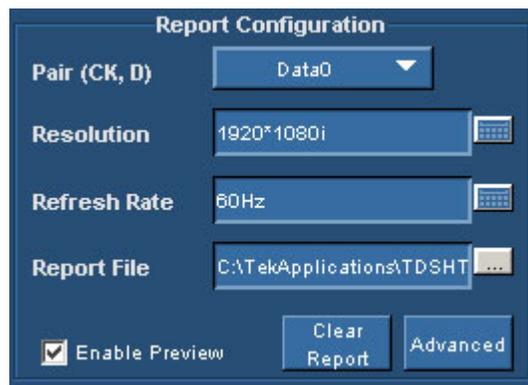


Figure 183: Report Configuration for Low Amplitude +

In the report configuration pane, you can configure the following parameters:

Table 101: Report Configuration options for Low Amplitude +

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

- In the result summary pane, click **Result Details** to display the details of the result.

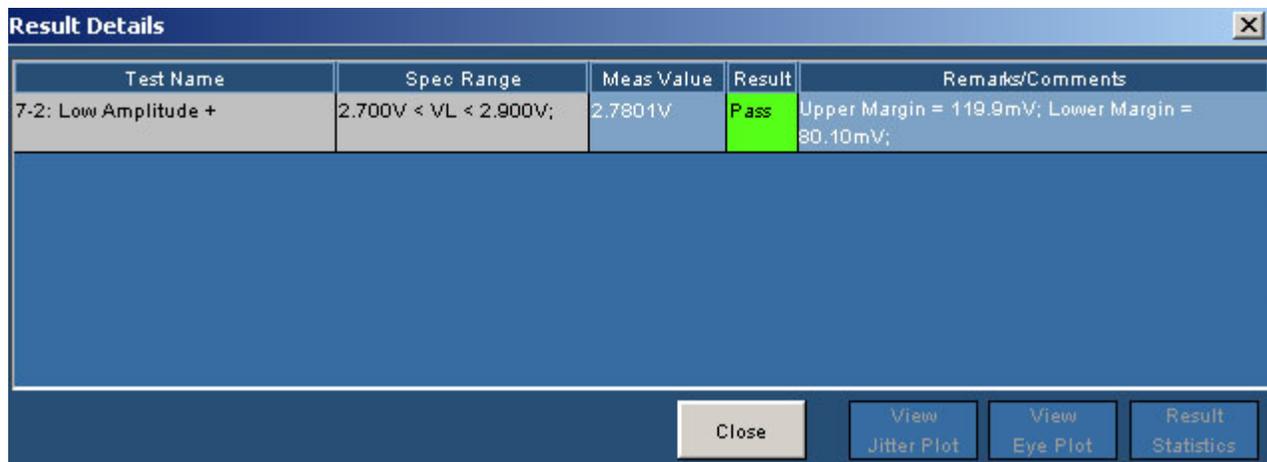


Figure 184: Results Details for Low Amplitude +

Table 102: Result Details for Low Amplitude +

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - D0+ (Data), CK (Clock). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |

Source – Low Amplitude -

This test allows you to confirm that DC voltage levels on the HDMI link are within specified limits for each TMDS signal.

You will need one supported oscilloscope, one single-ended probe, one DC power supply 3.3 V, one EDID emulator, and one TPA-P-SE fixture.

- On the menu bar, click **Tests > Select > Source**.

- In the single-ended tests pane, select the **Low Amplitude -** check box.

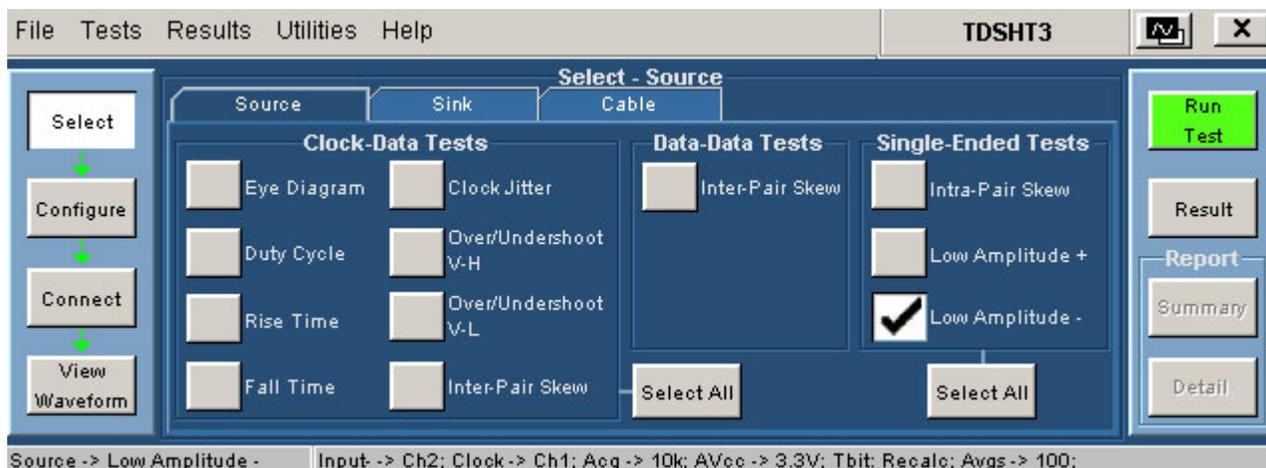


Figure 185: Select Source with Low Amplitude - test selected

- To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

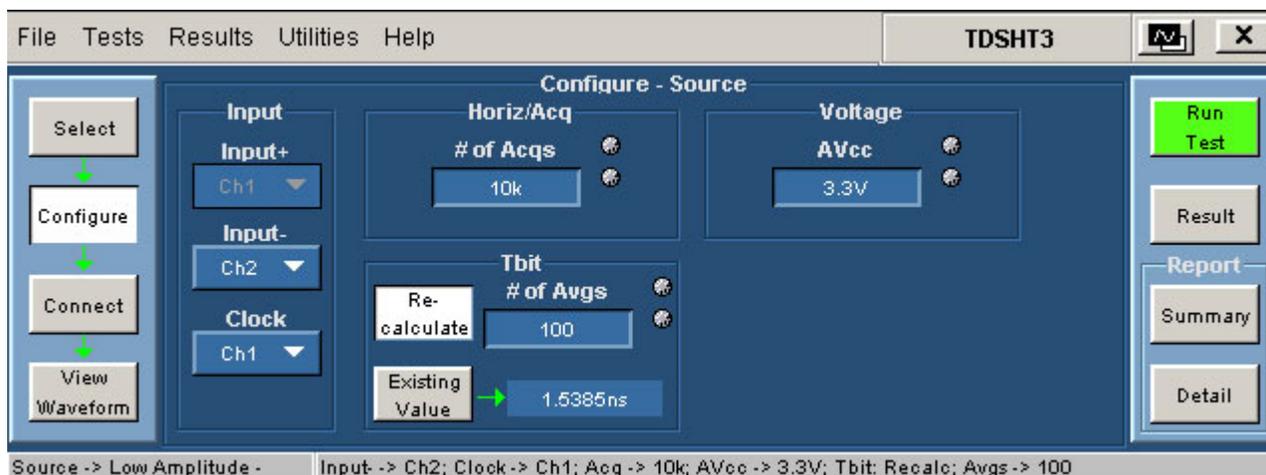


Figure 186: Configure Source for Low Amplitude -

4. In the input pane, you have the following options:

Table 103: Input options for Low Amplitude -

| Configure Parameter | Description |
|---------------------|--|
| Input- | Input- indicates the oscilloscope channel to which you will connect the positive input. The available choices are Ch1, Ch2, Ch3, and Ch4. |
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

5. In the horiz/acq pane, you have the following option:

Table 104: Horiz/acq option for Low Amplitude -

| Configure Parameter | Description |
|---------------------|--|
| # of Acqs | In the # of Acqs box, enter the desired number of acquisitions that are required for the test. The default value is 10 K. |

6. In the Tbit pane, you have the following options:

Table 105: Tbit options for Low Amplitude -

| Configure Parameter | Description |
|---------------------|---|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

7. In the voltage pane, you have the following option:

Table 106: Voltage option for Low Amplitude -

| Configure Parameter | Description |
|---------------------|--|
| AVcc | In the AVcc box, enter the desired voltage value. The default value is 3.3 V. |

8. To connect the DUT, click **Tests > Connect**.

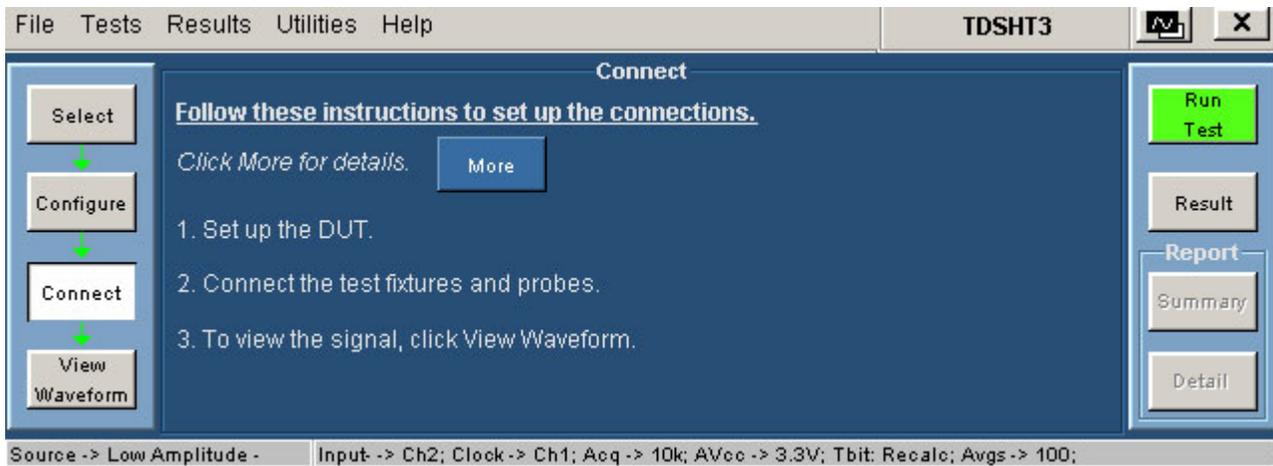


Figure 187: Connect pane for Low Amplitude -

9. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections. The waveform shown here is for the re-calculate Tbit option. Click **Run Test** to run the test. The **Confirm** dialog box appears. Click **Continue** to continue to run the test. Go to step 11.

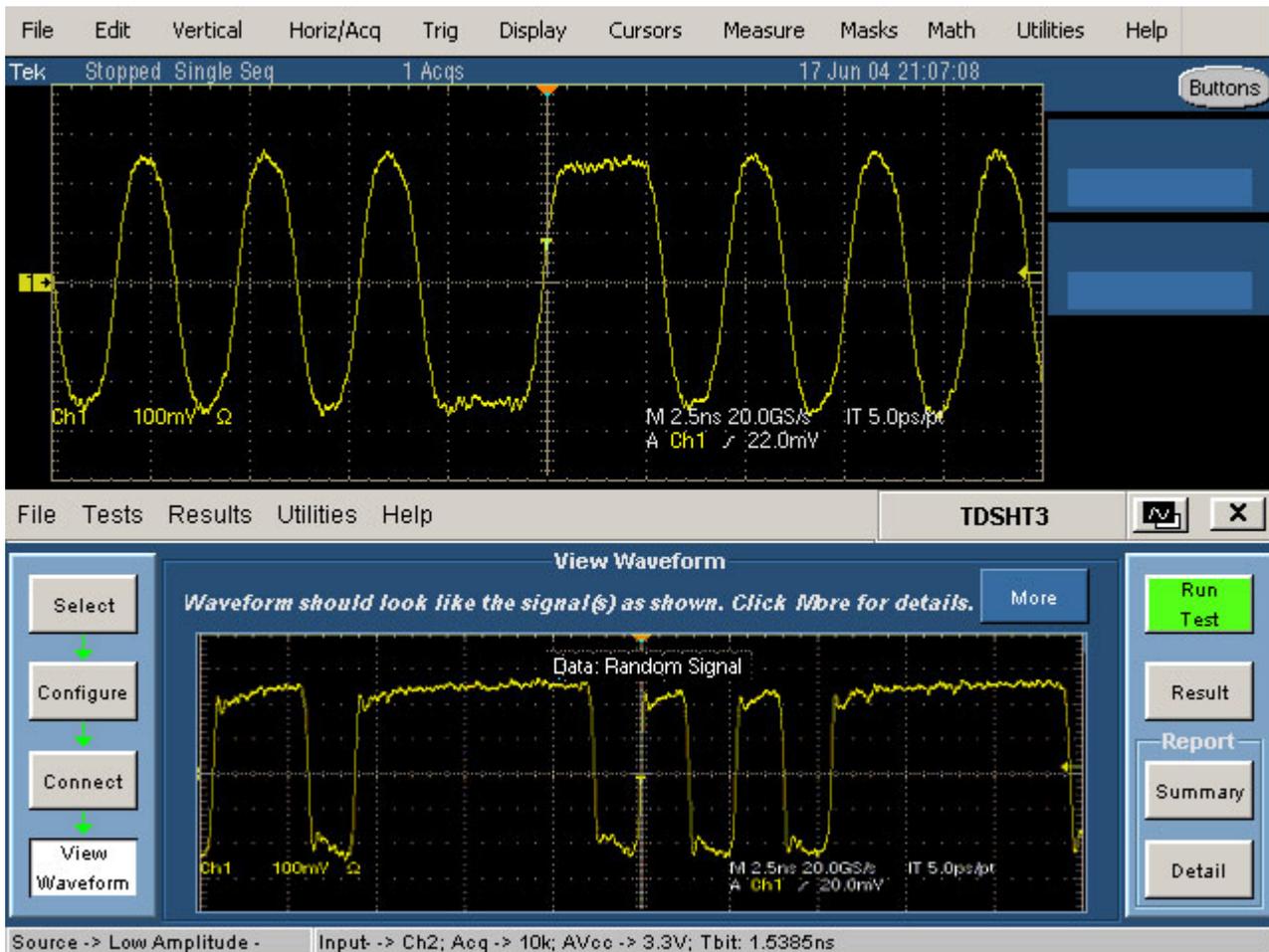


Figure 188: Waveform of Low Amplitude -

10. If you have selected existing Tbit value, then click **View Waveform** to get a different waveform on your display. Ensure that your signal in the oscilloscope display is similar to the sample signal.
11. Click **Run Test** to run the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.

- The software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

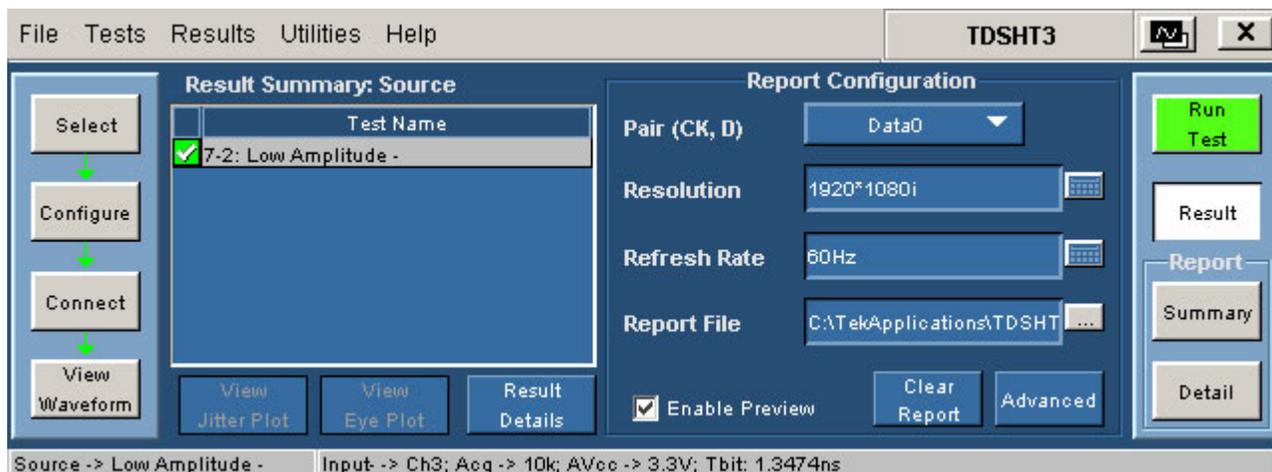


Figure 189: Result for Low Amplitude -

Table 107: Result for Low Amplitude -

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - D0- (Data), CK (Clock). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

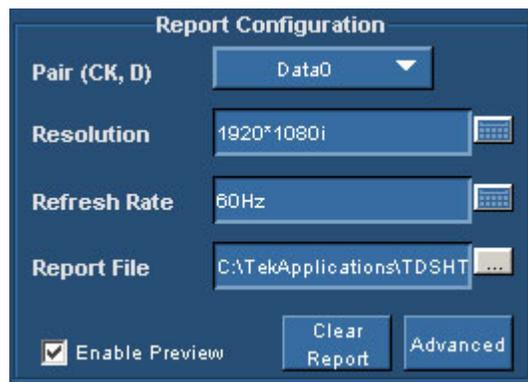


Figure 190: Report Configuration for Low Amplitude -

In the report configuration pane, you can configure the following parameters:

Table 108: Report Configuration options for Low Amplitude -

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

- In the result summary pane, click **Result Details** to display the details of the result.

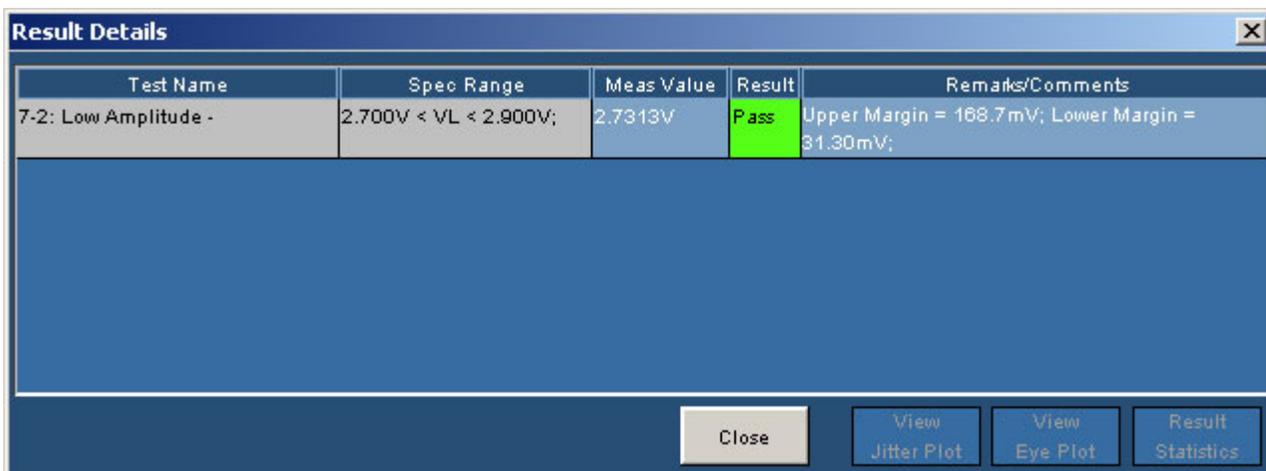


Figure 191: Result Details for Low Amplitude -

Table 109: Result Details for Low Amplitude -

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - D0- (Data), CK (Clock). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |

Sink – Min/Max-Diff Swing Tolerance

This test allows you to confirm that the Sink correctly supports TMDS differential voltages at minimum levels.

You will need one supported oscilloscope, one digital timing generator (DTG), one differential probe, one DC power supply, eight SMA cables, one GPIB controller, and one TPA-P-TDR fixture.

- On the menu bar, click **Tests > Select > Sink**.

- In the differential tests pane, select the **Min/Max-Diff Swing Tolerance** check box.

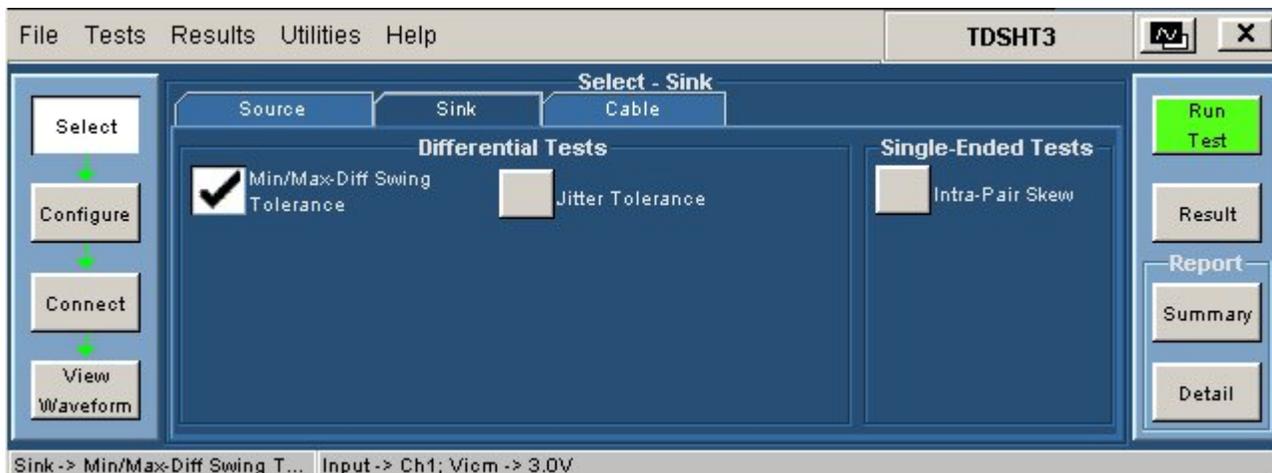


Figure 192: Select Sink with Min/Max-Diff Swing Tolerance test selected

- To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

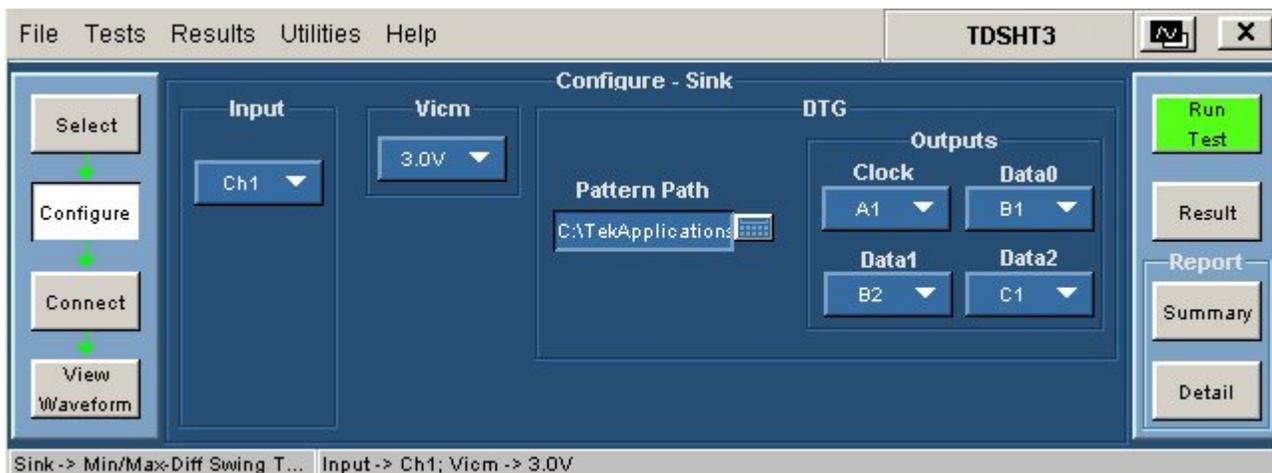


Figure 193: Configure Sink for Min/Max-Diff Swing Tolerance

4. In the input pane, you have the following option:

Table 110: Input option for Min/Max-Diff Swing Tolerance

| Configure Parameter | Description |
|---------------------|--|
| Input | Input indicates the oscilloscope channel to which you will connect the input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

5. Vicm indicates common mode voltage. In the Vicm pane, you have the following option:

Table 111: Vicm option for Min/Max-Diff Swing Tolerance

| Configure Parameter | Description |
|---------------------|---|
| Vicm | In the Vicm list, you can configure Vicm for either 3.0 V or 3.3 V. It is recommended that you conduct the test by using both the Vicm values. |

6. In the DTG pane, you have the following option:

Table 112: DTG option for Min/Max-Diff Swing Tolerance

| Configure Parameter | Description |
|---------------------|---|
| Pattern Path | In the Pattern Path box, enter the absolute path of the pattern file present in the DTG. |

7. In the outputs pane, you have the following options:

Table 113: Outputs options for Min/Max-Diff Swing Tolerance

| Configure Parameter | Description |
|---------------------|---|
| Clock | The Clock list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data0 | The Data0 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data1 | The Data1 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data2 | The Data2 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |

8. To connect the DUT, click **Tests > Connect**.

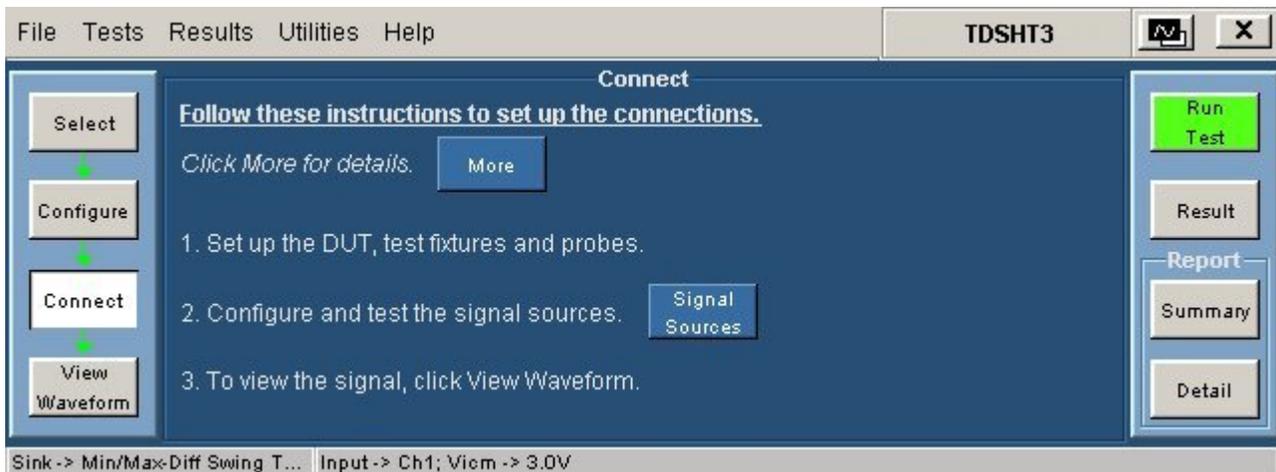


Figure 194: Connect pane for Min/Max-Diff Swing Tolerance

9. To configure and test the GPIB connection to the DTG, click **Signal Sources**. The **Signal Sources Setup** dialog box appears.



Figure 195: Signal Sources Setup for Min/Max-Diff Swing Tolerance

10. In the select pane, click **GPIB**. Configure the appropriate GPIB board number.
11. To test both the connection and the DTG GPIB configuration, click **Test Conn**.
12. Because no signal is connected to the oscilloscope, you cannot view the waveform for the min/max-diff swing tolerance test.

***Note:** To run the test successfully, ensure that the *Bus Timing* parameter is set to 2 μ sec on your GPIB board configuration. For more details, refer to the section on *Remote Control Caution*.*

13. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and conducts the test. Follow the instructions in the dialog box. Depending on your answer, a series of dialog boxes may prompt you for your input.

- If you successfully run the test, the software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

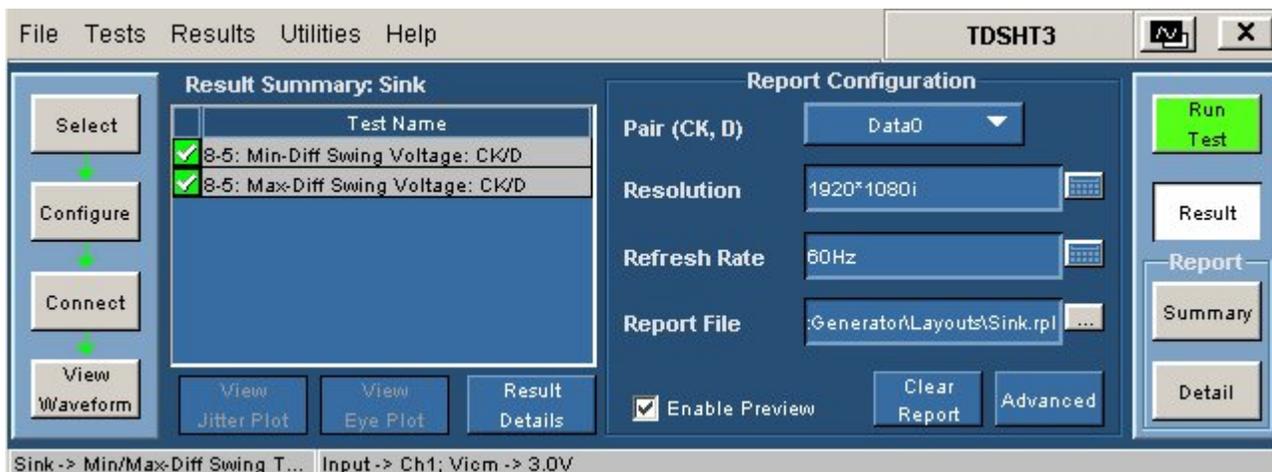


Figure 196: Result for Min/Max-Diff Swing Tolerance

Table 114: Result for Min/Max-Diff Swing Tolerance

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - D (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

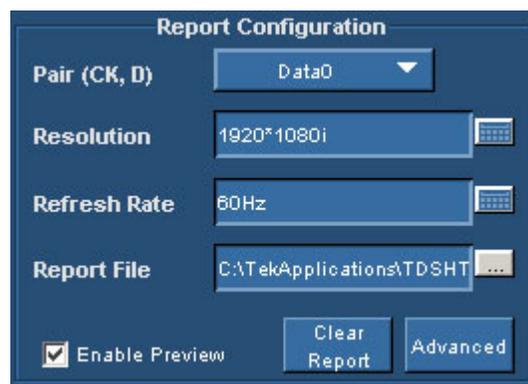


Figure 197: Report Configuration for Min/Max-Diff Swing Tolerance

In the report configuration pane, you can configure the following parameters:

Table 115: Report Configuration options for Min/Max-Diff Swing Tolerance

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

- In the result summary pane, click **Result Details** to display the details of the result.



Figure 198: Result Details for Min/Max-Diff Swing Tolerance

Table 116: Result Details for Min/Max-Diff Swing Tolerance

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - D (Data). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |

Sink – Jitter Tolerance

This test allows you to confirm that the maximum allowed TMDS clock jitter is supported by the Sink DUT.

You will need one supported oscilloscope, two differential probes, one digital timing generator (DTG), one arbitrary waveform generator (AWG), one DC power supply, 12 SMA cables, two bias-tees, one cable emulator, one GPIB controller, one TPA-R-DI, and one TPA-R-TDR.

1. On the menu bar, click **Tests > Select > Sink**.
2. In the differential tests pane, select the **Jitter Tolerance** check box.

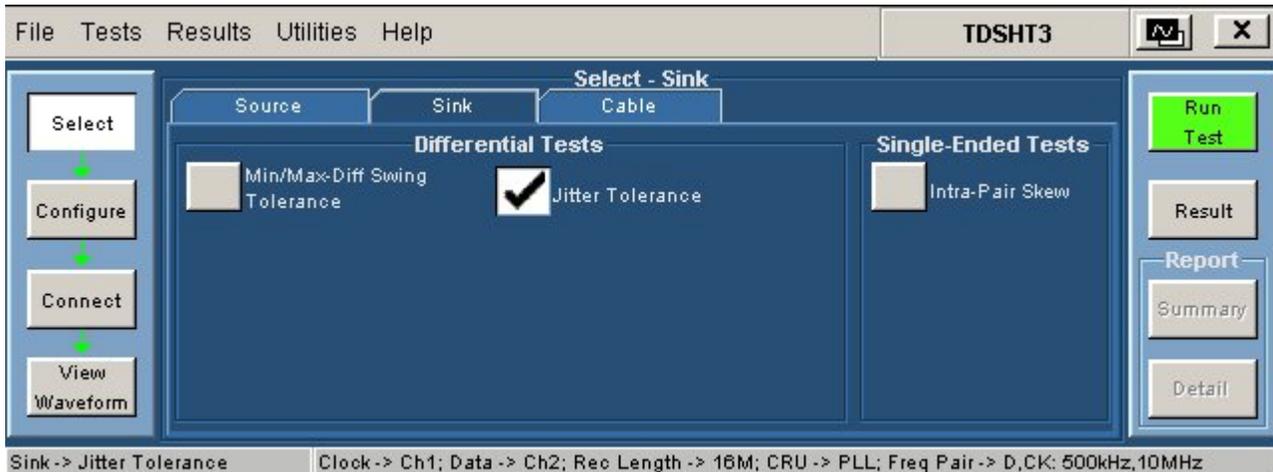


Figure 199: Select Sink with Jitter Tolerance test selected

3. To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

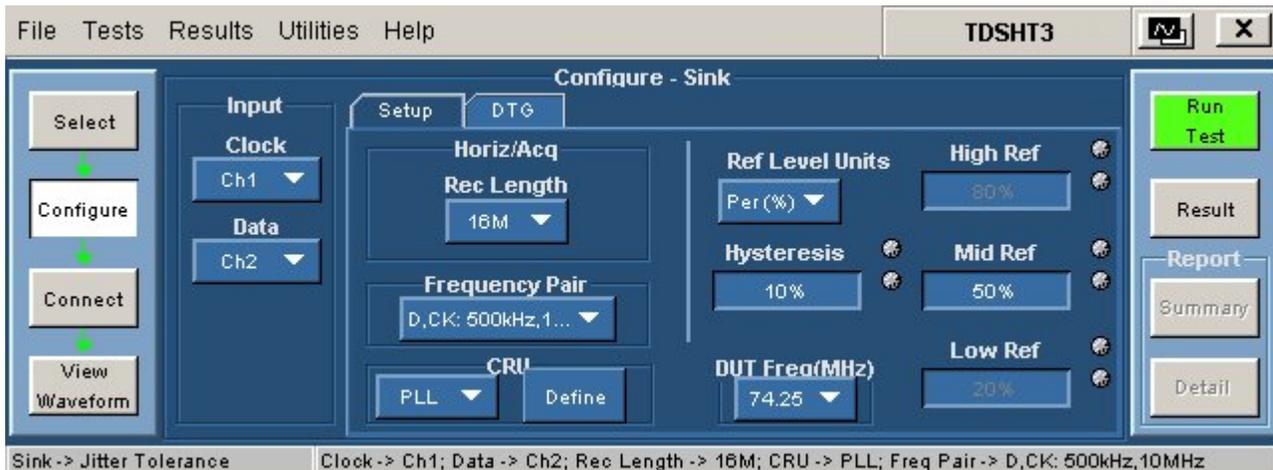


Figure 200: Configure Sink for Jitter Tolerance

4. In the input pane, you have the following options:

Table 117: Input options for Jitter Tolerance

| Configure Parameter | Description |
|---------------------|--|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, and Ch4. |
| Data | Data indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

5. On the **Setup** tab, in the horiz/acq pane, you have the following option:

Table 118: Horiz/acq option for Jitter Tolerance

| Configure Parameter | Description |
|---------------------|---|
| Record Length | In the Rec Length box, enter the desired record length value for the jitter tolerance tests. |

6. On the **Setup** tab, in the frequency pair pane, you have the following option:

Table 119: Frequency Pair option for Jitter Tolerance

| Configure Parameter | Description |
|---------------------|--|
| Frequency Pair | In the Frequency Pair list, click the desired value for the jitter tolerance tests. The available choices are D, Ck: 500 KHZ, 10 MHZ and D, Ck: 1 MHZ, 7 MHZ. |

7. On the **Setup** tab, in the CRU pane, you have the following option:

Table 120: CRU options for Jitter Tolerance

| Configure Parameter | Description |
|---------------------|---|
| CRU | The CRU list allows you to configure the CRU. The available choices are PLL, Raw, and Ideal. The default value is first order PLL and is used for compliance testing. Raw and Ideal are used for analysis. |
| Define | The Define is available only when PLL is selected. |

8. On the **Setup** tab, you also have the following options:

Table 121: Setup options for Jitter Tolerance

| Configure Parameter | Description |
|---------------------|--|
| Ref Level Units | The Ref Level Units list allows you to set the reference level units to either Per (%) or Abs. Per (%) indicates that the reference levels are a percentage of the Vswing value. Abs indicates that the reference levels are absolute voltage values. |
| Hysteresis | In the Hysteresis box, enter the desired hysteresis percent value. The default value is 10 percent. |
| Mid Ref | In the Mid Ref box, enter the desired mid reference voltage value. The default value is 50 percent. |

9. On the **DTG** tab, in the DTG pane, you have the following option:

Table 122: DTG option for Jitter Tolerance

| Configure Parameter | Description |
|---------------------|---|
| Pattern Path | In the Pattern Path box, enter the absolute path of the pattern file present in the DTG. |

10. On the DTG tab, in the outputs pane, you have the following options:

Table 123: DTG Outputs options for Jitter Tolerance

| Configure Parameter | Description |
|---------------------|---|
| Clock | The Clock list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data0 | The Data0 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data1 | The Data1 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data2 | The Data2 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |

- To connect the DUT, click **Tests > Connect**.

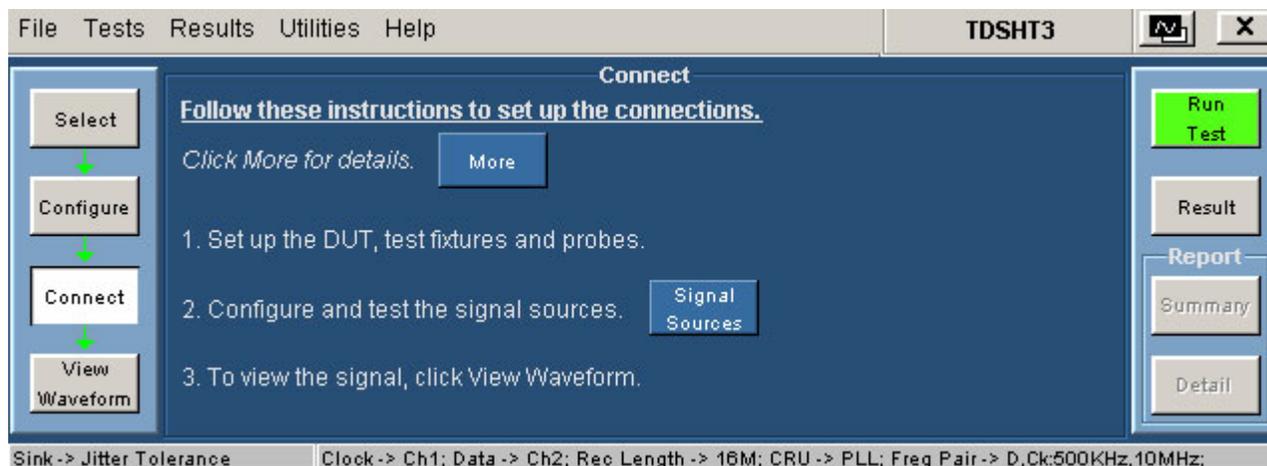


Figure 201: Connect pane for Jitter Tolerance

- To configure and test the GPIB connection to the DTG, click **Signal Sources**. The **Signal Sources Setup** dialog box appears.



Figure 202: Signal Sources Setup for Jitter Tolerance

- In the select pane, click **GPIB**. Configure the appropriate GPIB board number.
- To test both the connection and the DTG GPIB configuration, click **Test Conn**.
- Because no signal is connected to the oscilloscope, you cannot view the waveform for the jitter tolerance test.

Note: To run the test successfully, ensure that the Bus Timing parameter is set to 2 μ sec on your GPIB board configuration. For more details, refer to the section on Remote Control Caution.

16. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and conducts the test. The Sink Jitter Tolerance dialog box appears.

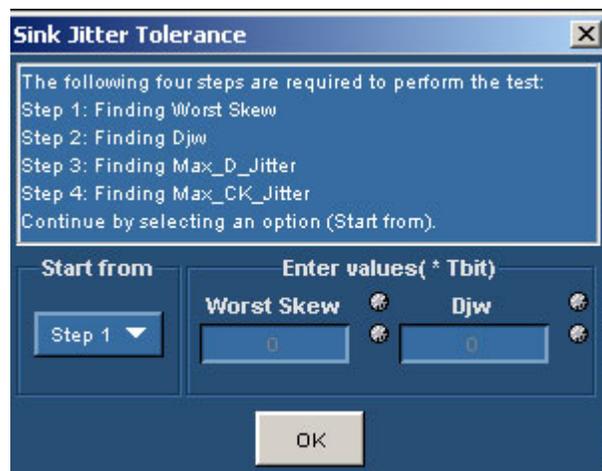


Figure 203: Sink Jitter Tolerance

17. Follow the instructions in the Sink Jitter Tolerance dialog box. Click **OK**. The **Connect Sink Device** dialog box appears.

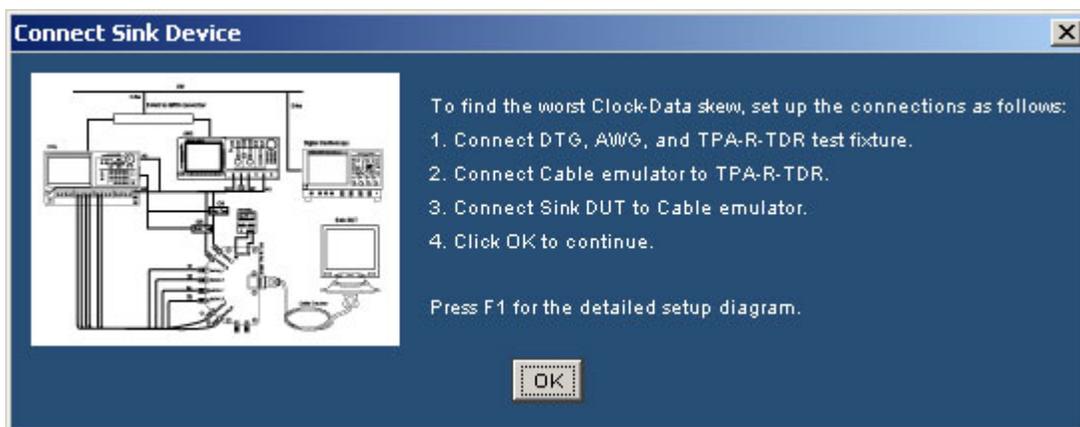


Figure 204: Connect Sink Device

18. Follow the instructions in the **Connect Sink Device** dialog box. Click **OK**. The test runs, displaying a progress indicator. The **Confirm Sink Device Support** dialog box appears.

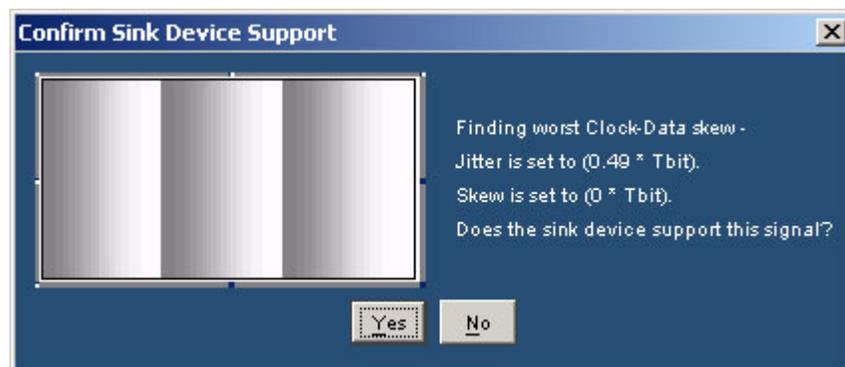


Figure 205: Confirm Sink Device Support

19. Follow the instructions in the dialog box. Depending on your answer, a series of dialog boxes may prompt you for your input.
20. If you successfully run the test, the software calculates the jitter values and displays the results. The software makes **Result** available automatically and displays the result summary, the eye diagram plot, and the clock jitter plot. For more information on the plots, refer the online help. You can also view the report configuration details in the result pane.

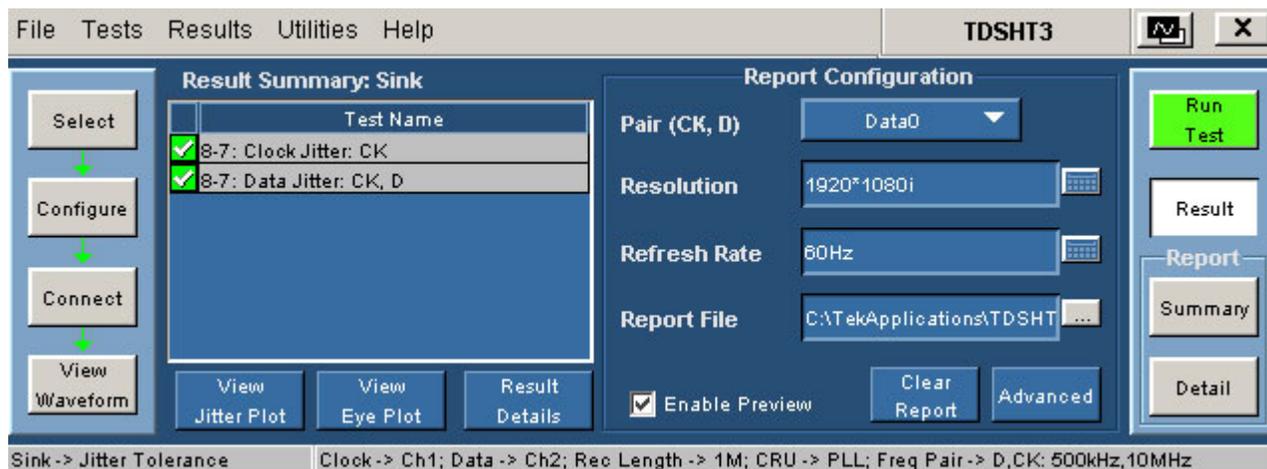


Figure 206: Result for Jitter Tolerance

Table 124: Result for Jitter Tolerance

| Option | Description |
|----------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

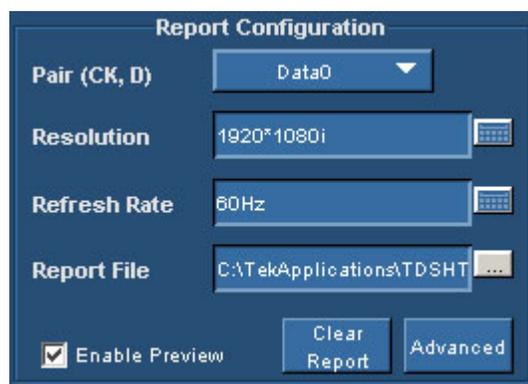


Figure 207: Report Configuration for Jitter Tolerance

In the report configuration pane, you can configure the following parameters:

Table 125: Report Configuration options for Jitter Tolerance

| Category | Description |
|--------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |

Table 125: Report Configuration options for Jitter Tolerance (Contd.)

| Category | Description |
|----------------|--|
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

- In the result summary pane, click **Result Details** to display the details of the result.



Figure 208: Result Details for Jitter Tolerance

Table 126: Result Details for Jitter Tolerance

| Option | Description |
|------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name – CK (Clock), D (Data). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |

Table 126: Result Details for Jitter Tolerance (Contd.)

| Option | Description |
|------------------|---|
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |
| View Jitter Plot | Click View Jitter Plot to view the jitter plot for the jitter tolerance test. |
| View Eye Plot | Click View Eye Plot to view the eye plot for the jitter tolerance test. |

Sink – Intra-Pair Skew

This test allows you to confirm that the maximum allowed timing skew within each TMDS pair is supported by the Sink DUT.

You will need one supported oscilloscope, one differential probe, one cable emulator, one TPA-P-DI fixture, one digital timing generator (DTG), one DC power supply, eight SMA cables, one GPIB controller, and one TPA-P-TDR fixture.

1. On the menu bar, click **Tests > Select > Sink**.
2. In the single-ended tests pane, select the **Intra-Pair Skew** check box.

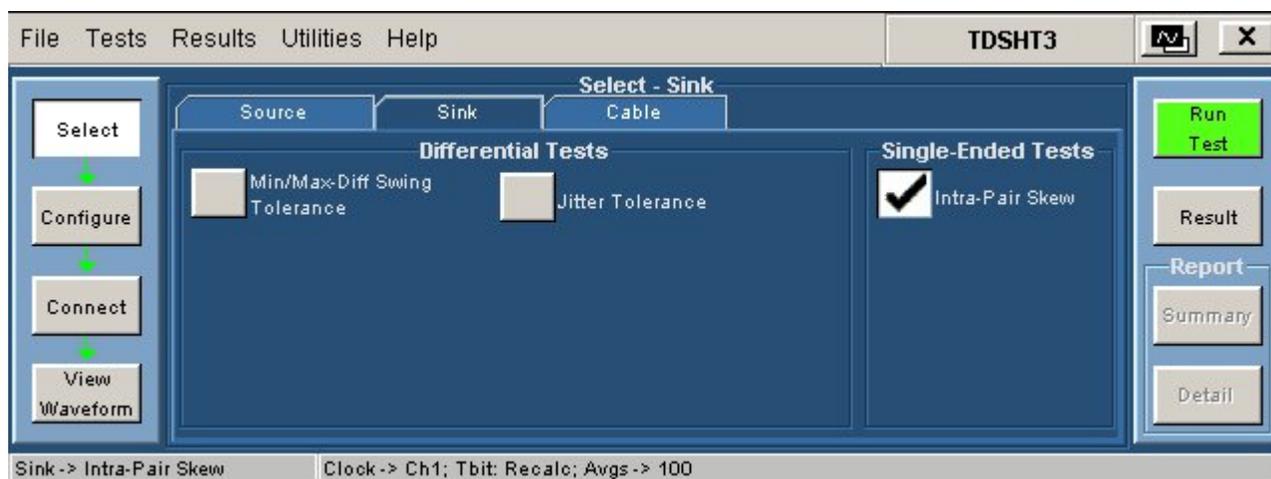


Figure 209: Select Sink with Intra-Pair Skew test selected

3. To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob

on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

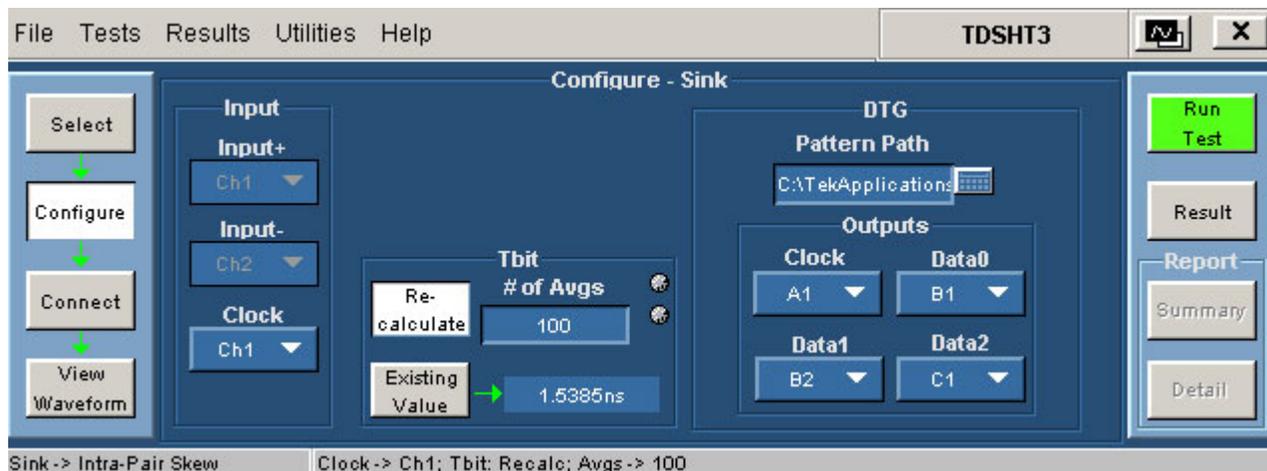


Figure 210: Configure for Sink Intra-Pair Skew

Note: The default configuration is to calculate the intra-pair skew of the clock channel. If you want to calculate the intra-pair skew for other data channels, then interchange the DTG physical channels of Data<X> with Clock. For example, to calculate the intra-pair skew of Data0, assign A1 to Data0 and assign B1 to Clock. Make the appropriate changes in the test connections.

4. In the input pane, you have the following option:

Table 127: Input option for Sink Intra-Pair Skew

| Configure Parameter | Description |
|---------------------|---|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

5. In the Tbit pane, you have the following options:

Table 128: Tbit options for Sink Intra-Pair Skew

| Configure Parameter | Description |
|---------------------|--|
| # of Avgs | In the # of Avgs box, enter the desired number of periods that are considered to calculate Tbit. The default value is 100. |
| Re-calculate | Click Re-calculate to recalculate the Tbit value. |
| Existing Value | Click Existing Value to use the previously calculated Tbit value. |

6. In the DTG pane, you have the following option:

Table 129: DTG option for Sink Intra-Pair Skew

| Configure Parameter | Description |
|---------------------|---|
| Pattern Path | In the Pattern Path box, enter the absolute path of the pattern file present in the DTG. |

7. In the outputs pane, you have the following options:

Table 130: Output options for Sink Intra-Pair Skew

| Configure Parameter | Description |
|---------------------|---|
| Clock | The Clock list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data0 | The Data0 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data1 | The Data1 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data2 | The Data2 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |

8. To connect the DUT, click **Tests > Connect**.

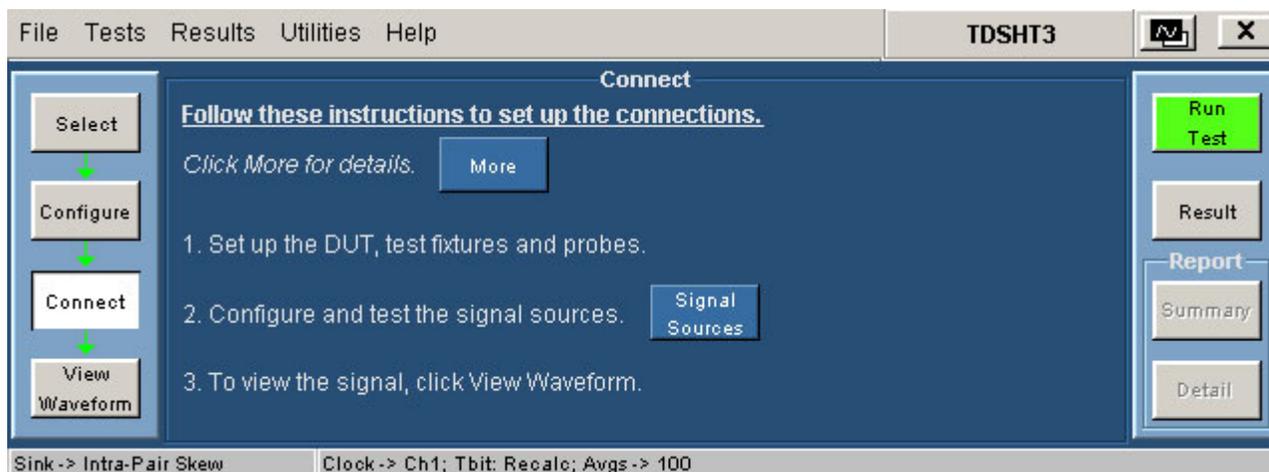


Figure 211: Connect pane for Sink Intra-Pair Skew

9. To configure and test the GPIB connection to the DTG, click **Signal Sources**. The **Signal Sources Setup** dialog box appears.



Figure 212: Signal Sources Setup for Sink Intra-Pair Skew

10. In the select pane, click **GPIB**. Configure the appropriate GPIB board number.
11. To test both the connection and the DTG GPIB configuration, click **Test Conn**.
12. Ensure that your signal in the oscilloscope display is similar to the sample signal. Click **View Waveform** to display a sample of the expected signal. If the displays are not similar, go back and check your configuration and connections. The sample signal appears if you have selected the re-calculate Tbit option.

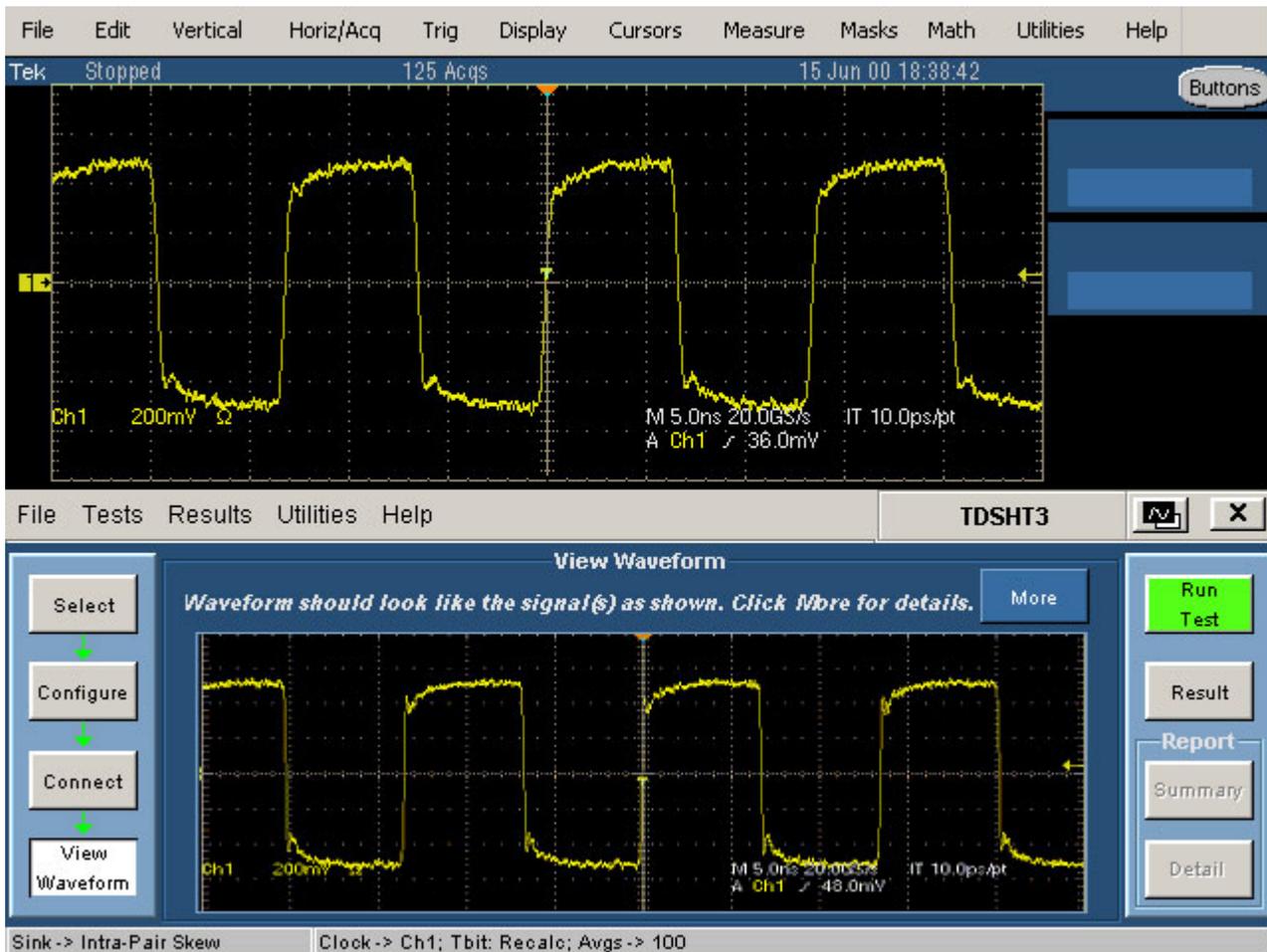


Figure 213: Waveform of Sink Intra-Pair Skew

Note: To run the test successfully, ensure that the Bus Timing parameter is set to 2 μ sec on your GPIB board configuration. For more details, refer to the section on Remote Control Caution.

13. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and conducts the test. Follow the instructions in the dialog box. Depending on your answer, a series of dialog boxes may prompt you for your input.
14. If you successfully run the test, the software makes **Result** available automatically and displays the result summary. You can also view the report configuration details in the result pane.

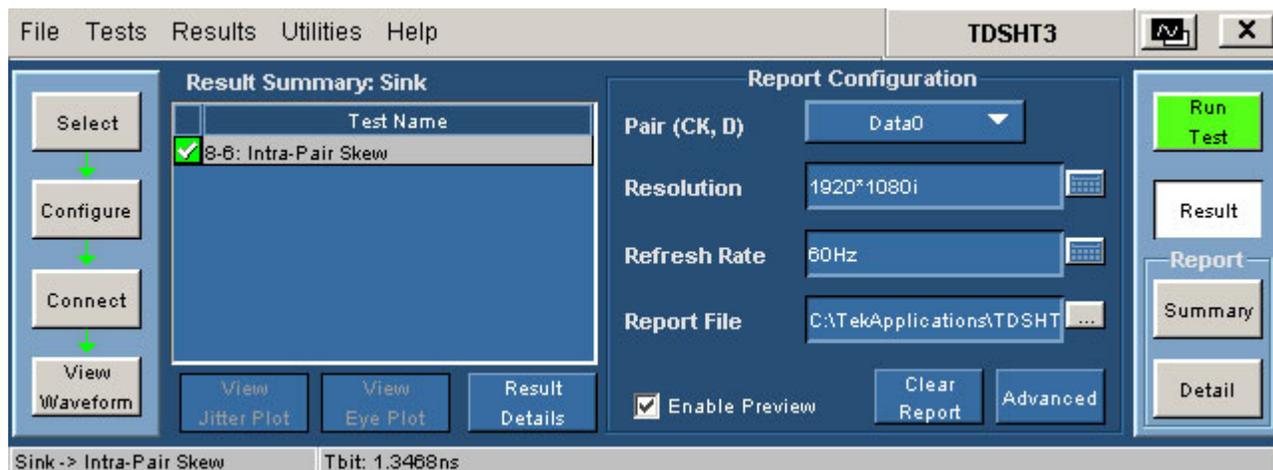


Figure 214: Result for Sink Intra-Pair Skew

Table 131: Result for Sink Intra-Pair Skew

| Option | Description |
|----------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

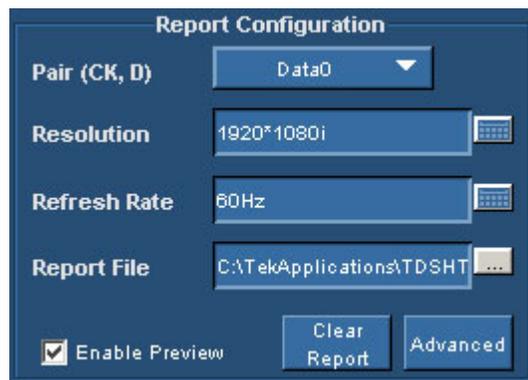


Figure 215: Report Configuration for Sink Intra-pair Skew

In the report configuration pane, you can configure the following parameters:

Table 132: Report Configuration options for Sink Intra-Pair Skew

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

- In the result summary pane, click **Result Details** to display the details of the result.

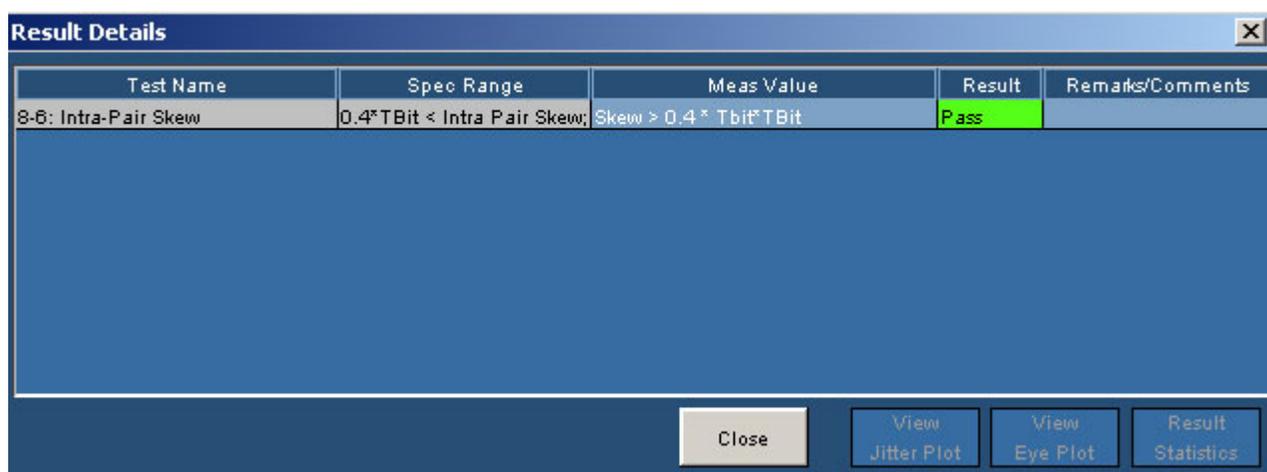


Figure 216: Result Details for Sink Intra-pair Skew

Table 133: Result Details for Sink Intra-Pair Skew

| Option | Description |
|------------------|---|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |

Cable – Eye Diagram

This test allows you to confirm that the Cable assembly outputs a compliant data eye. You can check the input test signal at TP1, and verify the output of the cable, for compliance, at TP2.

You will need one supported oscilloscope, two differential probes, one digital timing generator (DTG), one GPIB controller, one DC power supply 3.3 V, eight SMA cables, one TPA-R-DI fixture, and one TPA-R-TDR fixture.

1. On the menu bar, click **Tests > Select > Cable**.
2. In the differential tests pane, select the **Eye Diagram** check box.

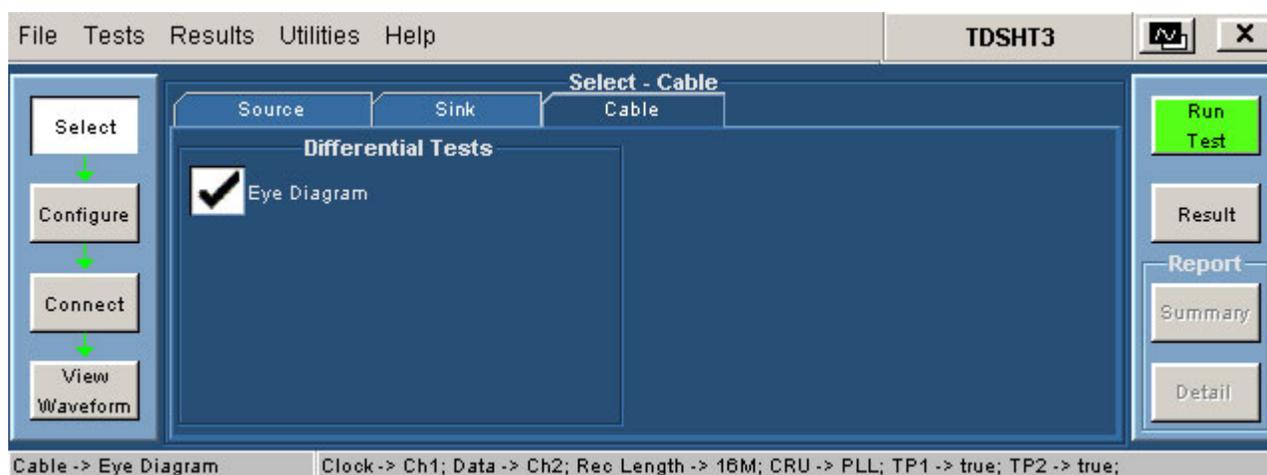


Figure 217: Select Cable with Eye Diagram test selected

- To change the configuration settings, click **Tests > Configure**. For most tests, you can use the factory default configuration. However, you can change the values by using the virtual keyboard or the general purpose knob on the oscilloscope front panel. Using the File menu, you can also restore the factory defaults or save and recall your own configuration settings.

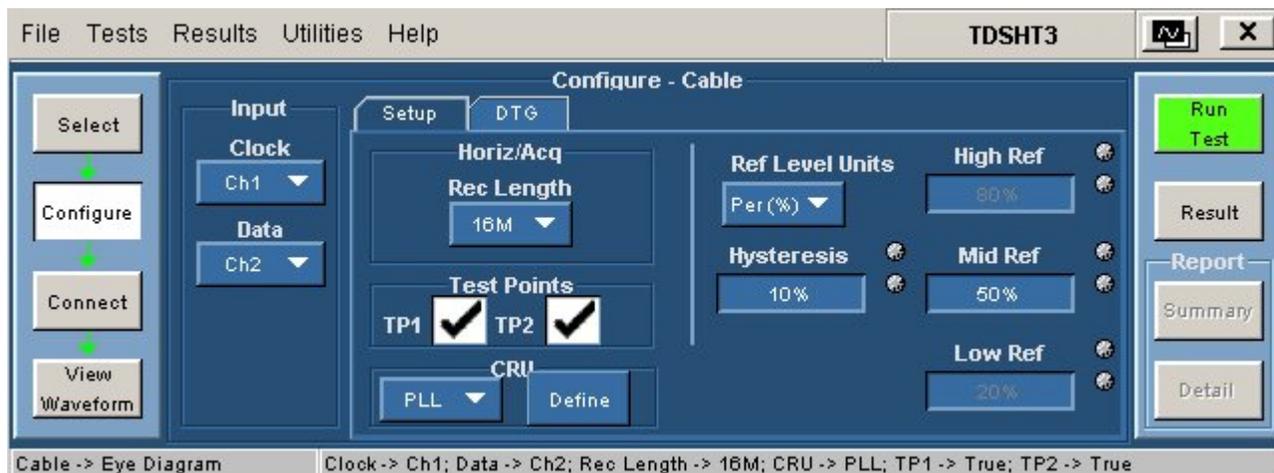


Figure 218: Configure Cable for Eye Diagram

- In the input pane, you have the following options:

Table 134: Input options for Cable Eye Diagram

| Configure Parameter | Description |
|---------------------|--|
| Clock | Clock indicates the oscilloscope channel to which you will connect the clock input. The available choices are Ch1, Ch2, Ch3, and Ch4. |
| Data | Data indicates the oscilloscope channel to which you will connect the data input. The available choices are Ch1, Ch2, Ch3, and Ch4. |

- On the **Setup** tab, in the horiz/acq pane, you have the following option:

Table 135: Horiz/Acq option for Cable Eye Diagram

| Configure Parameter | Description |
|---------------------|--|
| Record Length | In the Rec Length box, enter the desired record length value for the eye tests. |

6. On the **Setup** tab, in the test points pane, you have the following options:

Table 136: Test Points options for Cable Eye Diagram

| Configure Parameter | Description |
|---------------------|--|
| TP1 | TP1 represents the first test point. Feed the worst possible compliant signal at TP1. By default, the TP1 check box is selected. |
| TP2 | TP2 represents the second test point. The worst possible compliant signal fed at TP1 is transmitted through the cable. The same signal is tested at TP2 with the TP2 specification. By default, the TP2 check box is selected. |

7. On the **Setup** tab, in the CRU pane, you have the following option:

Table 137: CRU options for Cable Eye Diagram

| Configure Parameter | Description |
|---------------------|--|
| CRU | The CRU list allows you to configure the CRU. The available choices are PLL, Raw, and Ideal. The default value is first order PLL and is used for compliance testing. Raw and Ideal are used for analysis. |
| Define | The Define is available only when PLL is selected. |

8. On the **Setup** tab, you also have the following options:

Table 138: Setup options for Cable Eye Diagram

| Configure Parameter | Description |
|---------------------|---|
| Ref Level Units | The Ref Level Units list allows you to set the reference level units to either Per (%) or Abs. Per (%) indicates that the reference levels are a percentage of the Vswing value. Abs indicates that the reference levels are absolute voltage values. |
| Hysteresis | In the Hysteresis box, enter the desired hysteresis percent value. The default value is 10 percent. |
| Mid Ref | In the Mid Ref box, enter the desired mid reference voltage value. The default value is 50 percent. |

9. On the **DTG** tab, in the DTG pane, you have the following option:

Table 139: DTG option for Cable Eye Diagram

| Configure Parameter | Description |
|---------------------|---|
| Pattern Path | In the Pattern Path box, enter the absolute path of the pattern file present in the DTG. |

10. On the DTG tab, in the outputs pane, you have the following options:

Table 140: DTG Outputs options for Cable Eye Diagram

| Configure Parameter | Description |
|---------------------|---|
| Clock | The Clock list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data0 | The Data0 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data1 | The Data1 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |
| Data2 | The Data2 list allows you to configure the output. The available choices are A1, A2, B1, B2, C1, C2, D1, and D2. |

11. To connect the DUT, click **Tests > Connect**.

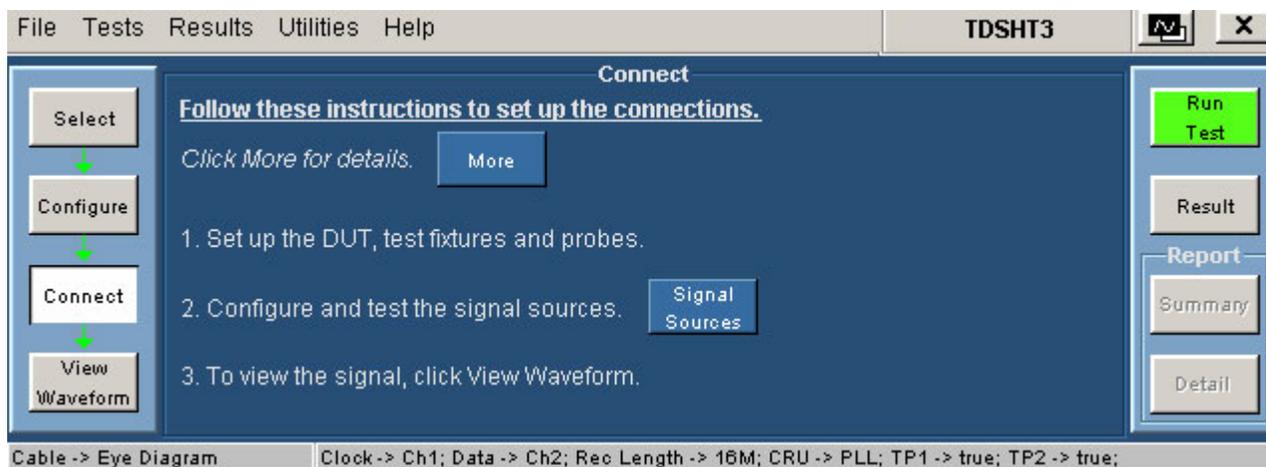


Figure 219: Connect pane for Cable Eye Diagram

12. To configure and test the GPIB connection to the DTG, click **Signal Sources**. The **Signal Sources Setup** dialog box appears.



Figure 220: Signal Sources setup for Cable Eye Diagram

13. In the select pane, click **GPIB**. Configure the appropriate GPIB board number.
14. To test both the connection and the DTG GPIB configuration, click **Test Conn**.
15. Because no signal is connected to the oscilloscope, you cannot view the waveform for the eye diagram test.

Note: To run the test successfully, ensure that the Bus Timing parameter is set to 2 μ sec on your GPIB board configuration. For more details, refer to the section on Remote Control Caution.

16. Click **Run Test** to perform the test. The TDSHT3 HDMI Compliance Test Software sets up the oscilloscope and the test runs, displaying a progress indicator.
17. The software creates a worst eye and asks you to verify the worst eye. If you want to adjust the eye diagram, change the parameters in the DTG, and then click either **Yes** or **No**. Follow the instructions in the dialog box. Depending on your answer, a series of dialog boxes may prompt you for your input.
18. If you have run the test successfully, the software makes **Result** available automatically and displays the eye diagram plot and the clock jitter plot for both TP1 and TP2. For more information on the plots, refer the online help. You can also view both the result summary of the test and the report configuration in the result pane as shown in the following diagram:

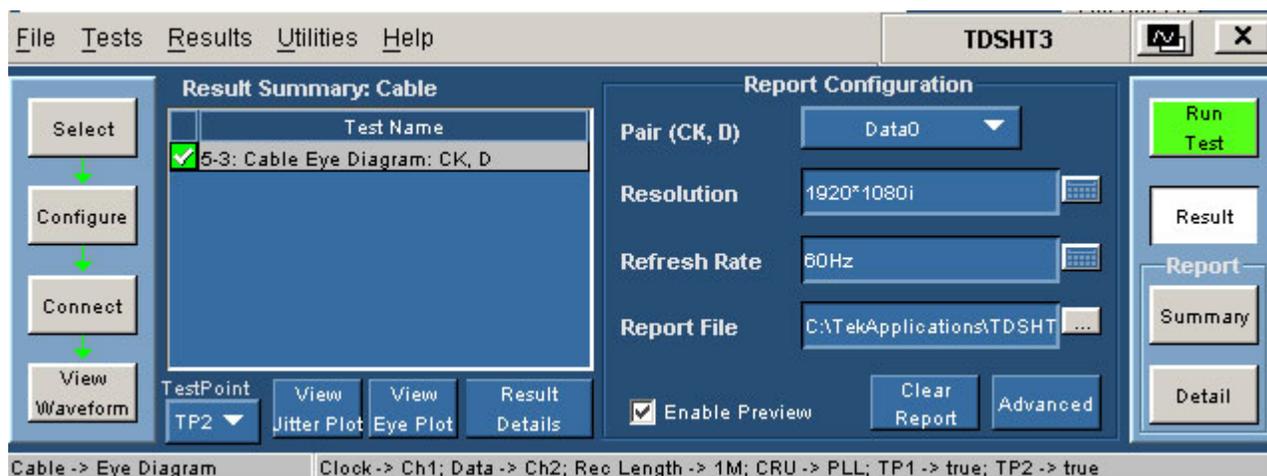


Figure 221: Result for Cable Eye Diagram

Table 141: Result for Cable Eye Diagram

| Option | Description |
|------------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Status | Status indicates the status of the test as Pass, Fail, or Error. |
| TestPoint | You can check the input test signal at TP1, and verify the output of the cable, for compliance, at TP2. From the TestPoint list, select either TP1 or TP2 to view the respective details. |
| View Jitter Plot | Click View Jitter Plot to view the jitter plot for the selected test point for the eye diagram test. |
| View Eye Plot | Click View Eye Plot to view the eye plot for the selected test point for the eye diagram test. |
| Result Details | Click Result Details to display the details of the result. |

Report Configuration pane

You can set the report details to identify and generate the report automatically. You can set a default report file.

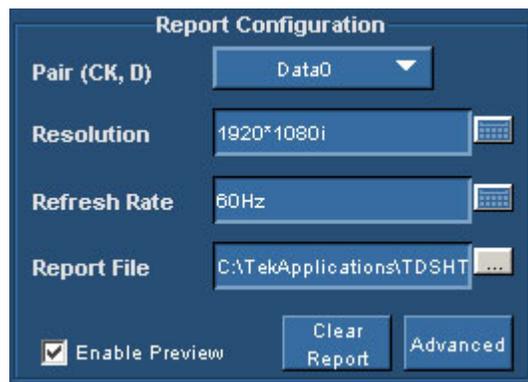


Figure 222: Report Configuration for Cable Eye Diagram

In the report configuration pane, you can configure the following parameters:

Table 142: Report Configuration options for Cable Eye Diagram

| Category | Description |
|----------------|--|
| Pair (CK, D) | The Pair (CK, D) list allows you to specify the unique pairs on which the test is conducted. |
| Resolution | The Resolution box allows you to specify the resolution on which the test is conducted. |
| Refresh Rate | The Refresh Rate box allows you to specify the refresh rate at which the test is conducted. |
| Report File | The Report File box allows you to specify the path and the file where the generated report will be saved. However, for the selected speed, a default file name and path already exists. |
| Enable Preview | Select the Enable Preview check box to preview the report automatically after generation. |
| Clear Report | Click Clear Report to clear all the results and records of the earlier tests. |
| Advanced | Click Advanced to open the Report Configuration Advanced dialog box. |

- In the result summary pane, click **Result Details** to display the details of the result.



Figure 223: Result Details for Cable Eye Diagram

Table 143: Result Details for Cable Eye Diagram

| Option | Description |
|-------------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal name - CK (Clock), D (Data). |
| Spec Range | The Spec Range box displays the HDMI standards and test specifications limit for the test. |
| Meas Value | The Meas Value box displays the measured value. |
| Result | The Result box displays the status of the test as Pass, Fail, or Error. |
| Remarks/Comments | The Remarks/Comments box displays the relevant details, for example, Tbit, and Margin. If the test could not be run, then an error code appears. |
| Close | Click Close to quit the Result Details dialog box. |
| TestPoint | You can check the input test signal at TP1, and verify the output of the cable, for compliance, at TP2. From the TestPoint list, select either TP1 or TP2 to view the respective details. |
| View Jitter Plot | Click View Jitter Plot to view the jitter plot for the selected test point for the eye diagram test. |
| View Eye Plot | Click View Eye Plot to view the eye plot for the selected test point for the eye diagram test. |
| Result Statistics | Click Result Statistics to display statistics based on the tests. |

20. In the **Result Details** dialog box, click **Result Statistics** to display statistics based on the tests.

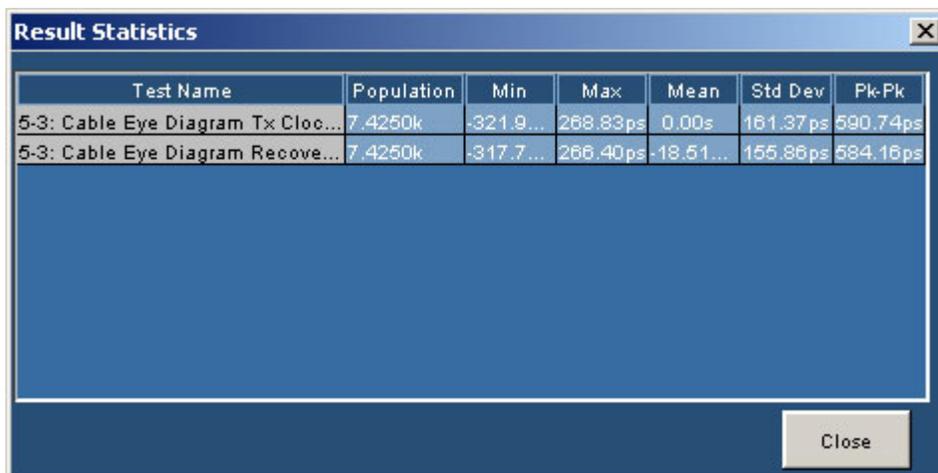


Figure 224: Result Statistics for Cable Eye Diagram

The software calculates statistics for each selected test, and logs the statistics on a cycle-by-cycle basis in a large waveform. The standard statistics are for the Maximum, Minimum, Mean, Standard Deviation, and Population.

Table 144: Result Statistics for Cable Eye Diagram

| Option | Description |
|------------|--|
| Test Name | The Test Name box displays the test id, test name, and signal names - CK (Clock), D (Data). |
| Population | The software calculates this statistic by using the following equation: Population (X) = N |
| Min | The software calculates this statistic by using the following equation: Min (X) = Lowest value of X |
| Max | The software calculates this statistic by using the following equation: Max (X) = Highest value of X |
| Mean | The software calculates this statistic by using the following equation: $Mean (X) = \bar{X} = \frac{1}{N} \sum_{n=1}^N X_n$ |

Table 144: Result Statistics for Cable Eye Diagram (Contd.)

| Option | Description |
|---------|---|
| Std Dev | <p>The software calculates this statistic by using the following equation:</p> $\text{Standard Deviation (X)} = \sigma_x = \sqrt{\frac{1}{(N-1)} \sum_{n=1}^N (X_n - \bar{X})^2}$ |
| Pk-Pk | <p>The software calculates this statistic by using the following equation: $X_{ppn} = \text{Max}(X) - \text{Min}(X)$</p> |
| Close | Click Close to quit the Result Statistics dialog box. |

Measurement Algorithms

Software CRU Technology

The HDMI specification mandates the Clock Recovery Unit (CRU) by using a Phase Locked Loop (PLL) with first order transfer function characteristics, to test both the jitter and the eye diagram. A PLL-based CRU implemented in hardware makes correlation of test results difficult due to differences in vendor-specific implementations. There are software PLL techniques that exist to extract clock and timing data from a serial data stream. The following method shows a more practical and affordable way to satisfy the requirement:

PLL Characteristics

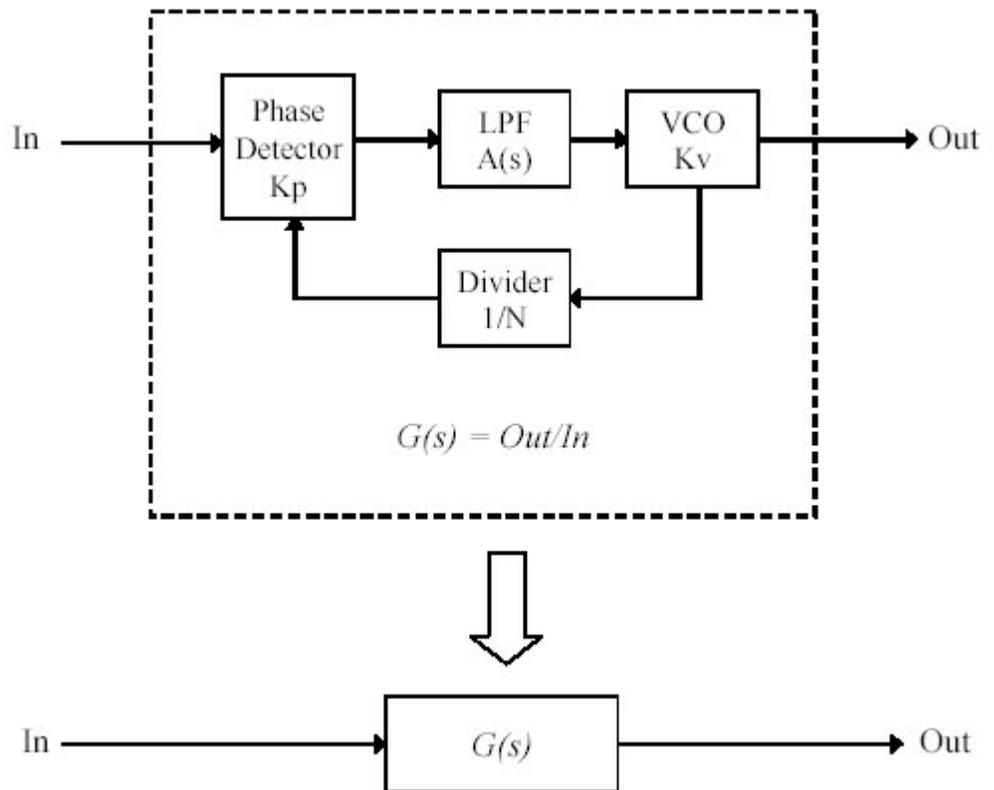


Figure 225: PLL design for CRU implementation

The diagram shows a simplified block diagram of generic phase-locked loop (PLL). A PLL consists of the Phase Detector (PD), Low-Pass Filter (LPF), Voltage Controlled Oscillator (VCO), and Frequency Divider (FD).

The phase of the input signal is compared to the phase of FD output. The input of the FD is the output of VCO, whose frequency is controlled by the LPF output. The LPF output is a filtered form of the PD output. When the phase of FD output is leading compared to the input phase, the PD output changes to decrease the VCO frequency. Thus, the FD output will lag. Due to the effect of this feedback mechanism, the frequency of VCO is locked to N-times of the input frequency.

The LPF restricts the quick variation of the incoming signal, so that high frequency changes in the input phase are attenuated before they are transferred to consecutive functional blocks. Therefore, the VCO output represents the average phase of input signal even if the input signal does not have the constant phase rotation (frequency). Using this approach, the PLL circuitry recovers the clock information from the modulated input signal.

The transfer function from the input phase to the output phase is represented by following equation:

$$G(s) = \frac{\frac{K_p \cdot K_v \cdot H(s)}{s}}{1 + \frac{K_p \cdot K_v \cdot H(s)}{s \cdot N}} = \frac{N \cdot K_p \cdot K_v \cdot H(s)}{s \cdot N + K_p \cdot K_v \cdot H(s)}$$

where K_p and K_v are the sensitivity coefficients of PD and VCO respectively, and N is the division factor of FD. $H(s)$ is the transfer function of LPF in the frequency domain.

Assuming that N , K_p , and K_v are constant, the function $G(s)$ can be simplified as follows:

$$G(s) = \frac{K_2 \cdot H(s)}{s + K_1 \cdot H(s)}$$

Note that $G(s)$ becomes the first order low-pass filter only when $H(s)$ is constant, namely when $H(s)$ is non-dependent on the frequency. This means that $H(s)$ is not a low-pass filter in this case. On the contrary, it is well known that the PLL is not stable without a low-pass filter in place of $H(s)$. Therefore, the first order transfer function that is required by CRU for HDMI may not be realized by the PLL circuitry as shown in the earlier PLL Functional Block diagram.

Conventional Method

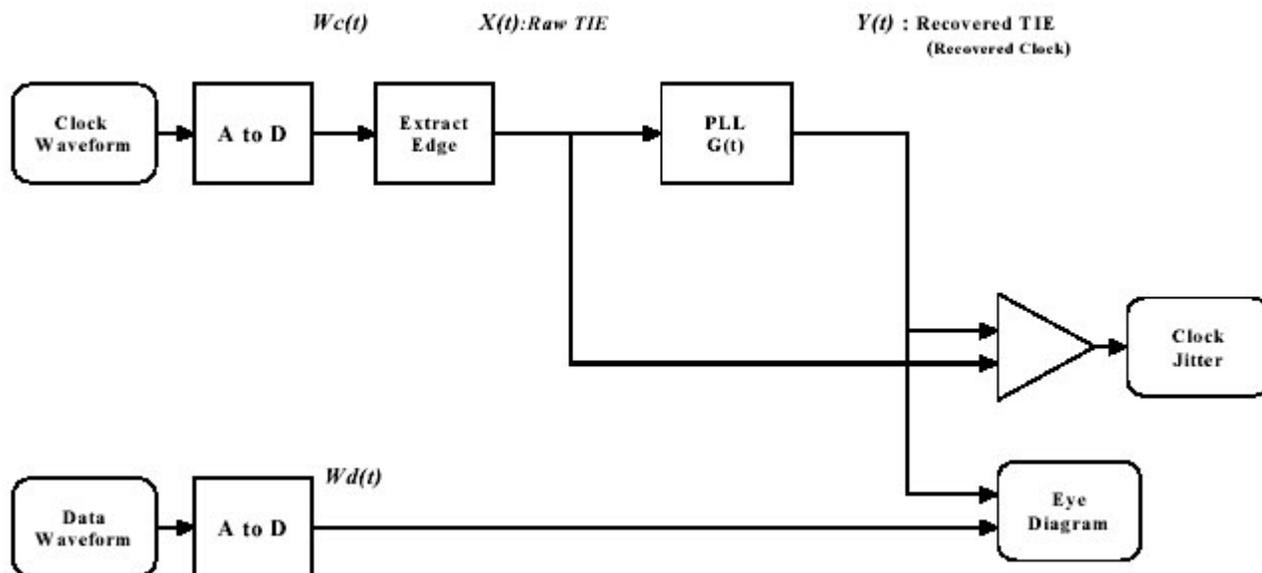


Figure 226: Conventional diagram of PLL design for CRU implementation

The diagram shows a simple PLL design for CRU, measuring both the clock jitter and eye diagram within a digital oscilloscope. The input signal is first converted to digital information with an A/D converter. The phase of the input signal is extracted by finding the rising (or falling) edges of the digitized signal. A digital simulation of an actual hardware PLL circuit may be realized because the input and output signals exist as just digital information. In this case, the voltage values at several points in the PLL circuit are expressed in the time domain, and are repetitively calculated to derive their time variation. The time interval of the calculation must be sufficiently small to retain the high precision of the simulation. Hence, it requires significant digital processing capability to simulate actual PLL within a reasonable amount of time.

In this method, the phase transfer function of the PLL is determined by the characteristics of the simulated components. As long as the simulation observes the laws of physics, the resultant transfer function does not differ from that of the actual hardware PLL circuit. Given the time to process the data in the simulation, using this method is not advisable. Hence, the first order transfer function to be realized by this method may not be useful either.

Another method to simulate a PLL in software is to use its time domain transfer function from the input phase error to output timing information. The impulse response is used as the time domain transfer function. In this case, given the input signal $X(t)$, the integral operation shown next gives the output signal $Y(t)$.

$$Y(t) = \int_{\tau=-\infty}^{\infty} X(\tau) \cdot G(t - \tau) d\tau$$

where $G(t)$ is the time domain representation of $G(s)$ mentioned in the previous section. This is called a convolution integral. In this case, the input signal is represented as discrete-time samples. The integration shown earlier should also be performed in discrete fashion as follows:

$$y(n) = \sum_{m=-\infty}^{\infty} g(m) \cdot x(n - m) = \sum_{m=-\infty}^{\infty} g(n - m) \cdot x(m)$$

There are two disadvantages in the time domain convolution method. One is that it still requires a huge number of multiplications and additions to calculate the values of all time points, as easily seen from the form of the equation above. Another is that it is not always practical to express the time domain transfer function as an explicit mathematical representation. In many cases, the human interpretation of the transfer function is made in frequency domain. Some means of conversion is required to derive the time domain response from the frequency domain characteristics. This requirement will complicate the design of the user interface.

It is important to mention that the first order transfer function characteristics can be realized by this convolution method, even though it has the difficulties described earlier. This method is inherently stable as far as an appropriate impulse response is adopted, because it does not include a feedback loop.

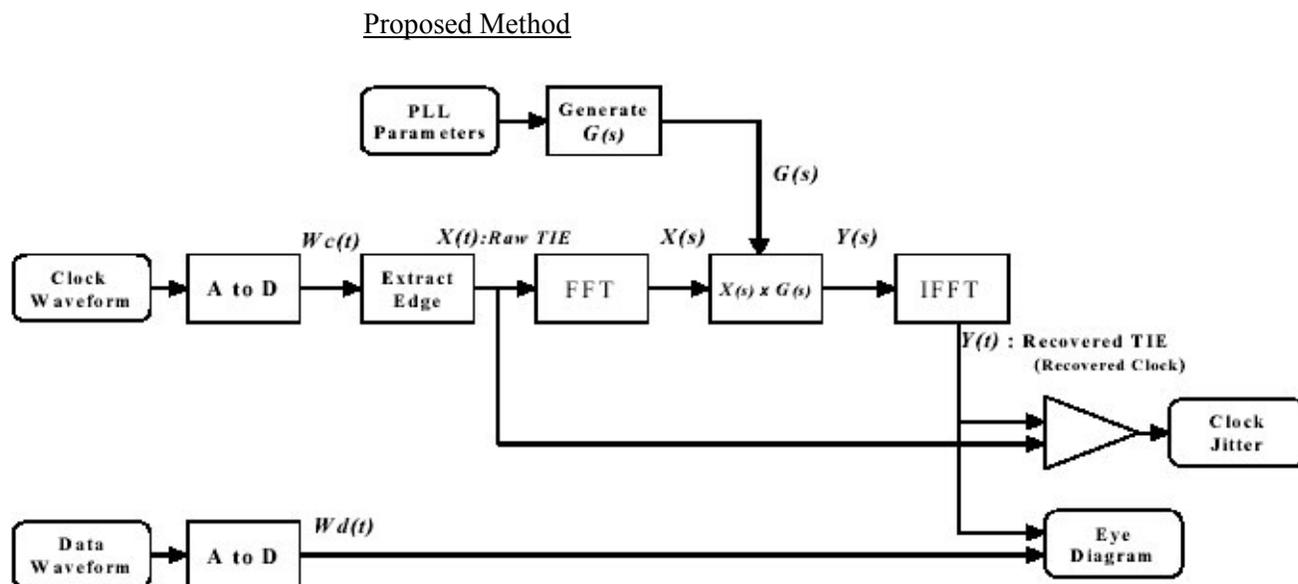


Figure 227: Proposed diagram of PLL design for CRU implementation

The PLL circuitry acts as a low-pass filter for incoming time information. In the frequency domain, the filter function is realized by multiplying the frequency response coefficients to the input spectrum. The convolution integral in the time domain is equivalent to simple multiplication between frequency-domain functions derived by the Fourier Transform. If the time information and the PLL characteristics are transformed to frequency domain, the PLL processing becomes much easier than in the time domain.

$$Y(s) = G(s) \cdot X(s)$$

As seen in this equation, the calculation becomes one per sample point multiplication (though between complex numbers). Hence, the demand for digital processing performance is low.

After the filter function is performed, the time information of the output signal may be derived with inverse transformation. Using an FFT algorithm, the forward and inverse transformation can be executed in relatively short time compared to simulation in time domain. Thus, the total time to calculate the recovered clock can be significantly reduced.

Jitter Test

The jitter of the incoming clock signal is measured by statistically analyzing the time difference between the incoming and recovered clocks. The timing information of both signals is already retained in digital form, so the jitter calculation is simple and straightforward. Usually, the peak-to-peak jitter value and the standard deviation (RMS) jitter value are used for evaluating the signal quality.

$$J_{pp} = \Delta T_{\max} - \Delta T_{\min}$$

$$J_{\sigma} = \sqrt{\frac{\sum (\Delta T_n - \overline{\Delta T})^2}{N}}$$

Appropriate sample points should be chosen to measure the jitter for specific cases such as the clock-to-data jitter at the first bit. Such a requirement is addressed by specifying a rectangular area with time range of $[-T..+T]$ and voltage range of $[-V..+V]$.

To obtain an accurate test, a large number of samples are required. As the earlier area restriction reduces the number of measured samples, the capability to process more and more samples is desired. Using the proposed method, it becomes realistic to gather a huge amount of statistical information for a more precise test.

Eye Diagram

An eye diagram is the incoming data waveform repeatedly drawn with the recovered clock used as the time reference. The recovered clock is represented as time information. Hence, it may be used to derive the position where the input data waveform should be drawn. The resulting diagram will precisely indicate the true marginal area with which the reliability of data transmission is determined.

The vertical coordinate to draw the incoming waveform is determined by using the data value itself. Determine the horizontal coordinate (x) by the following equation:

$$X_{coord} = T_n - T_{ref}$$

where T_n is the time of incoming waveform, and T_{ref} is the time of the reference signal (the recovered clock signal).

Test Methods

Source

Eye Diagram

This sequence explains the actions that the software takes while it performs an eye diagram test. For the procedure on how to make this test, see eye diagram test procedure.

1. Connect TPA-P-TDR to the Source DUT HDMI output connector.
2. Connect the SMA differential probes to TMDS Clock and configure as trigger.
3. Connect the second differential probe to TMDS Data.
4. Configure the Source DUT to output the first supported video format.
5. Set up the oscilloscope as follows:
 - Memory length of at least 16 M points
 - Single-shot trigger at rising edge of TMDS Clock (50 percent)
 - Sampling rate of at least 10 GS/s
 - Adjust the vertical scale to accommodate the waveform in six vertical divisions
6. Capture the waveforms on the oscilloscope.

Note: Do not transfer the waveforms.

7. Perform software clock recovery as follows:
 - Find V_H and V_L of both clock and data.
 - Find 50 percent reference level of the clock.
 - Pass the TIE values through the filter (FFT and IFFT) $H(s) = 1/(1+s\tau)$, where $\tau = 40$ nsec.

- Reconstruct the clock, and then create a bit clock (x10 clock) by using even up sampling.
8. Draw the eye diagram.
 - x10 clock is used for slicing.
 - Draw the eye diagram with $\frac{1}{2} \text{UI} + \text{UI} + \frac{1}{2} \text{UI}$ method. This will ensure that all UIs are overlapped.
 9. Create eye mask.
 - Calculate V_{SWING} by using V_{H} and V_{L} of the data.
 - Construct the mask co-ordinate by using T_{BIT} and V_{SWING} .
 10. Position the mask in such a way that one of its left side corners just touches the waveform.
 11. If any other part of the waveform either touches or crosses the data eye, then it implies FAIL.
 12. Calculate the data jitter by using the histogram technique. The histogram co-ordinates are $V_{\text{C}} \pm 5 \text{ mV}$.
 13. If data jitter is more than $(0.3 * T_{\text{BIT}})$, then it implies FAIL.
 14. Repeat the test for all the remaining TMDS_DATA pairs.
 15. Repeat the test for all supported pixel clock rates. Only one video format is required per pixel clock rate.

Duty Cycle

This sequence explains the actions that the software takes while it performs a duty cycle test. For the procedure on how to make this test, see duty cycle test procedure.

1. Connect a TPA-P-DI adapter to the Source DUT HDMI output connector.
2. Configure the Source DUT to output a video format with the required supported pixel clock frequency.
3. Connect a differential probe to the TMDS Clock.
4. Display the waveform of one clock period.

5. Set up the oscilloscope as follows:
 - Adjust the vertical scale to accommodate the waveform in six vertical divisions (Refer vertical setting).
 - Trigger: Edge trigger.
 - Acquire at least 10,000 waveforms in FastAcq.
6. Find the minimum and maximum duty cycle by using the following method:

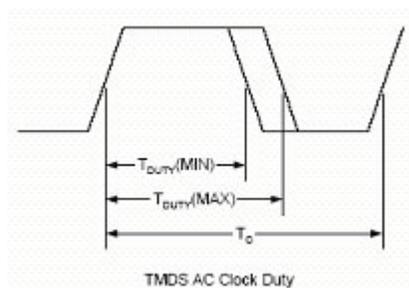


Figure 228: TMD5 AC Clock waveform

7. Compare with the limit value.
 - If minimum duty cycle is more than 40 percent, then it implies PASS.
 - If maximum duty cycle is less than 60 percent, then it implies PASS.

Rise/Fall Time

This sequence explains the actions that the software takes while it performs a rise/fall time test. For the procedure on how to make this test, see rise time test procedure and fall time test procedure.

1. Connect a TPA-P-DI adapter to the Source DUT HDMI output connector.
2. Connect the Power Supply to the TPA board.
3. Configure the Source DUT to output a video format with the required supported pixel clock frequency.
4. Connect a differential probe to TMD5_DATA0 and configure as trigger.
5. Set the trigger position at the center of the screen.

6. Set up the oscilloscope as follows:
 - Calculate T_{BIT} by using differential clock.
 - Set the vertical scale to accommodate the waveform in at least six divisions.
 - Set the horizontal scale to more than $2 * T_{BIT}$.
 - If pulse width trigger is selected, Trigger with pulse width trigger with $(4 * T_{BIT})$ pulse. or trigger with edge trigger.
7. Accumulate at least 10,000 triggered waveforms by acquiring the waveform in FastAcq mode of acquisition.
8. Calculate V_{SWING} of the signal ($V_{SWING} = V_H - V_L$), and then find the 20 percent and 80 percent of the level.
9. Measure the rise time and fall time.
 - Enable the oscilloscope rise time measurement. Set the reference level to 20 percent and 80 percent.
 - Acquire at least 10 K waveforms (RUN and STOP).
 - Calculate the rise time.
 - Set the trigger to negative pulse.
 - Enable the oscilloscope rise time measurement.
 - Acquire at least 10 K waveforms (RUN and STOP).
 - Calculate the fall time.
10. Compare with the limit.
 - If T_{RISE} is less than 75 ps or T_{RISE} is more than $(0.4 * T_{BIT})$, then it implies FAIL.
 - If T_{FALL} is less than 75 ps or T_{FALL} is more than $(0.4 * T_{BIT})$, then it implies FAIL.
11. Repeat the test for all the remaining TMDS clock and data pairs.

Clock Jitter

This sequence explains the actions that the software takes while it performs a clock jitter test. For the procedure on how to make this test, see clock jitter test procedure.

1. Connect TPA-P-DI to the Source DUT HDMI output connector.
2. Connect the differential probe to the TMDS Clock and configure as trigger.
3. Connect the second differential probe to TMDS_CLOCK.
4. Configure the Source DUT to output the required supported video format.
5. Set up the oscilloscope as follows:
 - Adjust the vertical scale to accommodate the waveform in six vertical divisions.
 - Set the record length to 16 M.
 - Set the sample rate to 10 Gs/Sec.
 - Trigger with the rising edge of the clock (50 percent level).
6. Capture the waveforms on the oscilloscope.
7. Do not transfer the waveforms.
8. Perform software clock recovery as follows:
 - Set the reference level to 50 percent of the clock and hysteresis to 10 percent of V_{SWING} .
 - Calculate the Software CRU filter as follows.
 - $H(s) = 1/(1+s\tau)$, where $\tau = 40$ nsec.
9. Draw the TMDS waveform with positive edge trigger.
10. Measure the clock jitter as follows:
 - Calculate V_{SWING} by using V_{H} and V_{L} of the clock.
 - Calculate the center voltage as follows:
 - $V_{\text{C}} = (V_{\text{H}}+V_{\text{L}})/2$
 - Draw the histogram at $V_{\text{C}}\pm 20$ mV.
 - Calculate Pk-Pk jitter and 'Interpolated' Pk-pk jitter.

11. If clock jitter exceeds ($0.25 \cdot T_{\text{BIT}}$), then it implies FAIL.

Overshoot/Undershoot

This sequence explains the actions that the software takes while it performs an overshoot/undershoot test. For the procedure on how to make this test, see over/undershoot V-H test procedure and over/undershoot V-L test procedure.

1. Connect an TPA-P-TDR adapter to the Source DUT HDMI output connector.
2. Control the Source DUT to output a video format with the required supported pixel clock frequency.
3. Connect a SMA differential probe to TMDS_DATA0 and TMDS_CLOCK.
4. Set up the oscilloscope and acquire the waveform.
 - Calculate T_{BIT} by using differential clock.
 - Set the vertical scale to accommodate the waveform in at least six divisions.
 - Set the horizontal scale to ($2 \cdot T_{\text{BIT}}$).
 - Trigger with pulse width trigger with ($4 \cdot T_{\text{BIT}}$) pulse (rising edge).
 - Acquire the waveform with FastAcq.
 - Acquire at least 10 K waveforms (RUN and STOP).

5. Measure the values V_H , V_L , V_{H+} , V_{H-} , V_{L+} , and V_{L-} by using the following method:
 - Measure the peak voltage (V_{H+}).
 - Measure the least voltage after the dip (V_{H-}).
 - Trigger with pulse width trigger with ($4 \cdot T_{BIT}$) pulse (falling edge).
 - Measure the minimum voltage (V_{L-}).
 - Measure the least voltage after the dip (V_{L+}).
 - Calculate $V_{DIFFSWING}$ ($V_H - V_L$).
 - Calculate overshoot and undershoot as follows:
 - Overshoot = $\max\{\text{abs}(V_{H+}) \text{ and } \text{abs}(V_{L-})\}$
 - Undershoot = $\max\{\text{abs}(V_{L+}) \text{ and } \text{abs}(V_{H-})\}$
 - If overshoot is more than 15 percent of $V_{DIFFSWING}$, then it implies FAIL.
 - If undershoot is more than 25 percent of $V_{DIFFSWING}$, then it implies FAIL.
 - Repeat for all the remaining TMDS clock and data (+ and -) signals.

Inter-Pair Skew

This sequence explains the actions that the software takes while it performs an inter-pair skew test. For the procedure on how to make this test, see inter-pair skew test procedure for clock-data tests and inter-pair skew test procedure for data-data tests.

1. Connect a TPA-P-DI adapter to the Source DUT HDMI output connector.
2. Connect the first differential probe to TMDS_DATA0.
3. Connect the second differential probe to TMDS_DATA1.
4. Configure the Source DUT to output a video format with the required supported pixel clock frequency.

5. Set up the oscilloscope and acquire the waveform.
 - Trigger with CTL pattern by using serial trigger.
 - Adjust the vertical scale to accommodate the waveform in six vertical divisions.
 - Calculate T_{BIT} by using differential clock.
 - Set the horizontal scale to at least $20 * T_{BIT}$ ($2 * T_{bit}$ per division).
 - Set the horizontal trigger position to 80%.
 - Trigger with CTL pattern (1101010100) this requires Option ST.
 - Set the bit rate based on the T_{BIT} value.
 - Acquire the waveform in real-time single shot.
6. Calculate the skew as follows:
 - For data-data inter-pair skew:
 - Find the CTL pattern in Data<X>.
 - Find the CTL pattern in Data<Y>.
 - Find the skew between the two channels in each transition.
 - Calculate the average skew.
 - For data-clock inter-pair skew:
 - Find the CTL pattern in Data<X>.
 - Find the rising edge of the clock.
 - Find the skew between the two rising edges.
6. If T_{SKEW} is less than $(0.2 * T_{PIXEL})$, then it implies FAIL.
7. Repeat the test for the remaining combinations of TMDS pairs.

Intra-Pair Skew

This sequence explains the actions that the software takes while it performs an intra-pair skew test. For the procedure on how to make this test, see intra-pair skew test procedure.

1. Connect a TPA-P-SE adapter to the Source DUT HDMI output connector.
2. Connect the first single-ended probe to TMDS_DATA0+.
3. Connect the second single-ended probe to TMDS_DATA0-.
4. Configure the Source DUT to output a video format with the highest supported pixel clock frequency.
5. Set up the oscilloscope as follows:
 - Calculate T_{BIT} by using differential clock.
 - Adjust the vertical scale to accommodate the waveform in six vertical divisions.
 - Set the horizontal scale to $(2 * T_{BIT})$.
 - Trigger with edge trigger of Data+ (Rising edge with 50 percent level).
6. Display the waveform of TMDS_DATA0+ and DATA0-. Accumulate at least 10,000 triggers by acquiring the waveform in FastAcq mode.
7. Determine the most common TMDS_DATA0- 50 percent point by using the histogram method.
8. Measure skew from most common TMDS_DATA0+ point to 50 percent point of first edge of TMDS_DATA0-.
8. If skew is less than $(0.15 * T_{BIT})$, then it implies FAIL.
9. Repeat the test for all the remaining TMDS differential pairs.

Sink

Min/Max-Diff Swing Tolerance

This sequence explains the actions that the software takes while it performs a min/max-differential swing tolerance test. For the procedure on how to make this test, see min/max-diff swing tolerance test procedure.

1. Configure the DTG to output any sink-supported video format.
 - Load the pattern that contains repeating RGB gray ramp 0, 1, 2...254, 255, 0, 1, 2... during each video period.
 - Map all the logical channels to physical channels.
 - Run the DTG.
 - Enable all the output channels.
2. Search for and record the minimum differential swing voltage that the Sink DUT supports without error at $V_{ICM} = 3.0$ V.
 - Set $V_{ICM} = 3.0$ V.
 - Set $V_{DIFF} = 170$ mV on all TMDS differential pairs. (Note that 'Amplitude and Offset' mode in the DTG 'Level' window should be chosen. In this mode, 'Amplitude' should be set to 0.085 Vpp to correspond to a 170 mV differential swing.)
 - Reduce V_{DIFF} , in 20 mV steps (corresponding to 0.01 Vpp steps in the 'Amplitude' setting), on all pairs until the Sink DUT outputs errors or V_{DIFF} of 70 mV is reached.
 - Record V_{DIFF} {minimum} at first voltage level where no error appears.
 - If V_{DIFF} {minimum} is more than or equal to 150 mV, then it implies FAIL.
3. Repeat the test for $V_{ICM} = 3.3$ V.

4. Verify the maximum differential voltage that the Sink DUT supports.
 - Set $V_{DIFF} = 1.2$ V on all TMDS differential pairs. (Note that 'Amplitude and Offset' mode in the DTG 'Level' window should be chosen. In this mode, 'Amplitude' should be set to 0.6 V_{pp} to correspond to a 1.2 V differential swing.)
 - Verify that the DUT continues to support the signal without errors.
 - If DUT fails to support the signal, then it implies FAIL.

Intra-Pair Skew

This sequence explains the actions that the software takes while it performs an intra-pair skew test. For the procedure on how to make this test, see intra-pair skew test procedure.

1. Configure the DTG to output any sink-supported video format that uses the maximum sink-supported pixel clock frequency. If multiple formats are available, a native format is preferred.
2. Calculate Tbit by using the differential clock.
3. For each of the TMDS clock and data pairs that act as the tested pair:
 - Set the delay for all outputs to 0 ns. Disable 'Differential Timing Offset' if it is previously enabled.
 - Move the TMDS '+' signal of the tested pair to DTG output module A, 1+.
 - Move the TMDS '-' signal of the tested pair to DTG output module A, 2+.
 - Change the DTG configuration to output the pattern for the tested TMDS channel on module A, 1.
4. In the DTG 'Timing,' set the tested channel (connected to 1A1) and enable 'Differential Timing Offset.'
5. Set the delay value in the differential timing offset to approximately $(0.1 * T_{BIT})$. This corresponds to the initial intra-pair skew value.
6. Increase the skew (Differential Timing Offset) by steps of less than or equal to $(0.1 * T_{BIT})$, until the Sink DUT outputs errors or until reaching either $(0.6 * T_{BIT})$ or 1 nsec.
7. If errors are seen on DUT, then:

- Reduce the skew one step, so that the Sink DUT outputs no errors.
- If intra-pair skew is less than $(0.4 * T_{BIT})$, then it implies FAIL.

Jitter Tolerance

This sequence explains the actions that the software takes while it performs a jitter tolerance test. For the procedure on how to make this test, see jitter tolerance test procedure.

1. Operate the Sink DUT to support the HDMI input signal.
2. Configure the DTG as follows:
 - Load the appropriate pattern in the DTG
 - No jitter on any output
3. Configure the AWG as follows:
 - Under 'Vertical' menu, set the following:
 - Filter-through
 - Amplitude = 0.5 V_{pp}
 - Offset = 0 V
 - Marker 1 = 0.00 V to 1.00 V
 - Marker 2 = 0.00 V to 2.00 V
 - No jitter on output initially, with ability to add two simultaneous jitter components.
4. Determine and use the worst-case TMDS_CLOCK to TMDS_DATA skew condition for the Sink DUT.
 - Connect the signals to DUT by using cable emulator.
 - Use binary search algorithm to find out the worst skew.
 - Set the DTG delay on all channels to this worst-case skew.
5. Measure jitter tolerance while verifying adequate support by sink.
 - For each of the two test cases:
 - D_JITTER = 500 kHz, C_JITTER = 10 MHz
 - D_JITTER = 1 MHz, C_JITTER = 7 MHz

6. The initialization sequence is as follows:
 - Set C_JITTER and D_JITTER amplitudes to levels at which $(0.3 * T_{BIT})$ of jitter is present on the TMDS_CLOCK pair as well as the output eye diagram of the TNDS_DATA pairs at the sink is worst case.
 - Create the eye diagram similar to the source eye diagram test.
 - Check the violation with sink minimum eye mask.
 - The data jitter component used in AWG is called as $D_{jw} [T_{BIT}]$.
7. Check the C_JITTER worst condition.
 - Set the C_JITTER component to $(0.3 * T_{BIT})$ in the equation.
 - Create and load the waveform in the AWG.
 - Connect the clock to the oscilloscope. Measure the C_JITTER value by using the source jitter measurement.
 - Readjust the equation. Create the C_JITTER component to $(0.3 * T_{BIT})$ (+/-2 percent).
 - Connect the signal to the DUT.
 - Increase the D_JITTER component from $(0.5 * T_{BIT})$ in steps of $(0.05 * T_{BIT})$ until the sink adequately supports the signal.
 - If the DUT fails, set the last supported jitter values in the AWG.
 - Connect the signals to the oscilloscope.
 - Measure D_JITTER by using the source eye diagram measurement. Find the maximum supported D_JITTER amplitude.
 - If maximum supported jitter is less than $(D_{jw} * T_{BIT})$, then it implies FAIL.

8. Check for the D_JITTER worst condition.
 - Set the D_JITTER component to $(D_{jw} * T_{BIT})$ in the AWG equation file.
 - Load the waveform in the AWG.
 - Connect the clock to the oscilloscope. Measure the C_JITTER value by using the source jitter measurement.
 - Readjust the equation. Create the D_JITTER component to $(D_{jw} * T_{BIT})$ (+/-2 percent).
 - Connect the signal to the DUT.
 - Increase the C_JITTER component from $(0.3 * T_{BIT})$ in steps of $(0.1 * T_{BIT})$ until the sink either fails to adequately support the signal or until testing at $(0.5 * T_{BIT})$ value.
 - If the DUT fails, set the last supported jitter values in the AWG.
 - Connect the signals to the oscilloscope.
 - Measure C_JITTER by using the source eye diagram measurement technique. This C_JITTER is the maximum supported C_JITTER amplitude at worst case D_JITTER.
 - If maximum supported C_JITTER amplitude is less than $(0.3 * T_{BIT})$, then it implies FAIL.
9. If the maximum supported C_JITTER amplitude is greater than or equal to $(0.3 * T_{BIT})$ and the D_JITTER amplitude is greater than or equal to D_{jw} , then it implies PASS.

Cable

Eye Diagram

This sequence explains the actions that the software takes while it performs an eye diagram test. For the procedure on how to make this test, see eye diagram test procedure.

1. Configure the DTG to output a video format corresponding to the specified bandwidth of the cable. If no bandwidth is specified, then configure the DTG to output 1920 x 1080i @ 60 Hz (74.25 MHz pixel clock).
 - Load the appropriate pattern file.
 - Set the logical channel to physical channel mapping.
 - Run the pattern.
 - Enable all the DTG output.
2. Configure the DTG to output worst-case eye as follows:
 - Adjust jitter on TMDS_CLOCK pair to output 0.4 ns at 500 KHz (worst jitter permitted at $(TP1 = 0.3 * T_{BIT})$ at 75 MHz).
 - Adjust the output swing voltage to 500 mV for every TMDS single-ended signal.
 - Using jitter/eye analyzer, measure the TMDS_CLOCK jitter and eye diagram of all the three TMDS_DATA pairs.
 - Repeat and readjust as necessary to create the input worst-case eye diagram.
3. Connect the cable DUT between the TPA-R-TDR and TPA-R-DI adapters.
4. Measure jitter at TPA-R-DI (procedure same as the source eye measurement).
 - If data jitter is greater than 0.67 ns ($= 0.5 * T_{BIT}$ at 75 MHz), then it implies FAIL.
 - Calculate the measurement BOX vertical setting as follows:
 - $V_C = (V_H + V_L) / 2 = \pm 5 \text{ mV}$
 - Test the eye diagram with sink minimum eye mask. If any of the points violates, then it implies FAIL.

5. Adjust the DTG swing voltage to $(V_H, V_L) = (3.3 \text{ V}, 2.9 \text{ V})$ without jitter (clock jitter should remain at the worst case input condition).
6. Measure the eye mask on all the TMDS_DATA channels at CTP2.
7. If any measured eyes do not meet the sink minimum eye mask, then it implies FAIL.

Report Generator

About Report Generator

Report Generator allows you to generate and print reports directly from the oscilloscope. It enhances the TDSHT3 HDMI Compliance Test Software capabilities by simplifying the process of creating and maintaining reports.

Report Generator automates the process of compiling the test results and generating the reports. It allows you to set up the template layout by using either the factory default templates or the custom templates. Report Generator allows you to save files in custom file formats such as .rgt, .rpl, or .rpt. You can also save the generated reports as an .rtf file. Report Generator is integrated with the TDSHT3 HDMI Compliance Test Software. You can also convert rtf to pdf by using third-party software.

How to Start Report Generator

Utilities > Report Generator

You can generate and print reports directly from the oscilloscope.

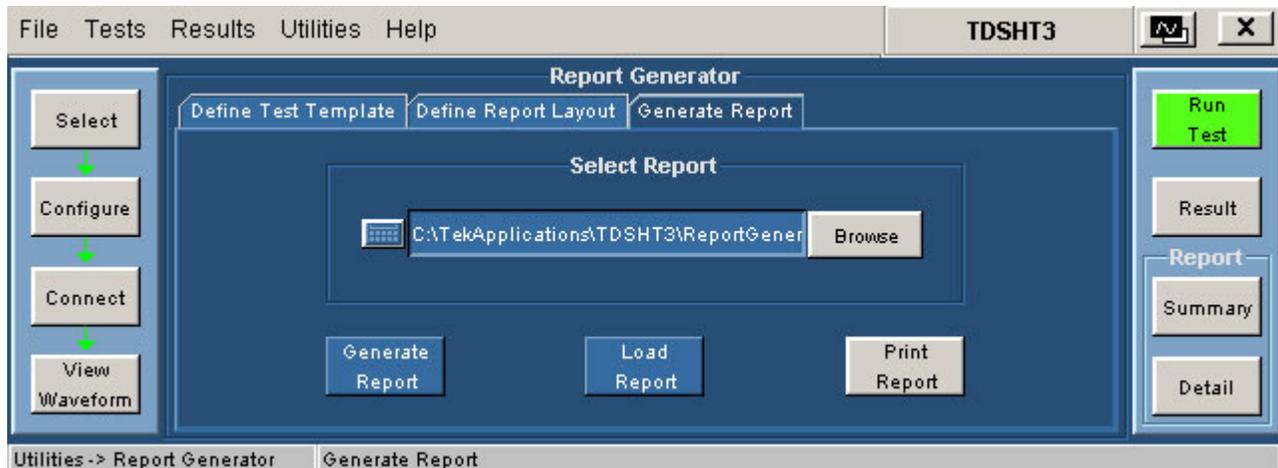


Figure 229: Generate Report pane

Perform the following steps to generate a report:

1. Create a new or edit an existing test template.

2. Define a new or edit an existing report layout.
3. Generate, print, or view a report.

*Note: The report image settings are similar to the existing export settings of the oscilloscope. It is recommended that you use **Graticule(s)** only for Image view setting in export setup.*

Shortcut Keys

Table 145: Shortcut Keys

| Action/Common Key | Shortcut Key |
|------------------------|--------------|
| Open | Ctrl+O |
| Save | Ctrl+S |
| Template Editor | |
| New | Ctrl+N |
| Find | Ctrl+F |
| Replace | Ctrl+H |
| Print | Ctrl+P |
| Cut | Ctrl+X |
| Copy | Ctrl+C |
| Paste | Ctrl+V |
| Delete | Del |
| Select All | Ctrl+A |
| Bring to Front | Ctrl+Plus |
| Send to Back | Ctrl+Minus |
| Edit Text | Alt+Enter |
| Report Layout | |
| New | Ctrl+R+N |
| GoTo | Ctrl+G |
| Refresh Template List | F5 |

Table 145: Shortcut Keys (Contd.)

| Action/Common Key | Shortcut Key |
|-------------------|--------------|
| Report Viewer | |
| Find | Ctrl+F |
| Select All | Ctrl+A |
| Del | Del |
| GoTo | Ctrl+G |
| Bring to Front | Ctrl+Plus |
| Send to Back | Ctrl+Minus |
| Edit Text | Alt+Enter |

How to Operate Report Generator

Template Editor

About Template Editor

The report generator provides you with factory default templates. You can also create your own templates. Use Template Editor to create and edit templates in the .rgt format (report generator template). A template stores the fields and their positions. You can save the templates and reuse them in any number of reports or report layouts. You can cut, copy, and paste across templates. Once the report is generated, the software fills in the fields of the template by using the acquired data from the oscilloscope.

Template Editor has a palette list that displays the following groups of fields: the TDSHT3 Fields, Oscilloscope Fields, and Native Fields. Template Editor allows you to create custom groups; once created, these groups appear in the palette list. The fields are listed according to the group selected. You can use these fields to design and create a template.

You can place the fields in the template, and then move and size them appropriately. Multiple fields can be selected and placed in the template. You can select more than one field and make the following changes: cut, copy, paste, align, delete, size, edit font, and change caption of the fields.

Once a template is defined and saved, either click **Done** to close the Template Editor, or use the **Layout** icon to go directly to the Report Layout Editor.

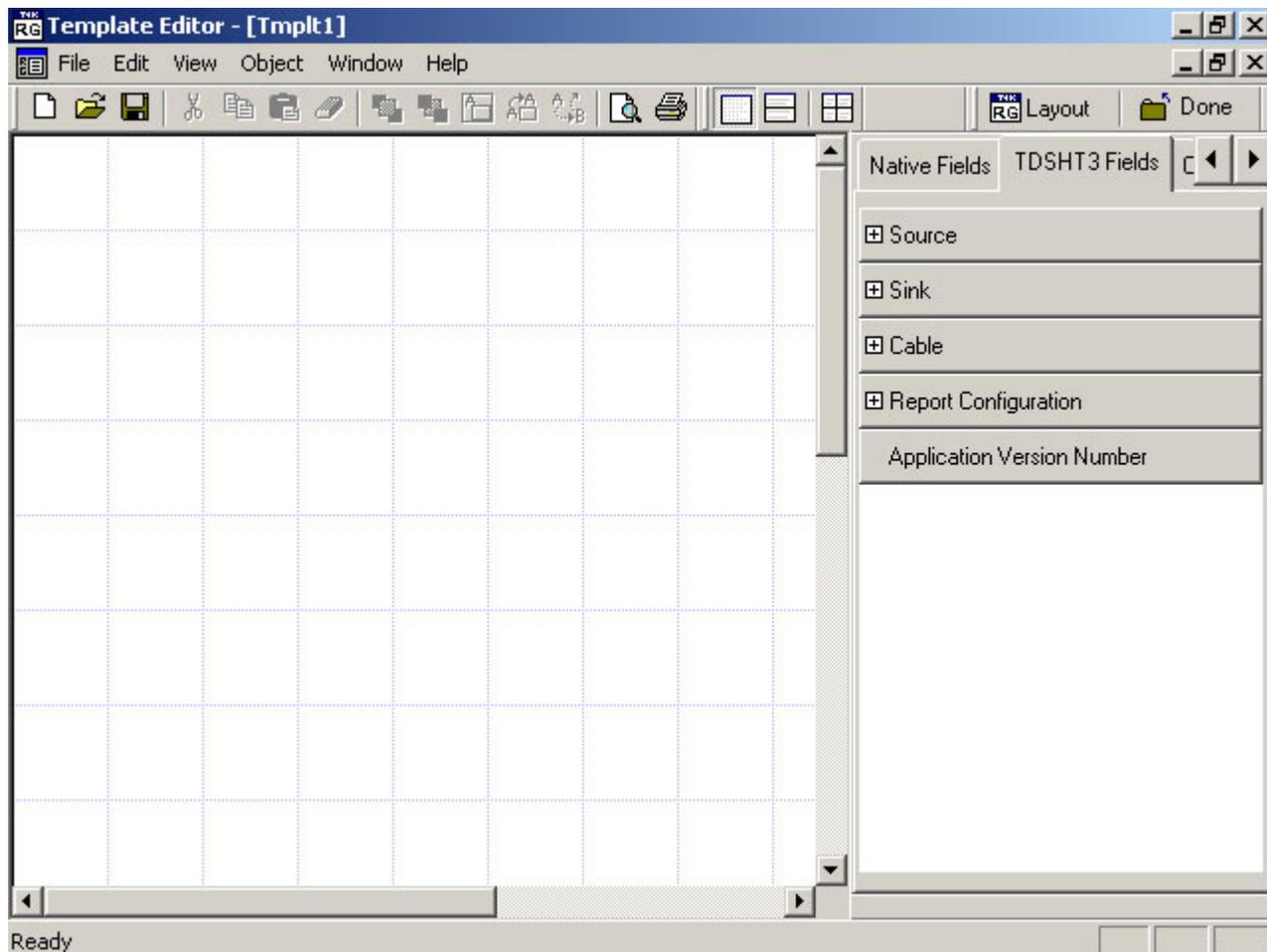


Figure 230: Report Layout Editor

Default Settings

Table 146: Template Editor Default Settings

| Parameter | Selection | Default Setting |
|--------------|----------------------|--|
| Page Size | Change Template Size | The default page size is 8.5 inches x 11 inches. |
| Palette List | None | The palette list displays TDSHT3 fields by default. If there are no TDSHT3 fields, then the oscilloscope fields are displayed. |
| Static Text | Static Text | The static text parameter inserts My Static Text . |
| Fields | None | The default size of the field dragged into the template is 200 pixels x 300 pixels. |

Application View – Template Editor Window

The Template Editor window includes a menu bar, toolbar, client area, palette list, and status bar. When you click **New Template** in the software, the client area in the Template Editor window is empty. When you click **Edit Template** in the software, the client area displays the selected template.

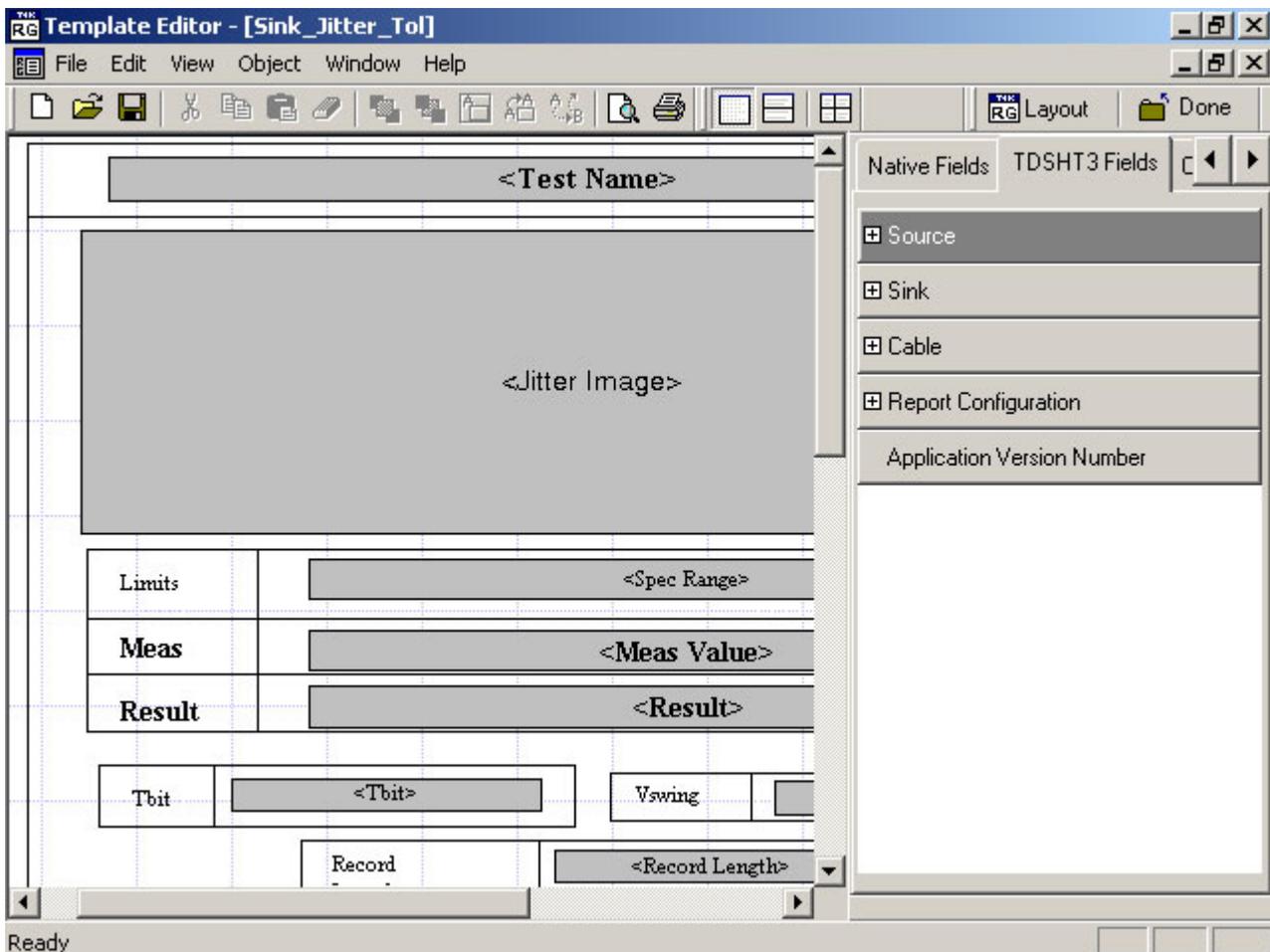


Figure 231: Template Editor Window

Application View – Palette List

View > Palette Toolbar

The palette list is a floating toolbar that has a list of Native Fields, TDSHT3 Fields, and Oscilloscope Fields grouped logically. You can drag and drop fields from the palette list into the template. The palette toolbar is displayed by default. Click **View > Palette Toolbar** to either show or hide the toolbar.

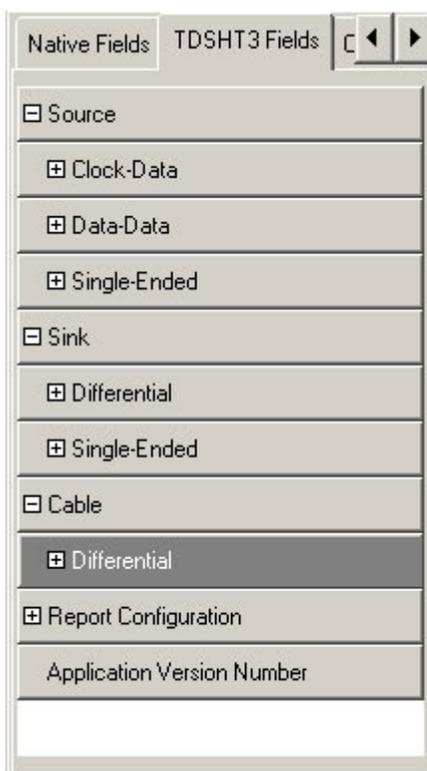


Figure 232: Palette list

The palette list groups the fields into the following categories:

- **Native Fields:** Native Fields are fields such as Static Text, Rectangle, Line, Logo, Table, Date, and Time.
- **TDSHT3 Fields:** TDSHT3 Fields are the fields that are related to the software.
- **Oscilloscope Fields:** Oscilloscope Fields are groups of fields that are related to the data acquired from the oscilloscope.
- **Custom Groups:** Custom Groups represent the custom groups created.

Application View – Palette List – Native Fields

You can enhance the report by using the following parameters from the Native Fields: Static Text, Rectangle, Line, Logo, Table, Date, and Time.

You can drag any field from the Native Field and drop it in the active template.

Static Text

1. From the Native Fields, drag and drop the static text.

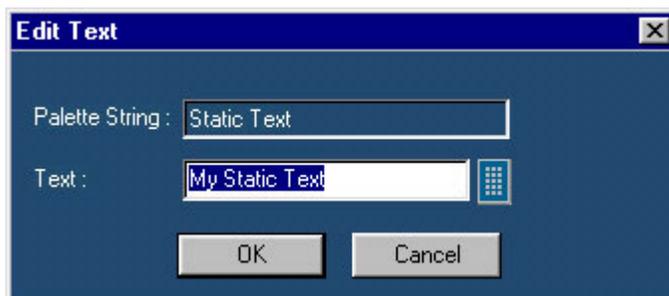


Figure 233: Edit Text dialog box

2. In the **Edit Text** dialog box,
 - Click the icon next to the **Text** box to open the Virtual Keyboard.
 - In the Virtual Keyboard, select the text, and then click **Enter**.
3. Click **OK**.

Rectangle

From the Native Fields, drag and drop the Rectangle into the active template.



The black squares that appear at the corners of the rectangle allow you to increase the size.

Line

From the Native Fields, drag and drop the Line into the active template.



The black squares that appear at the corners of the line allow you to increase the size.

Logo

1. From the Native Fields, drag and drop the Logo into the active template.

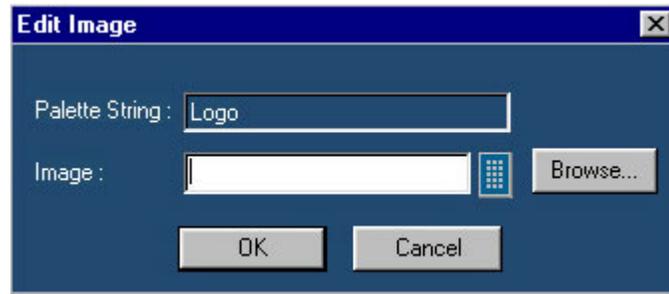


Figure 234: Edit Image dialog box

2. In the **Edit Image** dialog box,
 - Click the icon next to the **Image** box to open the Virtual Keyboard.
 - In the Virtual Keyboard, type the path and filename, and then click **Enter**; or, click **Browse** to navigate to the location where the image is available.
3. Click **OK**.

Table

1. From the Native Fields, drag and drop the Table into the active template.

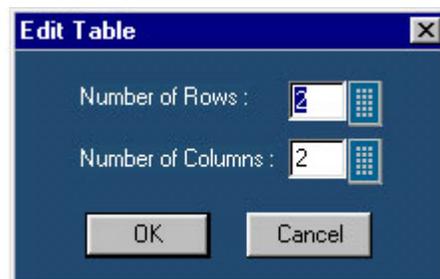


Figure 235: Edit Table dialog box

2. In the **Edit Table** dialog box, you can select the number of rows and columns.
 - Click the icon next to the **Number of Rows** box and the **Number of Columns** box to edit the number.
 - In the Virtual Keyboard, type the number, and then click **Enter**.
3. Click **OK**.

Date and Time

From the Native Fields, drag and drop the Date and Time.

Application View – Palette List – TDSHT3 Fields

Table 147: TDSHT3 Application Fields

| TDSHT3 Fields | | |
|---------------|----------------------------|--------------------------|
| Source | | |
| - Clock-Data | | |
| | - Configuration Parameters | |
| | | - Clock Input |
| | | - Data Input |
| | | - Ref Level Units |
| | | - Hysteresis |
| | | - High Ref Level |
| | | - Mid Ref Level |
| | | - Low Ref Level |
| | | - Number of Acquisitions |
| | | - Record Length |
| | | - Clock |
| | | - Tbit # of Avgs |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|---------------|------------------------|---|
| | - Eye Diagram Results | |
| | | - Statistics - Clock TIE Population - Clock TIE Min - Clock TIE Max - Clock TIE Mean - Clock TIE Std Dev - Clock TIE Pk-Pk - Recovered Clock TIE Population - Recovered Clock TIE Min - Recovered Clock TIE Max - Recovered Clock TIE Mean - Recovered Clock TIE Std Dev - Recovered Clock TIE Pk-Pk |
| | | - Test Name |
| | | - Spec Range |
| | | - Meas Value |
| | | - Result |
| | | - Remarks/Comments |
| | | - Eye Diagram Image |
| | | - Tbit |
| | | - Vswing |
| | | - Oscilloscope Image |
| | | - Mask Hits |
| | - Clock Jitter Results | |
| | | - Statistics - Clock TIE Population - Clock TIE Min - Clock TIE Max - Clock TIE Mean |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|---------------|---------------------------------------|--|
| | | - Clock TIE Std Dev - Clock TIE Pk-Pk - Recovered Clock TIE Population - Recovered Clock TIE Min - Recovered Clock TIE Max - Recovered Clock TIE Mean - Recovered Clock TIE Std Dev - Recovered Clock TIE Pk-Pk |
| | | - Test Name |
| | | - Spec Range |
| | | - Meas Value |
| | | - Result |
| | | - Remarks/Comments |
| | | - Clock Jitter Image |
| | | - Tbit |
| | | - Vswing |
| | | - Oscilloscope Image |
| | - Overshoot/Undershoot V-H Results | |
| | | - Clock Overshoot V-H+ - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Tbit - Vswing - Oscilloscope Image |
| | | - Clock Undershoot V-H- - Test Name - Spec Range |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|---------------|---------------------------------------|---|
| | | <ul style="list-style-type: none"> - Meas Value - Result - Remarks/Comments - Tbit - Vswing - Oscilloscope Image |
| | | <ul style="list-style-type: none"> - Data Overshoot V-H+ - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Tbit - Vswing - Oscilloscope Image |
| | | <ul style="list-style-type: none"> - Data Undershoot V-H- - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Tbit - Vswing - Oscilloscope Image |
| | - Overshoot/Undershoot V-L Results | |
| | | <ul style="list-style-type: none"> - Clock Overshoot V-L- - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Tbit - Vswing |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|---------------|----------------------|---|
| | | - Oscilloscope Image |
| | | - Clock Undershoot V-L+ - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Tbit - Vswing - Oscilloscope Image |
| | | - Data Overshoot V-L- - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Tbit - Vswing - Oscilloscope Image |
| | | - Data Undershoot V-L+ - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Tbit - Vswing - Oscilloscope Image |
| | - Duty Cycle Results | |
| | | - Max Duty Cycle - Test Name - Spec Range - Meas Value |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|---------------|---------------------|---|
| | | <ul style="list-style-type: none"> - Result - Remarks/Comments - Tbit - Oscilloscope Image |
| | | <ul style="list-style-type: none"> - Min Duty Cycle - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Tbit - Oscilloscope Image |
| | - Rise Time Results | <ul style="list-style-type: none"> - Clock Rise Time - Statistics - Clock Rise Population - Clock Rise Min - Clock Rise Max - Clock Rise Mean - Clock Rise Std Dev - Clock Rise Pk-Pk - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Tbit - Vswing - Oscilloscope Image |
| | | <ul style="list-style-type: none"> - Data Rise Time - Statistics - Data Rise Population |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|---------------|---------------------|---|
| | | <ul style="list-style-type: none"> - Data Rise Min - Data Rise Max - Data Rise Mean - Data Rise Std Dev <ul style="list-style-type: none"> - Data Rise Pk- Pk <ul style="list-style-type: none"> - Test Name - Spec Range - Meas Value - Result - Remarks/Comments <ul style="list-style-type: none"> - Tbit - Vswing - Oscilloscope Image |
| | - Fall Time Results | |
| | | <ul style="list-style-type: none"> - Clock Fall Time - Statistics - Clock Fall Population <ul style="list-style-type: none"> - Clock Fall Min - Clock Fall Max - Clock Fall Mean - Clock Fall Std Dev <ul style="list-style-type: none"> - Clock Fall Pk- Pk <ul style="list-style-type: none"> - Test Name - Spec Range - Meas Value - Result - Remarks/Comments <ul style="list-style-type: none"> - Tbit - Vswing - Oscilloscope Image |
| | | <ul style="list-style-type: none"> - Data Fall Time - Statistics |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|---------------|--|---|
| | | - Data Fall Population - Data Fall Min - Data Fall Max - Data Fall Mean - Data Fall Std Dev - Data Fall Pk-Pk - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Tbit - Vswing - Oscilloscope Image |
| | - Inter-Pair Skew (Clock-Data) Results | |
| | | - Test Name |
| | | - Spec Range |
| | | - Meas Value |
| | | - Results |
| | | - Remarks/Comments |
| | | - Tbit |
| | | - Vswing |
| | | - Oscilloscope Image |
| - Data-Data | | |
| | - Configuration Parameters | |
| | | - Data Input A |
| | | - Data Input B |
| | - Inter-Pair Skew (Data-Data) Results | |
| | | - Test Name |
| | | - Spec Range |
| | | - Meas Value |
| | | - Result |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|----------------|----------------------------|--------------------------|
| | | - Remarks/Comments |
| | | - Tbit |
| | | - Vswing |
| | | - Oscilloscope Image |
| - Single-Ended | | |
| | - Configuration Parameters | |
| | | - Clock Input |
| | | - Input + |
| | | - Input - |
| | | - Number of Acquisitions |
| | | - Avcc |
| | | - Tbit # of Avgs |
| | - Intra-Pair Skew Results | |
| | | - Test Name |
| | | - Spec Range |
| | | - Meas Value |
| | | - Result |
| | | - Remarks/Comments |
| | | - Tbit |
| | | - Oscilloscope Image |
| | - Low Amplitude + Results | |
| | | - Test Name |
| | | - Spec Range |
| | | - Meas Value |
| | | - Result |
| | | - Remarks/Comments |
| | | - Oscilloscope Image |
| | - Low Amplitude - Results | |
| | | - Test Name |
| | | - Spec Range |
| | | - Meas Value |
| | | - Result |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|----------------|--------------------------------|--------------------------------|
| | | - Remarks/Comments |
| | | - Oscilloscope Image |
| Sink | | |
| - Differential | | |
| | - Configuration Parameters | |
| | | - Clock Input |
| | | - Data Input |
| | | - Ref Level Units |
| | | - Hysteresis |
| | | - High Ref Level |
| | | - Mid Ref Level |
| | | - Low Ref Level |
| | | - Record Length |
| | | - Clock |
| | | - Min/Max-Diff Swing Tolerance |
| | | - Vicm |
| | | - Frequency Pair |
| | | - DUT Freq |
| | - DTG Configuration Parameters | |
| | | - DTG Filepath |
| | | - Physical Clock Channel |
| | | - Logical Clock Channel |
| | | - Physical Data Channel 0 |
| | | - Logical Data Channel 0 |
| | | - Physical Data Channel 1 |
| | | - Logical Data Channel 1 |
| | | - Physical Data Channel 2 |
| | | - Logical Data Channel 2 |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|----------------|---|---|
| | - Min/Max-Diff Swing Tolerance Results | |
| | | - Test Name |
| | | - Spec Range |
| | | - Meas Value |
| | | - Result |
| | | - Remarks/Comments |
| | | - Vswing |
| | | - Oscilloscope Image |
| | - Jitter Tolerance Results | |
| | | - Clock Jitter Results - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Jitter Image - Tbit - Vswing |
| | | - Data Jitter Results - Test Name - Spec Range - Meas Value - Result - Remarks/Comments - Eye Image - Tbit - Vswing - Mask Hits |
| - Single-Ended | | |
| | - Configuration Parameters | |
| | | - Clock Input |
| | - DTG Configuration Parameters | |
| | | - DTG Filepath |
| | | - Physical Clock |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|----------------|----------------------------|---------------------------|
| | | Channel |
| | | - Logical Clock Channel |
| | | - Physical Data Channel 0 |
| | | - Logical Data Channel 0 |
| | | - Physical Data Channel 1 |
| | | - Logical Data Channel 1 |
| | | - Physical Data Channel 2 |
| | | - Logical Data Channel 2 |
| | - Intra-Pair Skew Results | |
| | | - Test Name |
| | | - Spec Range |
| | | - Meas Value |
| | | - Result |
| | | - Remarks/Comments |
| | | - Tbit |
| | | - Vswing |
| | | - Oscilloscope Image |
| Cable | | |
| - Differential | | |
| | - Configuration Parameters | |
| | | - Clock Input |
| | | - Data Input |
| | | - Ref Level Units |
| | | - Hysteresis |
| | | - High Ref Level |
| | | - Mid Ref Level |
| | | - Low Ref Level |
| | | - Record Length |
| | | - Test Points |
| | | - Clock |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|---------------|--------------------------------|----------------------------------|
| | - DTG Configuration Parameters | |
| | | - DTG Filepath |
| | | - Physical Clock Channel |
| | | - Logical Clock Channel |
| | | - Physical Data Channel 0 |
| | | - Logical Data Channel 0 |
| | | - Physical Data Channel 1 |
| | | - Logical Data Channel 1 |
| | | - Physical Data Channel 2 |
| | | - Logical Data Channel 2 |
| | - Eye Diagram Results | |
| | | - Statistics |
| | | - T x Clock TIE Population |
| | | - T x Clock TIE Min |
| | | - T x Clock TIE Max |
| | | - T x Clock TIE Mean |
| | | - T x Clock TIE Std Dev |
| | | - T x Clock TIE Pk-Pk |
| | | - Recovered Clock TIE Population |
| | | - Recovered Clock TIE Min |
| | | - Recovered Clock TIE Max |
| | | - Recovered Clock TIE Mean |
| | | - Recovered Clock TIE Std Dev |
| | | - Recovered Clock |

**Table 147: TDSHT3 Application Fields
(Contd.)**

| TDSHT3 Fields | | |
|-----------------------------------|--|---|
| | | TIE Pk-Pk |
| | | - Test Name |
| | | - Spec Range |
| | | - Meas Value |
| | | - Result |
| | | - Remarks/Comments |
| | | - TP1 Eye Diagram Image |
| | | - TP1 Jitter Image |
| | | - TP2 Eye Diagram Image |
| | | - TP2 Jitter Image |
| | | - Tbit |
| | | - Vswing |
| | | - Oscilloscope Image |
| | | - Mask Hits (TP1) |
| | | - Mask Hits (TP2) |
| Report Configuration | | |
| | | - Pair (CK, D) - Resolution - Refresh Rate - Device ID - Device Details - Pair (Single-Ended) - Pair (D, D) |
| Application Version Number | | |

Application View – Palette List – Oscilloscope Fields

The Oscilloscope Fields are grouped into 10 different groups:

- **Waveform Group:** The Waveform Group has all the active live channels and independent channels (only CH1 to CH4) waveforms in both jpeg and bmp. These waveforms are generated to smooth out the stair-step effect seen on the display.
- **Vertical Group:** The Vertical Group has all vertical related fields, such as the vertical scale, position, and offset.
- **Horizontal Group:** The Horizontal Group has all horizontal related fields, such as the horizontal divisions, scale, record length, position, and sample rate.
- **Math Group:** The Math Group has all the math related fields, such as the math definition for a specified math channel, magnitude, spectral gate, spectral phase, spectral window, and spectral frequencies of the math channel.
- **Trigger Group:** The Trigger Group has all trigger related fields, such as the trigger type, mode, level, and various fields related to different trigger types.
- **Measurement Group:** The Measurement Group has all the measurements, such as the eight automated measurements and the immediate measurements.
- **Acquisition Group:** The Acquisition Group has all acquisition related fields, such as the acquisition mode, acquisition state, repetitive mode, and fast acquisition mode.
- **Cursor Group:** The Cursor Group has all the cursor related fields, such as the cursor mode, source, state and type of the cursor, H Bars, and V Bars.
- **Zoom Group:** The Zoom Group has all zoom related fields, such as the zoom horizontal position and horizontal scale.
- **Histogram Group:** The Histogram Group has all histogram fields, such as the co-ordinates of histogram box, mode, size, and source.
- **Screen Snapshot Group:** The Screen Snapshot Group has two variations: one in color and the other in black-and-white. For these screenshots, the attributes are graticule, ink-saver, and jpeg.

Menus – File menu

Table 148: Template Editor | File menu

| Menu Selection | Description |
|--------------------------|---|
| New | Click File > New to create a new template. |
| Open | Click File > Open to open a template file. |
| Close | Click File > Close to close the active template. |
| Save | Click File > Save to save changes to the file. |
| Save As | Click File > Save As to save the template to a different file by using the Save As dialog box. |
| Print | Click File > Print to either print all or part of the contents of the active template. |
| Print Preview | Click File > Print Preview to display a sample view of the active template as it would be printed. |
| List of recent templates | Click File > List of recent templates to open a previously (recently) opened template. |
| Exit | Click File > Exit to quit template editor. |

Menus – Edit menu

The available edit menu selections depend on whether a template is active or not. In other words, the client area is either empty or has an open template.

Table 149: Template Editor | Edit menu

| Menu Selection | Description |
|----------------------|--|
| Cut | Click Edit > Cut to cut the selected fields. |
| Copy | Click Edit > Copy to copy the selected fields. |
| Paste | Click Edit > Paste to paste the clipboard content. |
| Delete | Click Edit > Delete to delete the selected fields. |
| Select All | Click Edit > Select All to select all the fields. |
| Create Custom Group | Click Edit > Create Custom Group to create a custom group. |
| Edit Custom Group | Click Edit > Edit Custom Group to edit the custom group. |
| Change Template Size | Click Edit > Change Template Size to change the template size. |
| Find | Click Edit > Find to find the data that matches the search criteria. |
| Replace | Click Edit > Replace to replace the data that matches the search criteria with the specified data. |

Menus – View menu

A check mark appears next to the selected command.

Table 150: Template Editor | View menu

| Menu Selection | Description |
|----------------|--|
| Toolbar | Click View > Toolbar to either display or hide the selected toolbars such as Standard, Align Size, Layout, and Action. |
| Status Bar | Click View > Status Bar to either display or hide the status bar. |
| Palette Bar | Click View > Palette Bar to either display or hide the palette bar. |
| Grid Lines | Click View > Grid Lines to either display or hide the grid lines in the client area. |

Menus – Object menu

The available object menu selections depend on whether a parameter in the client area is selected or not.

Table 151: Template Editor | Object menu

| Menu Selection | Description |
|-------------------------------------|--|
| Bring to Front | Click Object > Bring to Front to bring the selected fields to the front. |
| Send to Back | Click Object > Send to Back to send the selected fields back. |
| Hide Text/Show Text | Click Object > Hide Text/Show Text to either hide or show the caption of the selected parameter. |
| Position Caption on Top/to the Left | Click Object > Position Caption on Top/to the Left to position the caption of the selected parameter either on top or to the left. |
| Edit Caption | Click Object > Edit Caption to edit the caption of the selected parameter. |
| Change Font | Click Object > Change Font to change the font of the selected parameter or the caption by using the Change Font dialog box. |
| Align Fields | Click Object > Align Fields to aligns fields to the top, bottom, left, or right. |
| Make Same Size | Click Object > Make Same Size to resize the selected objects to the same size by either height, width, or both. |

Menus – Windows menu**Table 152: Template Editor | Windows menu**

| Menu Selection | Description |
|------------------------|--|
| New Window | Click Window > New Window to open a new window duplicating the current active window. |
| Cascade | Click Window > Cascade to arrange the open templates in the client area from the upper left side to lower right side so that they overlap one another. |
| Tile | Click Window > Tile to arrange the open templates horizontally and vertically in the application client area without overlapping. |
| Arrange Icons | Click Window > Arrange Icons to arrange the icons of any templates you have minimized to the bottom left of the window. |
| List of open templates | Click Window > List of open templates to jump to another open template. |

Menus – Help menu**Table 153: Template Editor | Help menu**

| Menu Selection | Description |
|-----------------------|--|
| Help Topics | Click Help > Help Topics to display online help. |
| About Template Editor | Click Help > About Template Editor to display version and copyright information. |

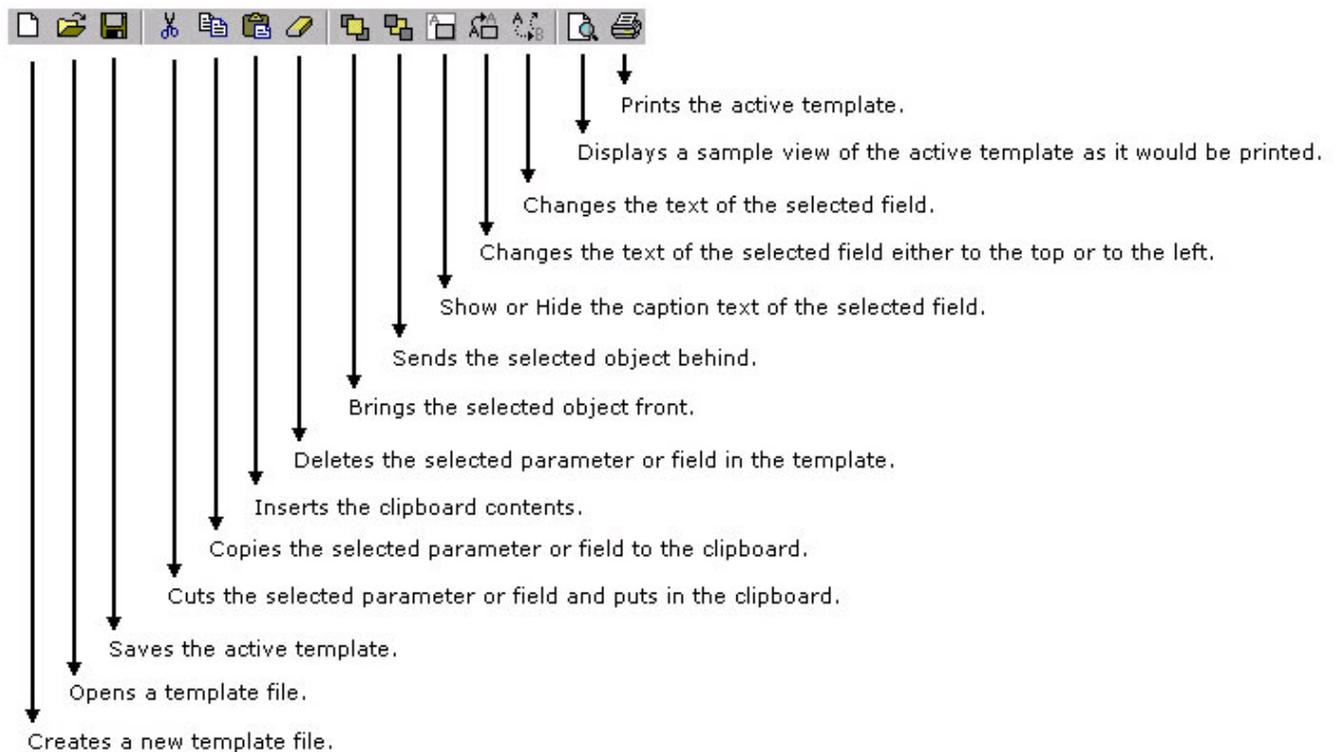
Toolbars

Click **View > Toolbars** to choose to either display or hide these toolbars.

Toolbars – Standard toolbar

View > Toolbar > Standard

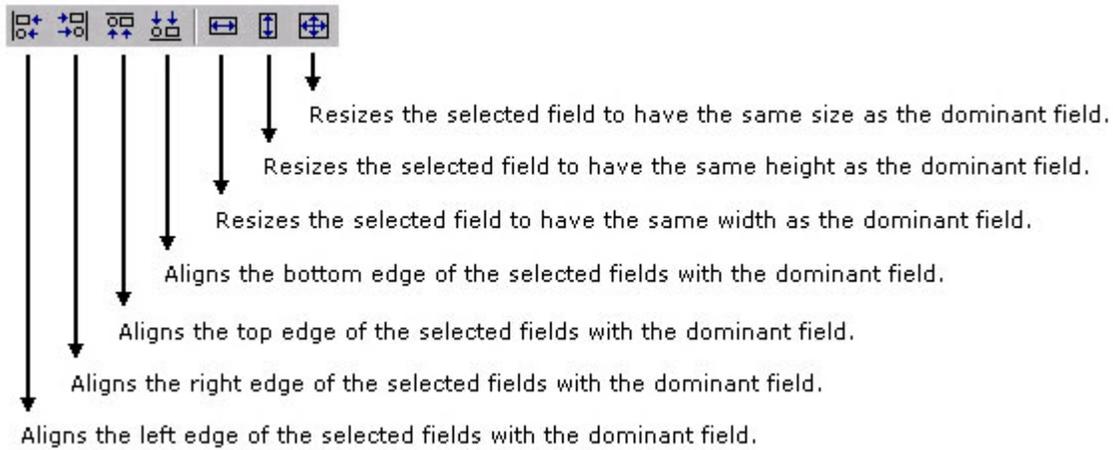
Click **View > Toolbar > Standard** to either display or hide the standard toolbar.



Toolbars – Align or Size toolbar

View > Toolbar > Align/Size

Click **View > Toolbar > Align/Size** to either display or hide the Align/Size toolbar.



Toolbars – Layout toolbar

View > Toolbar > Layout

Click **View > Toolbar > Layout** to either display or hide the layout toolbar.



Toolbars – Action toolbar

View > Toolbar > Action

Click **View > Toolbar > Action** to either display or hide the action toolbar.



Prompts to save documents and quits the application.
Closes the application and opens Report Layout Editor.

Status bar

The status bar displays the status of the application and tool tips for selected options.

How to Use Template Editor

To create a new template

1. From the **Palette List**, drag and drop the fields that you want in the report.

Note: If you drag and drop a group from the palette list, then all the fields within the group are placed in the active template.

2. Organize the fields as you want them to appear in the report.
3. After you have finished creating the template, click **File > Save**.

To edit an existing template

1. Organize the fields as you want them to appear in the report.

Note: From the Palette List, drag and drop the fields that you want in the report.

2. If you drag and drop a group from the palette list, then all the fields within the group are placed in the active template.
3. Organize the fields as you want them to appear in the report.

4. After you have finished editing the template, click **File > Save**.
 - You can create a custom group, edit a custom group, and change the template size.
 - You can also edit the caption, change a font, align the fields, and make the selected fields of the same size.

Create Custom Groups

Edit > Create Custom Group

You can create custom groups by using any fields from the palette list.

1. Click Edit > Create Custom Group.

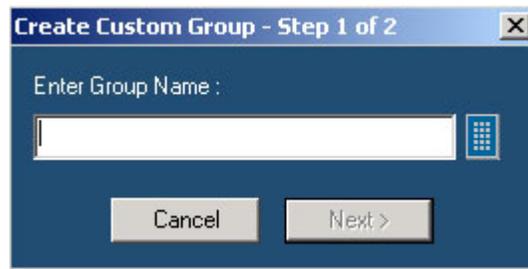


Figure 236: Create Custom Group - Step 1 of 2 dialog box

2. In the **Create Custom Group - Step 1 of 2** dialog box, type the group name. You can type the group name by using the Virtual Keyboard.

3. Click **Next**. The **Select Fields - Step 2 of 2** dialog box displays all the fields of the palette list.

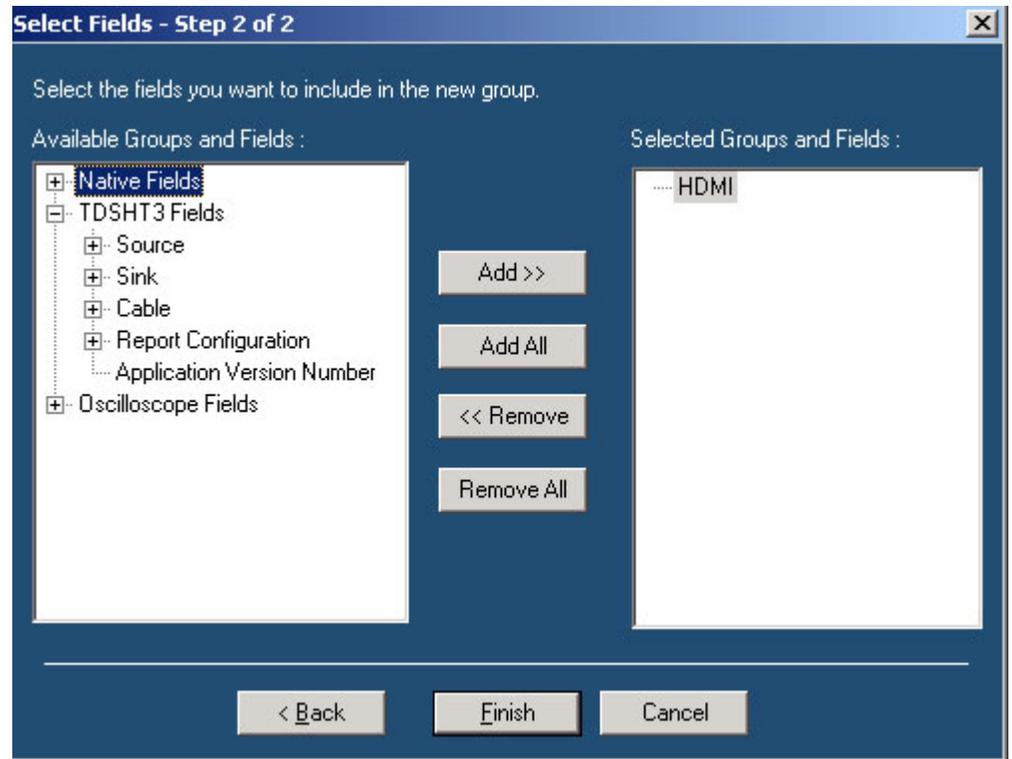


Figure 237: Select Fields - Step 2 of 2 dialog box

4. Using **Add >>**, **Add All**, **<< Remove**, or **Remove All**, you can click the fields you want to include in the new group.
5. Click **Finish**.

Edit Custom Groups

Edit > Edit Custom Group

You can edit custom groups.

1. Click Edit > Edit Custom Group.

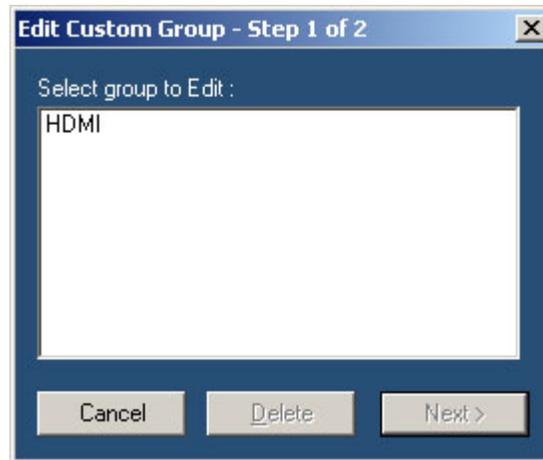


Figure 238: Edit Custom Group - Step 1 of 2 dialog box

2. In the **Edit Custom Group - Step 1 of 2** dialog box, click a group to edit.

3. Click **Next**.

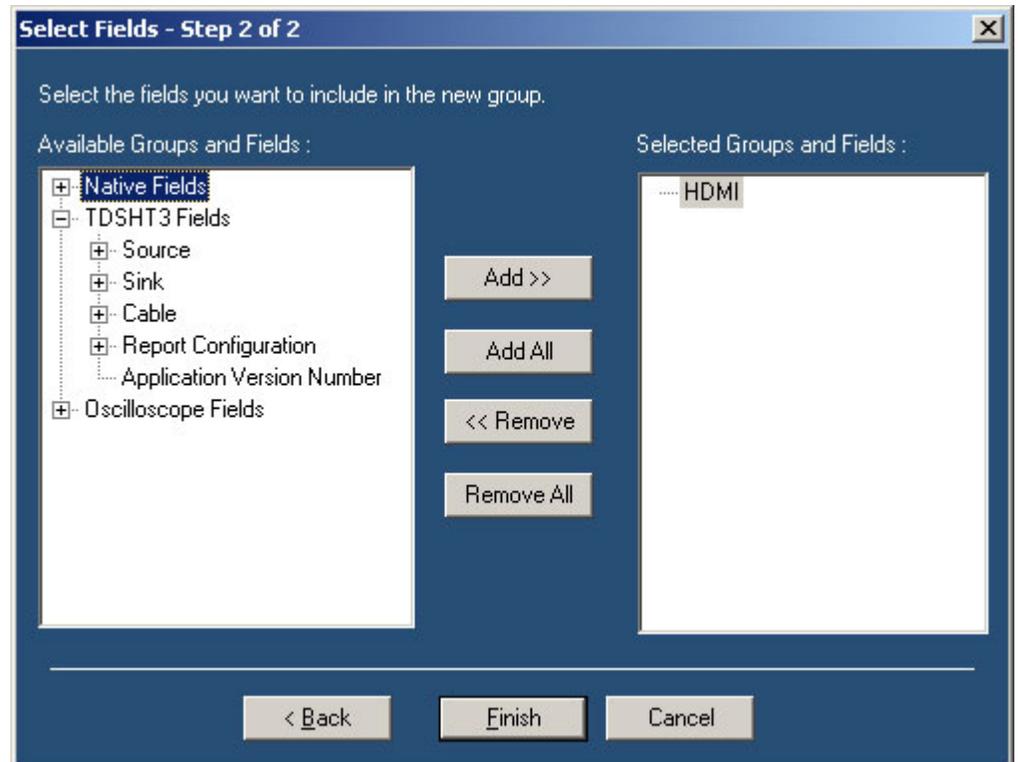


Figure 239: Select Fields - Step 2 of 2 dialog box

4. In the **Select Fields - Step 2 of 2** dialog box, click the fields you want to add or remove from the group by using **Add >>**, **Add All**, **<< Remove**, or **Remove All**.
5. Click **Finish**.

Delete Custom Groups

Edit > Edit Custom Group

You can delete custom groups.

1. Click Edit > Edit Custom Group.

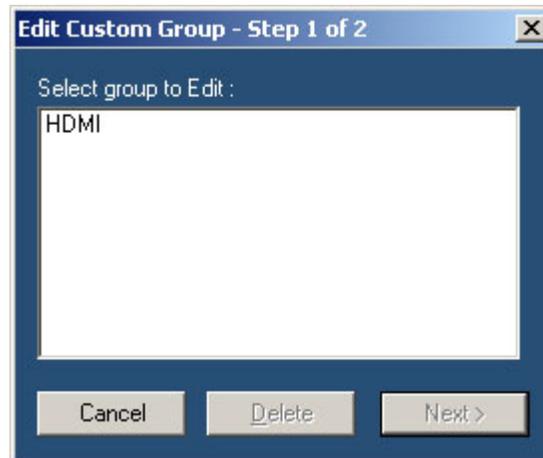


Figure 240: Edit Custom Group - Step 1 of 2 dialog box

2. In the **Edit Custom Group - Step 1 of 2** dialog box, click a group to delete.
3. Click **Delete**. A message box appears asking for your confirmation.
4. Click **Yes** to delete.

Change Template Size

Edit > Change Template Size

You can change the size and page setup for a template.

1. Click Edit > Change Template Size. The Change Template Size dialog box appears.

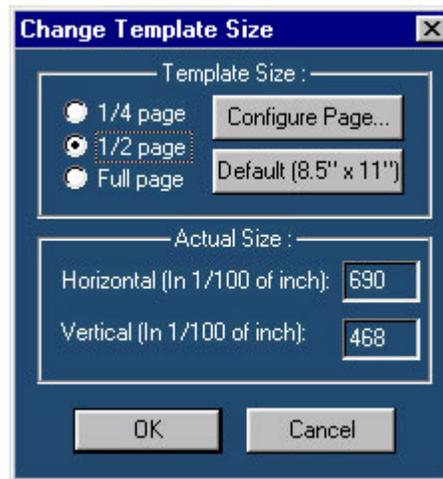


Figure 241: Change Template Size dialog box

2. In the **Change Template Size** dialog box,
 - Select the Template Size as either **1/4 page**, **1/2 page**, or **Full page**.
 - If the printer is not available, select the Page Size as **Default (8.5" x 11")**; else, click **Configure Page...**

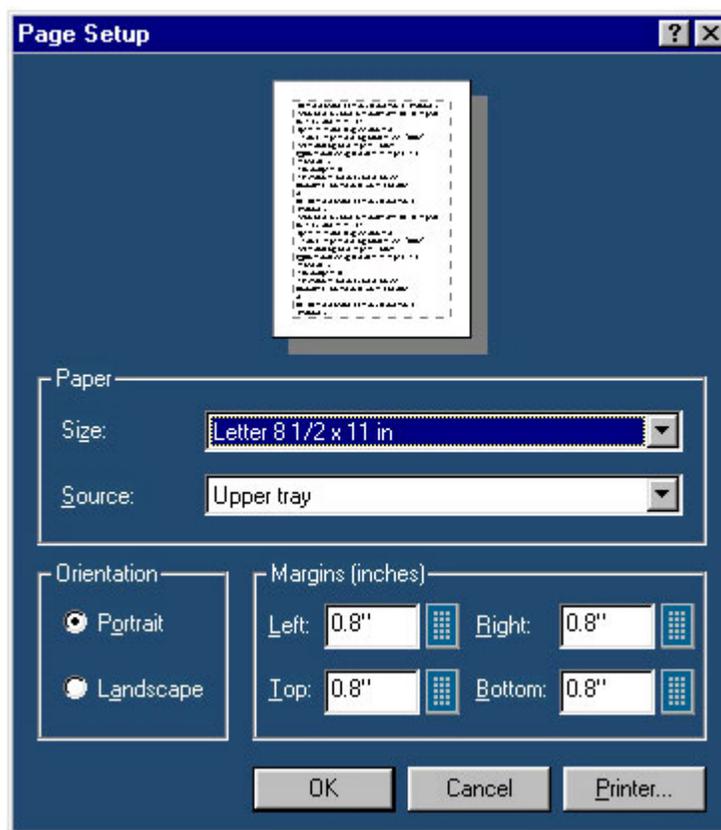


Figure 242: Page Setup dialog box

- In the **Page Setup** dialog box, select the paper size, source, orientation, and margins.
- Click **OK** to return to the **Change Template Size** dialog box.
- Click **OK**.

Note: Do not reduce the template size beyond the content filled in the template. You may lose information.

Select All

Edit > Select All

To cut, copy, or delete the fields from the active template, you need to select the fields. Click **CTRL + selecting the fields** to select the fields from the active template.

Find

Edit > Find

You can search for text in the active template.

1. Click **Edit > Find**.



Figure 243: Find dialog box

2. In the **Find** dialog box, type the search string by using the Virtual Keyboard.
3. Click **Find Next** until you find the required search string.

Replace

Edit > Replace

You can both search and replace the text in the active template.

1. Click Edit > Replace.



Figure 244: Replace dialog box

2. In the **Replace** dialog box, by using the Virtual Keyboard, type the search string in the **Find what** box.
3. In the **Replace with** box, by using the Virtual Keyboard, type the replacement string.
4. Click **Find Next** until you find the required search string.
5. Click **Replace** to replace one instance of the string, or click **Replace All** to replace all instances of the string.
6. Click **Cancel** after you have replaced the strings.

Bring To Front

Object > Bring To Front

You can bring the selected fields to the front.

Send To Back

Object > Send To Back

You can send the selected fields back.

Show/Hide Text

Object > Show/Hide Text

You can either show or hide the captions for the selected fields.

Position Caption

Object > Position Caption to the Left, or on Top

You can position the caption of the selected fields either to the left or on the top.

Edit Caption

Object > Edit Caption

You can edit the caption of the selected parameter or object.

1. Click **Object > Edit Caption**. The **Edit Caption** dialog box appears.

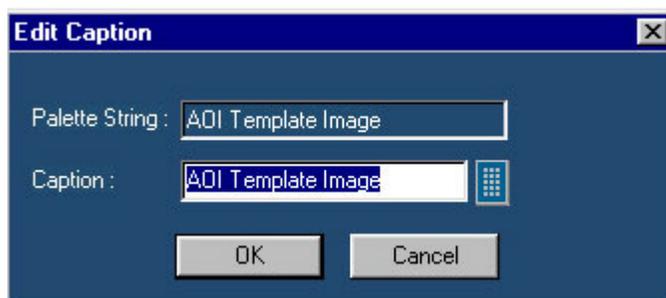


Figure 245: Edit Caption dialog box

2. In the **Edit Caption** dialog box, click the icon next to the Caption box to type the caption by using the Virtual Keyboard.
3. Click **OK**.

Change Font

Object > Change Font

You can change font for the selected field in the template.

1. Select the field or fields in the active template.

2. Click **Object > Change Font** or right-click the field to display the options.

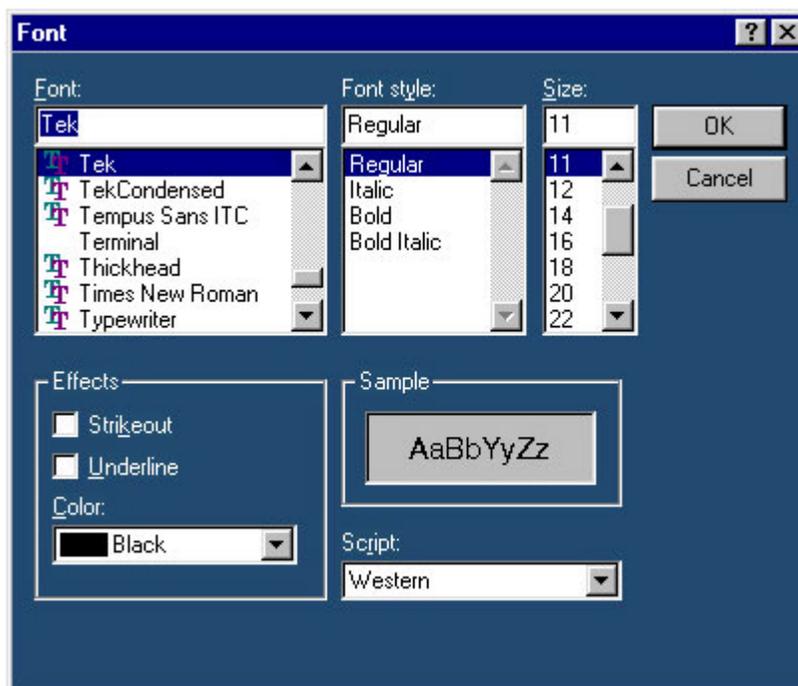


Figure 246: Font dialog box

3. In the **Font** dialog box, choose the font size, color, style, and effects.
4. Click **OK**.

Align Fields

Object > Align Fields

You can align the fields to either top, bottom, left, or right.

1. Select the fields in the active template.
2. Click **Object > Align Fields > Top, Bottom, Left, or Right** to align the fields accordingly.

Make Same Size

Object > Make Same Size

You can set the selected fields to either the same height, width, or both.

1. Select the fields in the active template.
2. Click **Object > Make Same Size > Height, Width, or Both** to make the selected fields of the same size.

Report Layout Editor

About Report Layout Editor

Report Layout Editor helps you to define the report layout to generate reports. The report layout, once created, can be reused to generate multiple reports.

You can select the number of test templates per page and position the templates in the report. The report can have multiple pages with different template sizes. Each template is a sub-report with a unique test title. This unique test title helps you select the required template when you generate a report. You can define headers and footers for the report layout.

To display Report Layout Editor, click **Define Report Layout > New Layout**.

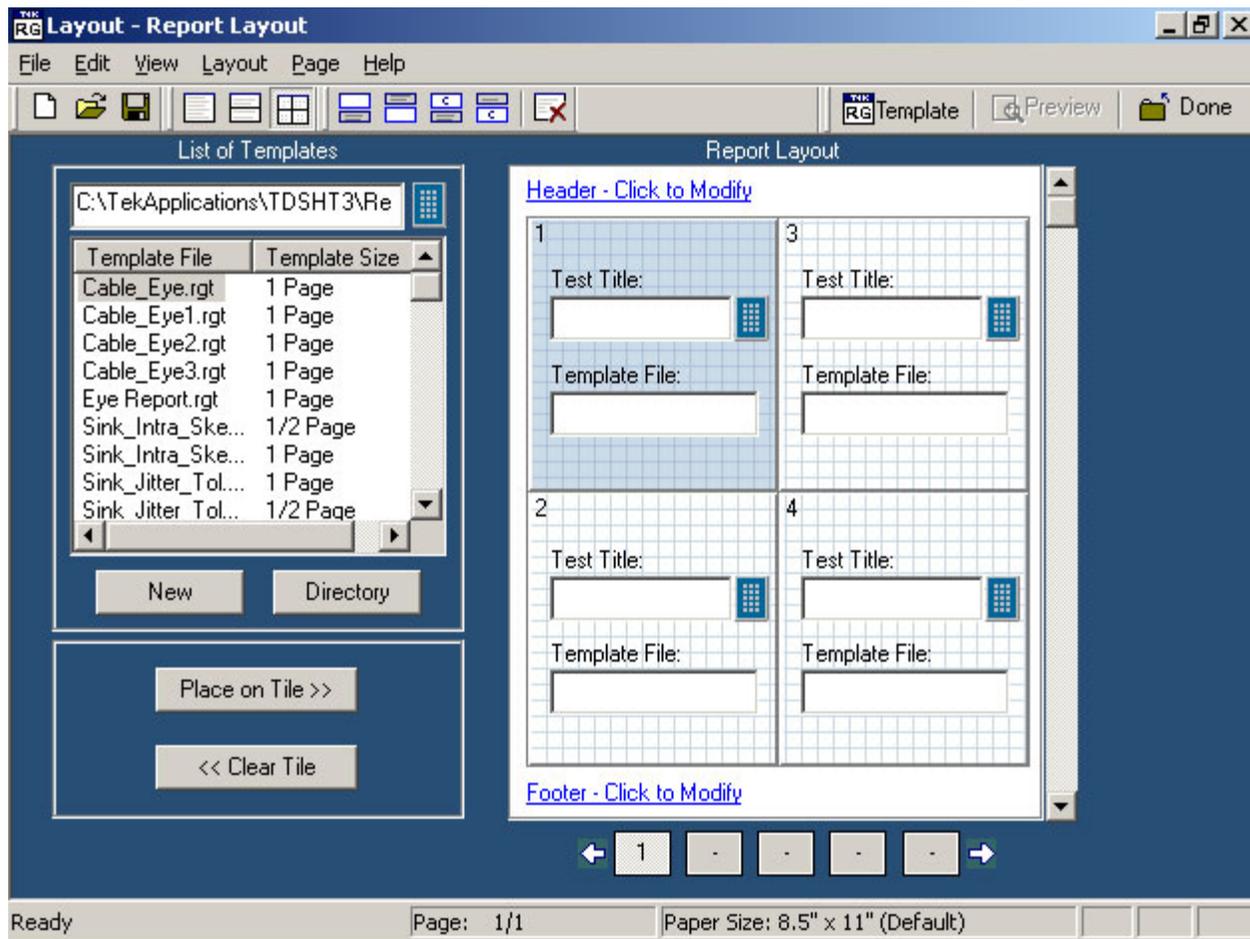


Figure 247: Report Layout window

The Report Layout Editor window has two panes.

- **List of Templates:** This pane displays a list of templates, template sizes, template folders, and buttons that allow you to clear or place a template in a report layout tile and to create new templates.
- **Report Layout:** This pane displays the selected report layout and the header, footer definition.

Default Settings

Table 154: Report Layout Default Settings

| Parameter | Selection | Default Setting |
|---------------------|------------|---|
| Report Layout | Layout | Four tests per page |
| Page Size | Page Setup | 8.5 inches x 11 inches |
| Layout Editor | None | One page |
| Go to | Edit | Displays the current page number in the page layout |
| Font | None | Arial > Regular 9 |
| Default Margin Size | None | Margin size on all sides of the paper is 0.8 inch |

Application View – Report Layout Editor Window

The Report Layout Editor window includes a menu bar, toolbar, list of templates pane, and a report layout pane.

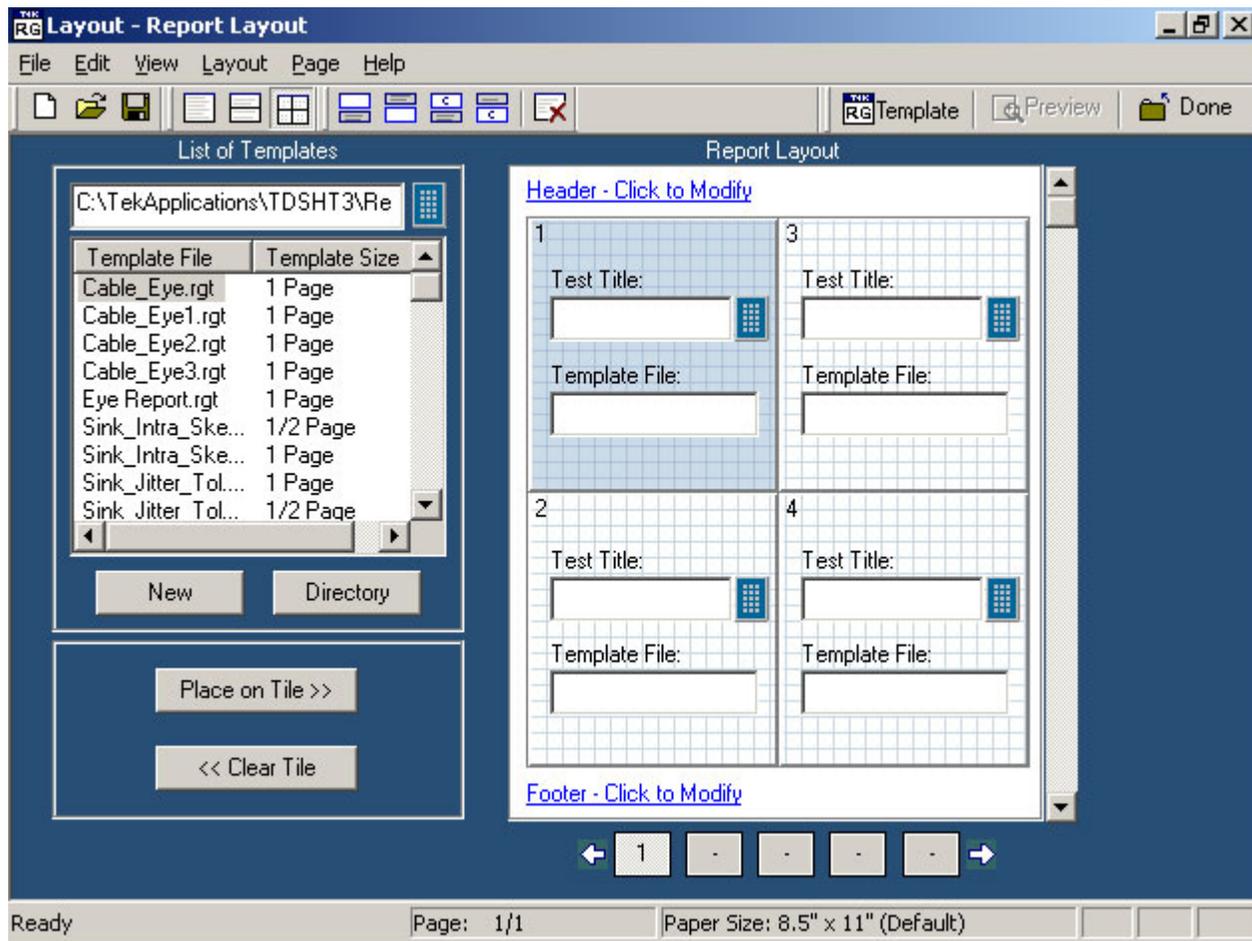


Figure 248: Report Layout Editor window

Application View – List of Templates pane

The list of templates pane displays the path of the template, templates in the folder, file names, and template sizes. You can select the template from this list and place it in the report layout pane.

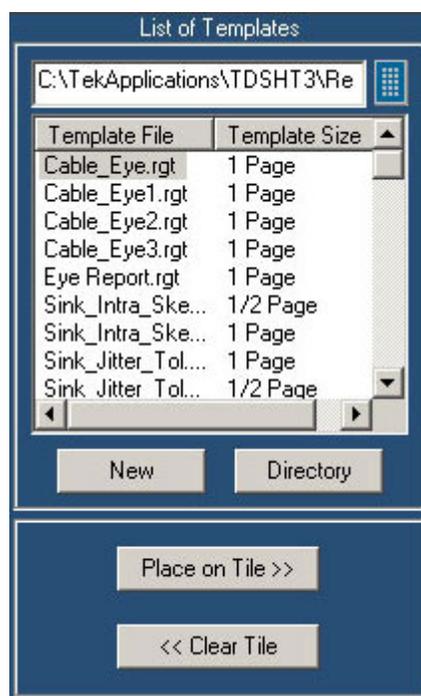


Figure 249: List of Templates pane

In the list of templates pane, you can:

- Select a different path where you have saved the customized templates either by using the Virtual Keyboard or clicking **Directory** that displays a **Browse for Folder** dialog box.
- Click **New** to create a new template. The Template Editor window appears, where you can create a new template.
- Drag and drop the template file to the report layout pane's tile, or select the template file and then click **Place on Tile >>**.
- Click **<< Clear Tile** to clear the selected tile in the report layout pane.

Application View – Report Layout pane

Depending on the number of tests selected per page, the report layout pane appears as follows:

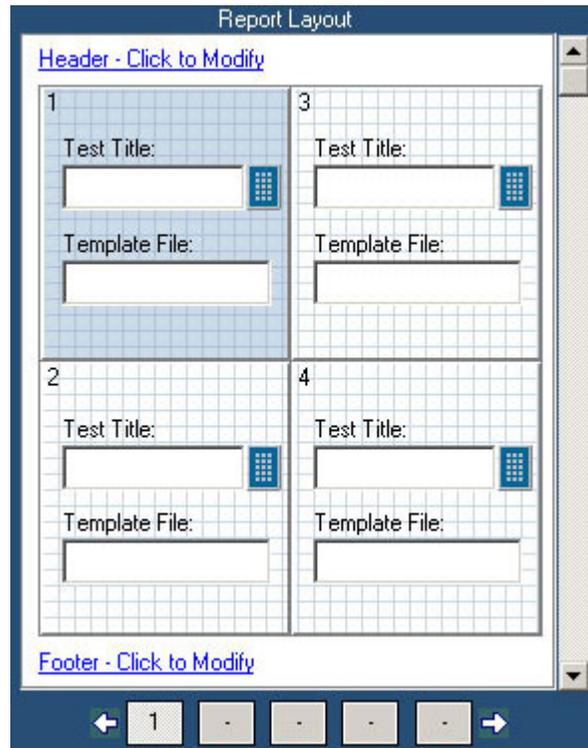


Figure 250: Report Layout pane

In the report layout pane, you can do the following:

- Specify a title for each test.
- Define or modify the header and footer.
- Navigate between pages of the report layout.

Menus – File menu

Table 155: File menu selection and Description

| Menu Selection | Description |
|----------------------------------|--|
| New | Click File > New to create a new report layout. |
| Open | Click File > Open to opens a report layout file. |
| Save | Click File > Save to save changes to the file. |
| Save As | Click File > Save As to save the report layout to a different file by using the Save As dialog box. |
| Page Setup | Click File > Page Setup to print either all or part of the contents of the active template. |
| Configure Page | Use the Page Setup dialog box to configure the paper size, source, orientation, and margins. |
| Default (8.5 inches X 11 inches) | Use the Page Setup dialog box to configure the page setup to default - 8.5 inches x 11 inches. |
| Layout Preview | Click File > Layout Preview to display a sample view of the active report layout as it would be printed. |
| List of recent report layouts | Click File > List of recent report layouts to open a previously (recently) opened report layout. |
| Exit | Click File > Exit to quit report layout editor. |

Menus – Edit menu

Table 156: Edit menu selection and Description

| Menu Selection | Description |
|----------------|--|
| Go To | Click Edit > Go To to go to the page that was typed in the Go To Page dialog box. |

Menus – View menu

A check mark appears next to the selected command.

Table 157: View menu selection and Description

| Menu Selection | Description |
|-----------------------|--|
| Toolbar | Click View > Toolbar to either display or hide the selected toolbars such as Standard, Page, Layout, and Action. |
| Status Bar | Click View > Status Bar to either display or hide the status bar. |
| Refresh Template List | Click View > Refresh Template List to update the template list in the list of templates pane. |

Menus – Layout menu

A check mark appears next to the selected command.

Table 158: Layout menu selection and Description

| Menu Selection | Description |
|---------------------|--|
| One Test Per Page | Click Layout > One Test Per Page to change the report layout to fit one test per page. |
| Two Tests Per Page | Click Layout > Two Tests Per Page to change the report layout to fit two tests per page. |
| Four Tests Per Page | Click Layout > Four Tests Per Page to change the report layout to fit four tests per page. |

Menus – Page menu

Table 159: Page menu selection and Description

| Menu Selection | Description |
|---------------------|--|
| Insert Blank | |
| Before Current Page | Click Page > Insert Blank > Before Current Page to insert a blank page before the current page. |
| After Current Page | Click Page > Insert Blank > After Current Page to insert a blank page after the current page. |

Table 159: Page menu selection and Description (Contd.)

| Menu Selection | Description |
|---------------------|---|
| Insert Copy | |
| Before Current Page | Click Page > Insert Copy > Before Current Page to insert a copy of the current page before the current page. |
| After Current Page | Click Page > Insert Copy > After Current Page to insert a copy of the current page after the current page. |
| Delete | Click Page > Delete to delete the current page. |

Menus – Help menu

Table 160: Help menu selection and Description

| Menu Selection | Description |
|----------------------------|---|
| Help Topics | Click Help > Help Topics to display online help. |
| About Report Layout Editor | Click Help > About Report Layout Editor to display version and copyright information. |

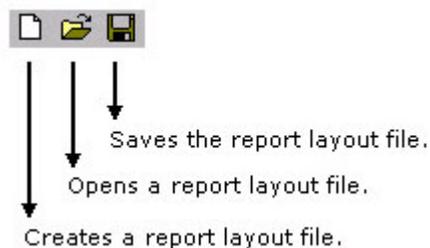
Toolbars

Click **View > Toolbars** to choose to either display or hide these toolbars.

Toolbars – Standard toolbar

View > Toolbars > Standard

Click **View > Toolbars > Standard** to either display or hide the standard toolbar.



Toolbars – Layout toolbar

View > Toolbars > Layout

Click **View > Toolbars > Layout** to either display or hide the layout toolbar.



- ↓ Changes the report layout to fit four tests per page.
- ↓ Changes the report layout to fit two tests per page.
- ↓ Changes the report layout to fit one test per page.

Toolbars – Page toolbar

View > Toolbars > Page

Click **View > Toolbars > Page** to either display or hide the page toolbar.

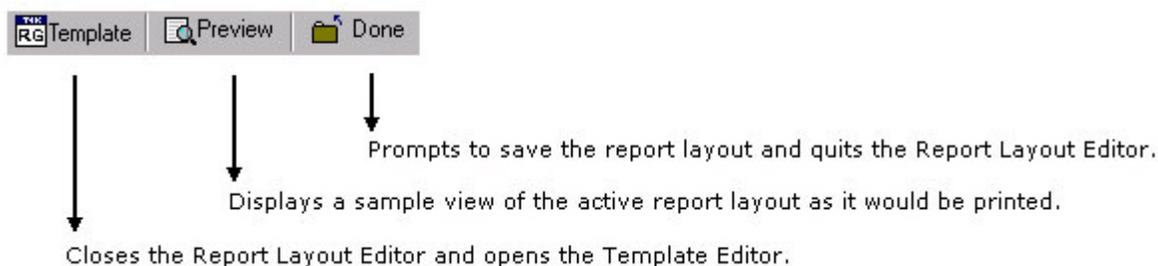


- ↓ Deletes the current page.
- ↓ Inserts a copy of the current page after the current page.
- ↓ Inserts a copy of the current page before the current page.
- ↓ Inserts new page after the current page.
- ↓ Inserts new page before the current page.

Toolbars – Action toolbar

View > Toolbars > Action

Click **View > Toolbars > Action** to either display or hide the action toolbar.



How to Use Report Layout Editor

To define a report layout, perform the following steps:

1. Set the report layout.
 - Click **Layout > One Test Per Page/Two Tests Per Page/Three Tests Per Page**. The report layout pane displays tiles depending on the selected number of tests per page.
2. Add the templates.
 - The list of templates pane displays the templates in the default directory - C:\TekApplications\TDSHT3\ReportGenerator\Templates.
 - From the list of templates pane, drag and drop the templates to the tiles in the report layout pane. You can use **Place on Tile** and **Clear Tile** to move the templates to the tiles and to clear the tiles.
 - If you want to define a new template, click **New** in the list of templates pane.
 - To browse for a different folder other than the default templates, click **Directory** to display the **Browse for Folder** dialog box. Navigate to the folder where you have the templates stored and then click **OK**.
3. Define Header and Footer.

4. Save the report layout.
 - Click **File** > **Save** to display the **Save** dialog box. Type the report layout name and then click **Save**.
 - The report layout is saved in the .rpl format.

To edit an existing report layout, perform the following steps:

1. Change the report layout.
 - Click **Layout** > **One Test Per Page/Two Tests Per Page/Three Tests Per Page**. The report layout pane displays tiles depending on the selected number of tests per page.
 - An alert message appears.
 - Click **Yes** to continue or click **No** to stop.
2. Add or remove the templates.
 - In the report layout pane, click the tile to which you want to either add or remove the template.
 - To remove a template from the report layout, complete the following steps:
 - In the list of templates pane, click **Clear Tile**.
 - An alert message appears.
 - Click **Yes** to continue or click **No** to stop.
 - To add a template to the report layout, complete the following steps:
 - The list of templates pane displays the templates in the default directory -
C:\TekApplications\TDSHT3\ReportGenerator\Templates.
 - From the list of templates pane, drag and drop the templates to the tiles in the report layout pane. Click **Place on Tile** to move the template to the selected tile.
 - If you want to define a new template, click **New** in the list of templates pane.
 - To browse for a different folder other than the default templates, click **Directory** to display the **Browse for Folder** dialog box. Navigate to the folder where you have the templates stored and then click **OK**.

3. Modify Header and Footer.
4. Save the report layout.
 - Click **File > Save** to display the **Save** dialog box. Type the report layout name and then click **Save**.
 - The report layout is saved in the .rpl format.

Note: Each report can have up to five pages.

How to Add a Template

Using the Report Layout Editor, you can add a template to an existing report. Follow these steps to add a template to the report:

1. Click **Define Report Layout** to open a new layout.
2. Click **File > Open** and browse for generated reports. The report is displayed in the report layout pane.
3. From the standard toolbar, click **Insert New Page before Current Page** or **Insert New Page after Current Page**.
4. From the list of templates pane, select the template that you want to add to the current page layout. Drag and drop the template file on to the report or click **Place on Tile** to add the template.
5. Add test titles for this layout.
6. Click **File > Save** to save the modified report as an .rpl or .rpt file.
7. Click **Generate Report** to generate a report for the unfilled template from the .rpl or .rpt file.

Configure Page

File > Page Setup > Configure Page

You can configure the paper size, source, orientation, and margins.

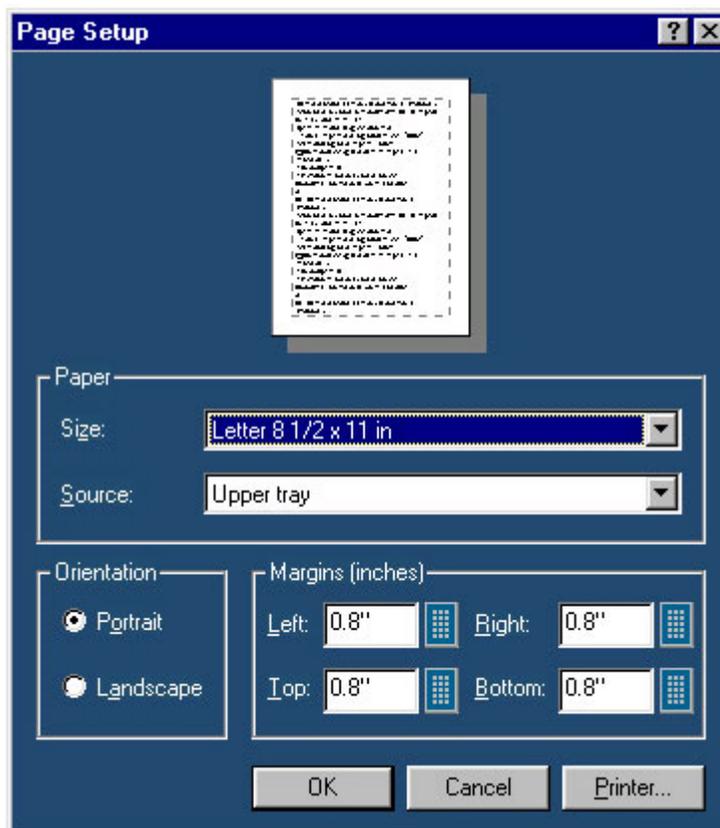


Figure 251: Page Setup window

After you have configured the page setup, click **OK**.

Go To Page

Edit > Go To

Use the **Go To Page** dialog box to go to different pages in the report layout.



Figure 252: Go To Page dialog box

1. In the **Enter Page Number** box, either enter the page number or click the icon next the **Enter Page Number** box to display the Virtual Keyboard.
2. Click **Go To**. The report layout pane displays the relevant page.

Change Report Layout

Layout > One Test Per Page/Two Tests Per Page/Four Tests Per Page

You can change the report layout to fit either one, two, or four tests per page.



- Changes the report layout to fit four tests per page.
- Changes the report layout to fit two tests per page.
- Changes the report layout to fit one test per page.

Header/Footer Definition

To modify Header Definition, do the following:

1. In the report layout pane, click **Header - Click to Modify**.

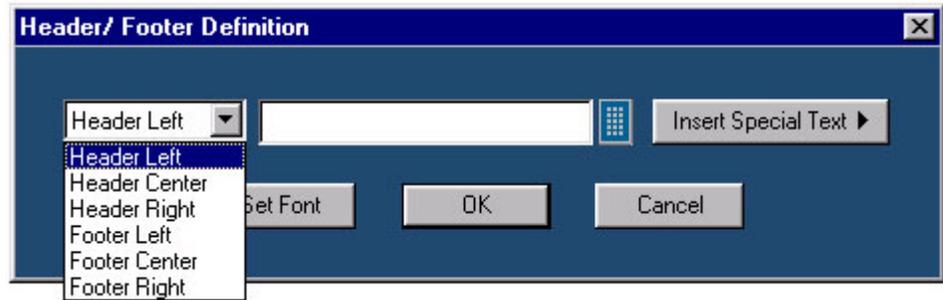


Figure 253: Header/Footer Definition dialog box

2. In the **Header/Footer Definition** dialog box, select the header position - Header Left, Header Center, or Header Right.
3. Type the Header Definition in the text box.
 - Click the icon next to the text box to display the Virtual Keyboard. In the Virtual Keyboard, type the text, and then click **Enter**.
 - To insert special text, click **Insert Special Text** to display a submenu. Click **Date**, **File Name**, **Author**, **Page X of Y**, **Page X**, or **Logo**.
4. Click **Set Font** to change the font style, size, effects, color, and script for each field separately, and then click **OK**.
5. In the **Header/Footer Definition** dialog box, click **OK**.

To modify Footer Definition, do the following:

1. In the report layout pane, click **Footer - Click to Modify**.

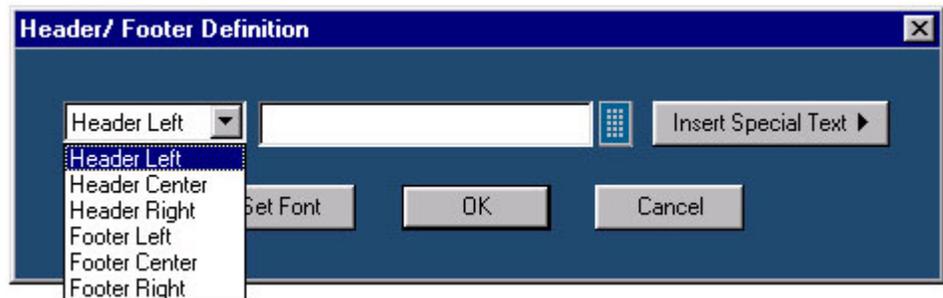


Figure 254: Header/Footer Definition dialog box

2. In the **Header/Footer Definition** dialog box, select the footer position - Footer Left, Footer Center, or Footer Right.
3. Type the Footer Definition in the text box.
 - Click the icon next to the text box to display the Virtual Keyboard. In the Virtual Keyboard, type the text, and then click **Enter**.
 - To insert special text, click **Insert Special Text** to display a submenu. Click **Date**, **File Name**, **Author**, **Page X of Y**, **Page X**, or **Logo**.
4. Click **Set Font** to change the font style, size, effects, color, and script for each field separately, and then click **OK**.
5. In the **Header/Footer Definition** dialog box, click **OK**.

Insert Pages

To insert pages, do the following:

- Click **Page > Insert Blank > Before Current Page/After Current Page** to insert a new page before the current page or after the current page.
- Click **Page > Insert Copy > Before Current Page/After Current Page** to insert copy of the current page before the current page or after the current page.

Note: When you insert a copy of a page before or after the current page, the current page layout is the same as the new page.

Report Viewer

About Report Viewer

Report Viewer allows you to view the generated report.

On the **Generate Report** tab, either click **Load Report** or click **Generate Report** to display Report Viewer and browse for the report that you want to view or generate.

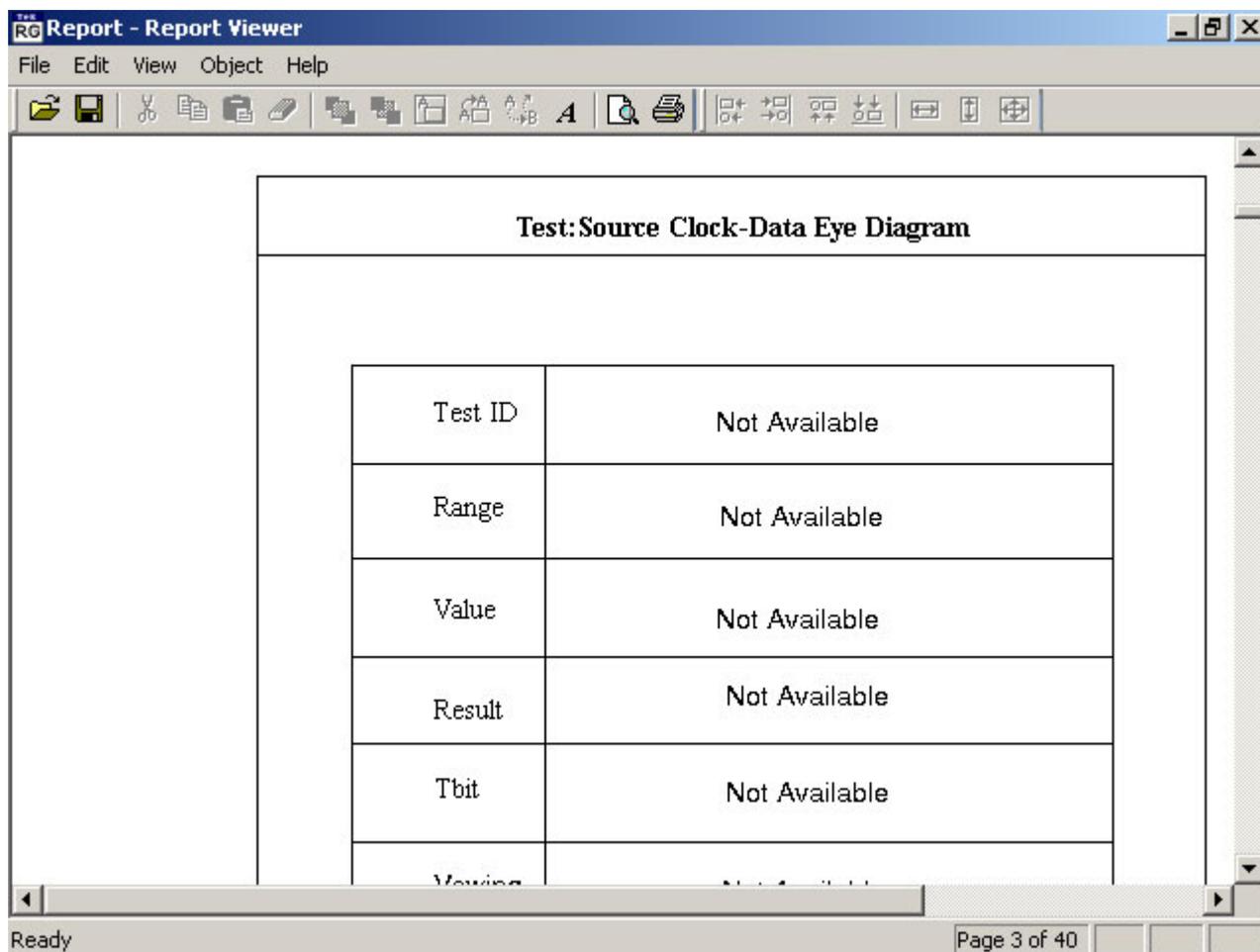


Figure 255: Application Report Viewer window

Application View – Report Viewer Window

The Report Viewer window includes a menu bar, toolbar, align/size bar, and client area.

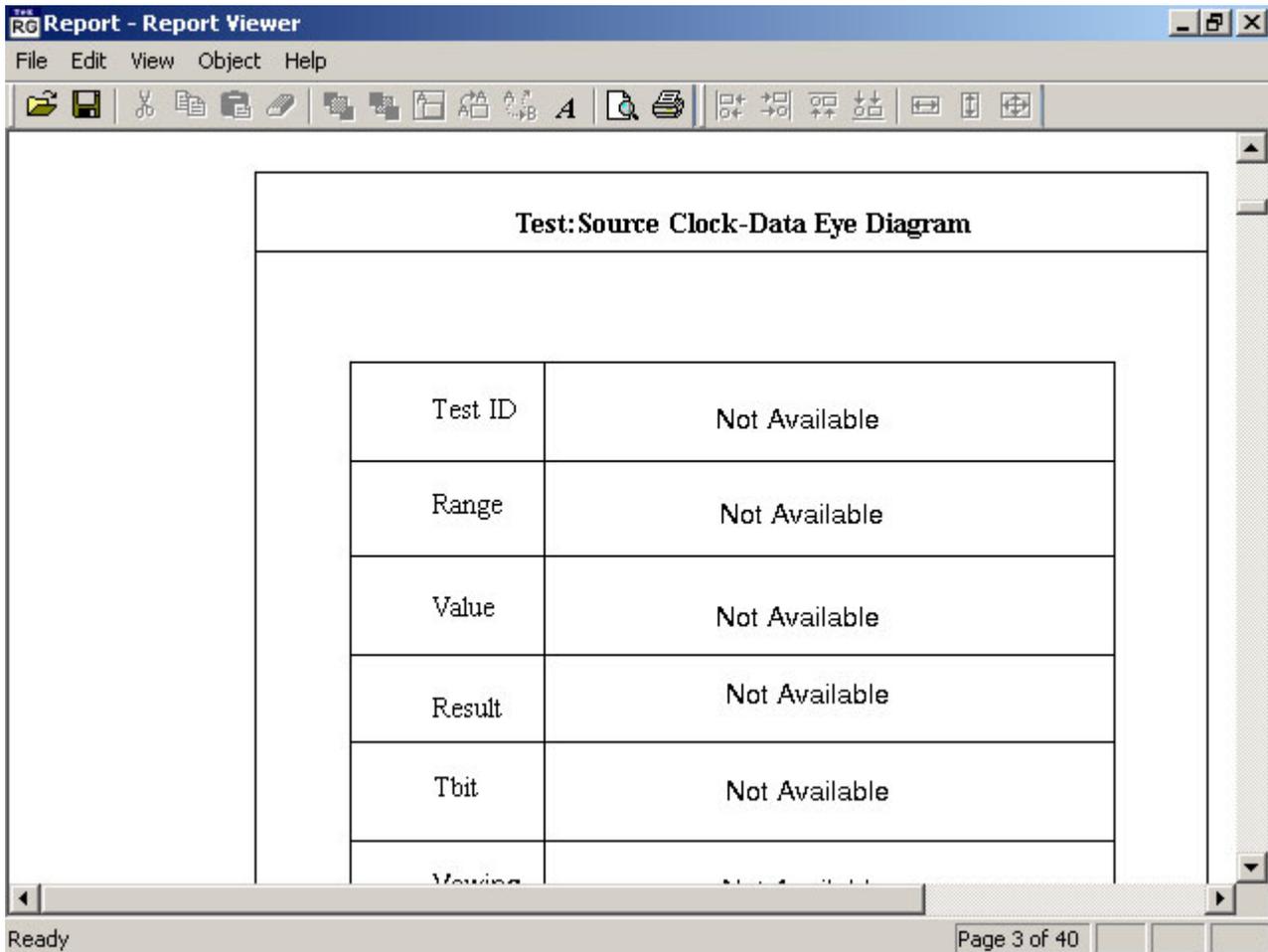


Figure 256: Report Viewer window

Menus – File menu

Table 161: File menu selection and Description

| Menu Selection | Description |
|--------------------------|---|
| Open | Click File > Open to open a template file. |
| Save | Click File > Save to save changes to the file. |
| Save As | Click File > Save As to save the template to a different file by using the Save As dialog box. |
| Print | Click File > Print to either print all or part of the contents of the active template. |
| Print Preview | Click File > Print Preview to display a sample view of the active template as it would be printed. |
| Print Setup | Click File > Print Setup to set up the printer. |
| Export to RTF | Click File > Export to RTF to export the report in rich text format (.rtf). |
| List of recent templates | Click File > List of recent templates to open a previously (recently) opened template. |
| Exit | Click File > Exit to quit Report Viewer. |

Menus – Edit menu

The available edit menu selections depend on whether a field is selected or not.

Table 162: Edit menu selection and Description

| Menu Selection | Description |
|----------------|--|
| Cut | Click Edit > Cut to cut the selected fields and place it on the clipboard. |
| Copy | Click Edit > Copy to copy the selected fields to the clipboard. |
| Paste | Click Edit > Paste to paste the clipboard content. |
| Delete | Click Edit > Delete to delete the selected fields. |
| Select All | Click Edit > Select All to select all the fields. |
| Add Text Field | Click Edit > Add Text Field to add a text field to the report. |
| Find | Click Edit > Find to find the data that matches the search criteria. |
| Replace | Click Edit > Replace to replace the data that matches the search criteria with the specified data. |
| Go To | Click Edit > Go To to go to the page number specified in the Go To Page dialog box. |

Menus – View menu

A check mark appears next to the selected command.

Table 163: View menu selection and Description

| Menu Selection | Description |
|----------------|---|
| Toolbar | Click View > Toolbar to either display or hide the standard toolbar. |
| Align/Size Bar | Click View > Align/Size Bar to either display or hide the align/size toolbar. |
| Status Bar | Click View > Status Bar to either display or hide the status bar. |
| Separators | Click View > Separators to either display or hide the separators. |

Menus – Object menu

The available object menu selections depend on whether a field in the client area is selected or not.

Table 164: Object menu selection and Description

| Menu Selection | Description |
|-------------------------------------|--|
| Bring To Front | Click Object > Bring To Front to bring the selected field to front. |
| Send To Back | Click Object > Send To Back to send the selected field back. |
| Hide Text/Show Text | Click Object > Hide Text/Show Text to either show or hide the caption of the selected field. |
| Position Caption on Top/to the Left | Click Object > Position Caption on Top/to the Left to position the caption of the selected field either to the left or on top. |
| Edit Text | Click Object > Edit Text to edit the text in the selected field. |
| Change Font | Click Object > Change Font to change the font of the selected field or the caption by using the Change Font dialog box. |
| Align Fields | Click Object > Align Fields to align fields to the top, bottom, left, or right. |
| Make Same Size | Click Object > Make Same Size to resize the selected fields to the same size by either height, width, or both. |

Menus – Help menu

Table 165: Help menu selection and Description

| Menu Selection | Description |
|---------------------|--|
| Help Topics | Click Help > Help Topics to display online help. |
| About Report Viewer | Click Help > About Report Viewer to display version and copyright information. |

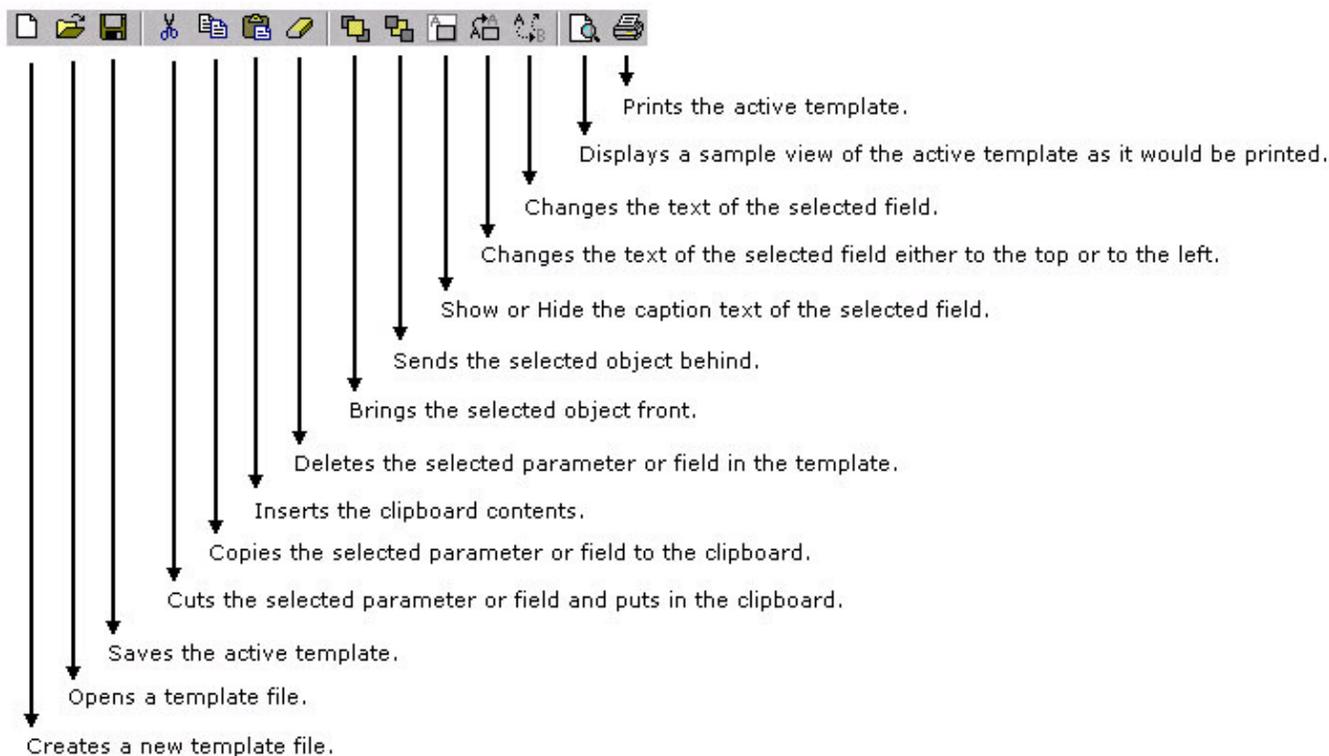
Toolbars

Click **View > Toolbars** to choose to either display or hide these toolbars.

Toolbars – Standard toolbar

View > Toolbar > Standard

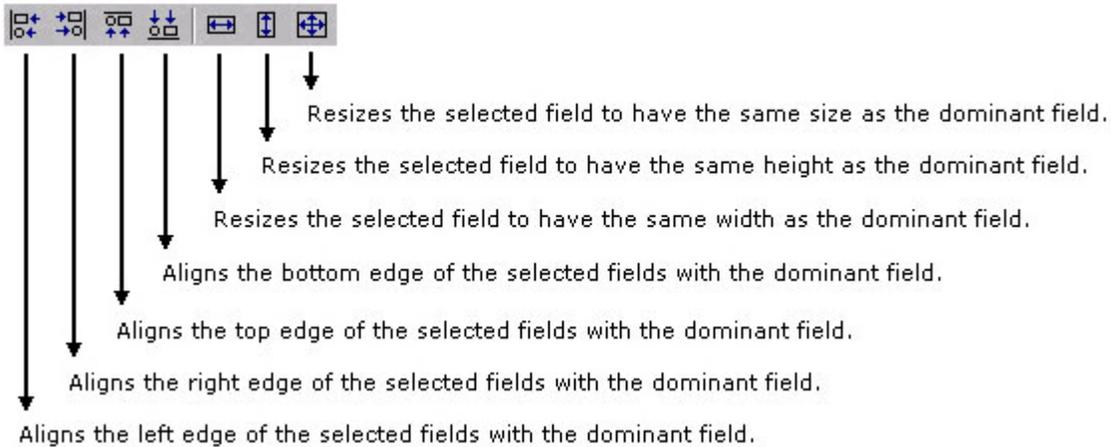
Click **View > Toolbar > Standard** to either display or hide the standard toolbar.



Toolbars – Align or Size toolbar

View > Toolbar > Align/Size

Click **View > Toolbar > Align/Size** to either display or hide the Align/Size toolbar.



Status bar

The status bar displays the status of the application and tool tips for selected options.

Separators

View > Separators

Click **View > Separators** to either display or hide the template separators.

How to Use Report Viewer

With the report viewer, you can:

- View a report
- Edit text
- Find text
- Replace text

You can select some objects and bring them front or send them back. You can show/hide text, position caption to the left, or on top. You can edit caption or

change font. You can align selected fields or make the selected fields of the same size. You can export a report to an .rtf file.

Export to RTF

File > Export to RTF

You can export a report to a rich text format (.rtf) file.

Note: Report Generator exports the report to an .rtf file in a compressed format to ensure that the file size is small. If you edit the .rtf file by using Microsoft Word, then the file size may increase.

Find

Edit > Find

You can search for text in the report.

1. Click **Edit > Find**. The **Find** dialog box appears.



Figure 257: Find dialog box

2. In the **Find** dialog box, type the search string by using the Virtual Keyboard.
3. Click **Find Next** until you find the required search string.

Replace

Edit > Replace

You can search and replace the text in the report.

1. Select Edit > Replace.

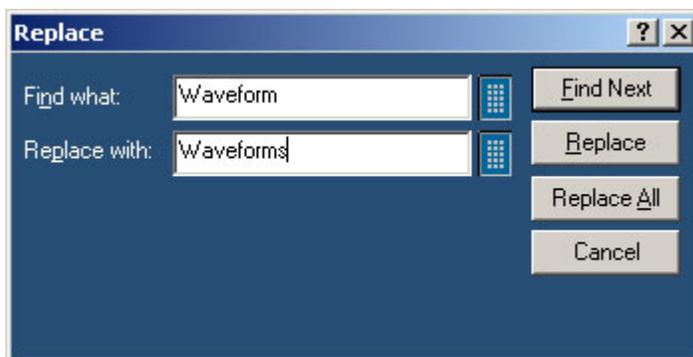


Figure 258: Replace dialog box

2. In the **Replace** dialog box, enter the search string by using the Virtual Keyboard in the **Find what** box.
3. In the **Replace with** box, by using the Virtual Keyboard, type the replacement string.
4. Click **Find Next** until you find the required search string.
5. Click **Replace** to replace one instance of the string, or click **Replace All** to replace all instances of the string.
6. Click **Cancel** after you have replaced the strings.

Bring To Front

Object > Bring To Front

You can bring the selected fields to the front.

Send To Back

Object > Send To Back

You can send the selected fields back.

Show/Hide Text

Object > Show/Hide Text

You can either show or hide the captions for the selected fields.

Position Caption

Object > Position Caption to the Left, or on Top

You can position the caption of the selected fields either to the left or on the top.

Edit Caption

Object > Edit Caption

You can edit the caption of the selected parameter or object.

1. Click **Object > Edit Caption**. The **Edit Caption** dialog box appears.

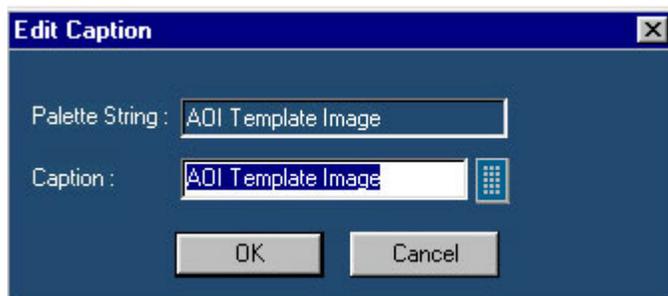


Figure 259: Edit Caption dialog box

2. In the **Edit Caption** dialog box, click the icon next to the **Caption** box to enter the caption by using the Virtual Keyboard.
3. Click **OK**.

Change Font

Object > Change Font

You can change font for the selected field in the template.

1. Select the field or fields in the active template.

2. Click **Object > Change Font** or right-click the field to display the options.

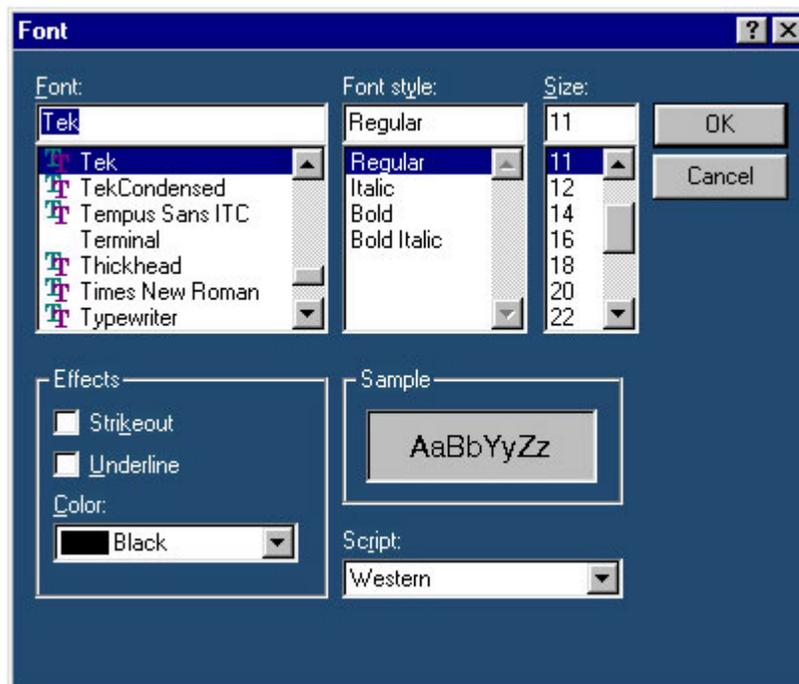


Figure 260: Font dialog box

3. In the **Font** dialog box, choose the font size, color, style, and effects.
4. Click **OK**.

Align Fields

Object > Align Fields

You can align the fields to either top, bottom, left, or right.

1. Select the fields in the active template.
2. Click **Object > Align Fields > Top, Bottom, Left, or Right** to align the fields accordingly.

Make Same Size

Object > Make Same Size

You can set the selected fields to either the same height, width, or both.

1. Select the fields in the active template.

2. Click **Object > Make Same Size > Height, Width, or Both** to make the selected fields of the same size.

How to...

Create or Edit a Test Template

Utilities > Report Generator > Define Test Template

You can either create a new test template or edit an existing template.

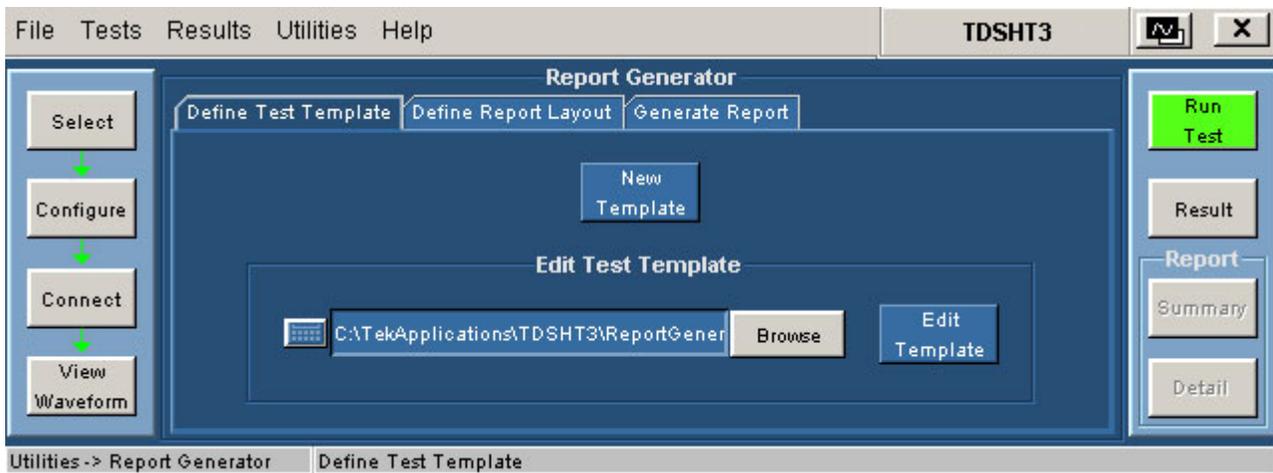


Figure 261: Define Test Template pane

To create a new test template

1. On the **Define Test Template** tab, click **New Template**.
2. The Template Editor window appears with an empty client area.
3. Create the template by using the palette list.
4. After you create a new test template, click **Done**.

To edit an existing test template

1. On the **Define Test Template** tab, click **Browse**. The **Open** dialog box appears.



Figure 262: Open dialog box to edit an existing test template

2. The **Open** dialog box displays the existing factory default templates and customized templates in the path
C:\TekApplications\TDSHT3\ReportGenerator\Templates.
3. Select the template that you want to use, and then click **Open**.
4. On the **Define Test Template** tab, click **Edit Template**.
5. The Template Editor window appears with the client area displaying the selected template.
6. Edit the template by using the palette list.
7. After you edit an existing test template, click **Done**.

Define or Edit a Report Layout

Utilities > Report Generator > Define Report Layout

You can either create a new report layout or edit an existing report layout.

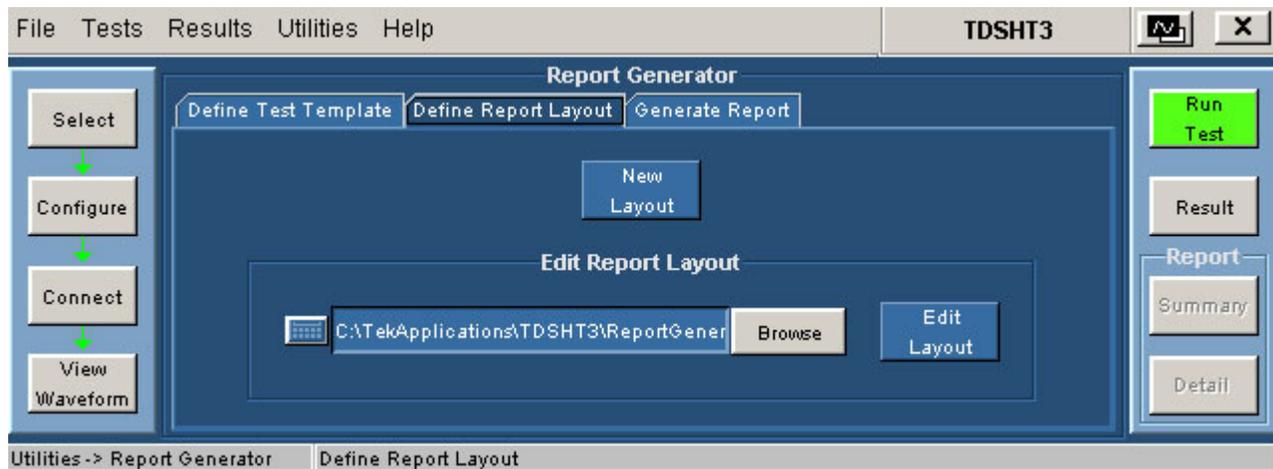


Figure 263: Define Report Layout pane

To create a new report layout

1. On the **Define Report Layout** tab, click **New Layout**.
2. The Report Layout Editor window appears with an empty report layout area.
3. Create the report by defining the report layout and dragging and dropping the templates to the report layout area.
4. After you create a new report layout, click **Done**.

To edit an existing report layout

1. On the **Define Report Layout** tab, click **Browse**. The **Open** dialog box appears.

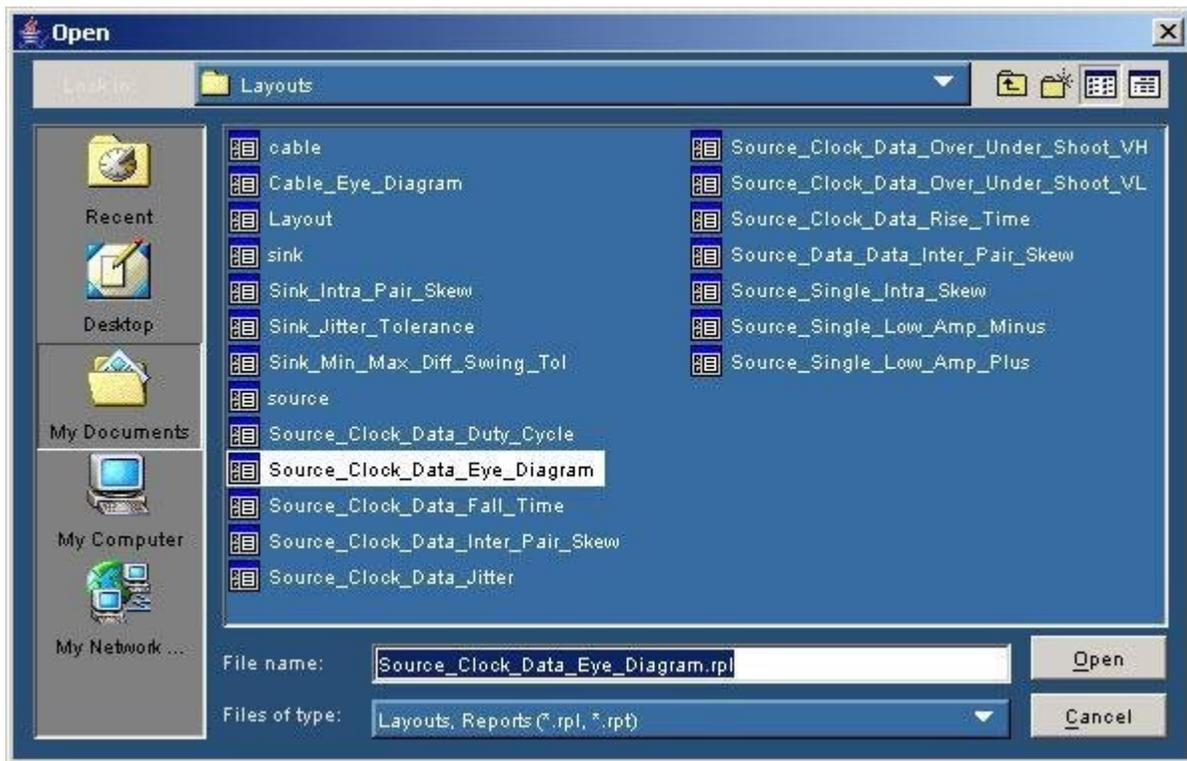


Figure 264: Open dialog box to edit an existing report layout

2. The **Open** dialog box displays the existing factory default report layout and customized report layouts in the path
C:\TekApplications\TDSHT3\ReportGenerator\Layouts.
3. Select the report layout that you want to use, and then click **Open**.
4. On the **Define Report Layout** tab, click **Edit Layout**.
5. The Report Layout Editor window appears with the report layout area displaying the customized report layout and the selected template files.
6. Edit the report layout by using the list of templates and defining the report layout.
7. After you edit an existing report layout, click **Done**.

Generate, Print, or View a Report

Utilities > Report Generator > Generate Report

You can generate, print, or view a report.

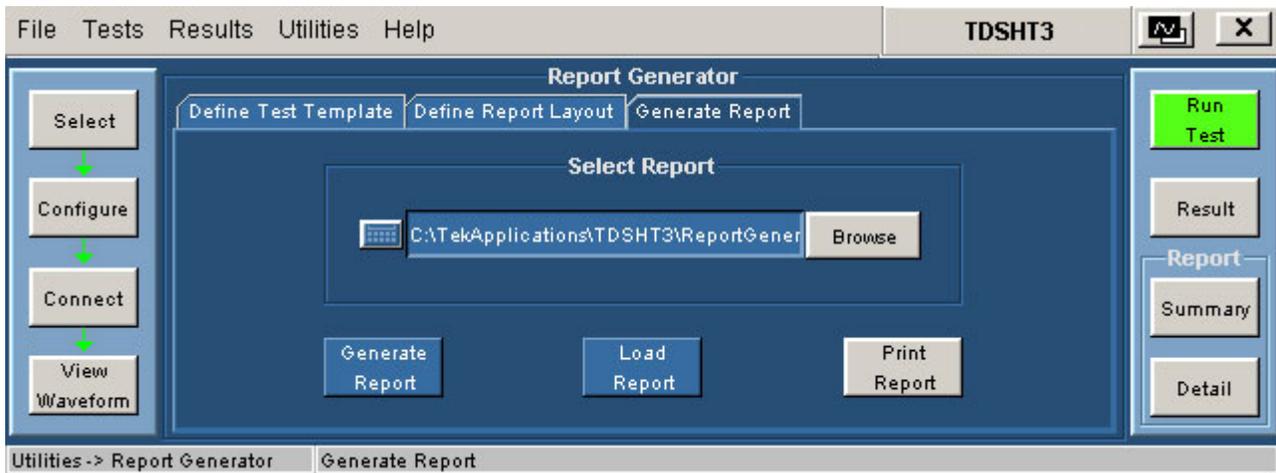


Figure 265: Generate Report pane

To generate a report

1. On the **Generate Report** tab, click **Browse**. The **Open** dialog box appears.

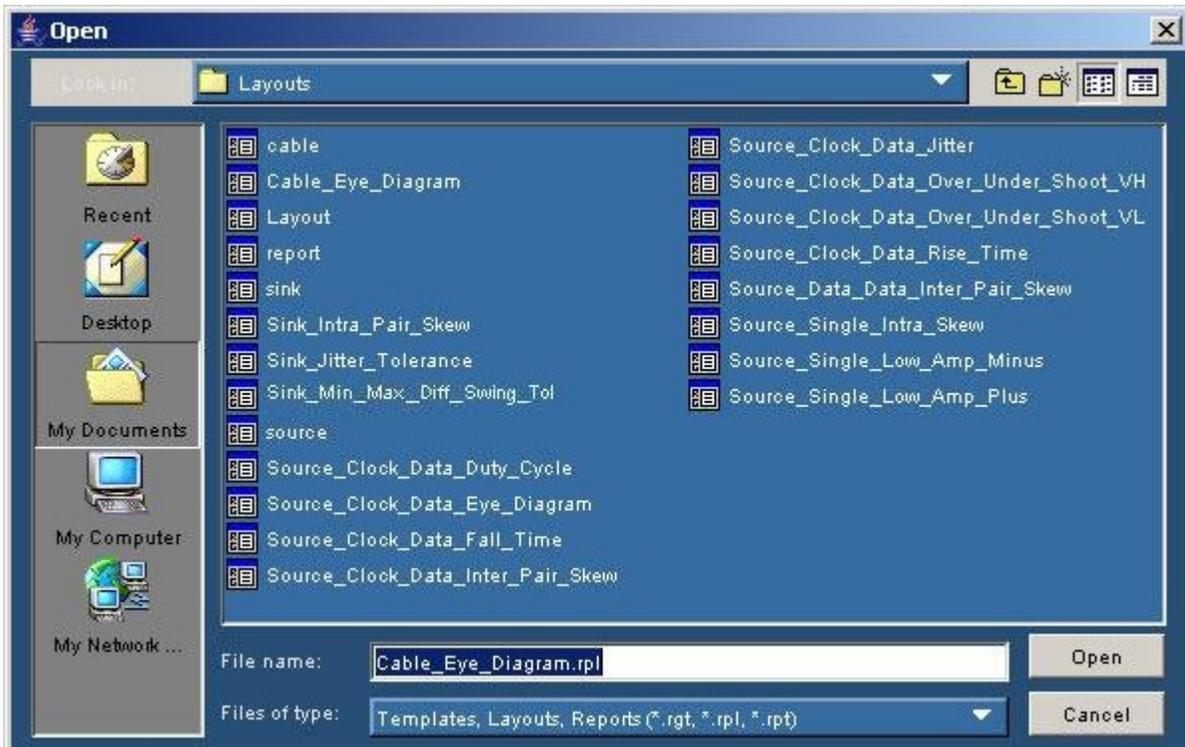


Figure 266: Open dialog box to generate a report

2. The **Open** dialog box displays the existing reports in the path C:\TekApplications\TDSHT3\ReportGenerator\Reports.
3. Select the report that you want to generate, and then click **Open**.

4. On the **Generate Report** tab, click **Generate Report**.

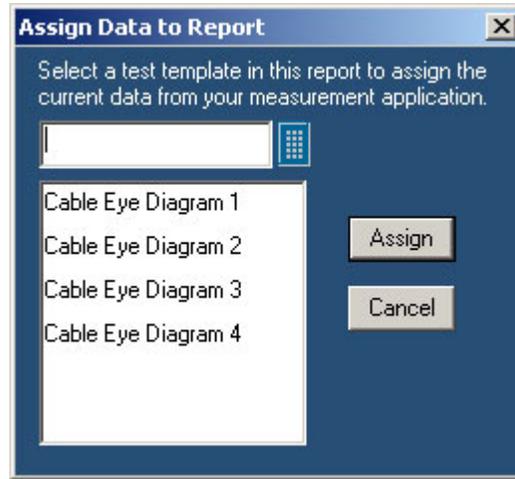


Figure 267: Assign Data to Report dialog box

5. In the **Assign Data to Report** dialog box, select a test template in this report to assign the current data from your test software.
6. Click **Assign**. Report Viewer displays the report with the current data from the software. You can choose to export the report to a .rtf format file.

To print a report

1. On the **Generate Report** tab, click **Browse**. The **Open** dialog box appears.

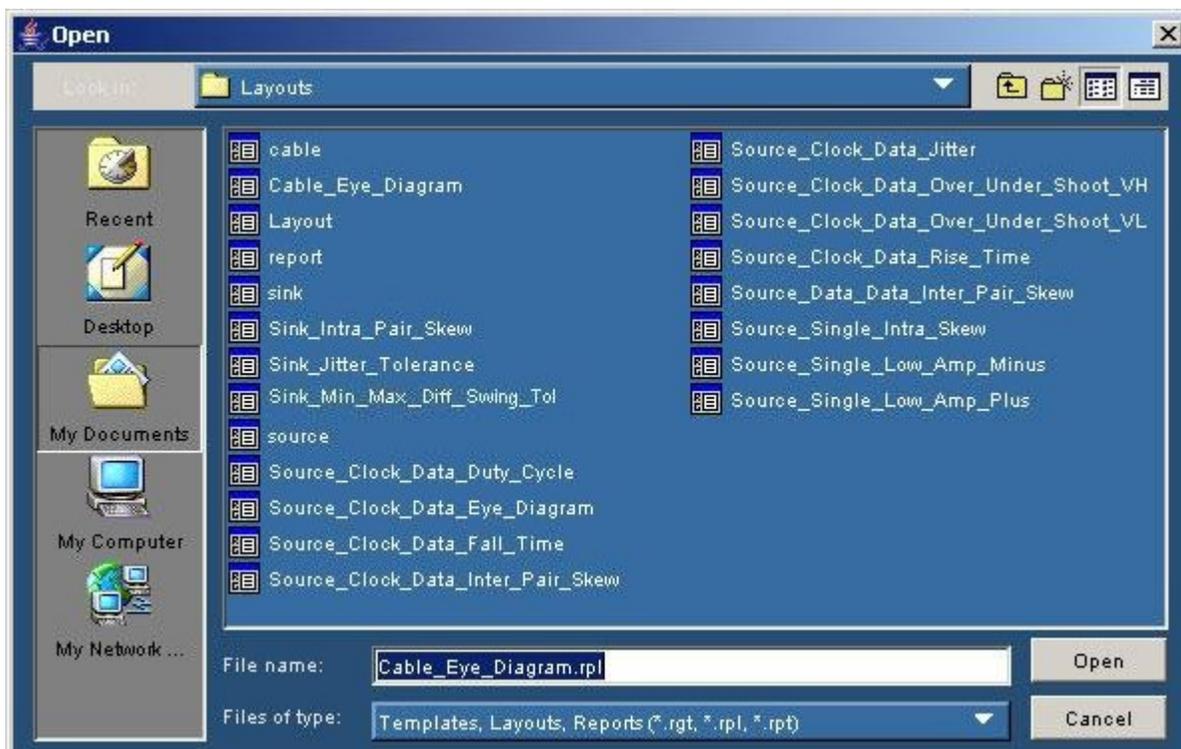


Figure 268: Open dialog box to print a report

2. The **Open** dialog box displays the existing reports in the path C:\TekApplications\TDSHT3\ReportGenerator\Reports.
3. Select the report that you want to print, and then click **Open**. Report Viewer displays the selected report with the current data from the software.
 - If the page settings do not match the page settings for the report, a **Page Size Mismatch** dialog box appears.
 - Click **Yes** to continue.
 - Click **No** to stop printing the report.
 - If the printer is available, the report is printed.

Report Generator Error Codes

Table 166: Report Generator Error Codes

| Error Code | Error Message | Description | Possible Solution |
|---|--|--|--|
| Report Generator Interface Error Codes | | | |
| 741 | Some installation files are missing or corrupted, try reinstalling the application. The application will now exit. | The application FDB file path that is retrieved from the registry is either corrupted or the file path is invalid. | Remove the application and try reinstalling. |
| 742 | Some installation files are missing or corrupted, try reinstalling the application. The application will now exit. | Application id that is retrieved from the registry is invalid (< 0). | Remove the application and try reinstalling. |
| 743 | Some installation files are missing or corrupted, try reinstalling the application. The application will now exit. | The application version is invalid. | Remove the application and try reinstalling. |
| 744 | Some installation files are missing or corrupted, try reinstalling the application. The application will now exit. | The application is unable to spawn Report Viewer. | Report Viewer executable file is missing, or there might be a resource crunch if there are many applications currently running. Try closing some of the other applications. If this does not work, then remove and reinstall the application. |
| 745 | Internal initialization error. The application will exit now. | The memory map file or synchronization events for communication with RGScope are already open. The application was previously not shut down completely. Try closing RGScope. | The application was not closed completely last time. A module RGScope might be still running in the background. Try closing it. |

Table 166: Report Generator Error Codes (Contd.)

| Error Code | Error Message | Description | Possible Solution |
|------------|--|---|--|
| 746 | Some installation files are missing or corrupted, try reinstalling the application. The application will exit now. | The application is unable to spawn the oscilloscope interface. | RGScope file is missing, or there might be a resource crunch if there are many applications currently running. Try closing some of the other applications. If this does not work, then remove and reinstall the application. |
| 747 | Some installation files are missing or corrupted, try reinstalling the application. The application will exit now. | The application FDB file read failed. The file may be read only. | Remove and reinstall the application. |
| 748 | Some installation files are missing or corrupted, try reinstalling the application. The application will exit now. | The Acc application FDB file read failed. The file may be read only. | Remove and reinstall the application. |
| 749 | Some installation files are missing or corrupted, try reinstalling the application. The application will exit now. | Not invoked by the desired application. The application name passed by the invoking application is not found in the registry. | Remove and reinstall the application. |
| 750 | Some installation files are missing or corrupted, try reinstalling the application. The application will exit now. | The application is unable to spawn the Report Layout Editor. | The Report Layout Editor executable file is missing, or there might be a resource crunch if there are many applications running currently. Quit some of the other applications. If this does not work, then remove and reinstall the application. |
| 751 | Some installation files are missing or corrupted, try reinstalling the application. The application will exit now. | The application is unable to spawn the Template Editor. | The Template Editor executable file is missing, or there might be a resource crunch if there are many applications running currently. Quit some of the other applications. If this does not work, then remove and reinstall the application. |

Report Layout Editor Error Codes

| | | | |
|-----|---|---|---------------------------------------|
| 721 | Some installation files are missing or corrupted, try reinstalling the application. | Not invoked by the desired application. The application name passed by invoking the application is not found in the registry. | Remove and reinstall the application. |
| | | | |
| | | | |

Table 166: Report Generator Error Codes (Contd.)

| Error Code | Error Message | Description | Possible Solution |
|---|--|--|---|
| 722 | The Selected file is not a valid layout for this application. | The layout belongs to some other application. | The layout file being opened belongs to an older application, which may have been removed. It is not possible to open a file belonging to another application. |
| 723 | Layout file is not valid for the current version of the Application. | The layout was created for some other version of the application. | The opened layout file belongs to a different version of the same application, which may have been removed. It is not possible to open a file belonging to another version. |
| Template Editor Error Codes | | | |
| 761 | Error in Initialization of Application. | The dlls and application executables are not properly installed. | Remove and reinstall the application. |
| 762 | Invalid Application Name. | The registry entries are not appropriate. | Remove and reinstall the application. |
| 763 | The Selected file is not a valid template for this application. | The template belongs to some other application. | The opened template file belongs to a different version of the same application, which may have been removed. It is not possible to open a file belonging to another version. |
| 764 | Template file is not valid for the current version of the Application. | The template was created for some other version of the application. | The opened template file belongs to a different version of the same application, which may have been removed. It is not possible to open a file belonging to another version. |
| 765 | A Group with the specified name already exists. | The user tried to create a custom group with the same name as an existing group. | Try to use a different name other than the existing groups. |
| Oscilloscope Interface Error Codes | | | |
| 781 | MFC initialization failed. | The MFC dlls are not properly installed. | Reinstall the application. |
| 782 | Error in creating or setting system resource. | The system resources that are required for communication are already open. | Quit all the application related executables and try again. |
| 783 | RGScope already running. | RGScope.exe is already running on the system. | Quit RGScope and restart the application. |
| 784 | Memory exception occurred + <context specific message>. | The application has performed an illegal memory access. | Quit the application and restart. |
| 785 | An exception occurred. | An unknown exception has occurred in the application. | Quit the application and restart. |
| 786 | File Exception occurred + <context specific message>. | An exception occurred while accessing a file. | Quit the application and restart. |

Table 166: Report Generator Error Codes (Contd.)

| Error Code | Error Message | Description | Possible Solution |
|------------|---|---|--|
| 787 | Error in acquiring window resources + <context specific message>. | The application was not able to acquire windows resources such as GDI objects. | Quit the application and restart. |
| 788 | Failed to connect to the oscilloscope. | The application was not able to connect to the oscilloscope. Ensure that TekScope.exe is running. | If this does not solve the problem, then reinstall the application. |
| 789 | Error querying registry. | Either the required registry key does not exist or an error occurred while getting its value. | Quit the application and restart. If this does not solve the problem, then reinstall the application. |
| 790 | Error in reading FDB file. | Either the FDB file does not exist or it may be read-only. | Ensure that the FDB file is present and not read-only. If this does not solve the problem, then reinstall the application. |
| 791 | Invalid frame received. | Oscilloscope interface received an invalid message from RG interface. | Quit the application and restart. |
| 792 | Error in allocating memory. | There was an error in getting memory from the system. | Quit one or more applications running on the system, and then restart RGAApp. |
| 793 | <context specific message>. | There was an error in creating the jpeg file. | Ensure that the 'temp' folder exists and there is sufficient free space on the hard disk drive. |

Message Boxes and Dialogs in the User Interface

| | | | |
|-----|---|--|---|
| 701 | Error initializing Report Generator. | The system resources cannot be allocated. Try closing some of the other applications. | If this does not work, then remove and reinstall the application. |
| 702 | No valid file name was provided. | This happens when no filename is selected in the application for generating a report. | Select a valid file. |
| 703 | <Path of the file selected> The template file name is invalid. | The reading of the template file fails. This will happen if the application fails to read the .rgt file. | Select another valid template file. |
| 704 | <filename> is not a valid Report Layout. | An invalid report layout was provided. This happens if the application fails to read the layout file. | Select another valid layout file. |
| 705 | <filename> is not a valid Report Layout file for the application. | The layout is not valid for the application. This means that the file was read properly but the application name and version for the .rpl file do not match that of the application. | Select another valid layout file for the application. |
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Table 166: Report Generator Error Codes (Contd.)

| Error Code | Error Message | Description | Possible Solution |
|------------|--|--|--|
| 706 | Invalid report file specified. | A file other than the Report Generator file(s) is selected with the extension (.rpt, .rgt, .rpl) used by Report Generator files. | Select another valid file. |
| 707 | Invalid file format. | Other file types such as text are selected. | Select another valid file. |
| 708 | <filename> is not a valid report file for <AppName>. | The application name and version for the report file do not match that of the application. | Select another valid report file for that application. |
| 709 | Unable to read the report file. | An exception occurs for a rpt file. This happens if the application cannot read the report .rpt file. | Select another valid report file for that application. |